

**Report 11384  
January 1999**

**AMSU-A VERIFICATION TEST REPORT  
METSAT PHASE LOCKED OSCILLATOR ASSEMBLY**

**TEST ITEM:  
AMSU-A PHASE LOCKED OSCILLATOR ASSEMBLY  
P/N 1348360-1  
SERIAL NUMBERS F09, F10**

**PREPARED FOR  
NATIONAL AERONAUTICS AND SPACE ADMINISTRATION  
GODDARD SPACE FLIGHT CENTER  
GREENBELT, MARYLAND 20771**

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AZUSA, CALIFORNIA 91702-0296**



Summary of Test Results for AMSU-A Phase Locked Oscillator Testing  
Serial Numbers F09 and F10

Paragraph	Description	Requirements	F09	F10
3.2.1.1	Input Voltage and Current	600 mA max, +15V 100 mA max, -15V	522 mA for +15V, 64 mA for -15V	533 mA for +15V, 70 mA for -15V
3.2.1.2	Operating Temperature	+1°C to 44°C	-24°C to +60°C	0°C to 57°C
3.2.1.3	Start-up	All loads, +60°C and -30°C; in vacuum	Verified at +60 and -30°C, ambient	Verified at +60 and -30°C, ambient
3.2.1.4 & 3.2.1.5	Frequency Stability from 57.290344 GHz	±200 kHz	+0kHz, -33 kHz	+16 kHz, -0 kHz
3.2.1.6	RF Output Power	17 to 20 dBm	18.1 dBm	17.9 dBm
3.2.1.7	Output Power Stability	<1.5 dB	1.4 dB	1.5 dB
3.2.1.8	Load VSWR	2.01:1 or less	Verified	Verified
3.2.1.9	AM Noise	<-130 dBc/Hz @ 1 MHz	-145 dBc/Hz @ 1MHz	-140 dBc/Hz @ 1Mhz
3.2.1.10	FM Noise	<-100 dBc/Hz @ 1 MHz	-104 dBc/Hz @ 1 MHz	-105 dBc/Hz @ 1 MHz
3.2.1.11	Spurious and Sub-Harmonic Signals	<-90 dBc	< -90 dBc	< -90 dBc
3.2.1.12	Harmonics	<-30 dBc	-40 dBc	- 70 dBc
3.2.1.14	Warm-up Time	< 30 minutes	Verified	Verified
3.2.1.15	Grounding and Shielding		By Design	By Design
3.2.1.16	Input Voltage Protection		By Design	By Design
3.2.1.17	Reverse Polarity Protection		By Design	By Design
Environmental Testing				
Microphonics		AE-26633	TCXO Test	TCXO Test
Radiation Hardness		AE-26633	By Analysis	By Analysis
EMI/RFI		AE-26633	Not Required	Not Required
Vibration		AE-26633	Acceptance Level	Acceptance Level
Thermal Vacuum		AE-26633	Verified at Ambient Pressure Only	Verified at Ambient Pressure Only
Weight		2.0 lbs	2.0 lbs	2.0 lbs



## **1.0 SUMMARY**

Two Flight Model AMSU-A Phase Locked Oscillators (P/N 1348360-1, S/N F09 and F10) have been tested per AES Test Procedure AE-26758 Rev. C, which includes full functional testing, vibration testing, thermal testing, and AM/FM Noise testing. Both assemblies satisfactorily passed all performance requirements of the AE-26633 Product Specification.

During the manufacture of PLO F09, the DRO CCA lid was rotated 180 degrees, which rendered the unit unable to lock. After removing the 10 fastening screws and installing the lid in the correct orientation, the unit functioned to all specifications. During the vibration of PLO F10, the dielectric puck of the DRO was dislodged from its bonded attachment to the CCA. The PLO and DRO were opened, the puck was re-attached, and the unit was restored to full operation. The MAI was enhanced to increase the reliability of the bonding.

## **2.0 REQUIREMENTS**

The acceptance test procedure AE-26758C consists of tests designed to show compliance of the Phase Locked Oscillator with all requirements stated in the PLO Product Specification AE-26633. The tests reported herein demonstrate the acceptability of the AMSU-A PLO assemblies S/N's F09 and F10, and therefore compatibility with the AMSU-A Receiver Assembly.

## **3.0 RESULTS**

The results of the required tests are presented in the following section as test data. As indicated on the test data sheets, all measured data passed all requirements associated with the product specification.

## **4.0 TEST DATA**

A summary of the test data is provided at the start of each of the acceptance test sections. Furthermore, the raw data is reproduced as recorded, and is included in each section. The following table provides a concise summary of each unit's performance ability.



The remainder of this report contains the raw data taken during the tests of the two flight PLOs. The data is arranged by the following segmentation:

- Section 1A: Initial Functional Testing - F09
- 1B: Initial Functional Testing - F10
- Section 2A: Acceptance Level Vibration - F09
- 2B: Acceptance Level Vibration - F10
- Section 3A: Frequency and Power Hysteresis - F09
- 3B: Frequency and Power Hysteresis - F10
- Section 4A: EMI/RE02 Testing - F09 (not required)
- 4B: EMI/RE02 Testing - F10 (not required)
- Section 5A: Final Functional Testing - F09
- 5B: Final Functional Testing - F10
- Section 6A: AM/FM Noise Levels - F09
- 6B: AM/FM Noise Levels - F10



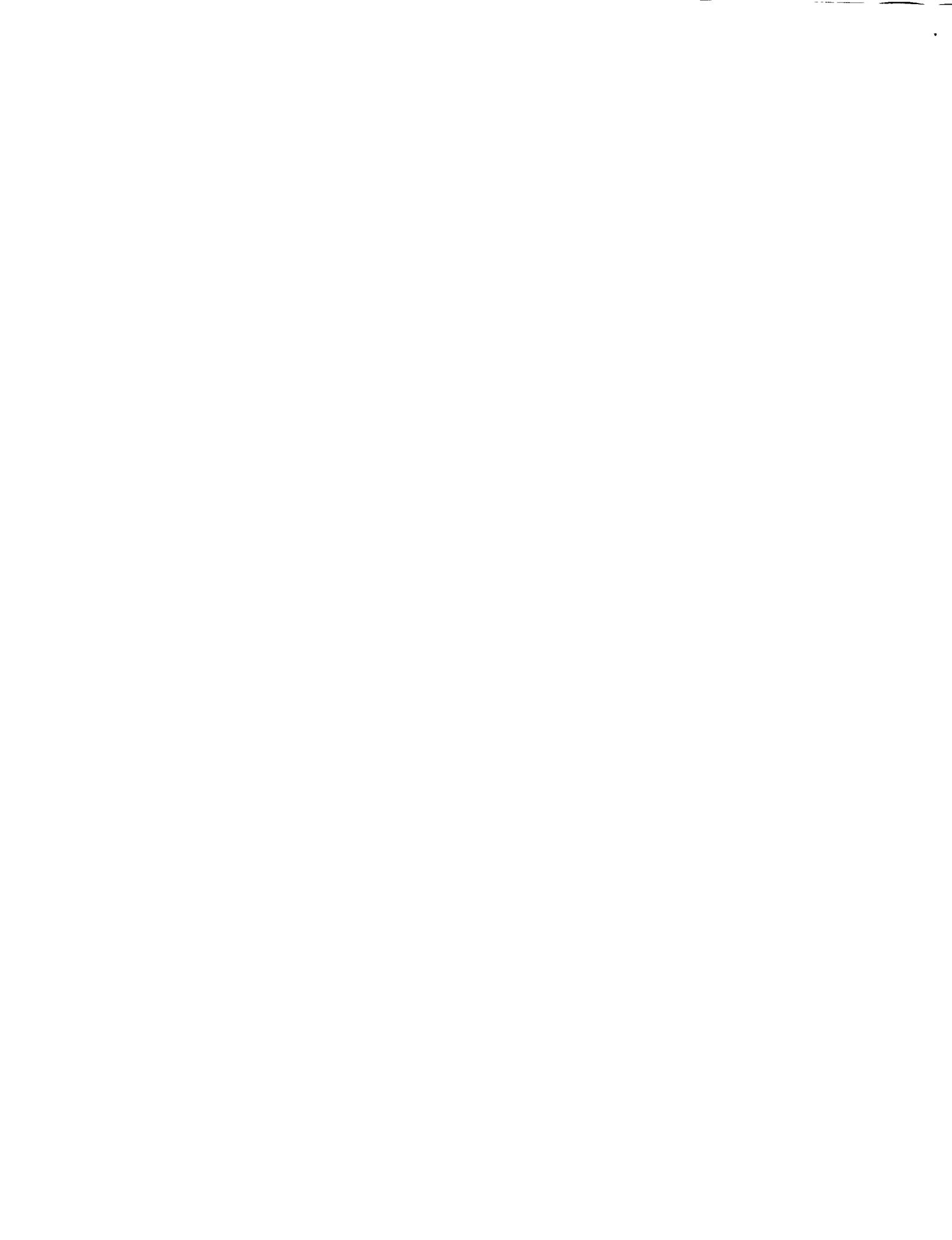
The remainder of this report contains the raw data taken during the tests of the two flight PLOs. The data is arranged by the following segmentation:

- Section 1A: Initial Functional Testing - F09
- 1B: Initial Functional Testing - F10
- Section 2A: Acceptance Level Vibration - F09
- 2B: Acceptance Level Vibration - F10
- Section 3A: Frequency and Power Hysteresis - F09
- 3B: Frequency and Power Hysteresis - F10
- Section 4A: EMI/RE02 Testing - F09 (not required)
- 4B: EMI/RE02 Testing - F10 (not required)
- Section 5A: Final Functional Testing - F09
- 5B: Final Functional Testing - F10
- Section 6A: AM/FM Noise Levels - F09
- 6B: AM/FM Noise Levels - F10



### **Section 1A: Initial Functional Testing - F09**

This section contains the results of a full functional test over temperature taken before PLO F09 endured thermal cycling. All tests passed.



TEST DATA SHEET 6A (Sheet 1 of 4)  
Functional Testing (Paragraph 4.2.1)

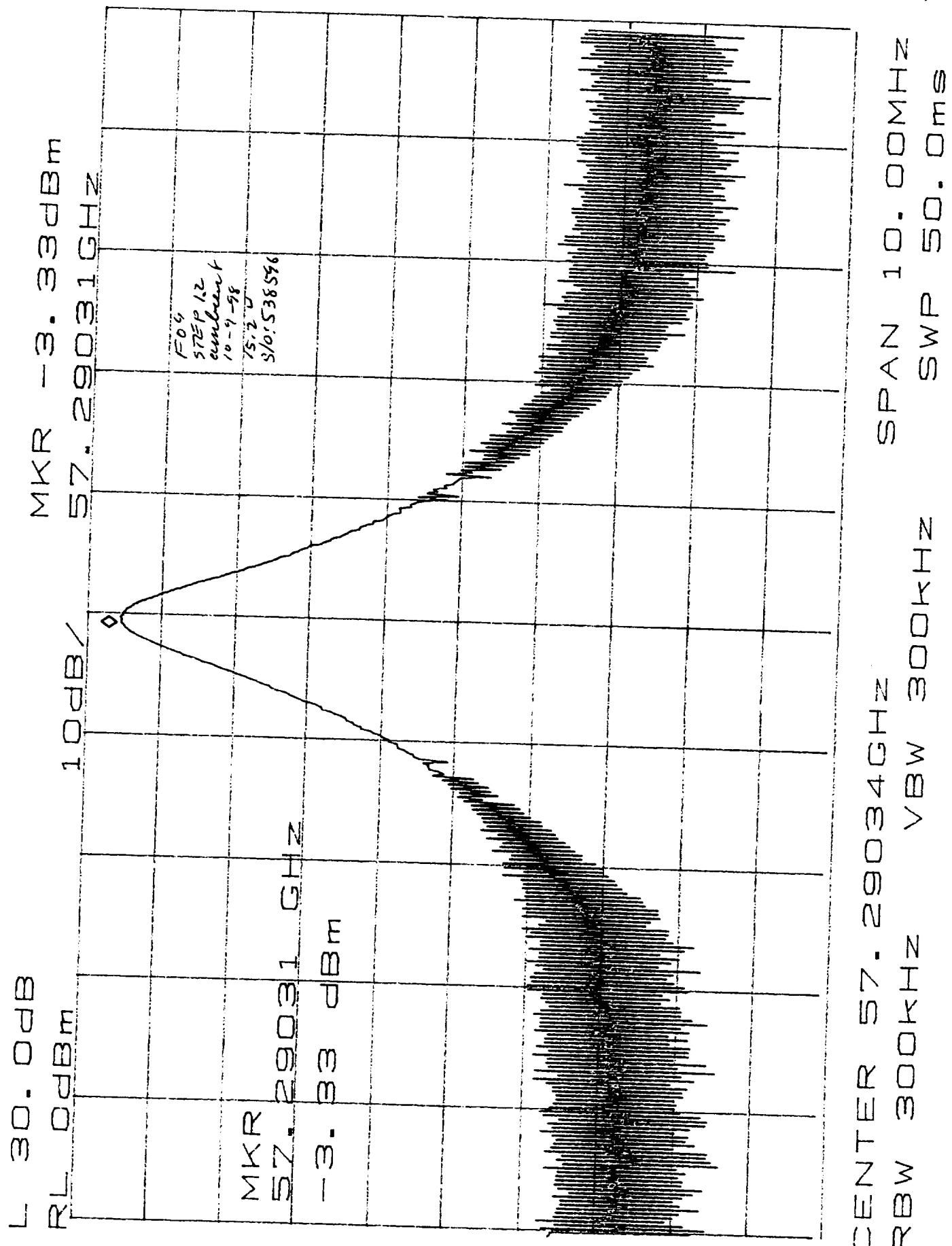
Pre-Environmental CPT

Test Setup Verified: Signature  
Signature

Paragraph 4.2.1.3, Functional Testing:

Step	Test	Expected	Measured	Pass/Fail
1	Potential Difference from $\pm 15$ V RTN to:			
	PLO Base Plate	< 1.0 Vac	0.01	Pass
	Spectrum Analyzer	< 1.0 Vac	0.03	Pass
	Frequency Counter Chassis	< 1.0 Vac	0.01	Pass
	Power Meter Chassis	< 1.0 Vac	0.04	Pass
4	Evacuate vacuum chamber and record pressure	$<10^{-2}$ torr	N/A <i>OK AS IS SURVEYING 11-12-98</i>	N/A*
5	Thermal couple readings	TC1 = $22 \pm 2$ °C	TC1 = <u>22.3</u> °C	Pass
			TC2 = <u>22.5</u> °C	N/A
			TC3 = <u>21.8</u> °C	N/A
6	DRO L/A	0 to 1V	DRO L/A = <u>78 mV</u>	Pass
	PLO L/A	4.3 - 4.7 V to 1V	PLO L/A = <u>4.52 V</u>	Pass
	Is PLO locked?	Yes <i>10/12/98</i>	Yes <input checked="" type="checkbox"/>	
7	PLO Frequency	$57.290344 \pm .0002$ GHz	Freq. = <u>57.290321180</u> GHz	Pass
	PLO Power	17 to 20 dBm	P = <u>17.77</u> dBm	Pass
8	Input Voltage and Current			
	VM1 Voltage	$+15 \pm 0.1$ V	VM1 = <u>+15.40</u> V	Pass
	VM2 Voltage	$-15 \pm 0.1$ V	VM2 = <u>-15.19</u> V	Pass
	IM1 Current	600 mA max.	IM1 = <u>522 mA</u> mA	Pass
	IM2 Current	100 mA max.	IM2 = <u>-64.7 mA</u> mA	Pass
	DRO L/A Voltage	4.3 - 4.7 V to 1V	DRO L/A = <u>4.52 V</u> <i>78 mV</i>	Pass
12	RF Output Power and Frequency	17 to 20 dBm	P = <u>17.77</u> dBm	Pass
		$57.290344 \pm .0002$ GHz	Freq. = <u>57.290321180</u> GHz	Pass
		Baseplate Temp. (TC1)	TC1 = <u>22.3</u> °C	Pass
13	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+15.2 $\pm 0.05$ V	+Voltage = <u>15.20</u> V	Pass
		-15.2 $\pm 0.05$ V	-Voltage = <u>15.2</u> V	Pass
		$57.290344 \pm .0002$ GHz	Freq. = <u>57.290321322</u> GHz	Pass
		17 to 20 dBm	P = <u>17.67</u> dBm	Pass

\*Record data only if performing test under vacuum

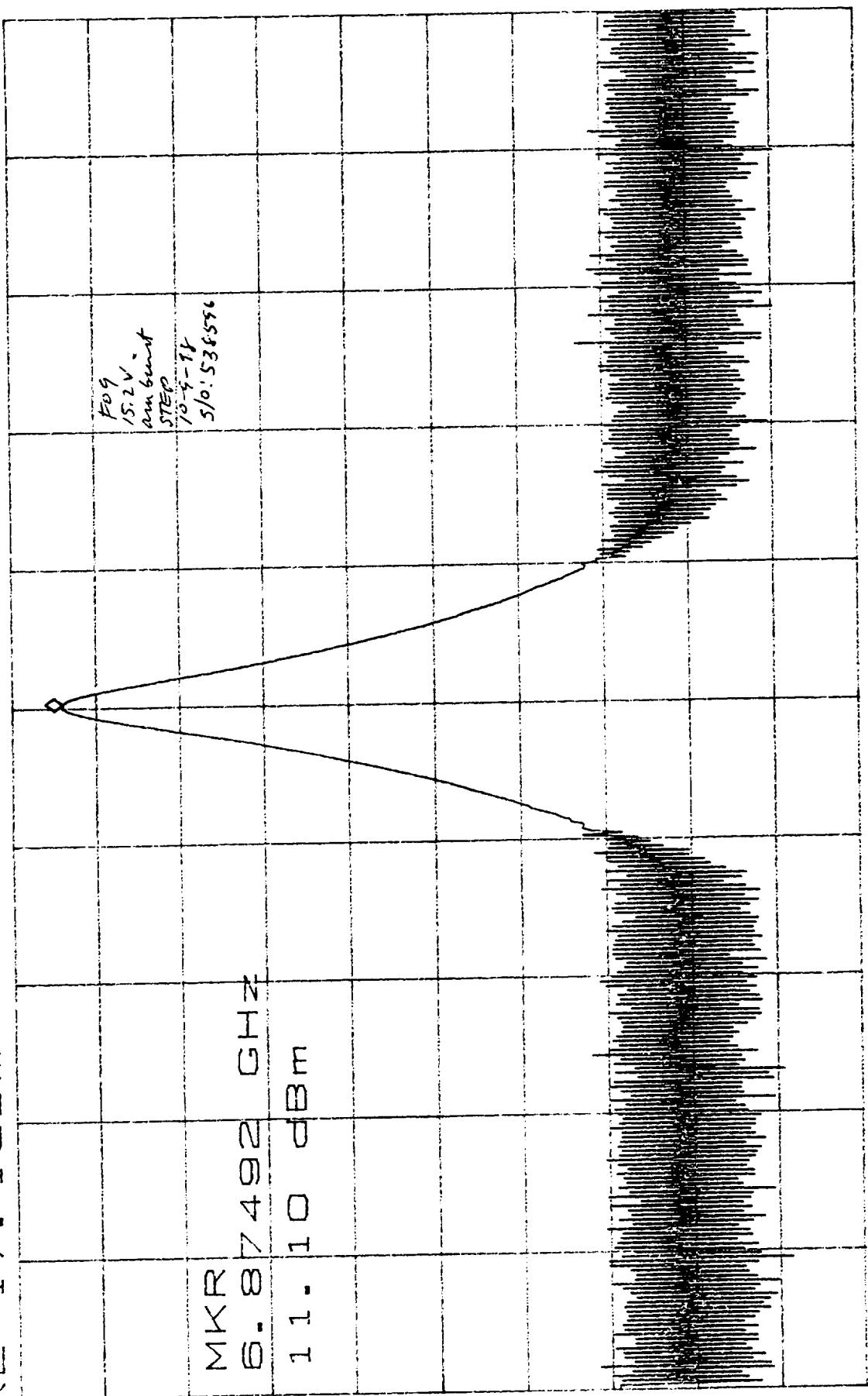


ATTEN 30dB  
RL 17. 1dBm

MKR 11. 10dBm  
RL 17. 1dBm  
10dB / 6. 87492GHz

F09  
15.2V  
run limit  
STEP  
13-4-14  
5/6.536596

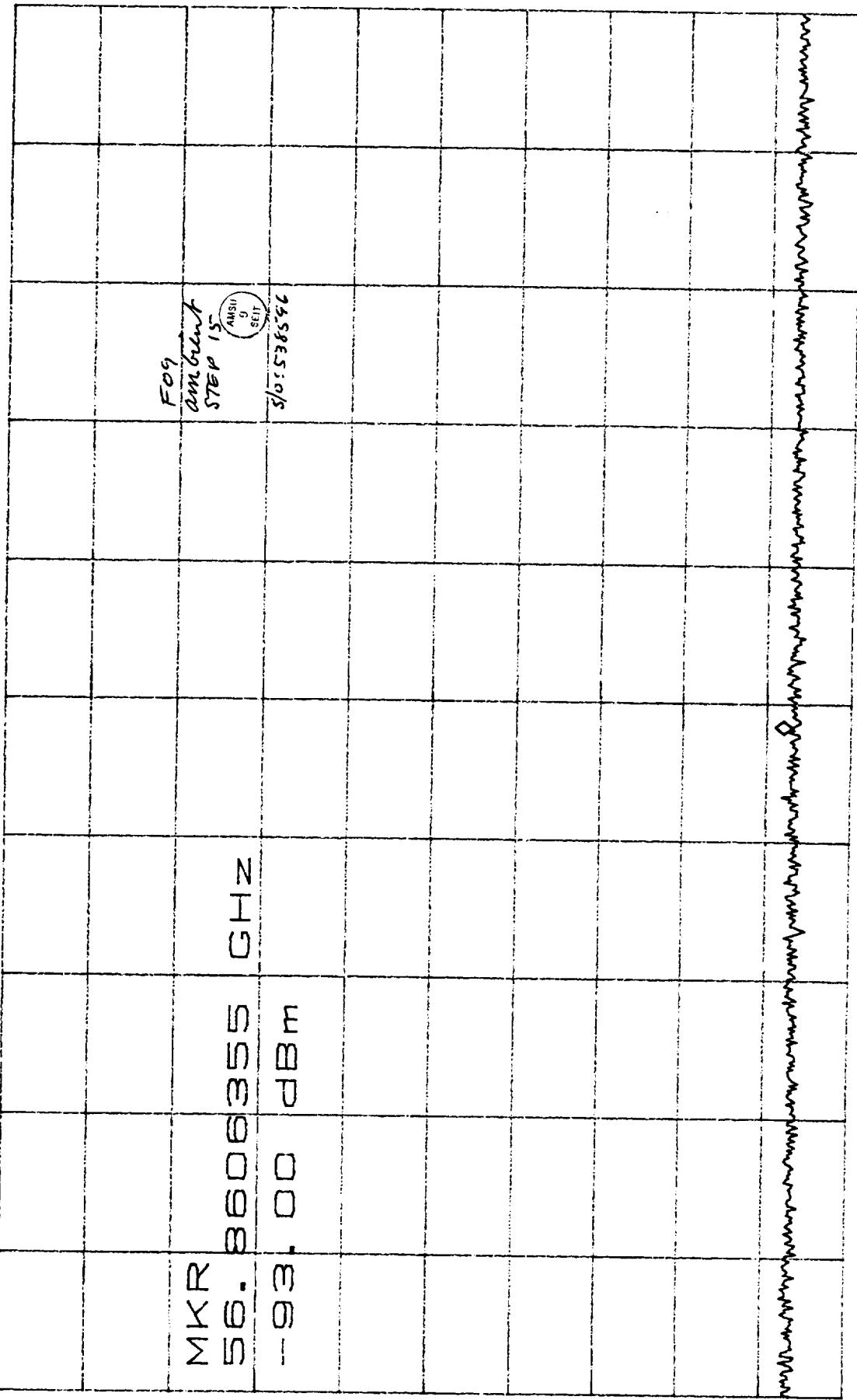
MKR  
6.87492 GHz  
11.10 dBm



CENTER 6.87485GHz \*VBW 300kHz  
\*RBW 300kHz

SPAN 20.00MHz  
SWP 50.0ms

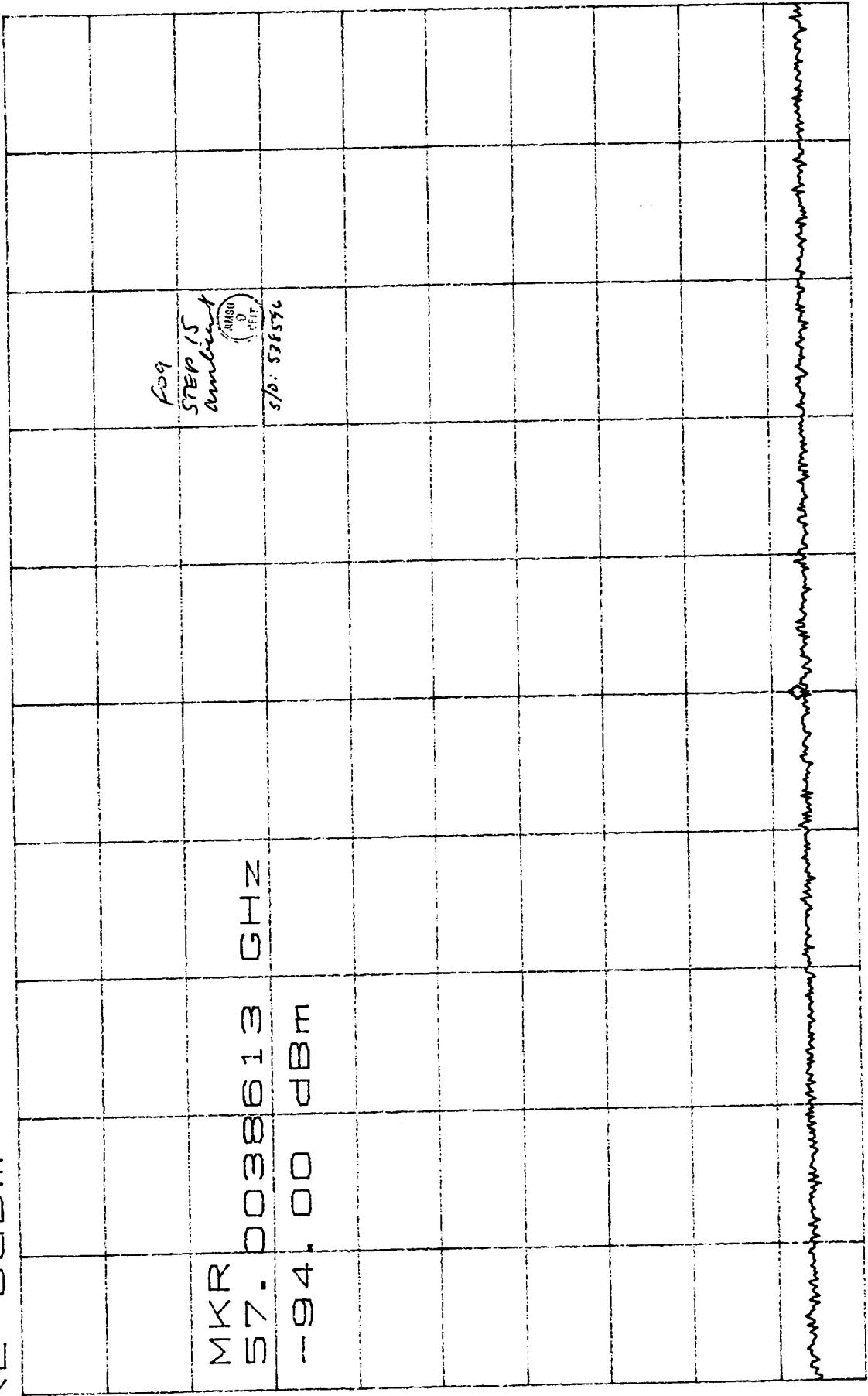
CL 30. DBB V AVG 6 MKR - 93. 00 DBM  
RL DBM 10DB / 56. 8606355GHZ



CENTER 56.86006439GHz SPAN 500.0KHz  
RBW 3.0KHz \*VBW 1.0KHz  
\*SWP 2.0000000000000002

CL 30. 0dB  
RL 0dBm

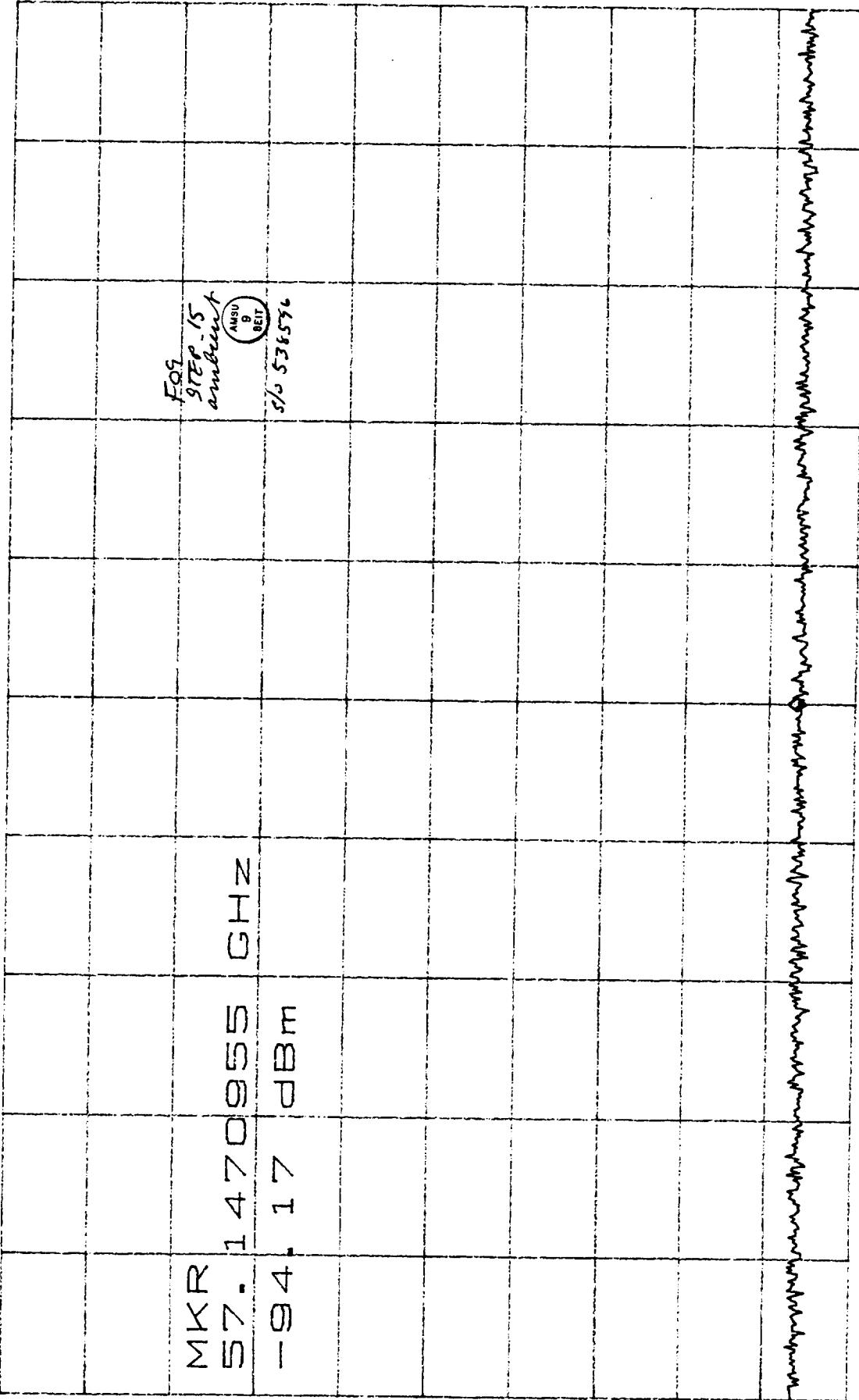
V A V G 29  
10dB/  
MKR -94. 00dBm



□

CENTER 57. 0038613 GHz \*RBW 3. 0kHz \*VBW 1. 0kHz SPAN 500. 0kHz  
\*SWP 2. 00sec

CL 30.0dB VAVG 5 MKR -94.17dBm  
RL 0dBm 10dB / 57.1470955GHz



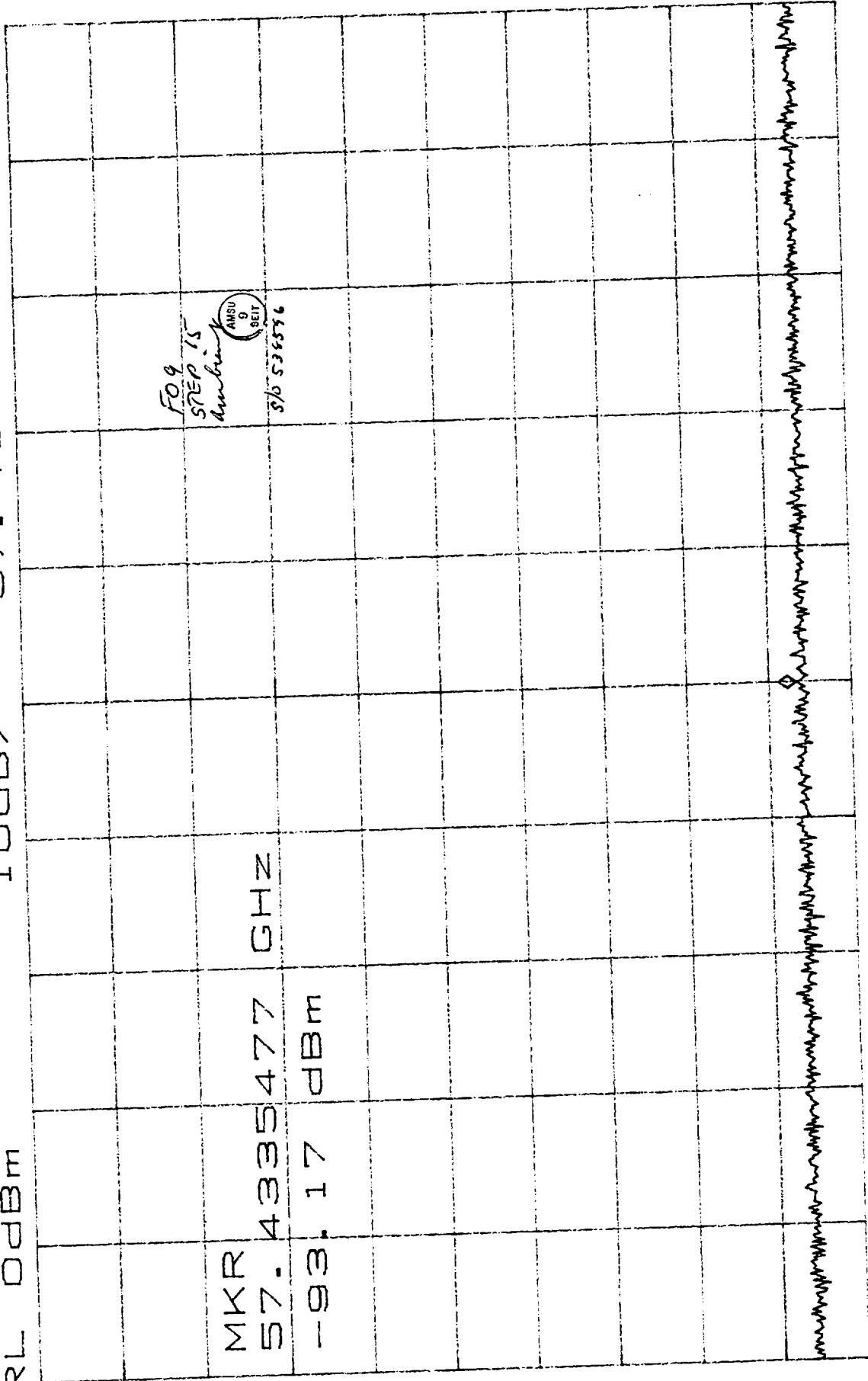
□

CENTER 57.1470955GHz SPAN 500.0kHz  
\*RBW 3.0kHz \*VBW 1.0kHz \*SWP 2.00sec

CL 30. 0dB  
RL 0dBm

VAVG 5  
10dB /

MKR -93. 17dBm  
57. 4335477GHz



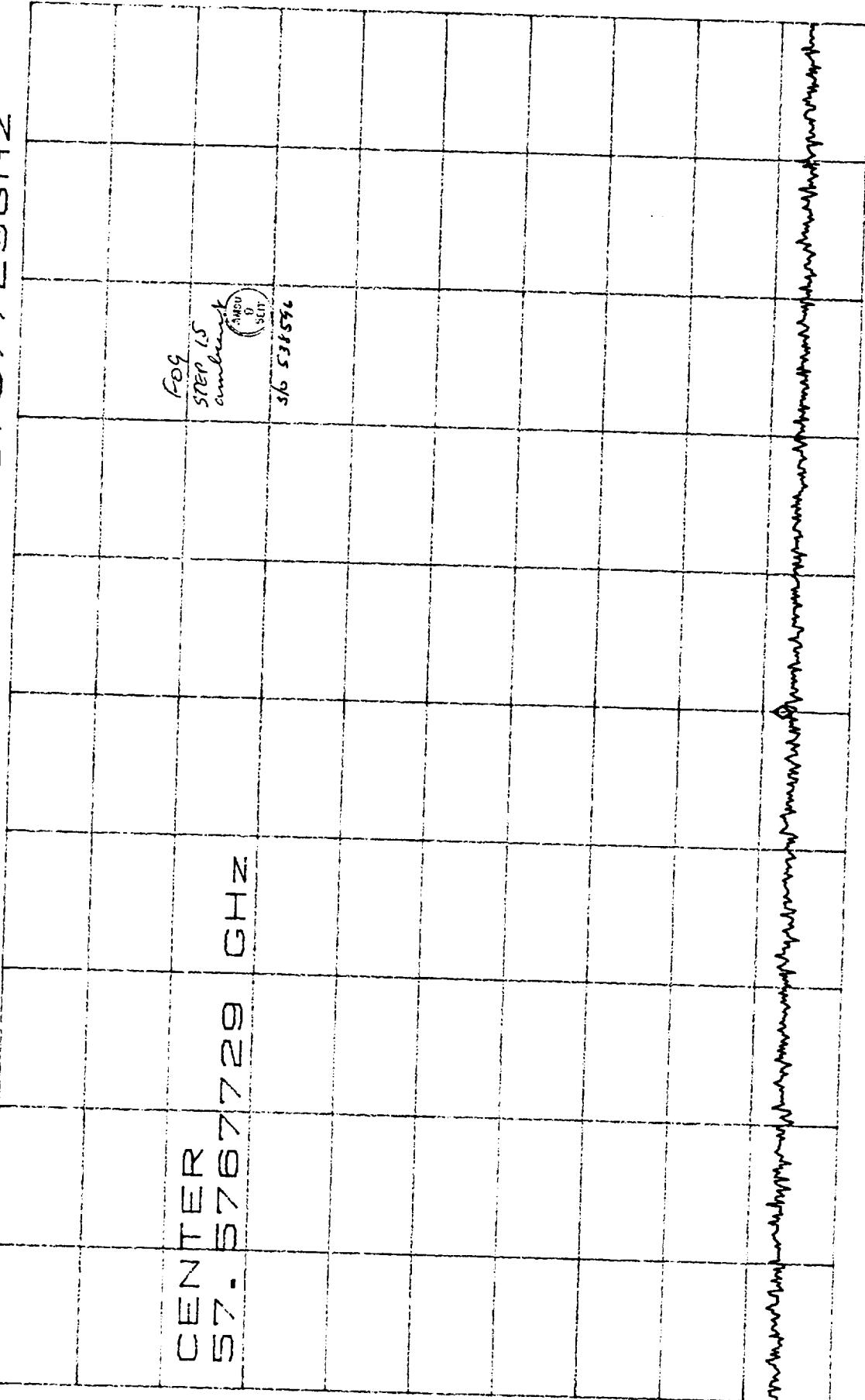
□

CENTER 57. 4335477GHz  
\*RBW 3. 0kHz \*VBW 1. 0kHz  
SPAN 500. 0kHz  
\*SWP 2. 00sec

CL 30.0dB  
RL 0dBm

VAVG 5  
10dB/

MKR -93.17dBm  
57.5767729GHz



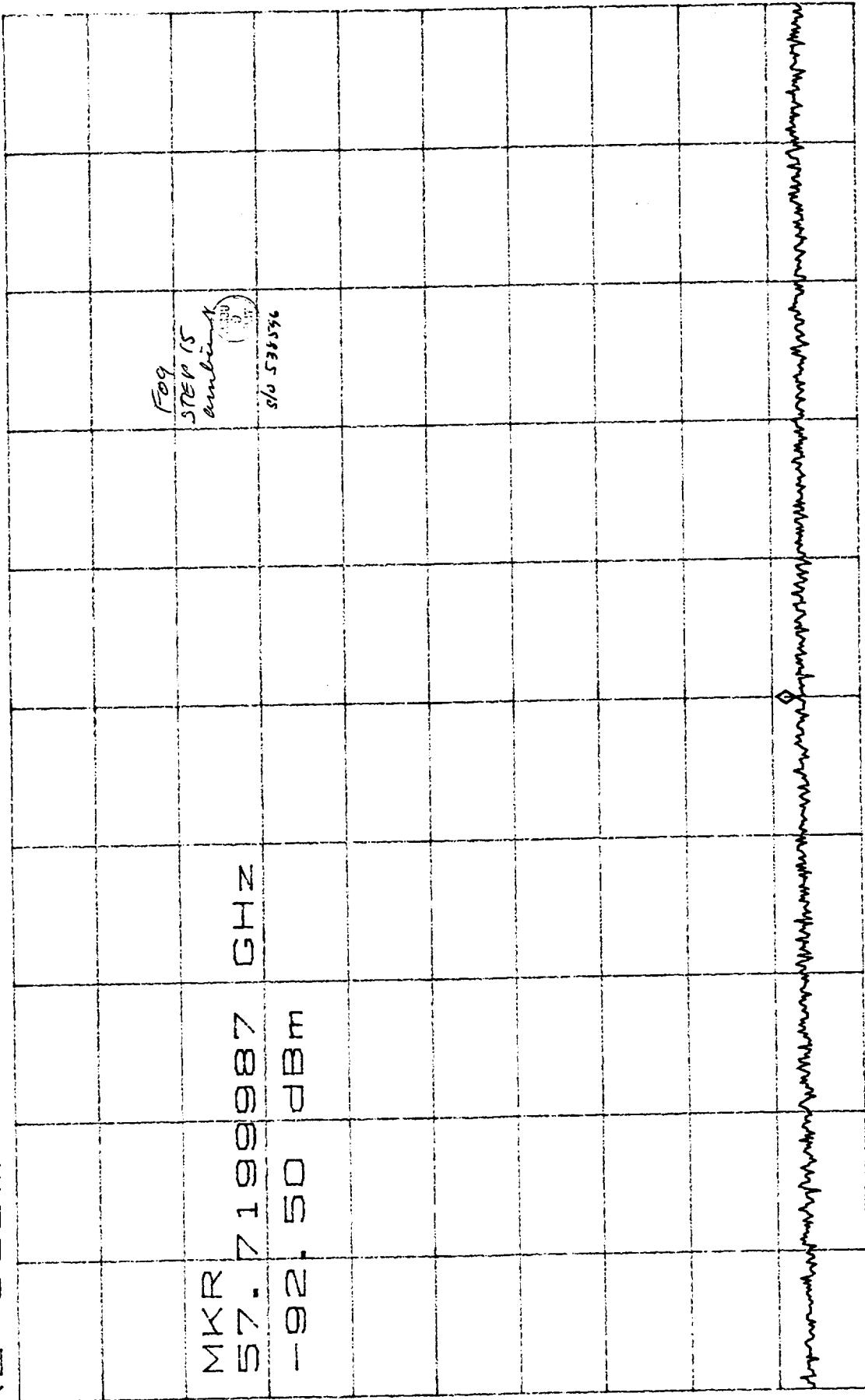
□

CENTER 57.5767729GHz \*VBW 1.0kHz  
\*RBW 3.0kHz SPAN 500.0kHz  
\*SWP 2.00sec

CL 30.0dB  
RL 0dBm

VAVG 6  
10dB/  
RL

MKR -92.50dBm  
57.7199987GHz

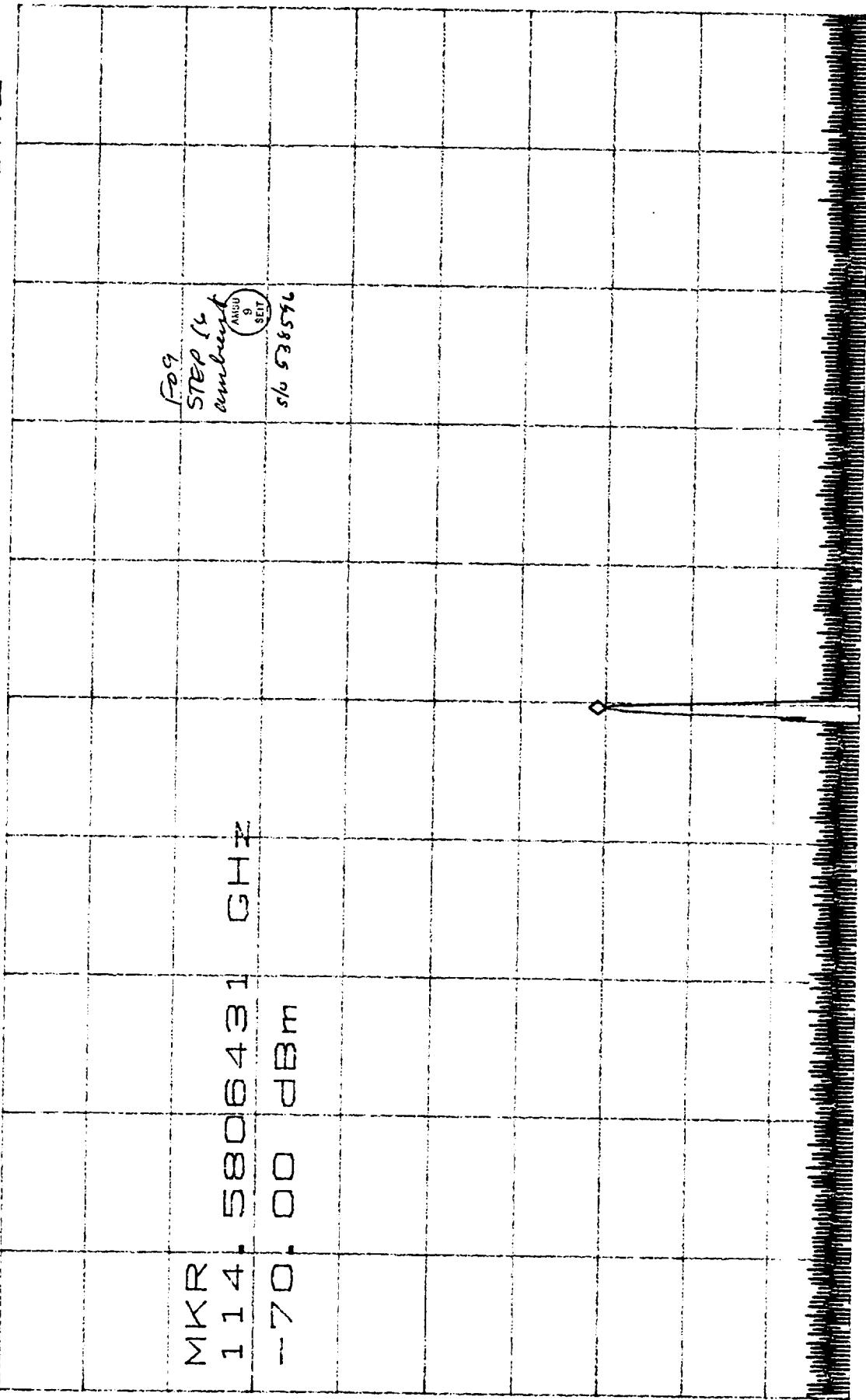


D

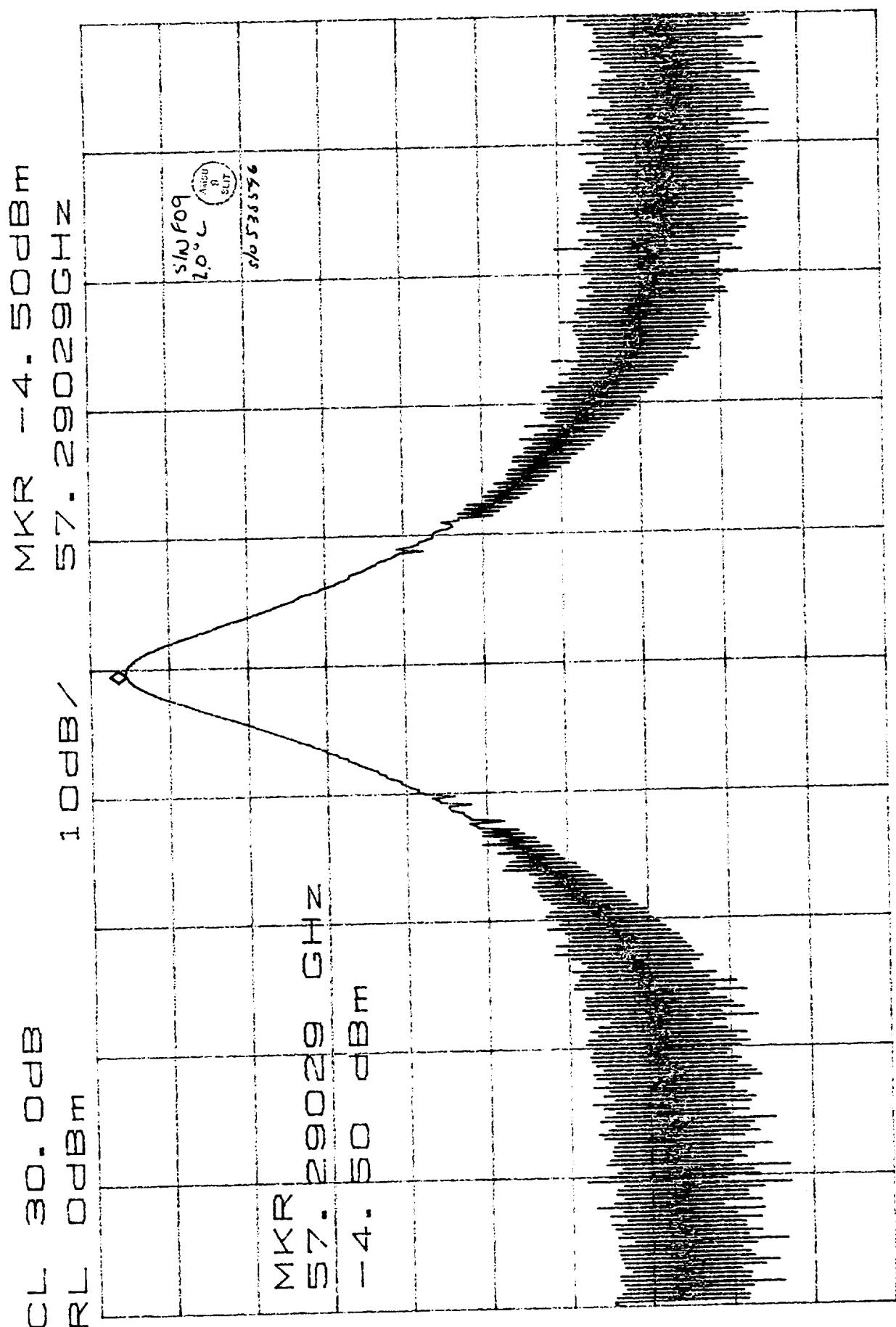
CENTER 57.7199987GHz \*VBW 1.0kHz  
\*RBW 3.0kHz \*SWP 2.00sec  
SPAN 500.0kHz

CL 30. 0dB  
RL 0dBm

MKR -70. 00dBm  
114. 5806431GHz



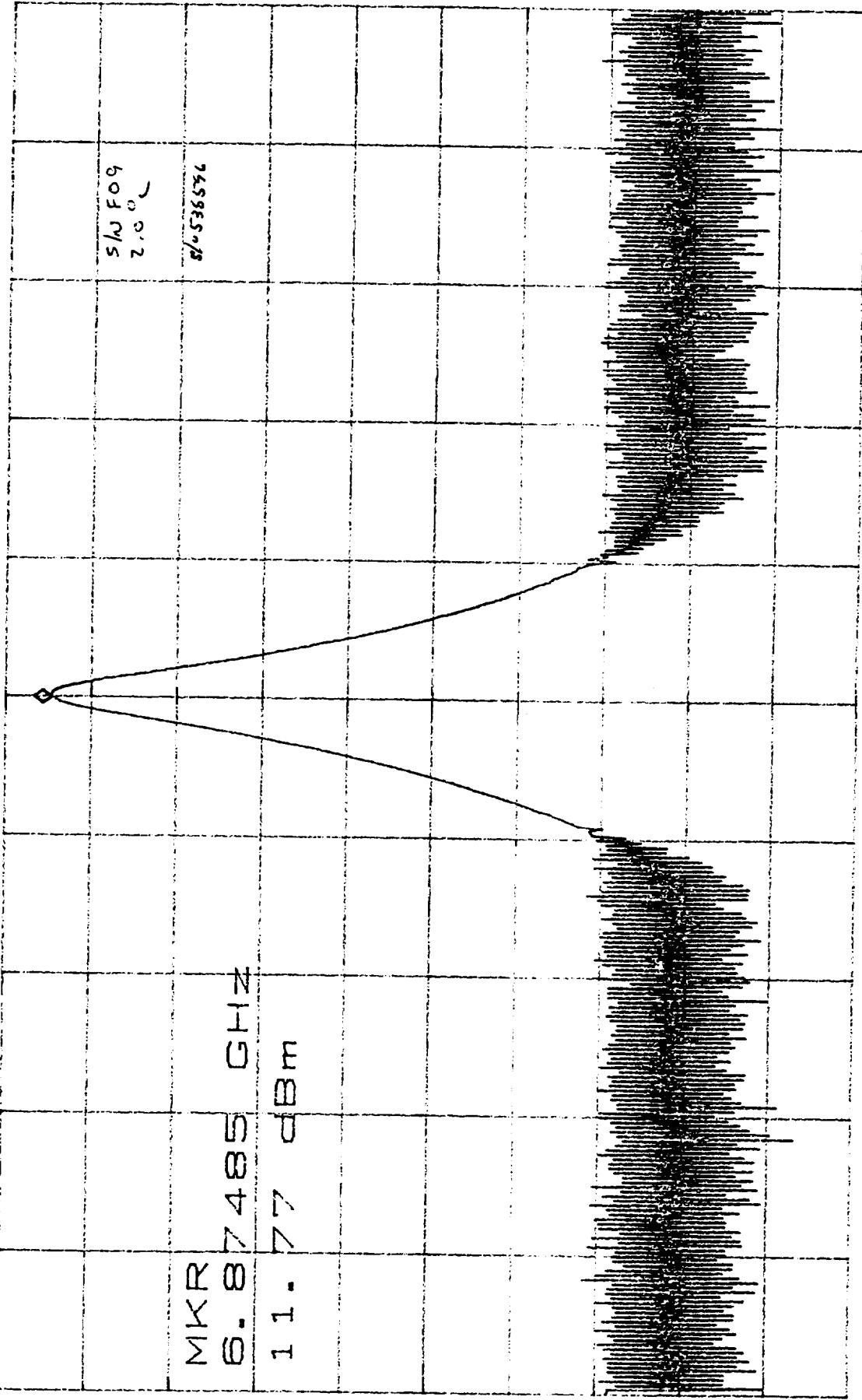
CENTER 114. 5806434GHz  
\*RBW 300Hz \*VBW 1. 0kHz \*SPAN 100. 0kHz  
\*SWP 2. 80sec



CENTER 57. 29034GHz  
\*RBW 300kHz VBW 300kHz  
SPAN 10. 00MHz SWP 50. 0ms

ATTEN 30dB  
RL 17.1 dBm

MKR 11.77 dBm  
6.87485 GHz



CENTER 6.87485 GHz  
\*RBW 300kHz \*VBW 300kHz SPAN 20.00MHz  
SWP 50.0ms

TEST DATA SHEET 6A (Sheet 2 of 4)  
Functional Testing (Paragraph 4.2.1)

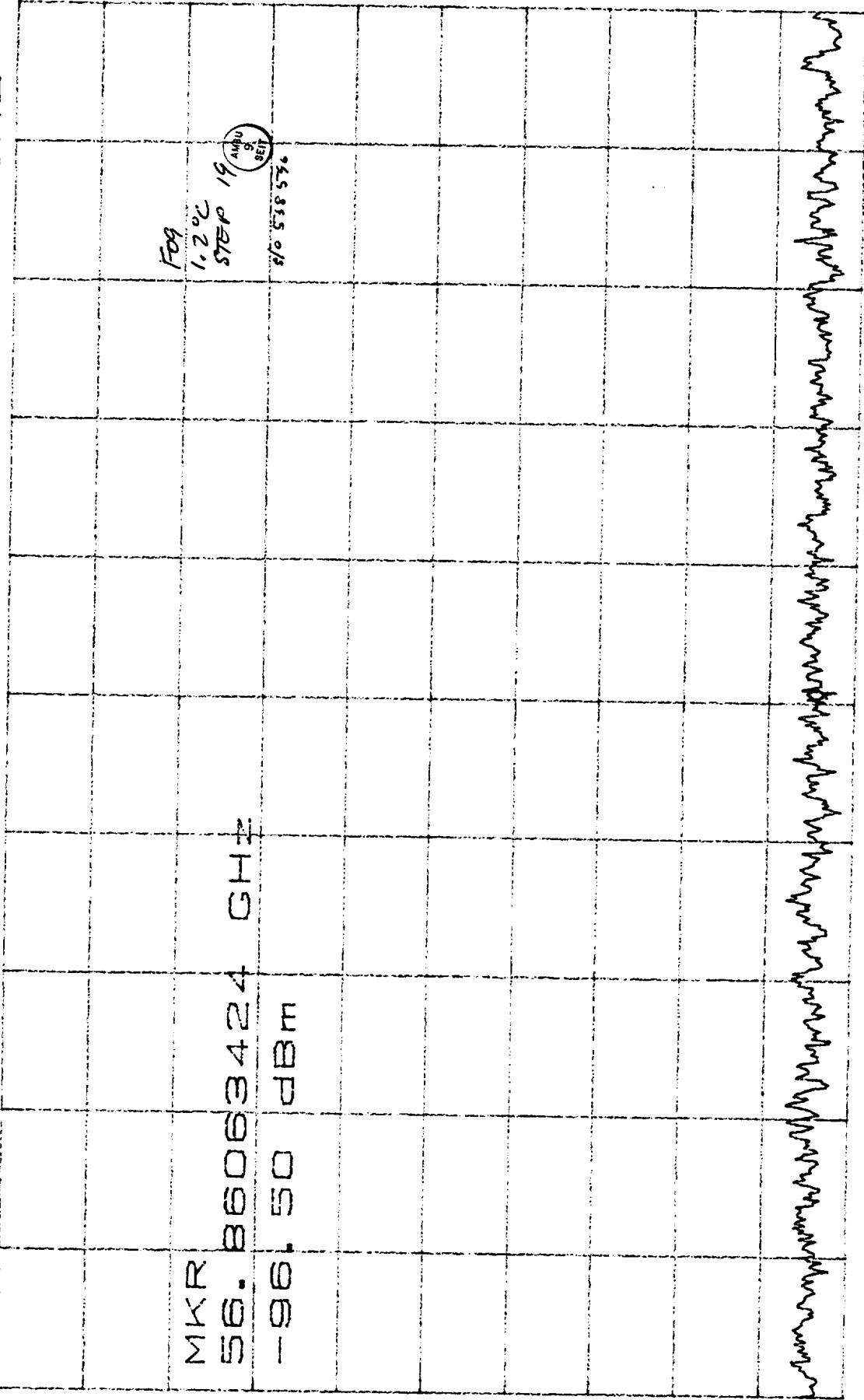
## Pre-Environmental CPT

## Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
14	Frequency vs. Voltage	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	Pass
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.29034027</u> GHz	Pass
		17 to 20 dBm	P = <u>17.65</u> dBm	Pass
15	Spurious and Sub	-200 to -90 dBc	See plots	Pass
16	Power level of 114.58 GHz signal	<10 dBm	<u>-70</u> dBm	Pass
17	Load VSWR and Frequency Pulling	N/A	Worst Case Freq = <u>10.6</u>	N/A
		N/A	Worst Case Power = <u>.35</u> dB Peak	N/A
		TC1 = 1 ± 2°C	TC1 = <u>2.3</u>	
		TC2 = <u>2.4</u>	TC2 = <u>2.4</u>	N/A
18	Operating Temperature @ 1°C baseplate	TC3 = <u>1.9</u>	TC3 = <u>1.9</u>	N/A
		0 - 1V	DRO L/A = <u>64.9 mV</u>	Pass
		<u>4.3 - 9.7 - 0 - 1V</u>	PLO L/A = <u>4.6</u> V	/
		<u>4.3 to 9.7 to 0 to 1V</u>		
19	Input Voltage and Current	VM1 Voltage	VM1 = <u>15.0</u> V	
		VM2 Voltage	VM2 = <u>-15.0</u> V	
		IM1 Current	IM1 = <u>50.8</u> mA	
		IM2 Current	IM2 = <u>-63.2</u> mA	
		DRO L/A Voltage	DRO L/A = <u>64.9 mV</u>	
		PLO L/A Voltage <u>(20)</u>	PLO L/A = <u>4.6</u> V	
		RF Output Power <u>(10) to (9)</u>	Power = <u>18.17</u> dBm	
		Frequency	Freq. = <u>57.290311900</u> GHz	
19	Frequency vs. Voltage	+15.2 ± 0.05 V	+Voltage = <u>15.2</u> V	
		-15.2 ± 0.05 V	-Voltage = <u>-15.2</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290311595</u> GHz	
		17 to 20 dBm	Power = <u>18.26</u> dBm	
19	Frequency vs. Voltage	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.29031177</u> GHz	
		17 to 20 dBm	Power = <u>18.30</u> dBm	Pass

CL 30.0dB  
RL 0dBm

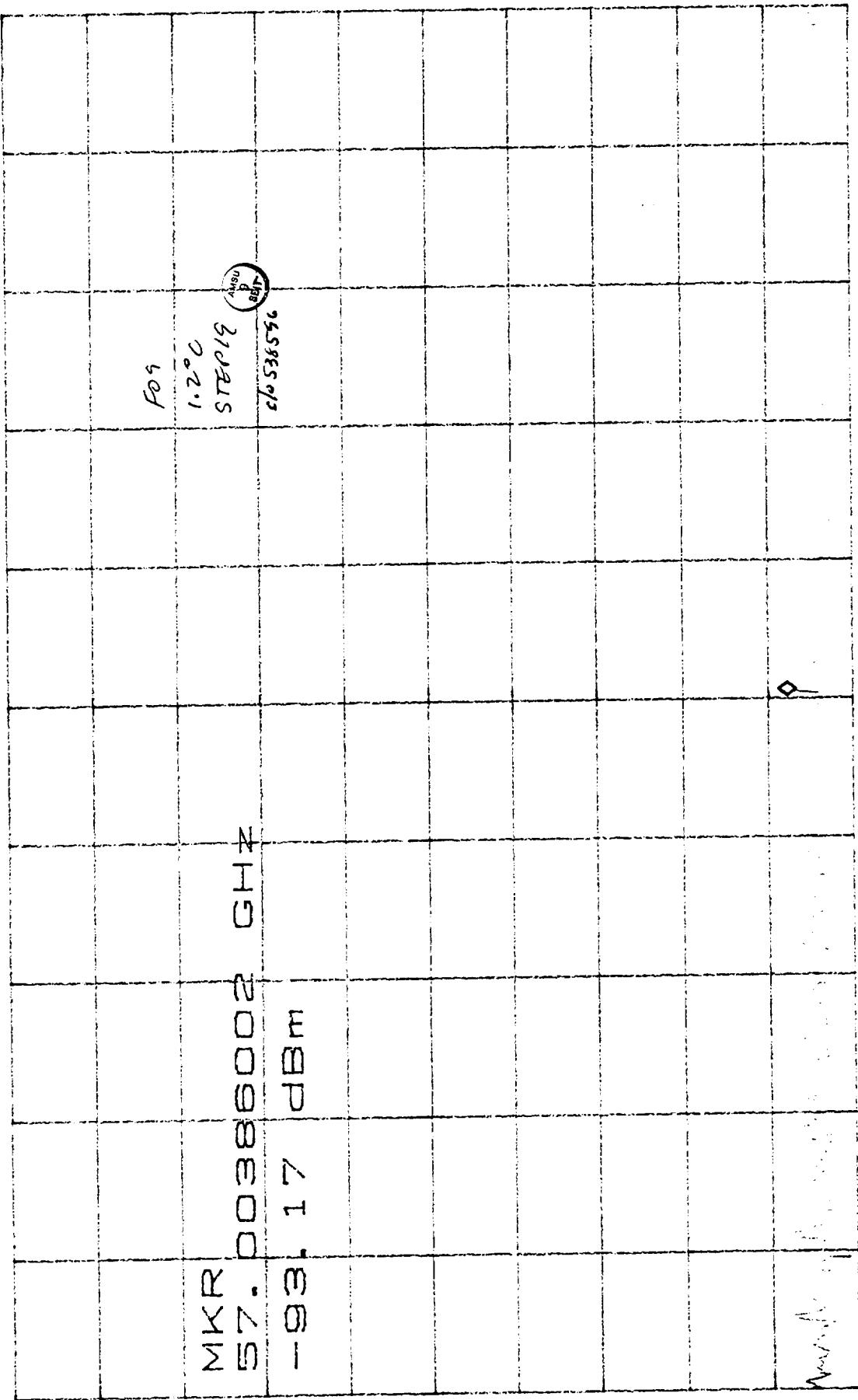
MKR -96.50dBm  
56.86063424GHz



CENTER 56.86063391GHz \*RBW 1.0kHz SPAN 50.00kHz  
\*RBW 1.0kHz SWP 200ms

CL 30. 0dB  
RL 0dBm

MKR -93. 17dBm  
57. 00386002GHz



CENTER 57. 00385969GHz \*VBW 1. 0kHz SPAN 50. 00kHz  
\*RBW 1. 0kHz SWP 200ms

CL 30.0dB  
RL 0dB

10881

MKR - 94. 50dBm  
57. 14708580CH 2

MKR	57.	14708580 GHz	
-94	50	dBm	
Fo9	STEP 13	1120C	
		10-9-98	
		6 ANCH	
		S/A 53456	

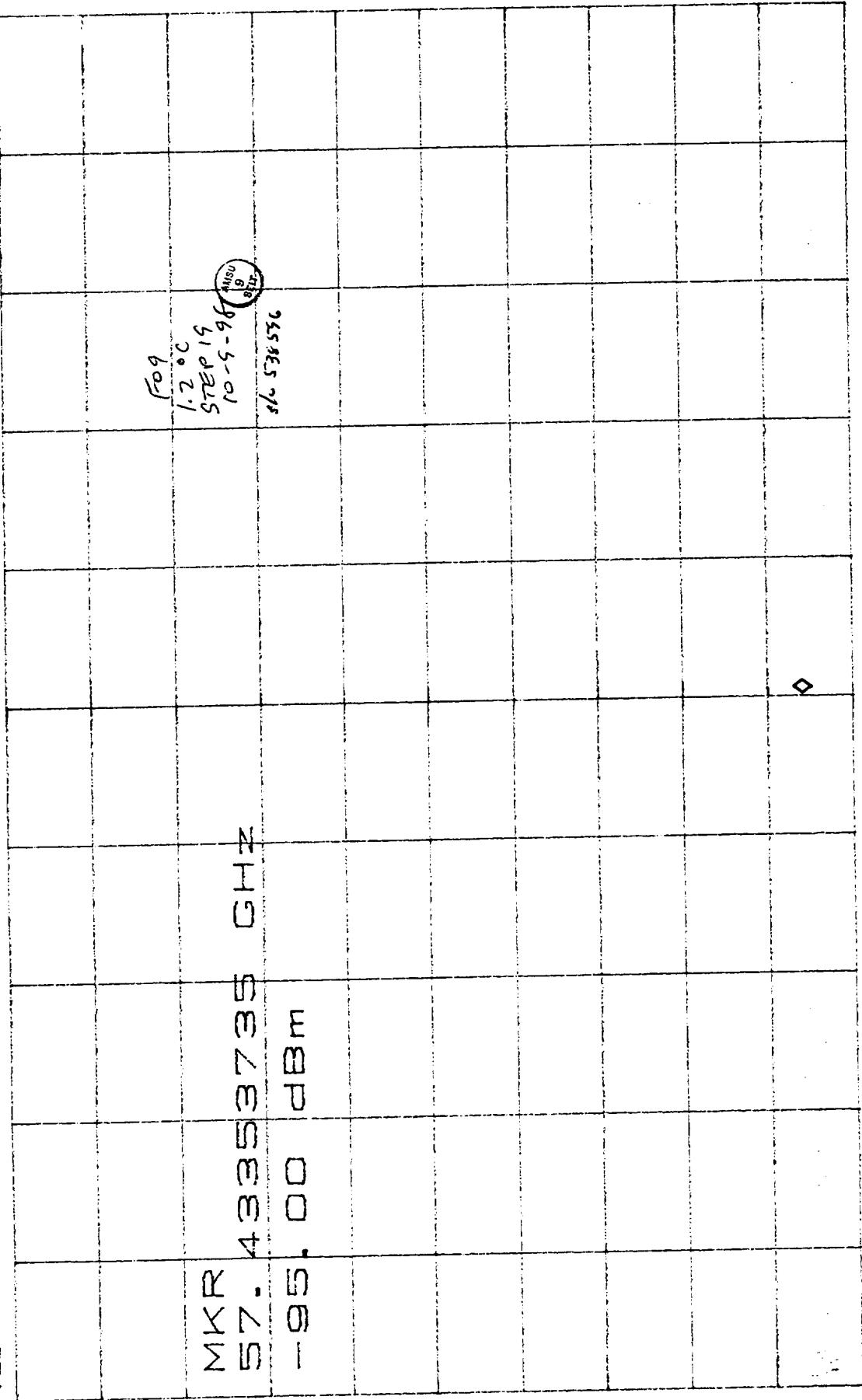
CENTER 57.14708546GHz  
\*RBW 1.0kHz \*VBW 1.0kHz

SPAN 50.00KHN  
SWP 20000S

CL 30.0 dB  
RL 0 dBm

10 dB /

MKR -95.00 dBm  
57.43353735 GHz

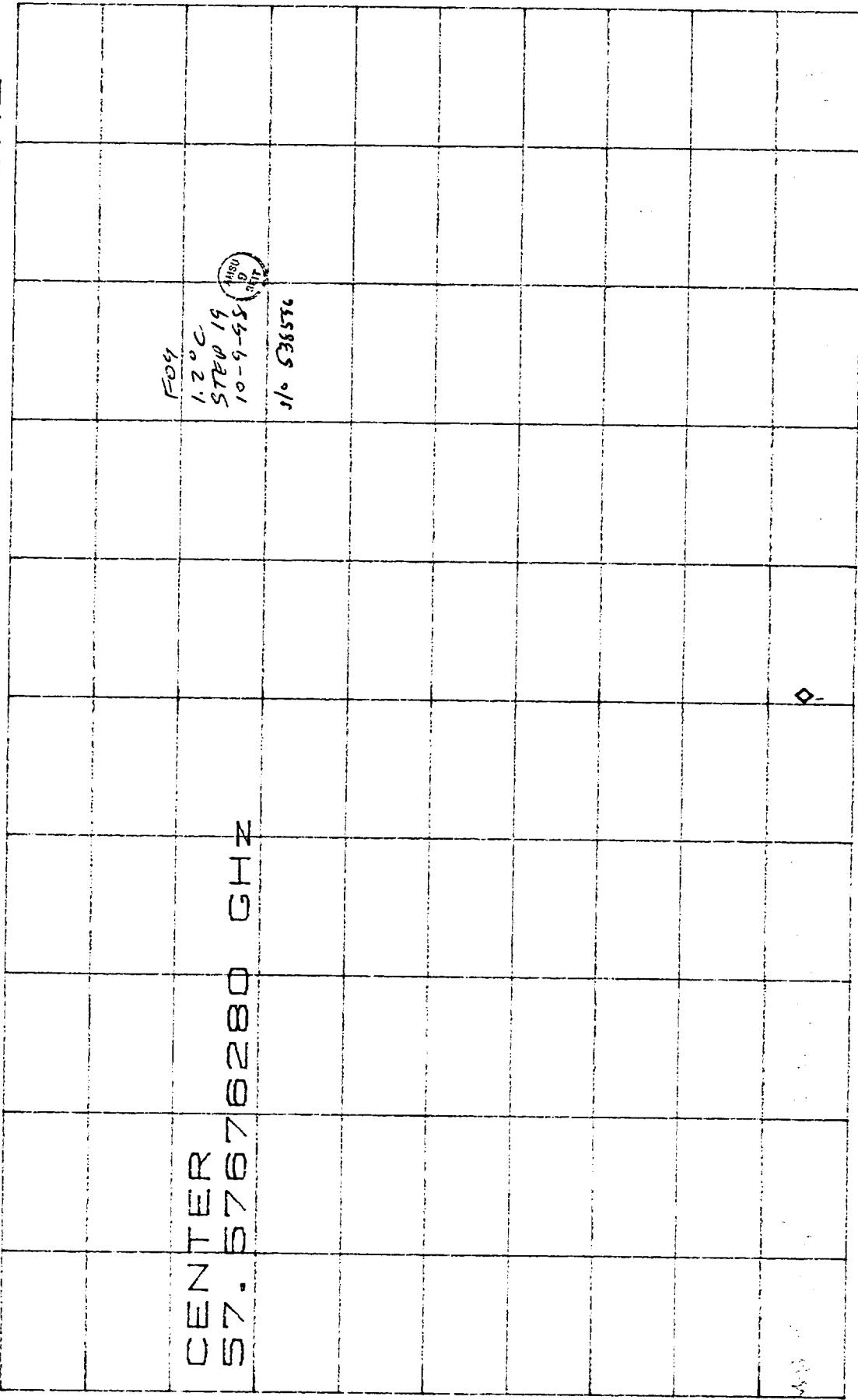


CENTER 57.43353702 GHz \*VBW 1.0 kHz SPAN 50.00 kHz  
\*RBW 1.0 kHz SWP 200 ms

CL 30.0dB  
RL 0dBm

10dB/  
10dBm

MKR -95.17dBm  
57.57676313GHz

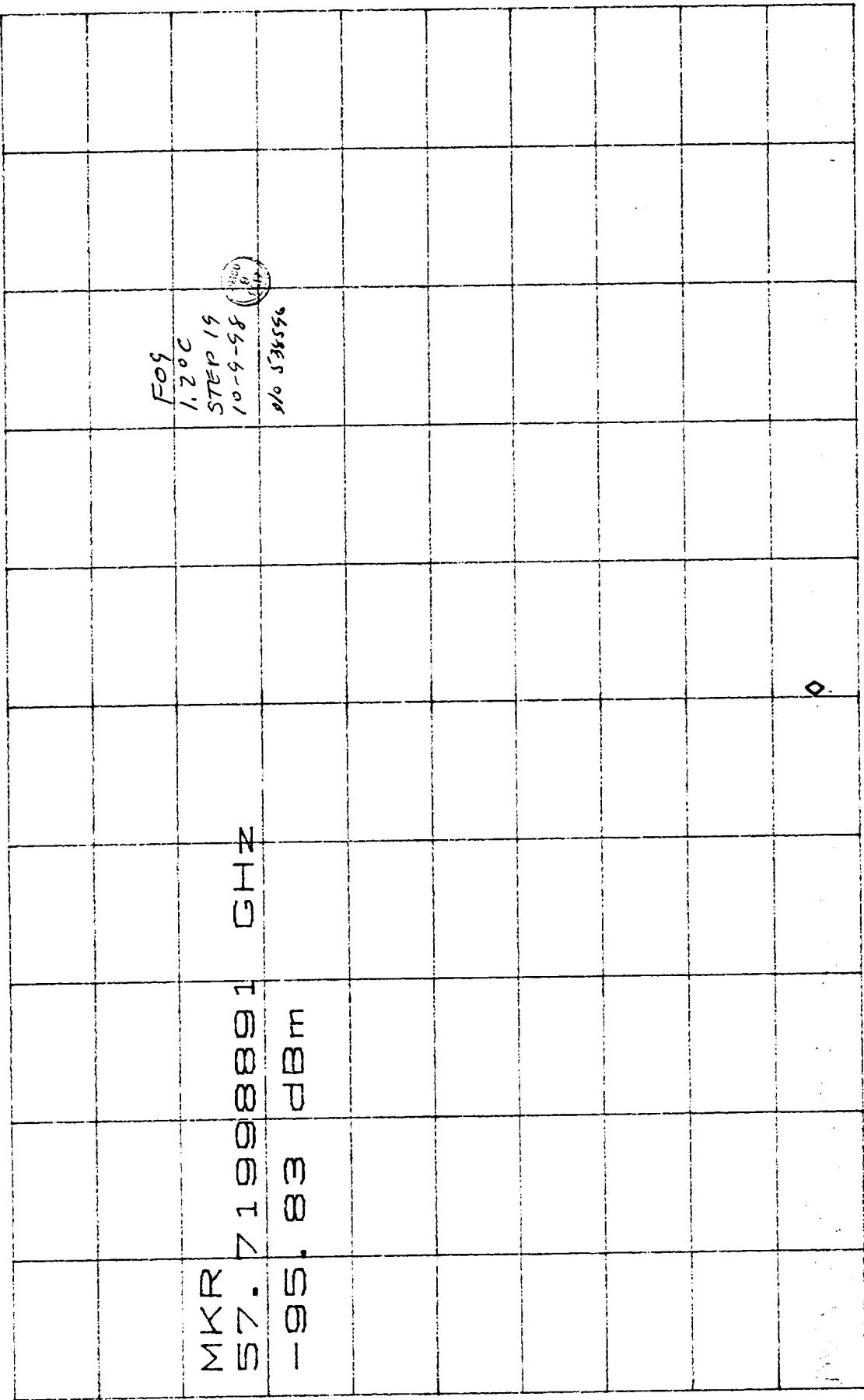


CENTER 57.57676280GHz \*RBW 1.0kHz SPAN 50.00kHz  
\*RBW 1.0kHz \*VBW 1.0kHz SWP 200ms

CL 30.0dB  
RL 0dBm

10dB/  
RL

MKR -95.83dBm  
57.719988891GHz

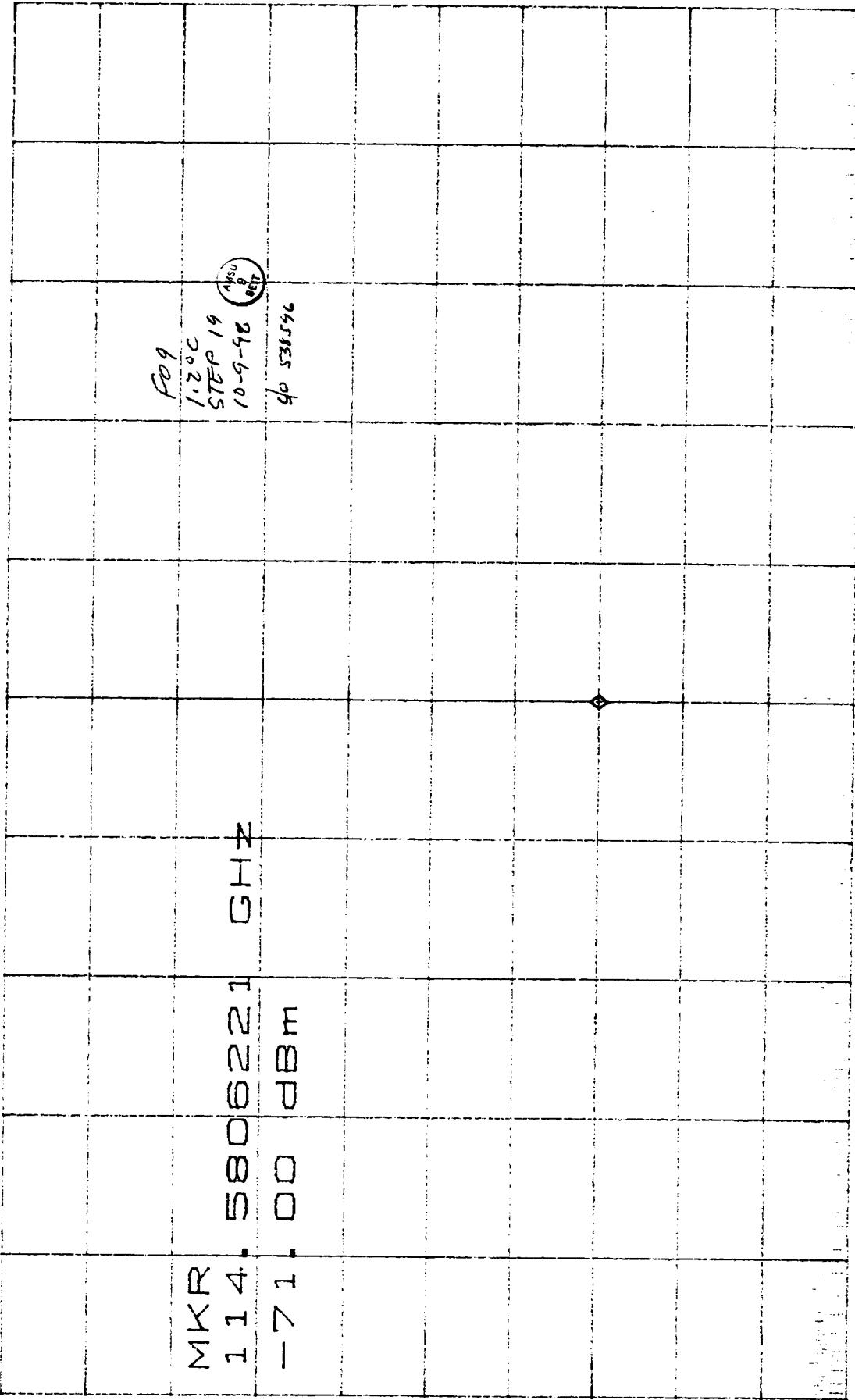


CENTER 57.719988858GHz \*VBW 1.0kHz SPAN 50.00kHz  
\*RBW 1.0kHz SWP 200ms

CL 30.0dB

RL 0dBm

MKR -71.00dBm  
114.5806221GHz



CENTER 114.5806221GHz \*VBW 1.0kHz \*RBW 300Hz  
SPAN 100.0kHz \*SWP 2.80sec

TEST DATA SHEET 6A (Sheet 3 of 4)  
Functional Testing (Paragraph 4.2.1)

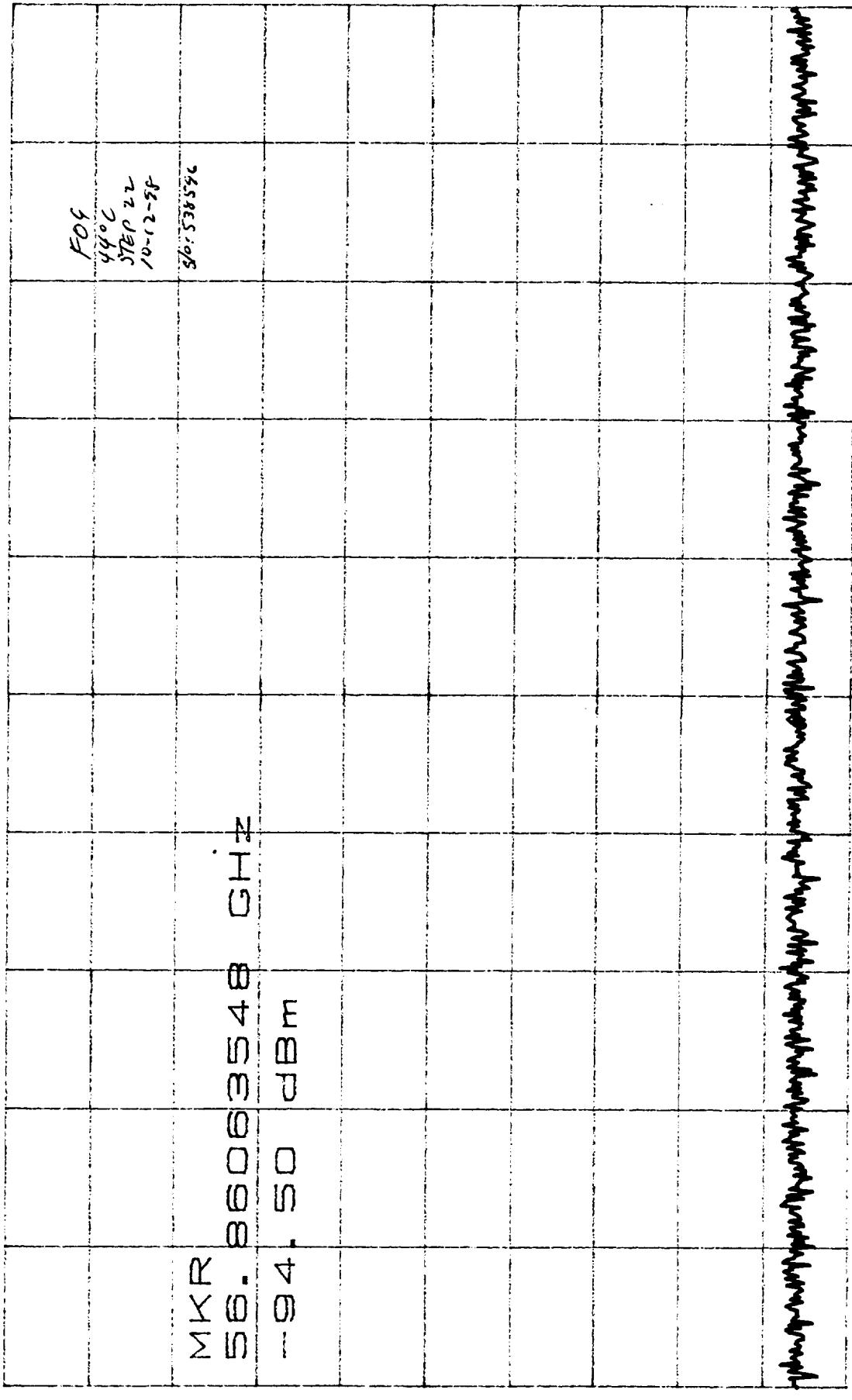
Pre-Environmental CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
19 (Cont)	Spurious and Sub Power level of 114.58 GHz signal	-200 to -90 dBc <-10 dBm	<i>see plots</i> <u>-71.0</u> dBm	PASS PAS
	Load VSWR and Frequency Pulling			
	2:1 mismatch over $1\lambda$	N/A	Worst Case Freq = <u>12 Hz</u>	N/A
	2:1 mismatch over $1\lambda$	N/A	Worst Case Power = <u>-23</u> dB	N/A
21	Operating Temperature @ +44°C Baseplate	TC1 = $44 \pm 2^\circ\text{C}$	TC1 = <u>44.2</u> $^\circ\text{C}$	Pass
			TC2 = <u>44.3</u> $^\circ\text{C}$	N/A
			TC3 = <u>43.4</u> $^\circ\text{C}$	N/A
		0 - 1V	DRO L/A = <u>120mV</u>	Pass
		<u>0 to 1V 4.3-4.7V</u>	PLO L/A = <u>4.5</u> V	Pass
22	Input Voltage and Current <i>10/12/98</i>	+15 ± 0.1 V -15 ± 0.1 V 600 mA max. 100 mA max. 0 to 1V <u>0 to 1V 4.3-4.7V</u> 17 to 20 dBm 57.290344 ± .0002 GHz	VM1 = <u>+15.12</u> V VM2 = <u>-15.12</u> V IM1 = <u>535</u> mA IM2 = <u>~66</u> mA DRO L/A = <u>120mV</u> PLO L/A = <u>4.5</u> V Power = <u>17.04</u> dBm Freq. = <u>57.290313666GHz</u>	Pass Pass Pass Pass Pass Pass Pass Pass
	Frequency vs. Voltage			
	± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = <u>15.20</u> V	Pass
		-15.2 ± 0.05 V	-Voltage = <u>15.20</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.290313677GHz</u>	Pass
		17 to 20 dBm	Power = <u>17.02</u> dBm	Pass
	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	Pass
		-14.8 ± 0.05 V	-Voltage = <u>14.8</u> V	Pass
		57.290344 ± .0002 GHz	Freq. = <u>57.290313674GHz</u>	Pass
		17 to 20 dBm	Power = <u>17</u> dBm	Pass

CL 30.0dB VAVG 4  
RL 0dBm 10dB /

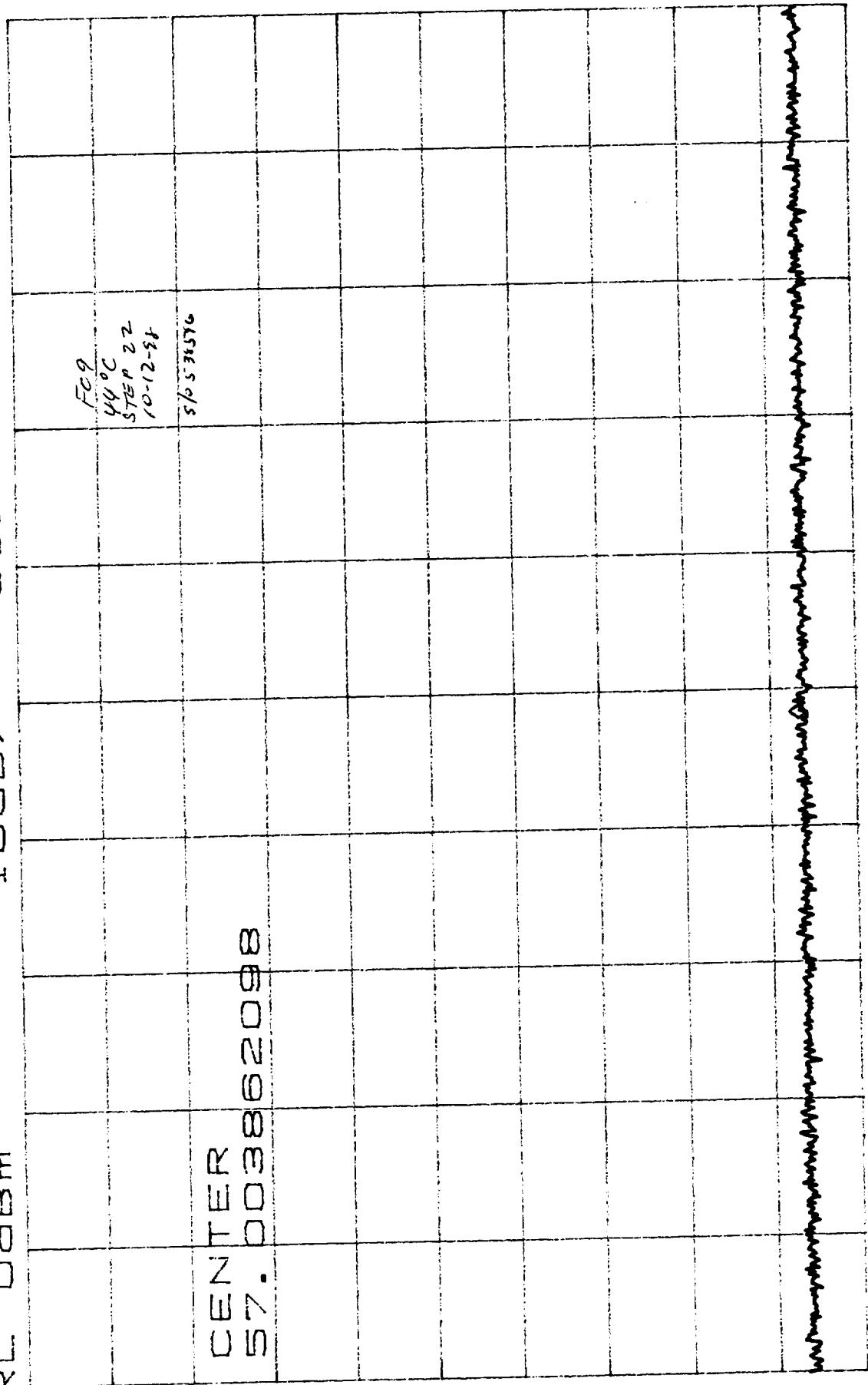
MKR - 94-50dBM  
56, 860635486H-2



CL 30.0dB  
RL 0dBm

V AVG 42  
10dB/  
RL

MKR -94. 17dBm  
56. 86063548GHz

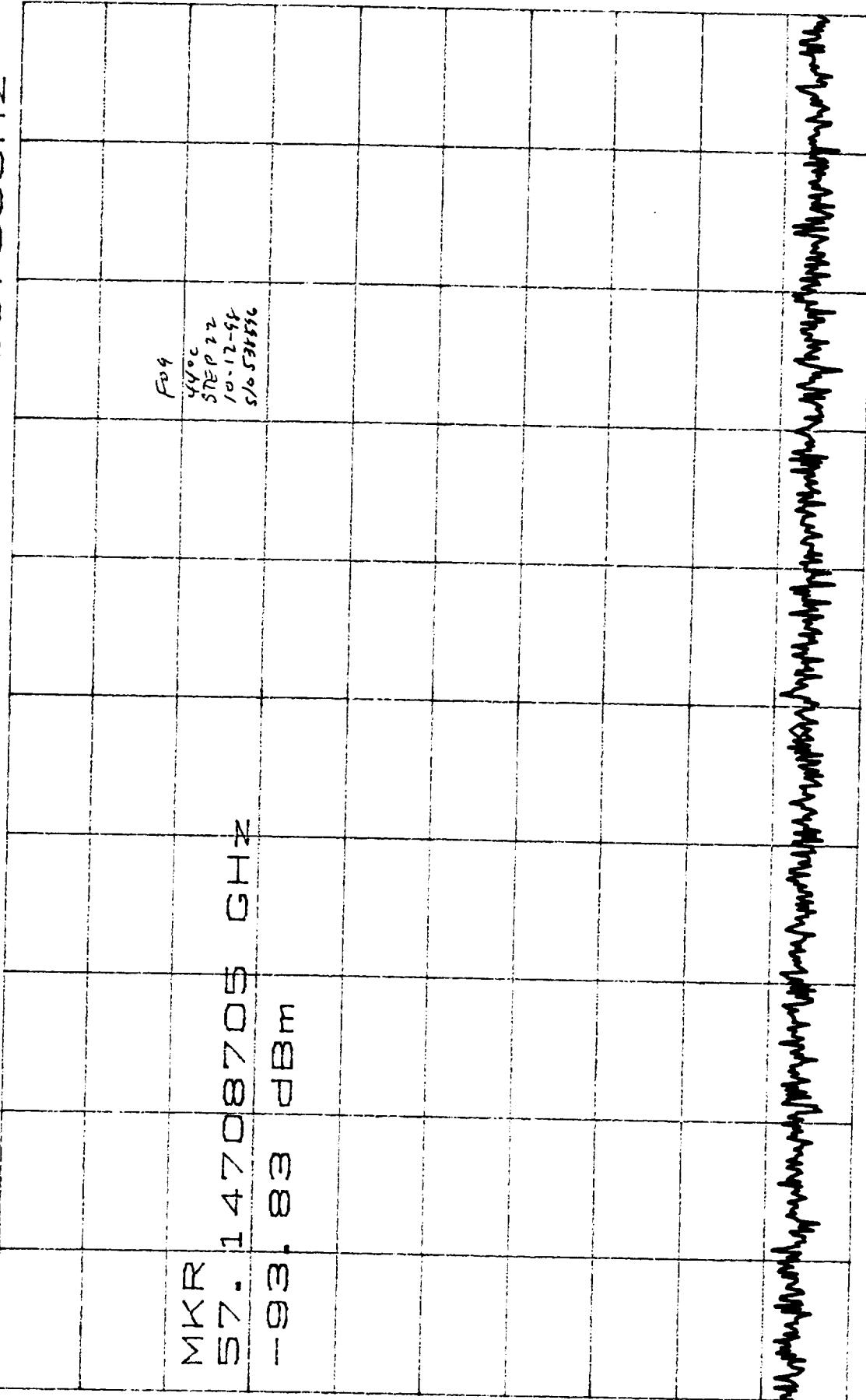


D

SPAN 50. 00KHz  
CENTER 56. 86063631GHz \*VBW 3. 0KHz \*RBW 3. 0KHz  
\*RBW 3. 0KHz \*VBW 3. 0KHz \*SWP 2. 00sec

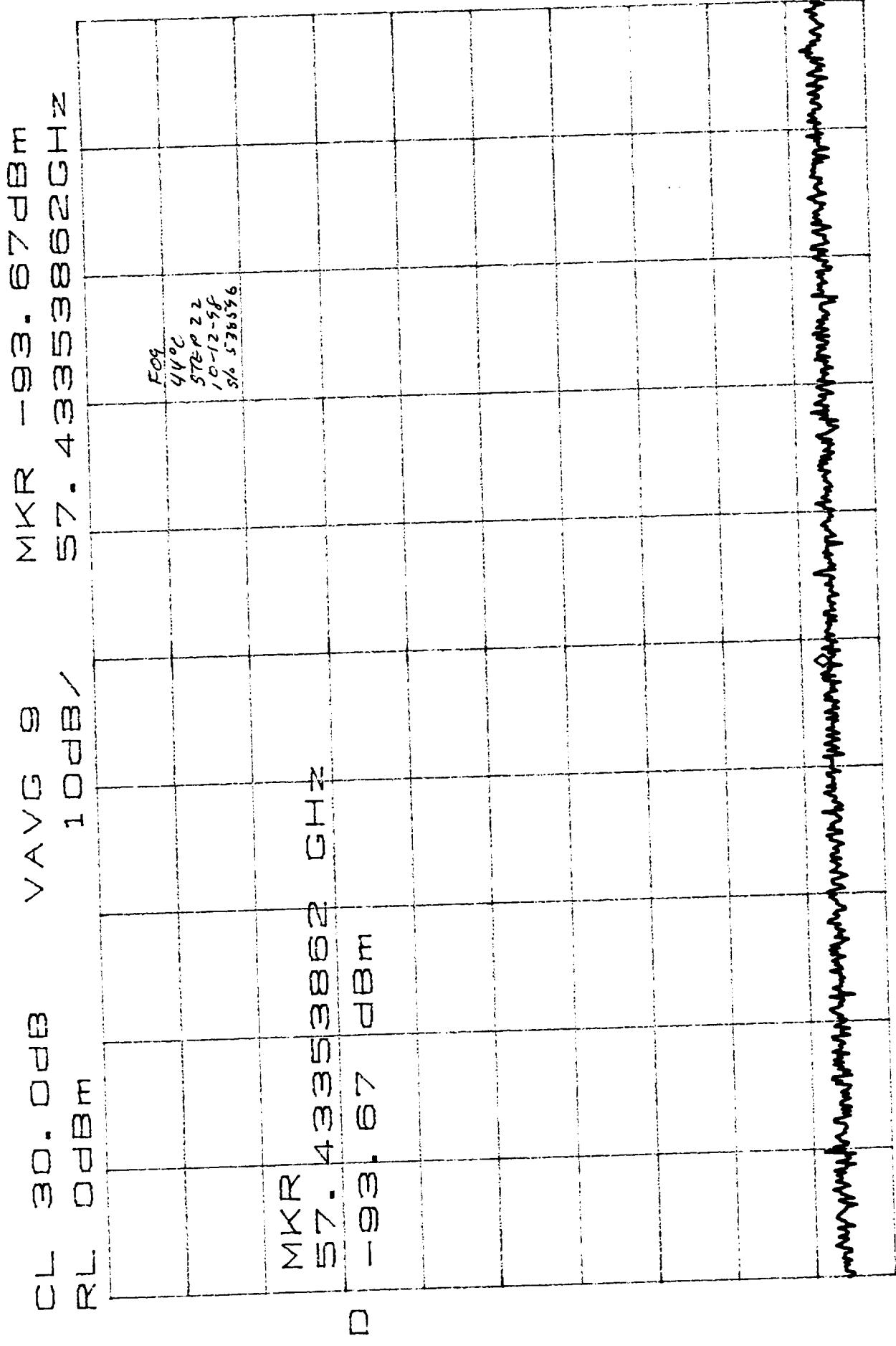
CL 30.0dB  
RL 0dBm

MKR -93.83dBm  
57.14708705GHz



D

CENTER 57.14708788GHz \*RBW 3.0kHz \*VBW 3.0kHz SPAN 50.00kHz \*SWP 2.00sec



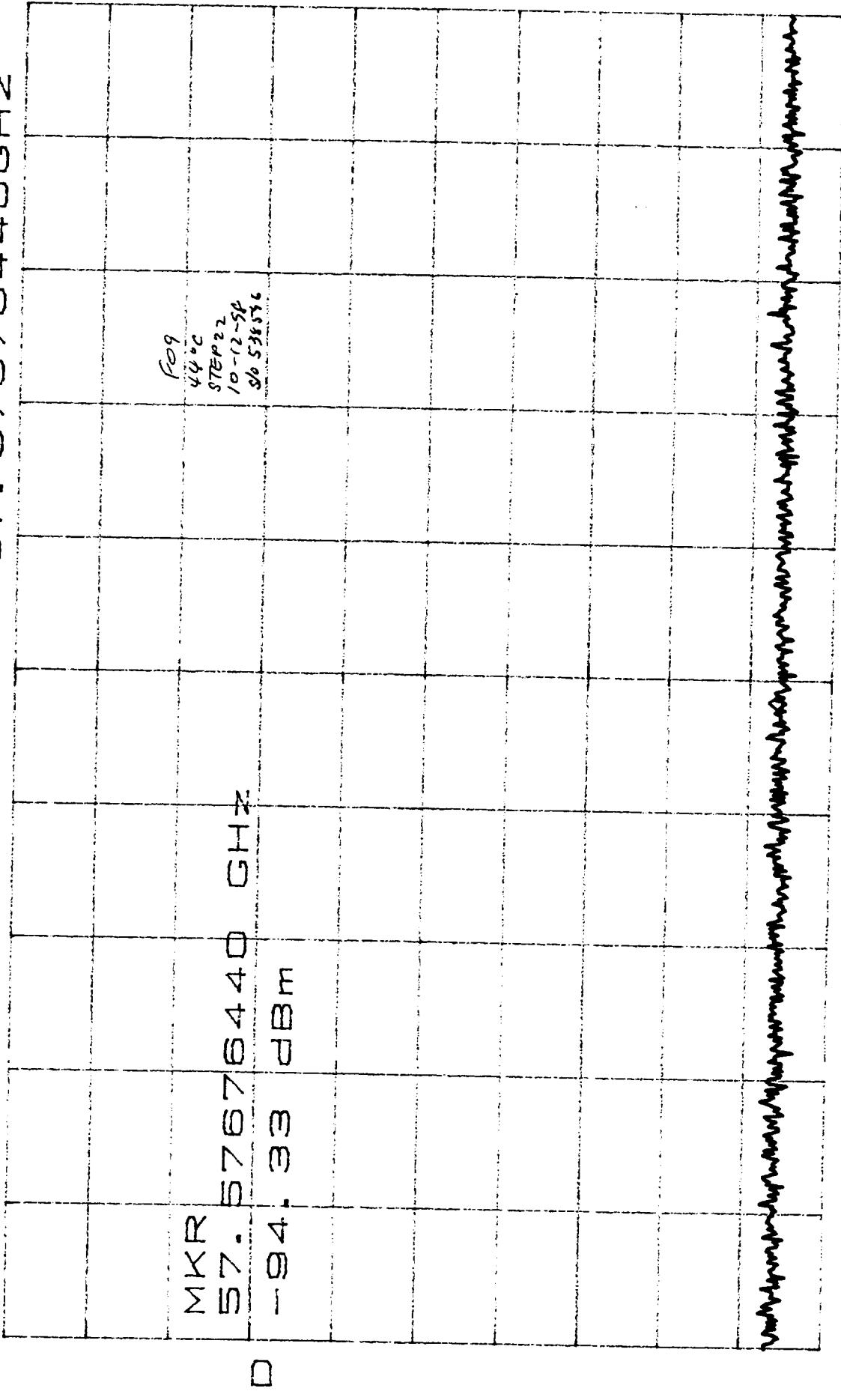
SPAN 50.0 kHz  
 CENTER 57.43353845 GHz  
 \*RBW 3.0 kHz \*\*VBW 3.0 kHz

CL 30.0dB  
RL 0dBm

V AVG 9

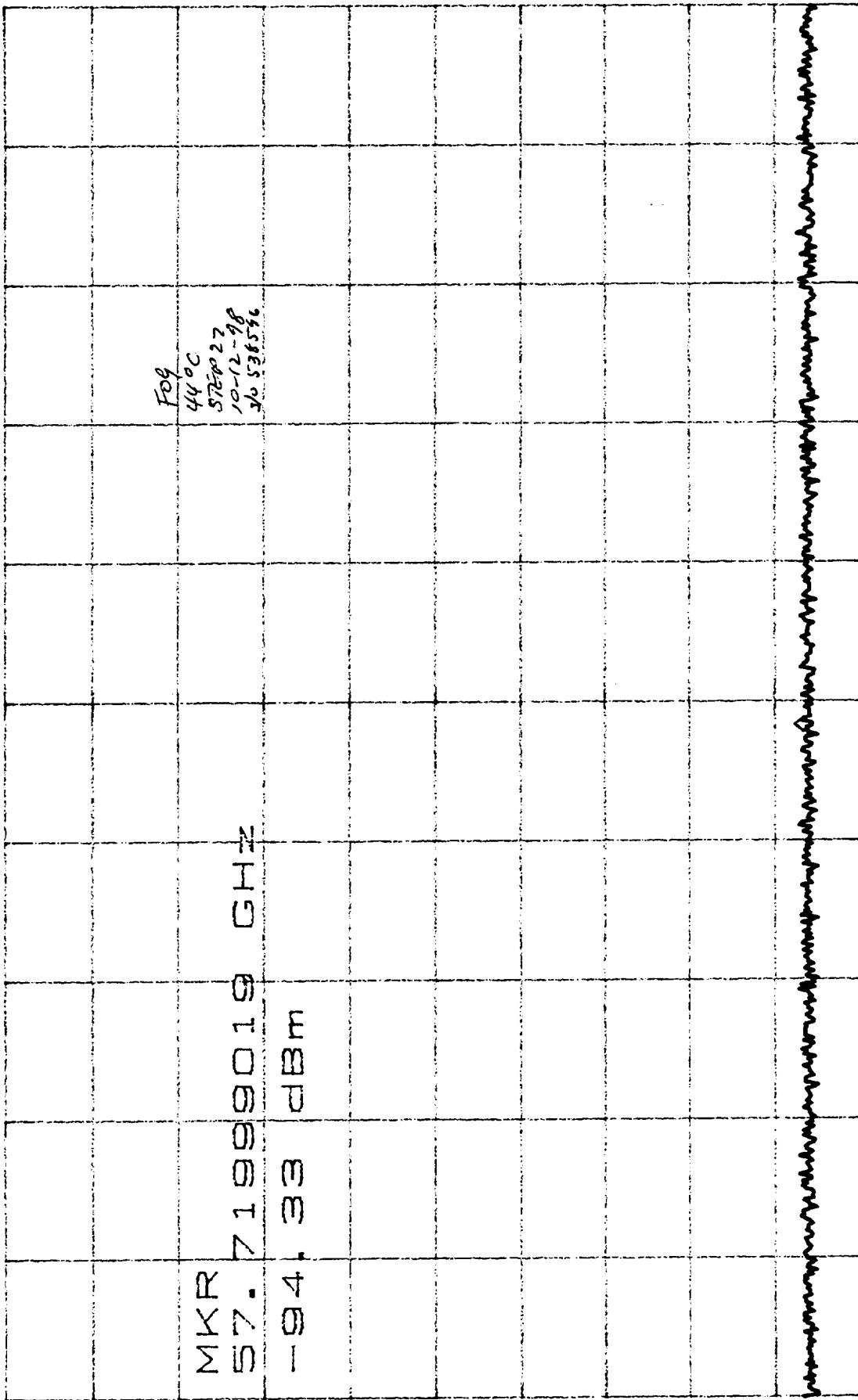
10dB/  
57.57676440GHz

MKR -94.33dBm  
57.57676440GHz



CENTER 57.57676523GHz  
\*RBW 3.0kHz \*VBW 3.0kHz  
SPAN 50.00kHz \*SWP 2.00sec

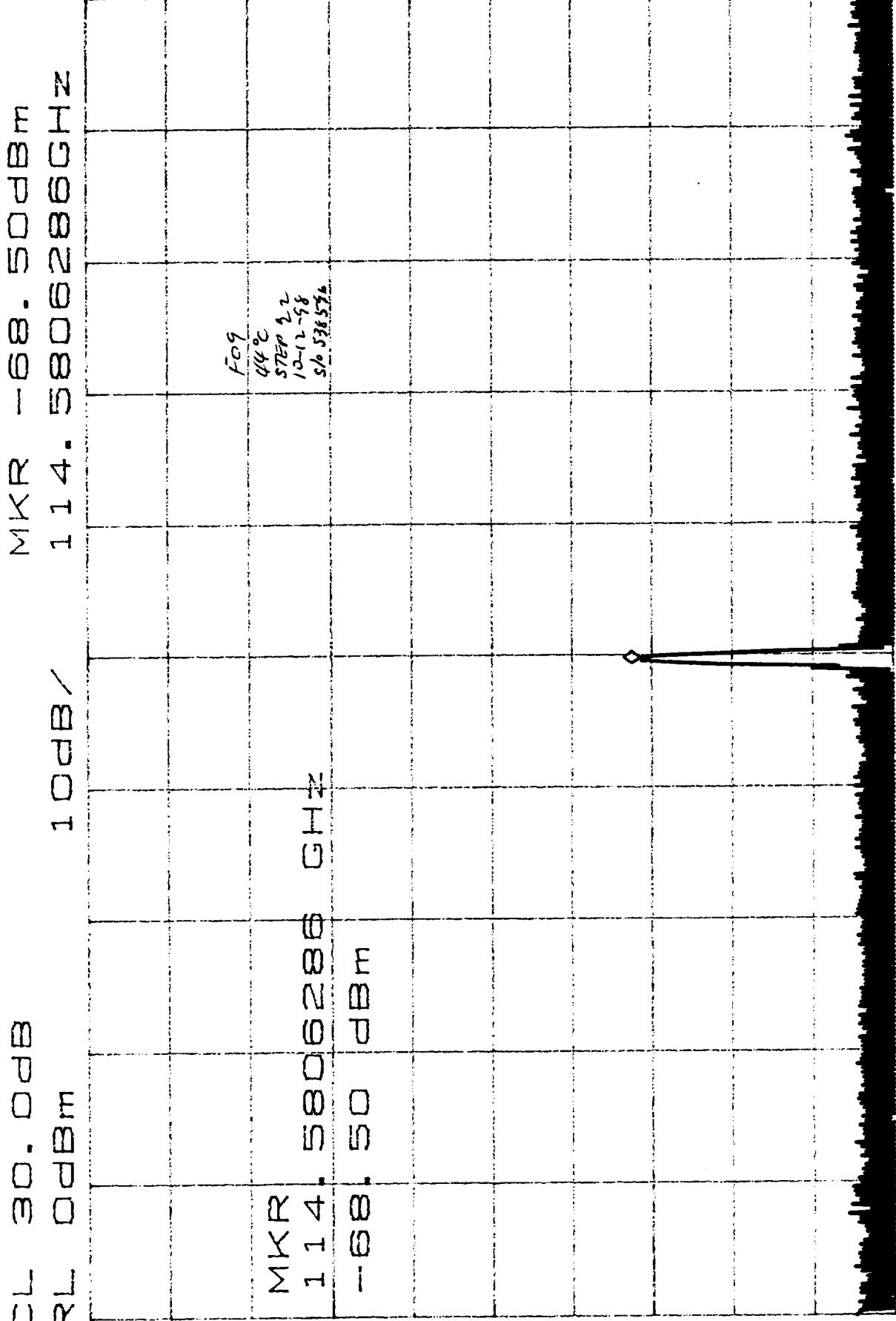
CL 30.0dB V AVG 23 MKR -94.33dBm  
RL 0dBm 10dB/  
57.71999019GHz



□

CENTER 57.71999102GHz SPAN 50.00kHz  
\*RBW 3.0kHz \*\*VBW 3.0kHz \*SWP 2.0sec

CL 30.0dB  
RL 0dBm



CENTER 114. 5806288GHz \*RBW 300Hz \*VBW 1. 0kHz  
\*SWP 2. 80sec

TEST DATA SHEET 6A (Sheet 4 of 4)  
Functional Testing (Paragraph 4.2.1)

## Pre-Environmental CPT

## Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
22 (Cont)	Spurious and Sub	-200 to -90 dBc	<i>see plot</i>	Pass
	Power level of 114.58 GHz signal	<-10 dBm	<i>-62</i> dBm	Pass
Load VSWR and Frequency Pulling				
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <i>10.62</i>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <i>-25</i> dB	N/A

Shop Order No.: 538596

Test Engineer: \_\_\_\_\_

Operation: 0110

Quality Control: \_\_\_\_\_



OCT 13 '98

Unit Serial No.: F09Govt. Rep.: J. Palangac 11-1Date: 10-12-98



### Section 1B: Initial Functional Testing - F10

This section contains the results of a full functional test over temperature taken before PLO F10 endured thermal cycling. All tests passed.



TEST DATA SHEET 6A (Sheet 1 of 4)  
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Test Setup Verified: J. C. Nguyen  
Signature

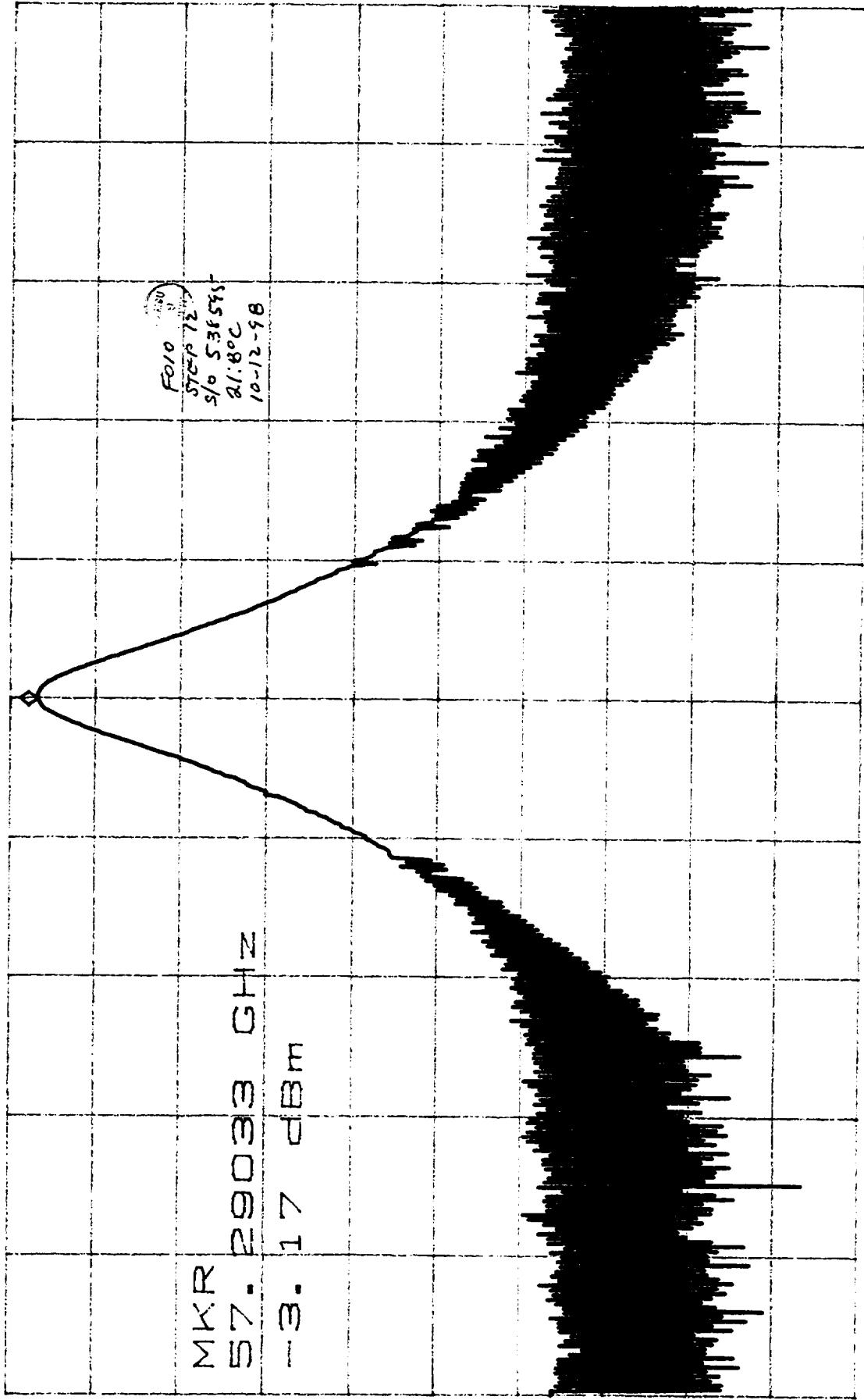
Paragraph 4.2.1.3, Functional Testing:

Step	Test	Expected	Measured	Pass/Fail
1	Potential Difference from $\pm 15$ V RTN to:			
	PLO Base Plate	< 1.0 Vac	0.03	Pass
	Spectrum Analyzer	< 1.0 Vac	0.03	Pass
	Frequency Counter Chassis	< 1.0 Vac	0.02	Pass
	Power Meter Chassis	< 1.0 Vac	0.03	Pass
4	Evacuate vacuum chamber and record pressure	< $10^{-2}$ torr	N/A	N/A*
5	Thermal couple readings	TC1 = $22 \pm 2$ °C	TC1 = 21.8 °C	
			TC2 = 22.3 °C	N/A
			TC3 = 21.22 °C	N/A
6	DRO L/A	0 to 1V	DRO L/A = 54 mV	Pass
	PLO L/A	0 to 1V 4.3-4.7v	PLO L/A = 4.49 V	
	Is PLO locked?	10/13/98 Yes	Yes ✓ No _____	
7	PLO Frequency	$57.290344 \pm .0002$ GHz	Freq. = 57.290341378 GHz	
	PLO Power	17 to 20 dBm	P = 18.48 dBm	
8	Input Voltage and Current			
	VM1 Voltage	+15 ± 0.1 V	VM1 = 15.0 V	
	VM2 Voltage	-15 ± 0.1 V	VM2 = -15.0 V	
	IM1 Current	600 mA max.	IM1 = 531 mA	
	IM2 Current	100 mA max.	IM2 = 67 mA	
	DRO L/A Voltage	0 to 1V	DRO L/A = 54 mV	
12	RF Output Power and Frequency	17 to 20 dBm 57.290344 ± .0002 GHz	P = 18.48 dBm Freq. = 57.290341378 GHz	
13	Baseplate Temp. (TC1)			
	Frequency vs. Voltage	TC1 = $22 \pm 2$ °C	TC1 = 21.8 °C	
± 15 V Supplies	+15.2 ± 0.05 V	+Voltage = 15.2 V		
	-15.2 ± 0.05 V	-Voltage = -15.2 V		
	57.290344 ± .0002 GHz	Freq. = 57.290341368 GHz		
	17 to 20 dBm	P = 18.40 dBm	Pass	

\*Record data only if performing test under vacuum

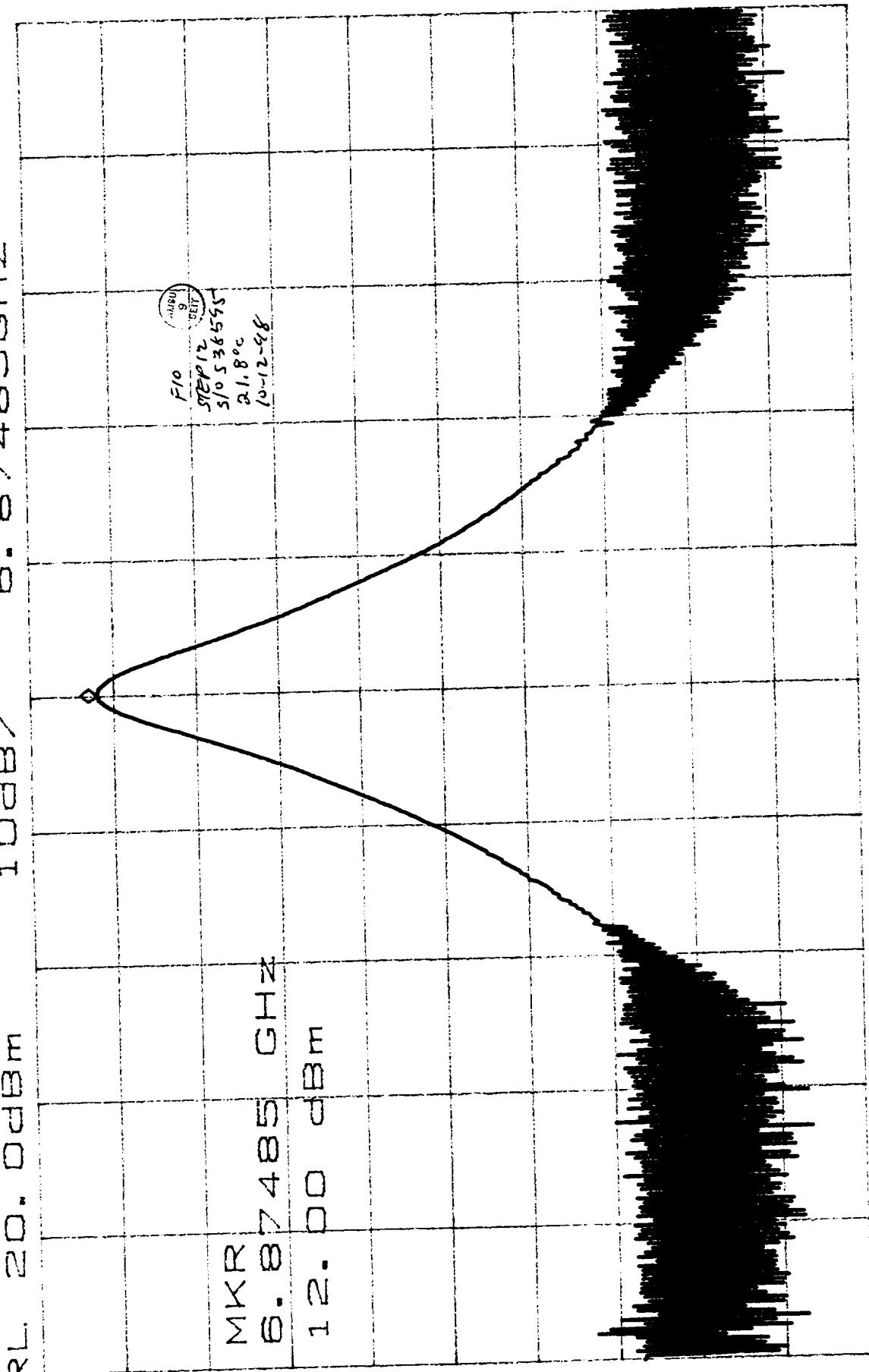
CL 30.0dB  
RL 0dBm

MKR -3.17dBm  
57.29033GHz



ATTEN 30dB  
RL. 20. 00dBm

MKR 12. 00dBm  
6. 87485GHz

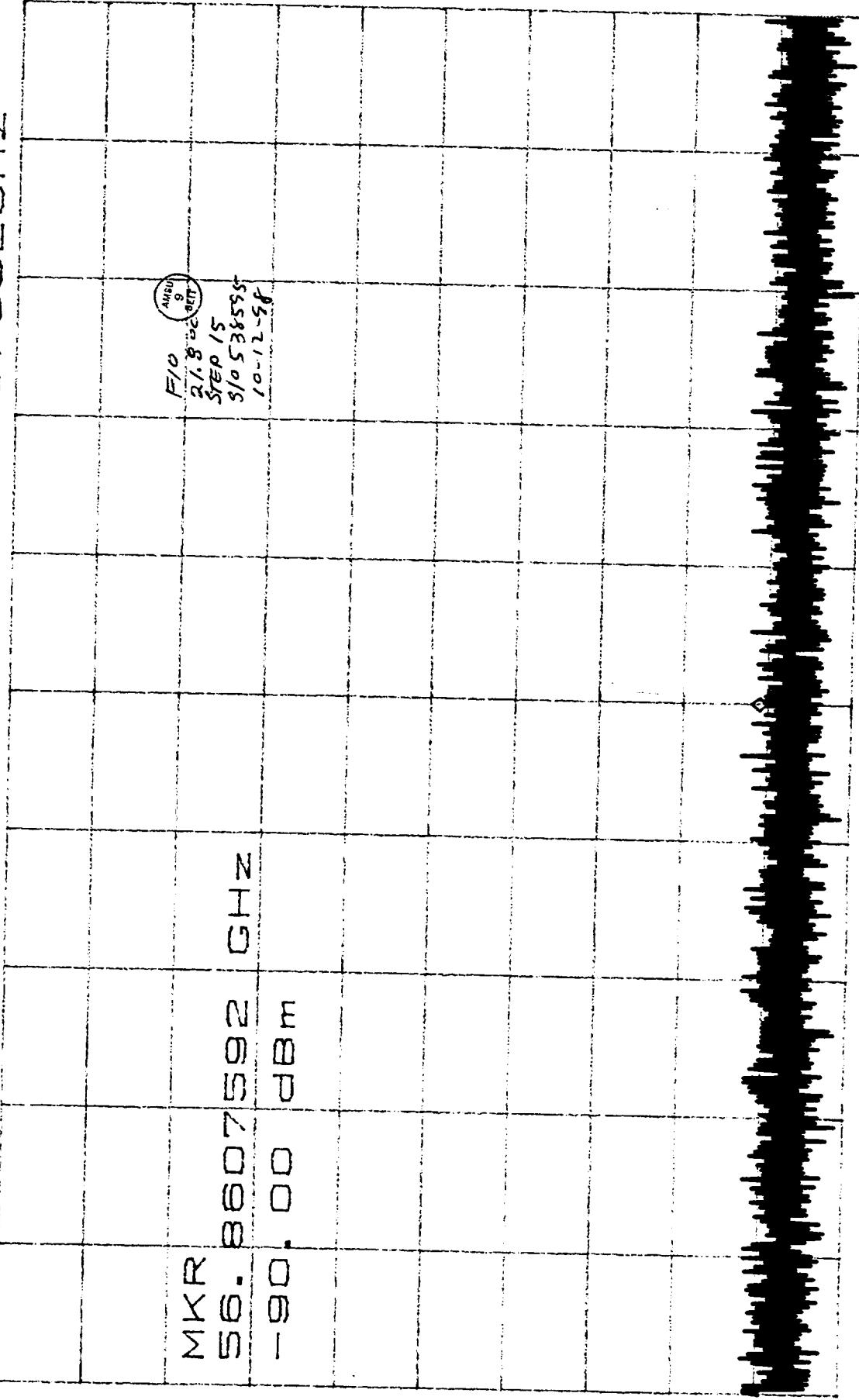


CENTER 6. 87483GHz  
\*RBW 300KHz VBW 300KHz

SPAN 10. 00MHz  
SWP 50. 0ms

CL 30.0dB  
RL 0dBm

MKR -90.00dBm  
56.8607592GHz



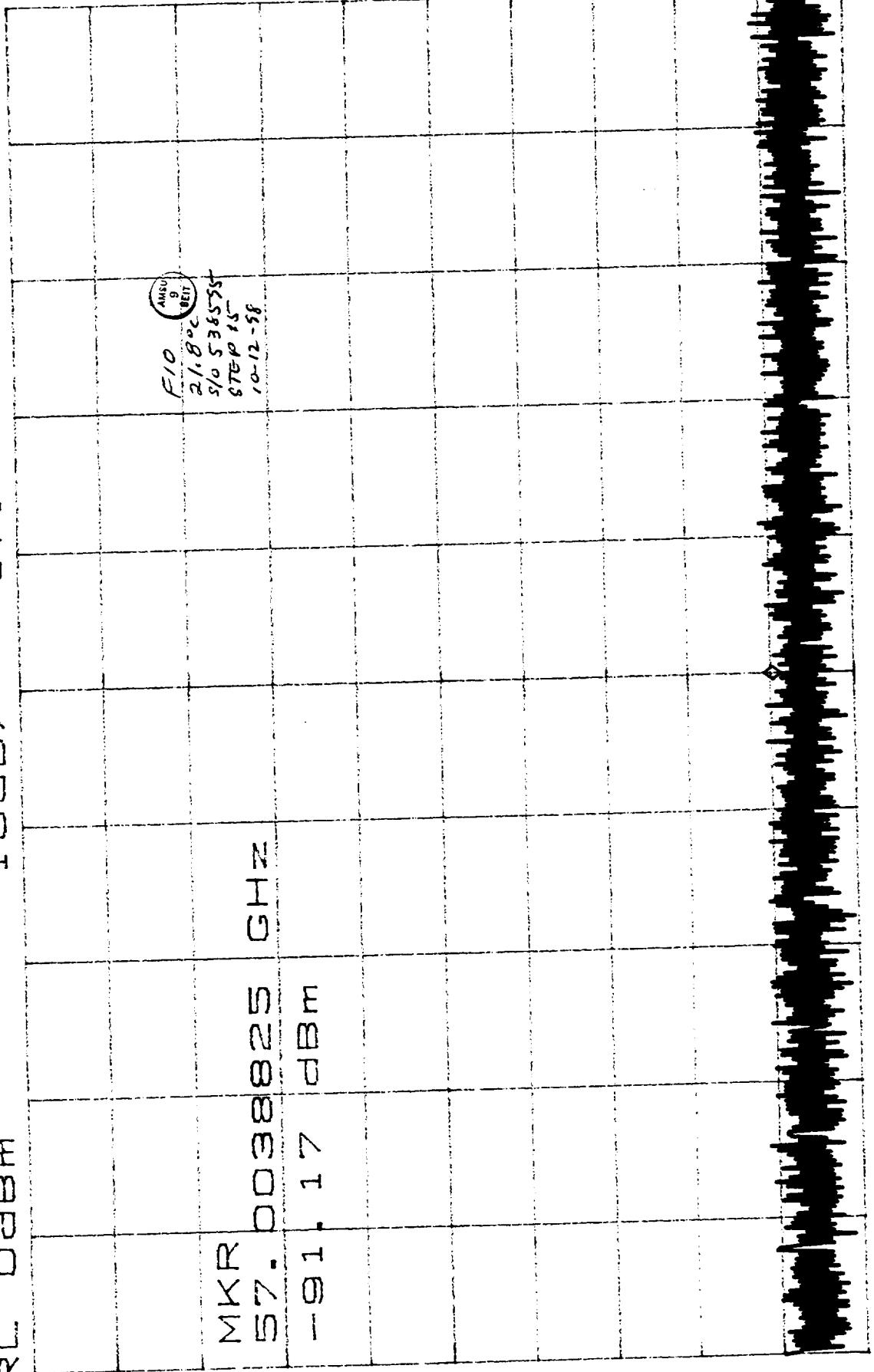
CENTER 56.8607592GHz  
RBW 3.0kHz \*VBW 1.0kHz  
SPAN 500.0kHz  
\*SWP 1.00sec

AMBIENT  
9  
F10  
218.000MHz  
STEP 1/5  
S10 S38595  
10-12-88

CL 30.0 dB  
RL 0dBm

MKR --91.17dBm  
57.0038825GHz

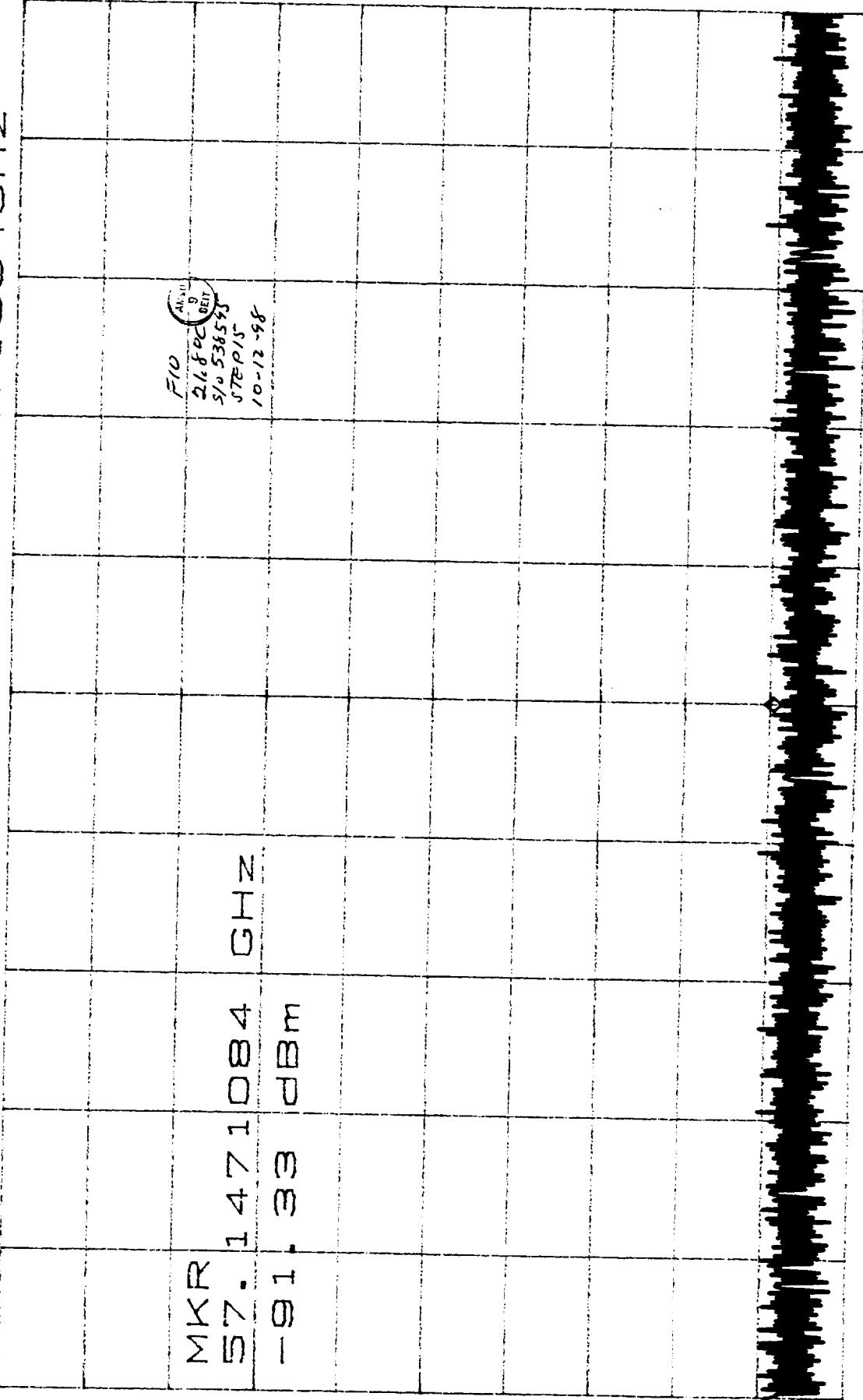
10dB /



CENTER 57.0038825GHz  
RBW 3.0kHz \*VBW 1.0kHz  
SPAN 500.0kHz  
\*SWP 1.00sec

CL 30.0dB  
RL 0dBm

MKR -91.33dBm  
57.1471084GHz

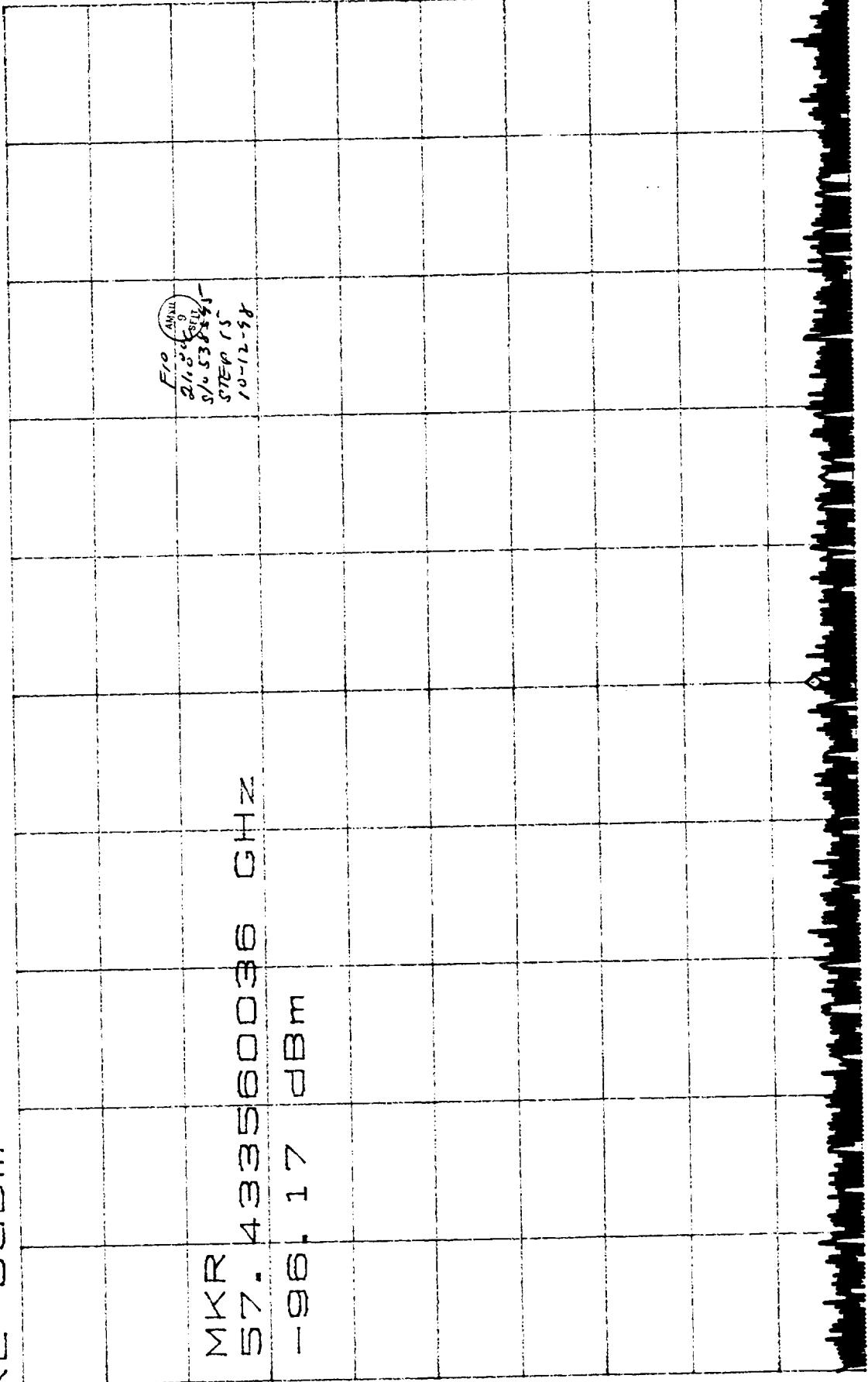


CENTER 57.1471084GHz  
RBW 3.0kHz \*VBW 1.0kHz  
SPAN 500.0kHz  
SWP 1.00sec

CL 30.0 dB  
RL 0dBm

MKR -96.17dBm  
57.433560036GHz

10dB/  
RL



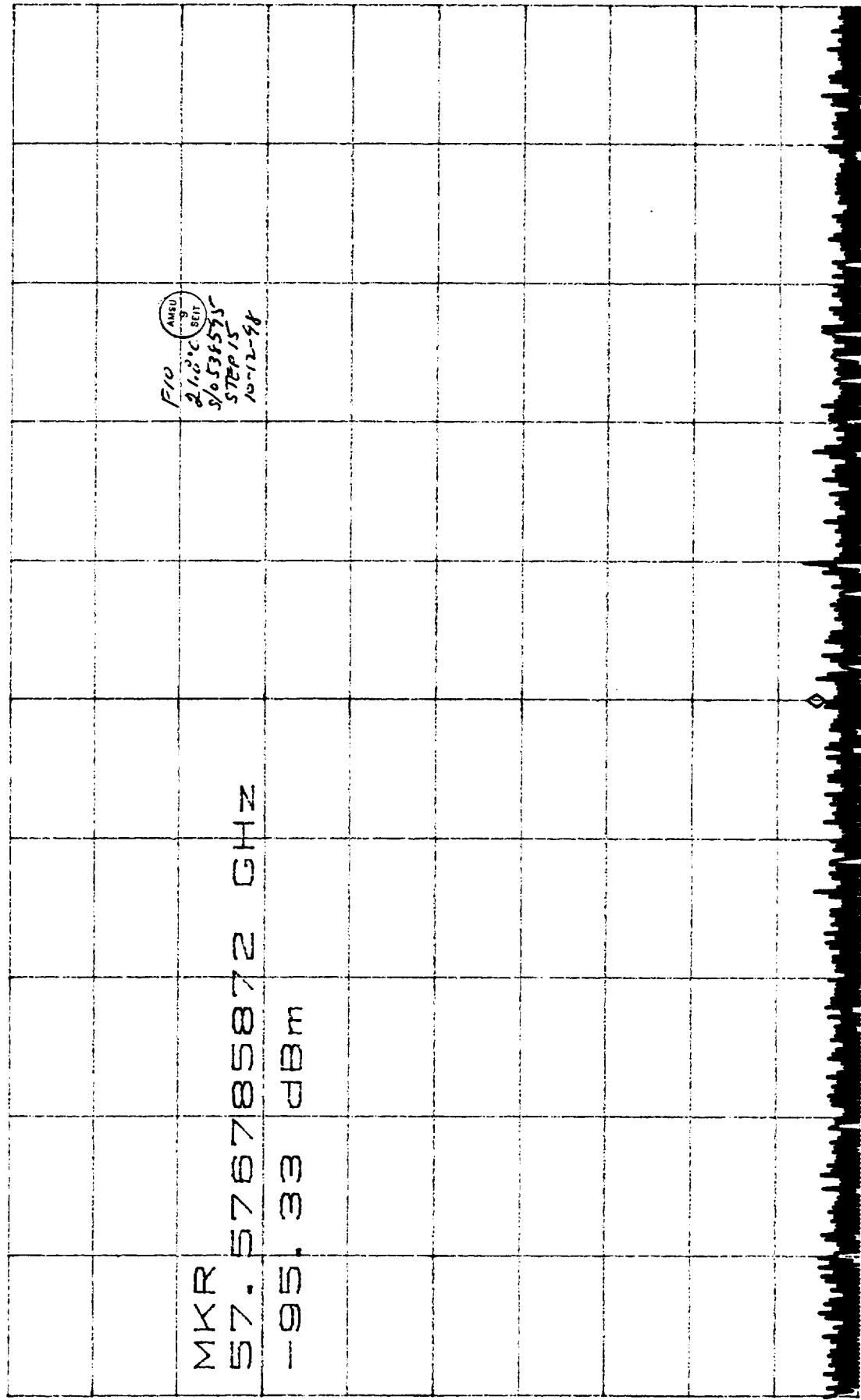
CENTER 57.433560036GHz  
RBW 300Hz \*VBW 1.0kHz

SPAN 5.400kHz  
\*SWP 1.00sec

CL 30.0dB

RL 0dBm

MKR -95. 33dBm  
57. 576785872GHz



CENTER 57. 576785872GHz \*VBW 1.0kHz SPAN 5. 400kHz  
RBW 300Hz \*\*SWP 1.00sec

CL 30.0dB  
RL 0dBm

10dB/  
RL 0dBm

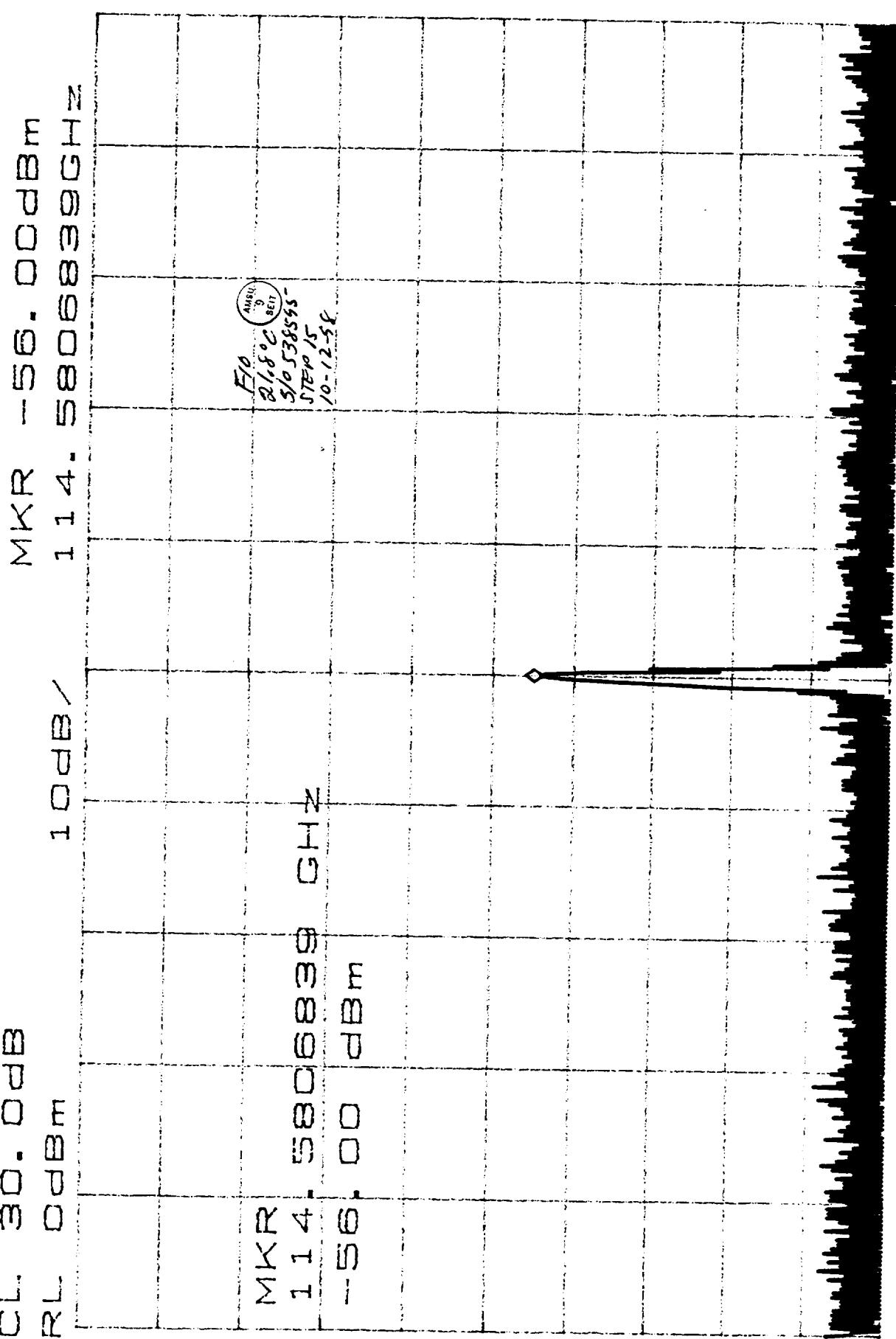
MKR -95.67dBm  
57.720011707GHz

MKR  
57.720011707 GHz  
-95.67 dBm

ANALOG  
9  
21.8°C  
S10 S11 S12 S13  
STEP 15  
10-2-38

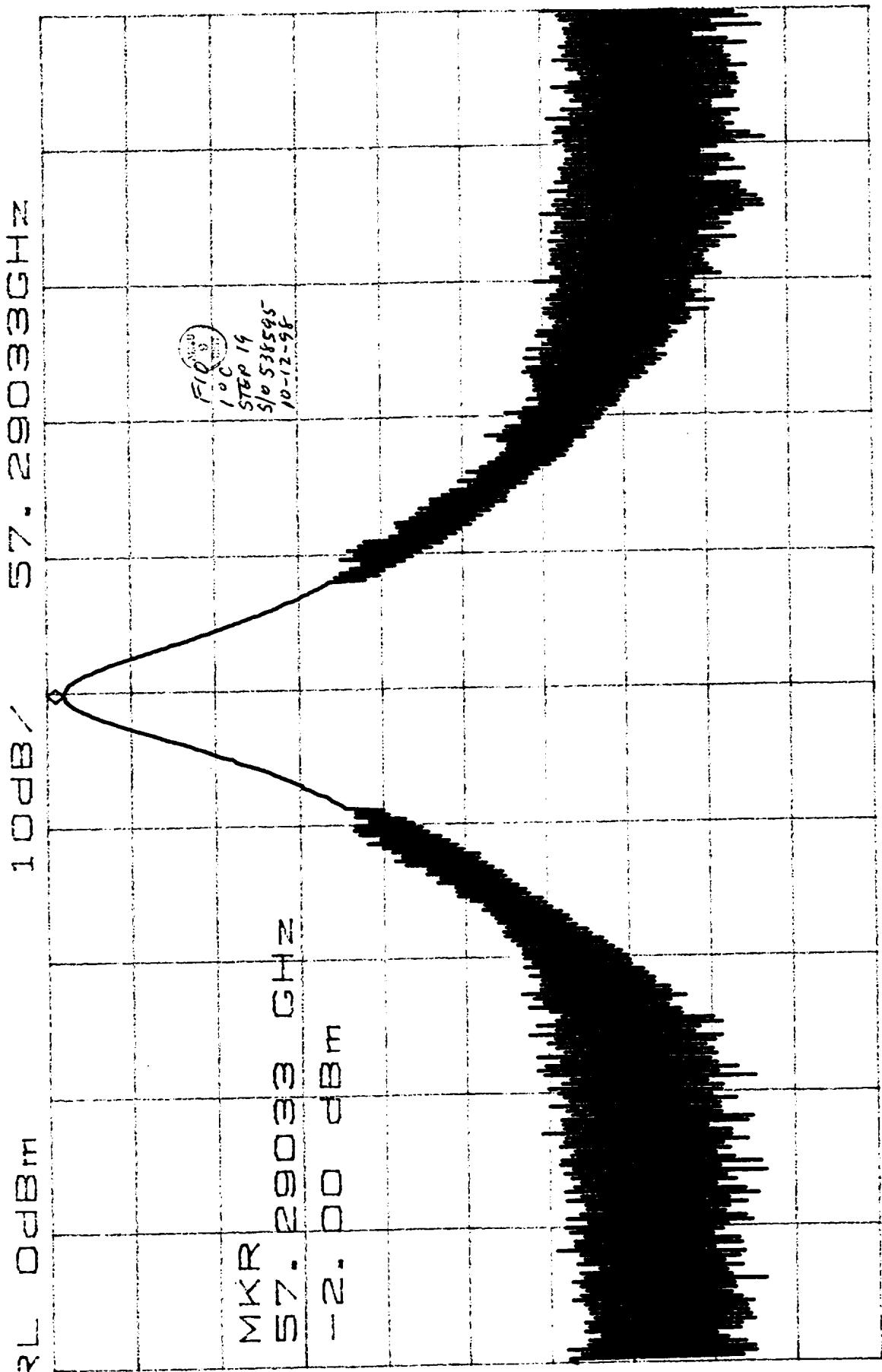
CENTER 57.720011707GHz  
RBW 300Hz \*VBW 1.0kHz  
SPAN 5.400kHz  
\*SWP 1.00sec

CL. 30. 0dB  
RL 0dBm



CL 30.0 dB  
RL 0 dBm

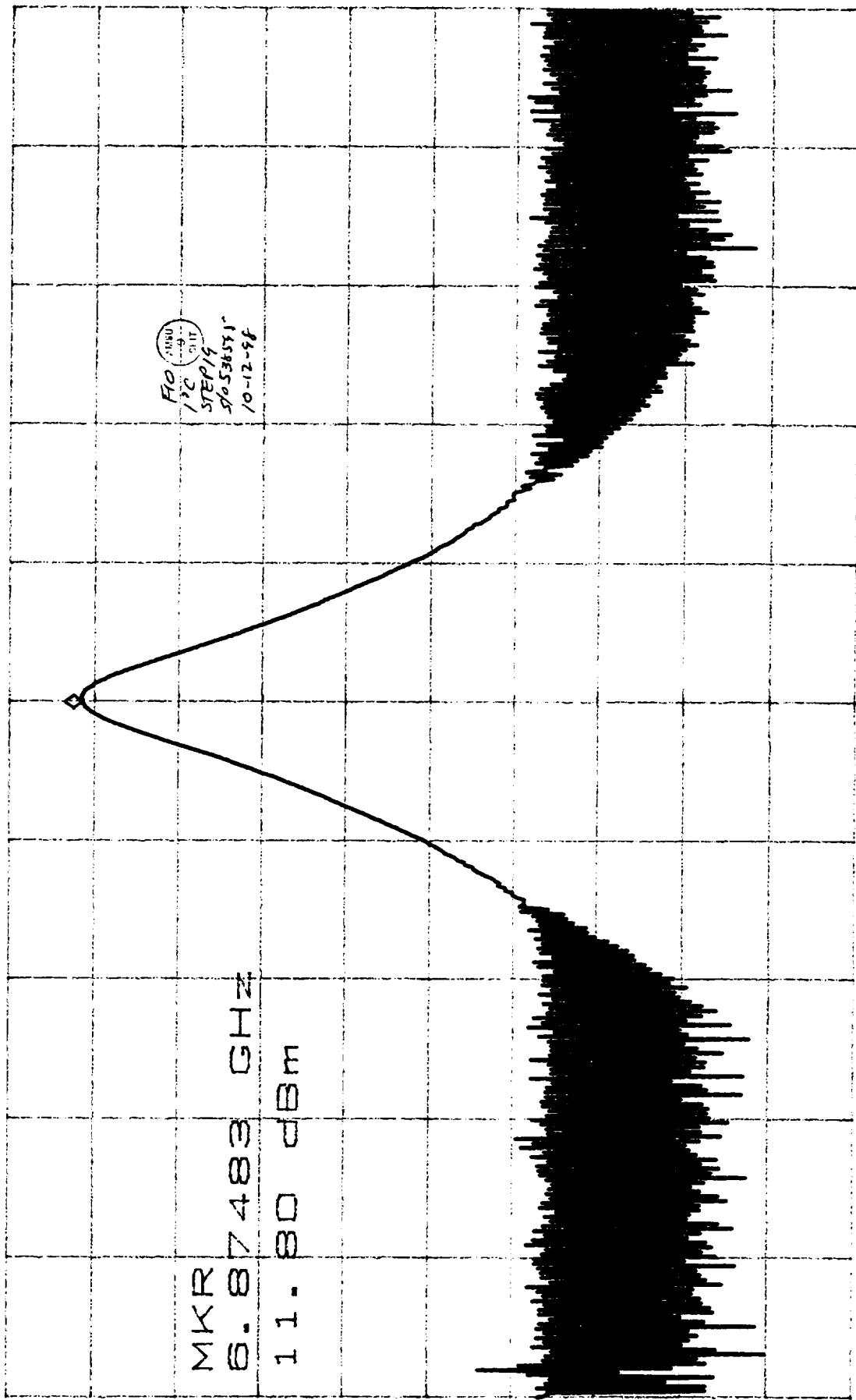
MKR -2.00 dBm  
57.29033 GHz



CENTER 57.29034 GHz \*VBW 300KHz  
\*RBW 300KHz \*SPAN 10.00MHz  
\*\*SWP 50.0ms

ATTEN 40dB  
RL 20.3dBm

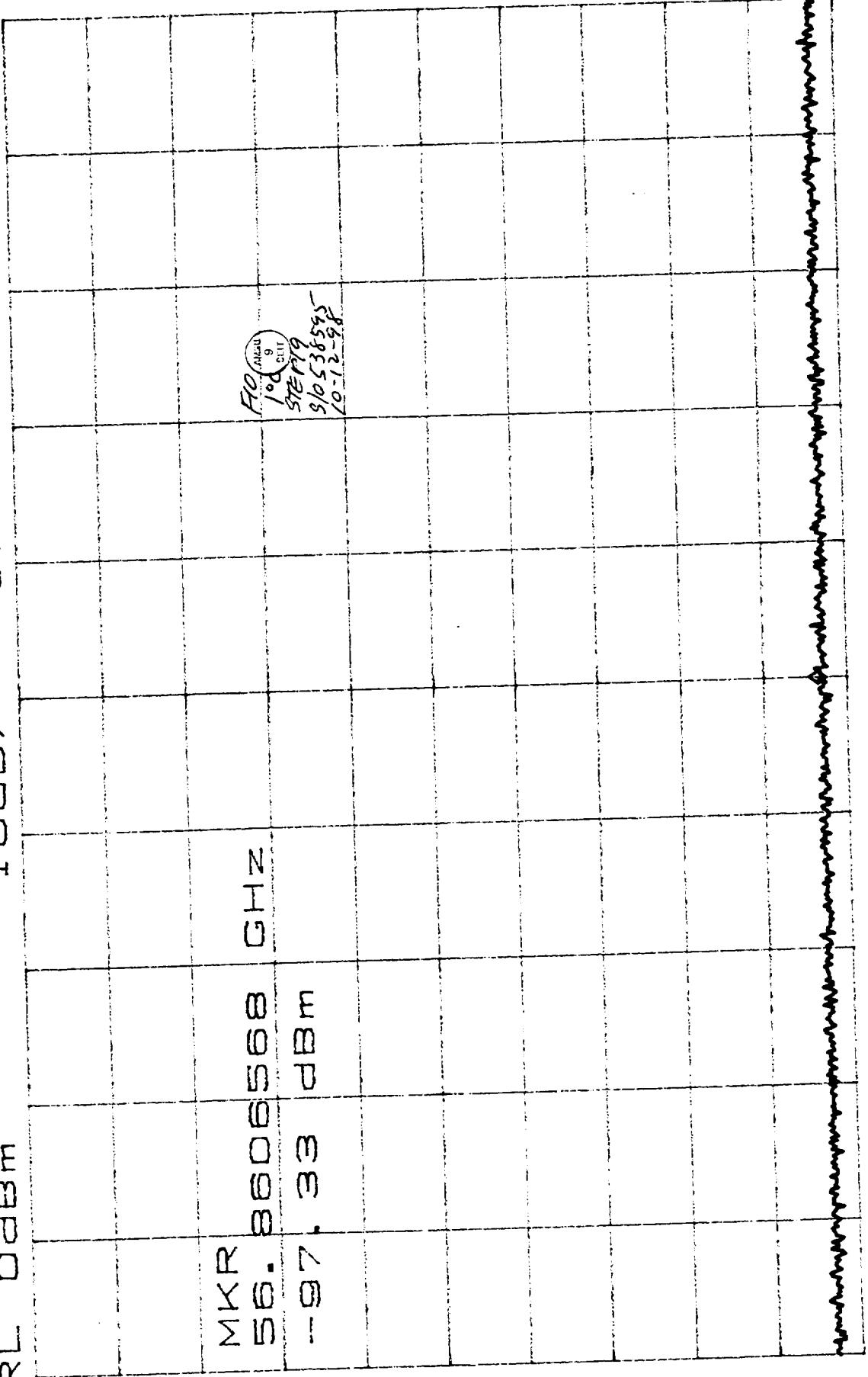
MKR 11-80dBm  
6.87483GHz  
10dB/



CENTER 6.87483GHz  
RBW 300kHz VBW 3

CL 30.0dB VAVG 26  
RL 0dBm

MKR -97.33dBm  
56.8606568GHz

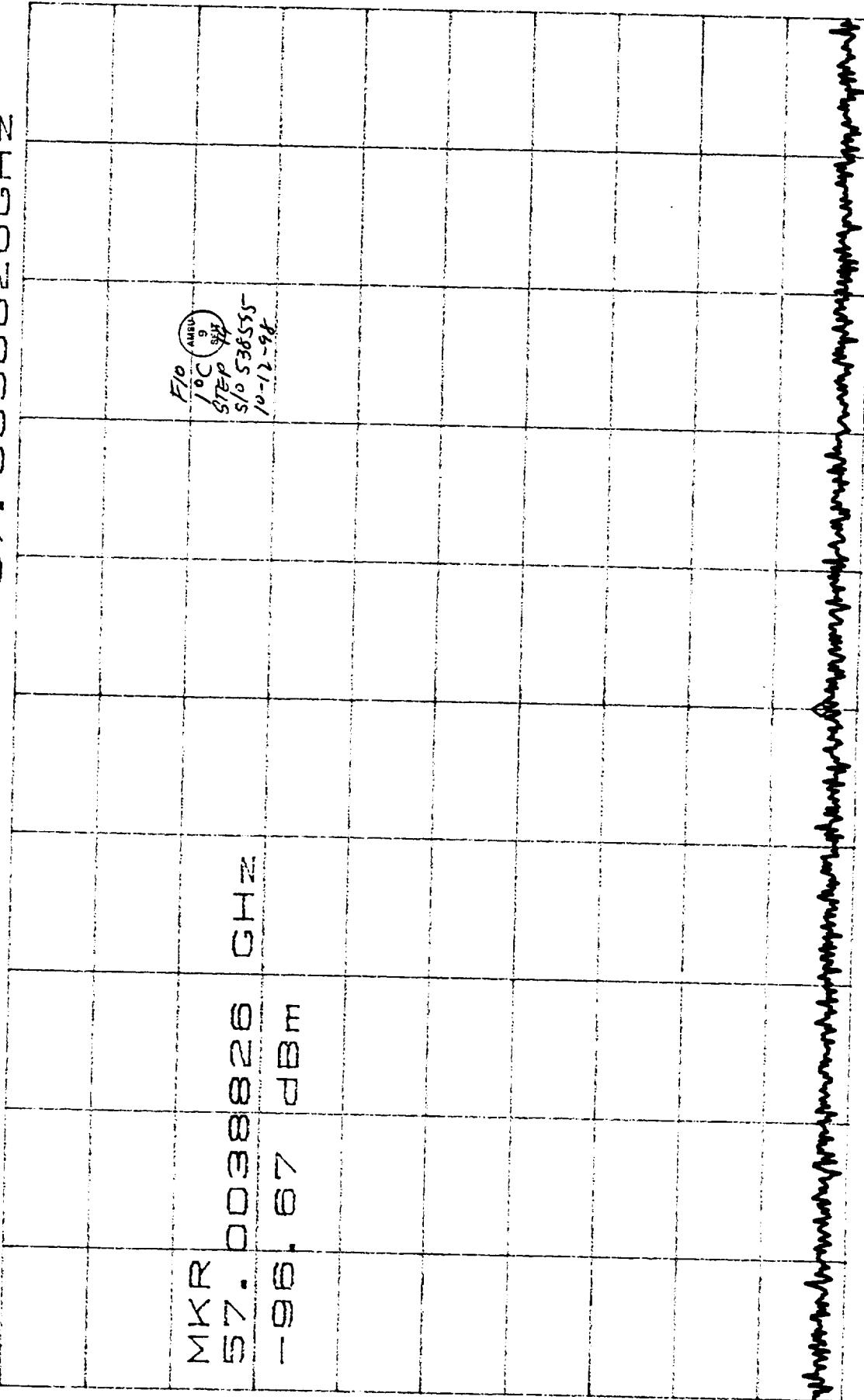


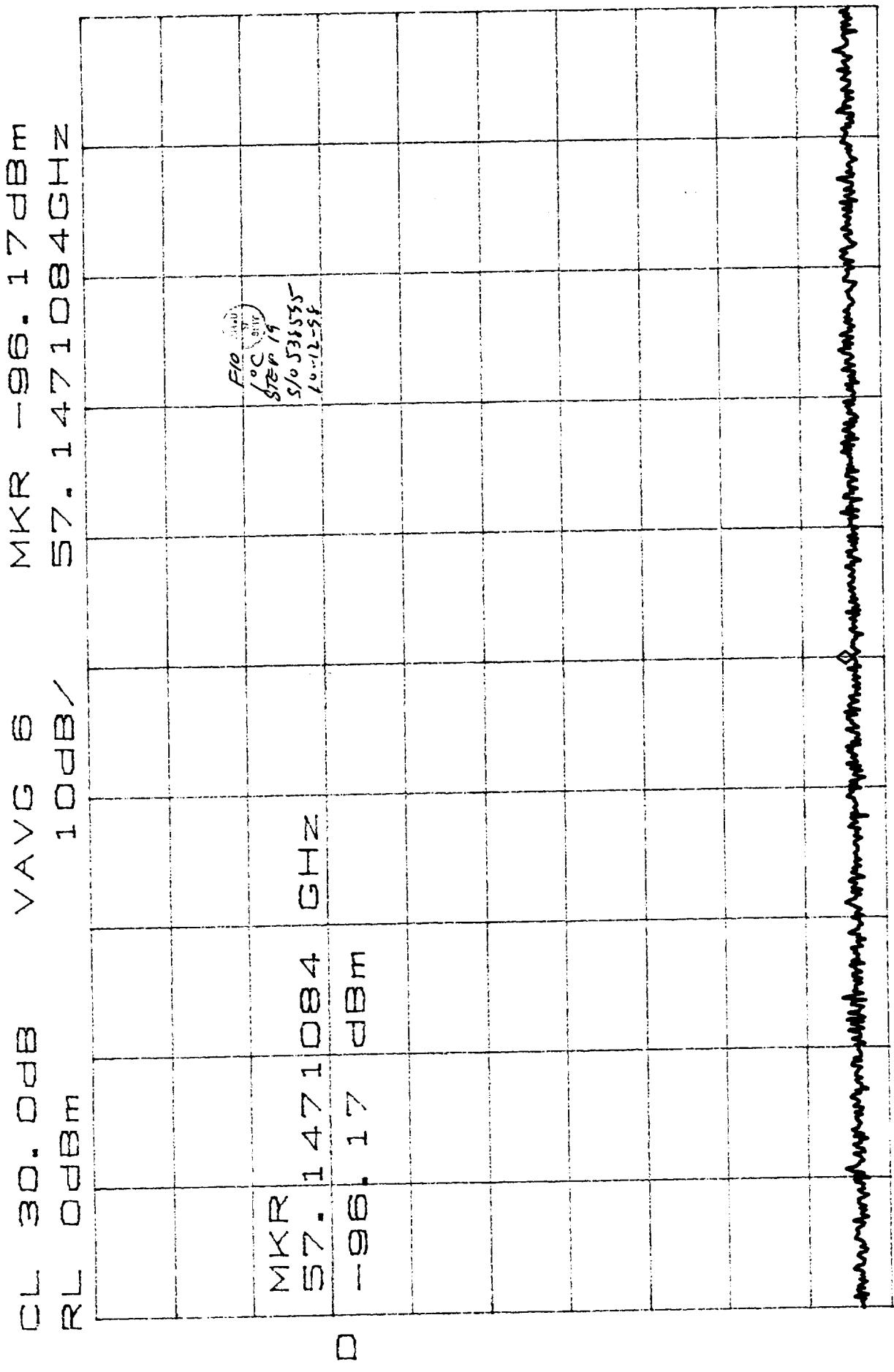
□

CENTER 56.8606568GHz  
\*RBW 1.0kHz VBW 1.0kHz  
SPAN 500.0kHz  
SWP 1-30sec

CL 30.0dB V AVG 5  
RL 0dBm

MKR -96.67dBm  
57.0038826GHz



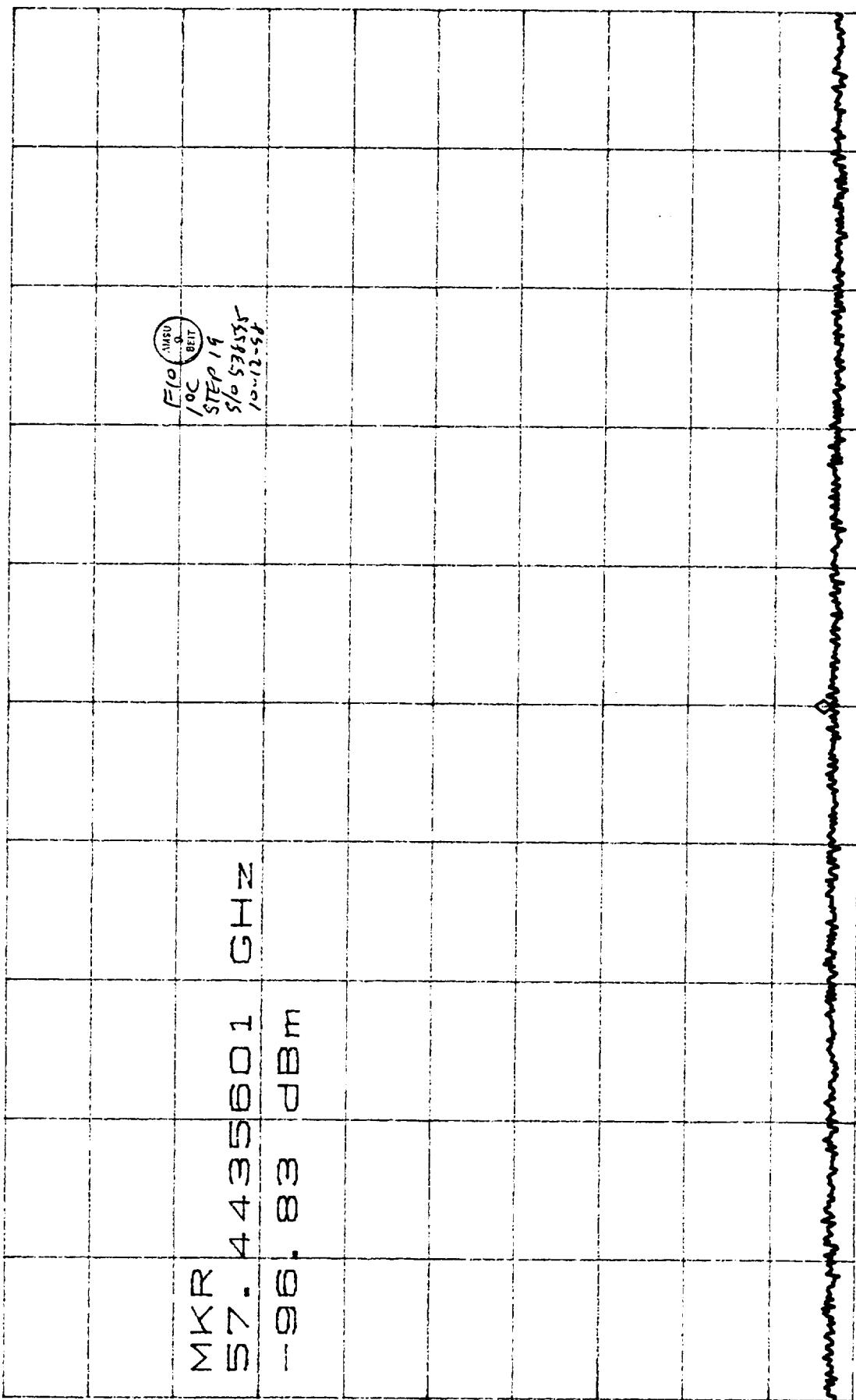


CENTER 57. 1471084GHz SPAN 500. 0kHz  
 \*RBW 1. 0kHz VBW 1. 0kHz SWP 1. 30sec

CL 30. DBB  
RL DBm

V AVG 45  
10 dB /

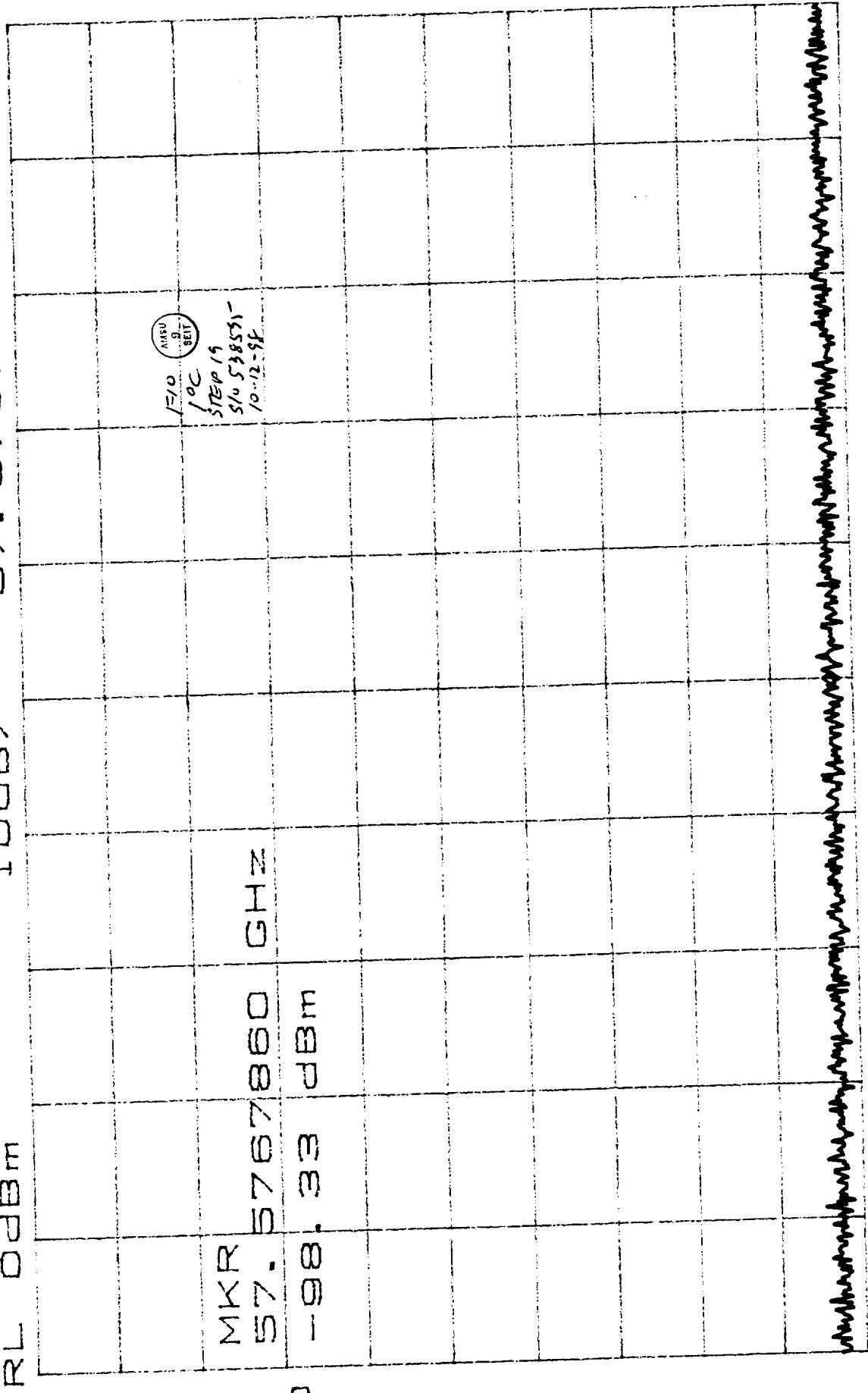
MKR -96. 83 dBm  
57. 4435601 GHz



□

CENTER 57. 4435601 GHz  
\*RBW 1. 0KHz VBW 1. 0KHz SPAN 500. 0KHz  
SWP 1 - 30sec

CL 30. 0dB VAVG 5 MKR -98. 33dBm  
RL 0dBm 10dB /

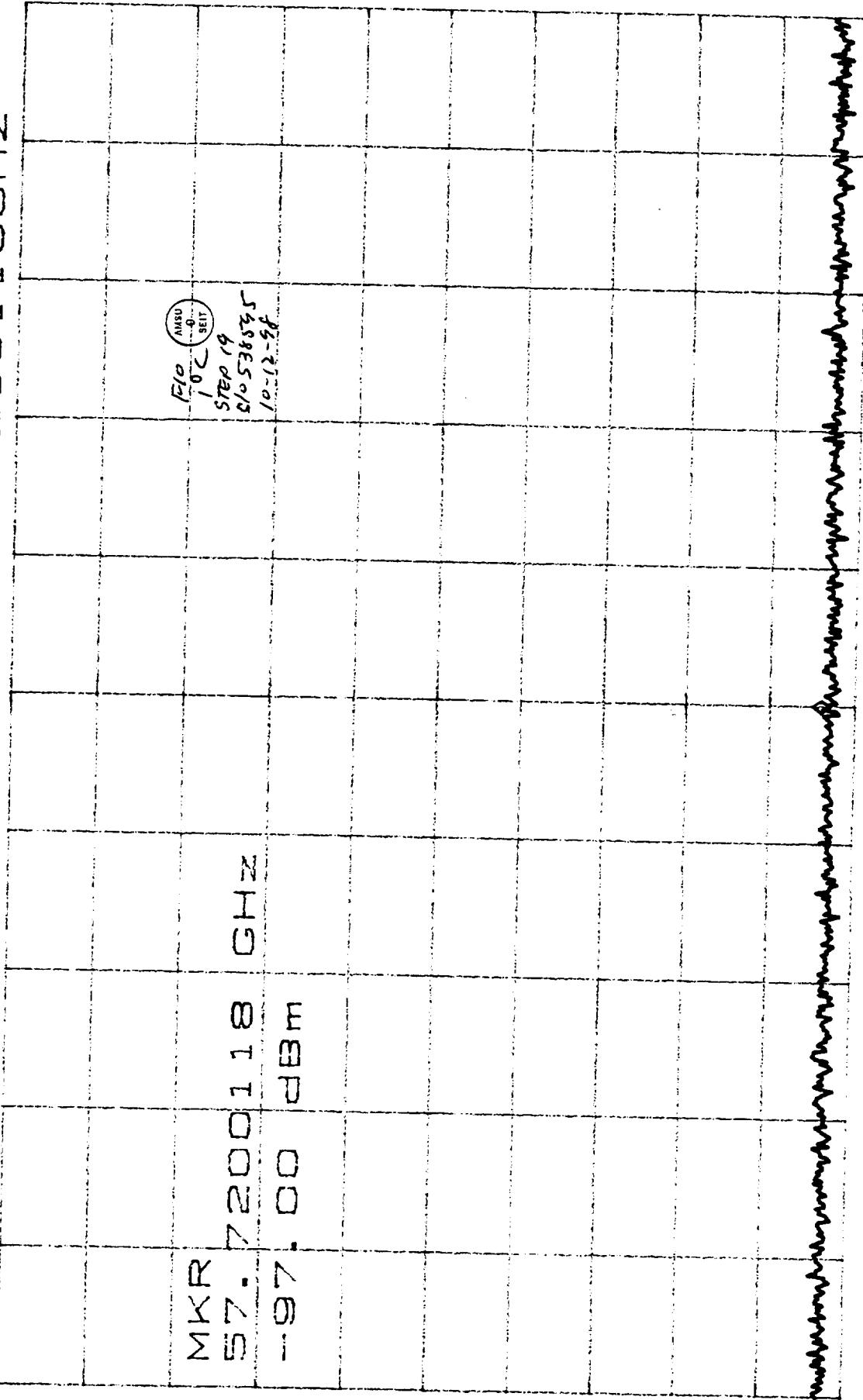


CENTER 57. 5767860 GHz  
RBW 1. 0kHz SWP 1. 30sec SPAN 500. 0kHz  
\*\*RBW 1. 0kHz

CL 30.0dB  
RL 0dBm

VAVG 8  
10dB/  
V

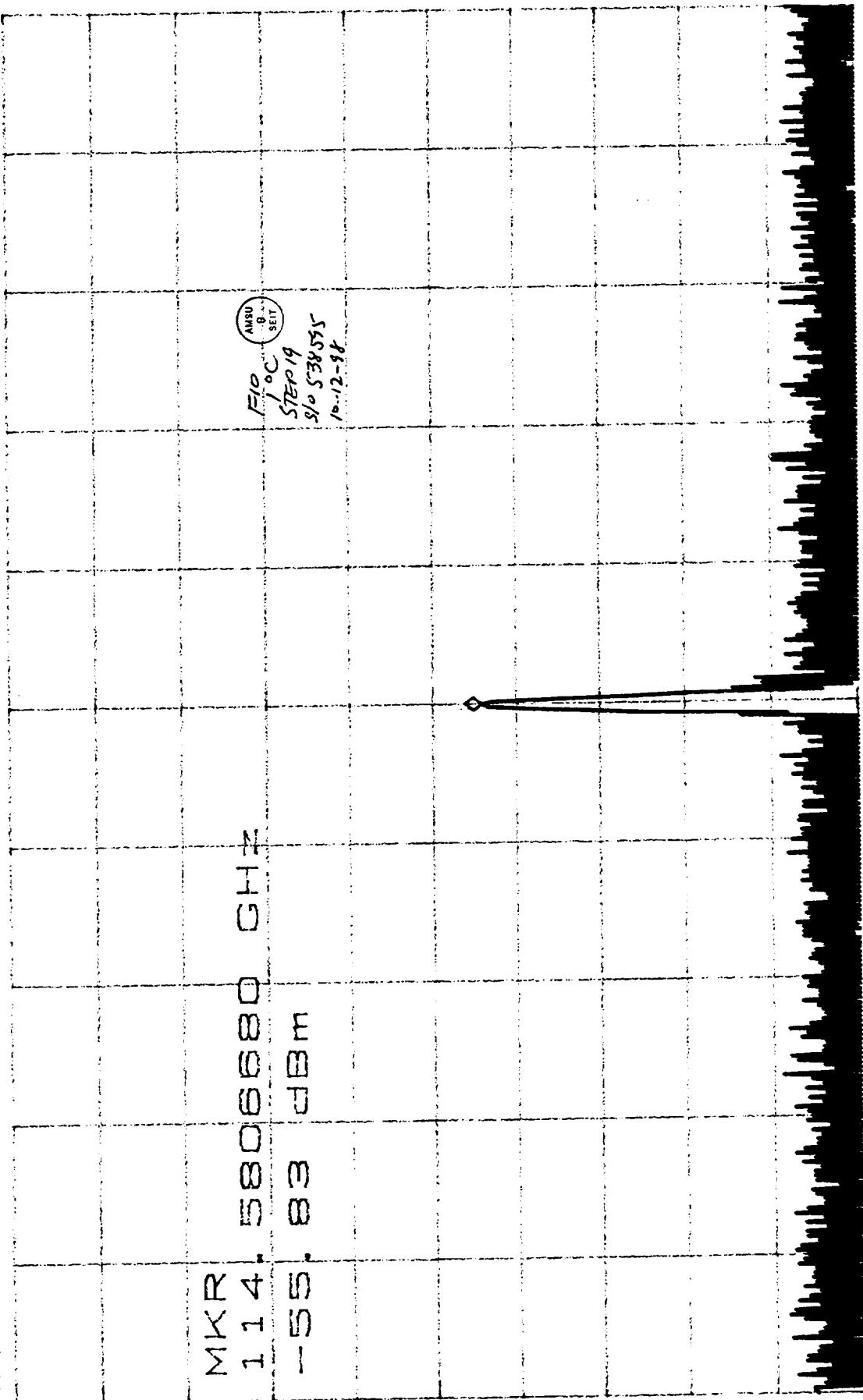
MKR -97.00dBm  
57.7200118GHz



CENTER 57.7200118GHz  
RBW 1.0kHz  
\*RBW 1.0kHz  
VWB 1.0kHz  
SPAN 500.0kHz  
SWP 1-30sec

30.04B  
QD3M  
CL

MKR - 55. 83dBm  
114. 5806680GHz  
10dB /



\*R3W 300HZ \*V3W 1.0KHZ  
CENTER 114.5806680GHZ

SPAN 100.0KHZ  
\*SWP 2.80SEC

TEST DATA SHEET 6A (Sheet 2 of 4)  
Functional Testing (Paragraph 4.2.1)

## Pre-Environmental CPT

## Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
14	Frequency vs. Voltage			
	± 15 V Supplies	+14.8 ± 0.05 V	+Voltage = <u>14.8</u> V	Pass
		-14.8 ± 0.05 V	-Voltage = <u>-14.8</u> V	✓
		57.290344 ± .0002 GHz	Freq. = <u>57.290342 008</u> GHz	
15	Spurious and Sub	-200 to -90 dBc	<u>see plots</u>	
	Power level of 114.58 GHz signal	<-10 dBm	<u>-56</u> dBm	Pass
17	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <u>6 Hz</u>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <u>-5 dB</u> dB Peak	N/A
18	Operating Temperature @ 1°C baseplate	TC1 = 1 ± 2°C	TC1 = <u>1.0</u>	Pass
			TC2 = <u>2.5</u>	N/A
			TC3 = <u>1.0</u>	N/A
		0 - 1V	DRO L/A = <u>44</u> mV	Pass
19	Input Voltage and Current	0 to 1V	PLO L/A = <u>4.54</u> V	Pass
		VM1 Voltage	VM1 = <u>15.0</u> V	Pass
		VM2 Voltage	VM2 = <u>-15.0</u> V	✓
		IM1 Current	IM1 = <u>519</u> mA	
		IM2 Current	IM2 = <u>-65</u> mA	
		DRO L/A Voltage	DRO L/A = <u>44</u> mV	
		PLO L/A Voltage	PLO L/A = <u>4.54</u> V	
		RF Output Power	Power = <u>19.36</u> dBm	
	Frequency vs. Voltage	Frequency	Freq. = <u>57.290344 28</u> GHz	
		± 15 V Supplies	+Voltage = <u>15.2</u> V	
			-Voltage = <u>-15.2</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.290339166</u> GHz	
		17 to 20 dBm	Power = <u>19.35</u> dBm	
		Frequency vs. Voltage		
		± 15 V Supplies	+Voltage = <u>14.8</u> V	
			-Voltage = <u>-14.8</u> V	
		57.290344 ± .0002 GHz	Freq. = <u>57.29033951</u> GHz	✓
		17 to 20 dBm	Power = <u>19.35</u> dBm	Pass

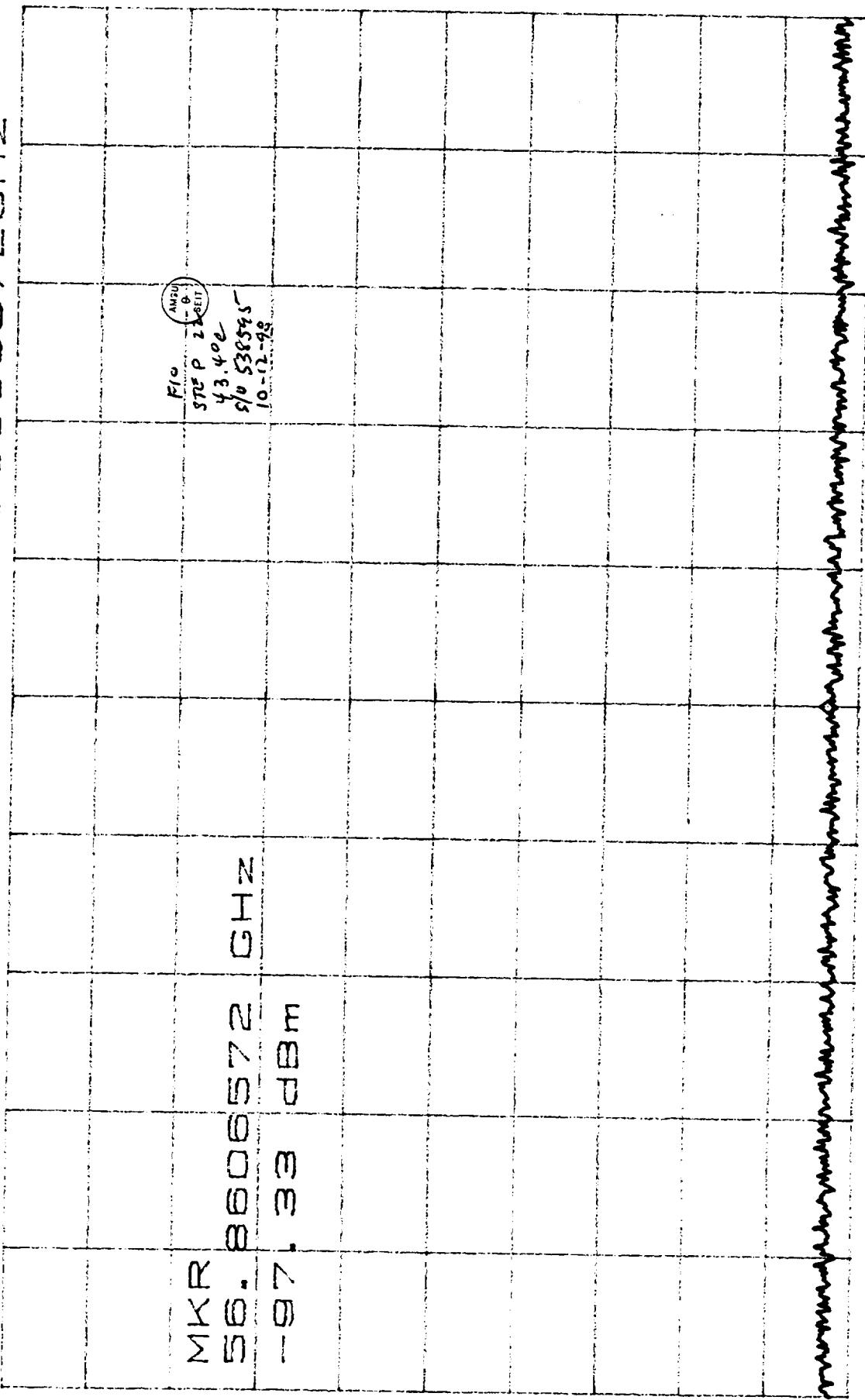
TEST DATA SHEET 6A (Sheet 3 of 4)  
Functional Testing (Paragraph 4.2.1)

Pre-Environmental CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
19 (Cont)	Spurious and Sub	-200 to -90 dBc	<u>see plots</u>	<u>Pass</u>
	Power level of 114.58 GHz signal	<-10 dBm	<u>-55.8</u> dBm	<u>Pass</u>
<b>Load VSWR and Frequency Pulling</b>				
	2:1 mismatch over $1\lambda$	N/A	Worst Case Freq = <u>6.443</u>	N/A
	2:1 mismatch over $1\lambda$	N/A	Worst Case Power = <u>1.38</u> dB	N/A
21	Operating Temperature @ +44°C Baseplate	TC1 = 44 ± 2°C	TC1 = <u>43.3</u>	N/A
			TC2 = <u>44.0</u>	N/A
			TC3 = <u>43.0</u>	N/A
			DRO L/A = <u>111 mV</u>	<u>Pass</u>
22	Input Voltage and Current	0 - 1V -0 to +V 4.3 - 4.7V	PLO L/A = <u>4.52 V</u>	<u>Pass</u>
			VM1 = <u>15.0</u> V	
			VM2 = <u>-15.0</u> V	
			IM1 = <u>542</u> mA	
			IM2 = <u>-65.7</u> mA	
			DRO L/A = <u>111 mV</u>	
			PLO L/A = <u>4.52 V</u>	
			Power = <u>17.54</u> dBm	
	Frequency vs. Voltage	57.290344 ± .0002 GHz	Freq. = <u>57.290333903</u> GHz	
			+Voltage = <u>15.2</u> V	
			-Voltage = <u>-15.2</u> V	
			Freq. = <u>57.290334133</u> GHz	
			Power = <u>17.53</u> dBm	
	Frequency vs. Voltage	± 15 V Supplies	+Voltage = <u>14.8</u> V	
			-Voltage = <u>-14.8</u> V	
			Freq. = <u>57.290334184</u> GHz	<u>Pass</u>
			Power = <u>17.54</u> dBm	<u>Pass</u>

CL 30.0dB VAVG 10 MKR -97.33dBm  
RL 0dBm 56.8606572GHz



CENTER 56.8606572GHz SPAN 500.0kHz  
\*RBW 1.0kHz \*\*VBW 1.0kHz \*SWP 1.30sec

CL 30. □ DIB

RUE D'BBE

3 VAG

100B/

MKR-94-6748m

54 - 008888002200

四

CENTER 57. 0038822GHZ  
\*RBW 1.0KHZ \*VBW 1.0KHZ

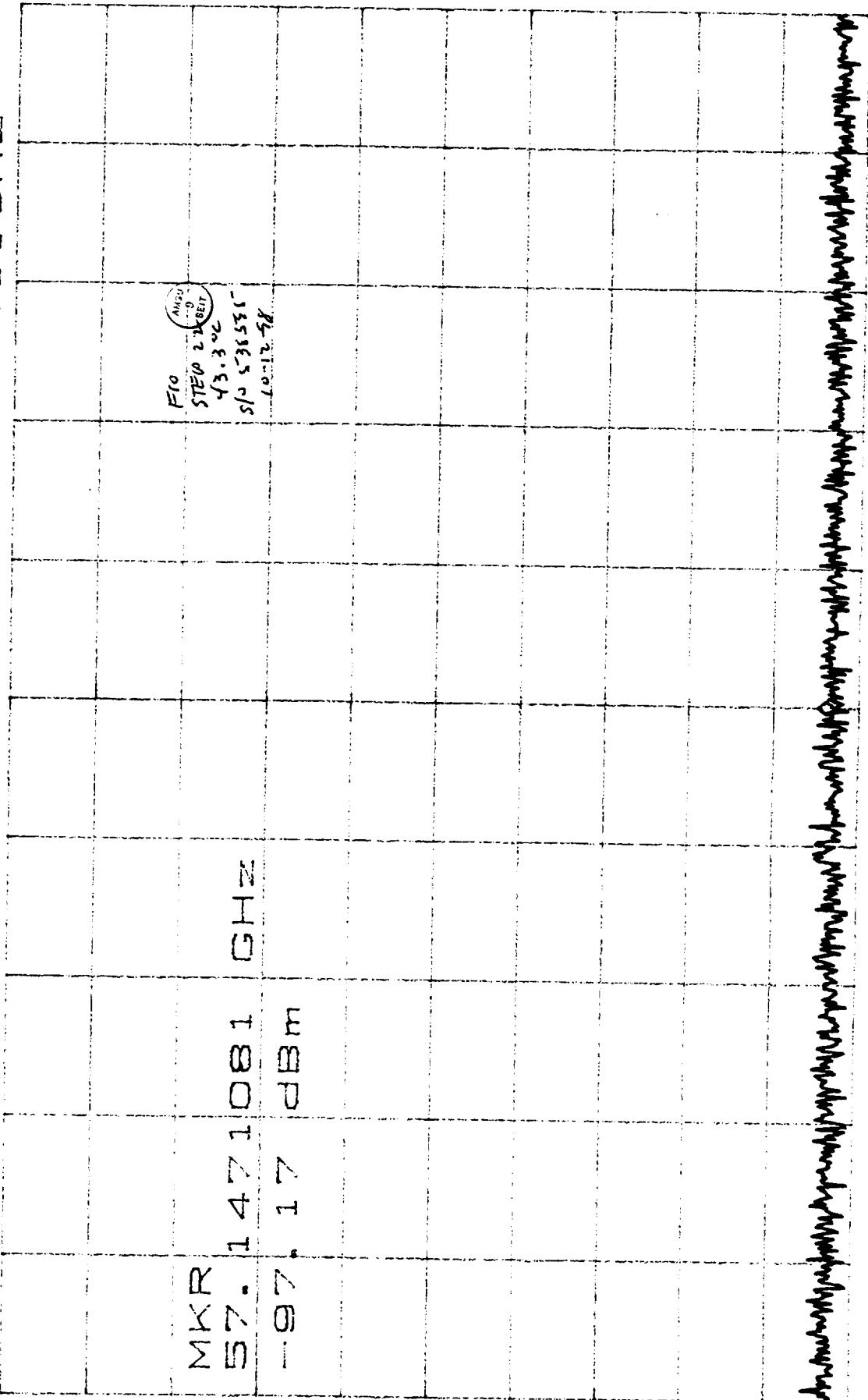
SPAN 500. OKHZ

1. SWP \* 300000

CL 30.0dB  
RL 0dBm

VAVG 2  
10dB/  
dBm

MKR -97.17dBm  
57.1471081GHz

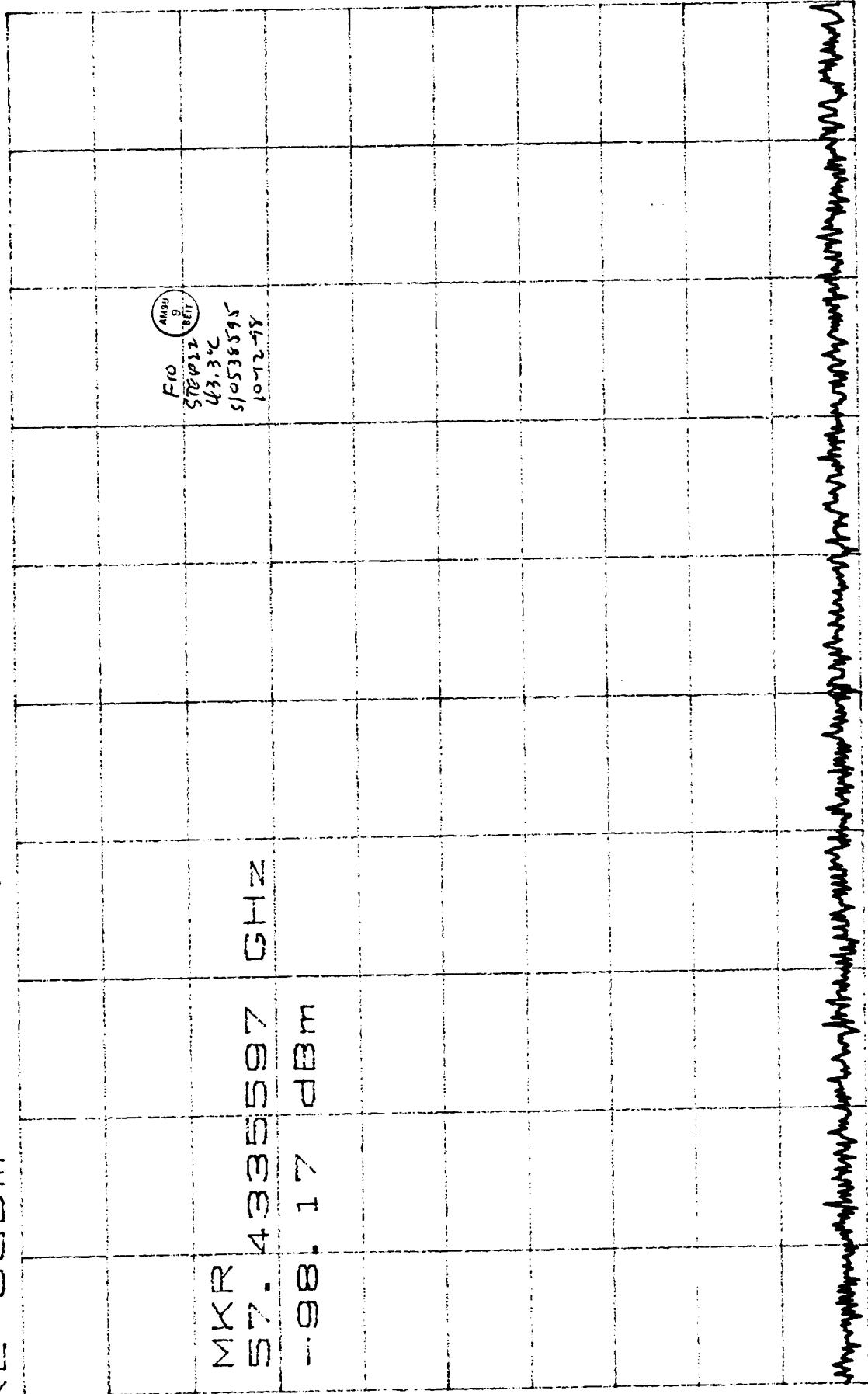


□

CENTER 57.1471081 GHz \*VBW 1.0kHz  
\*RBW 1.0kHz \*SPAN 500.0kHz  
\*SWP 1.30sec

CL 30.0dB  
RL 0dBm

VAVG 3 MKR -98.17dBm  
10dB/  
57.4335597GHz



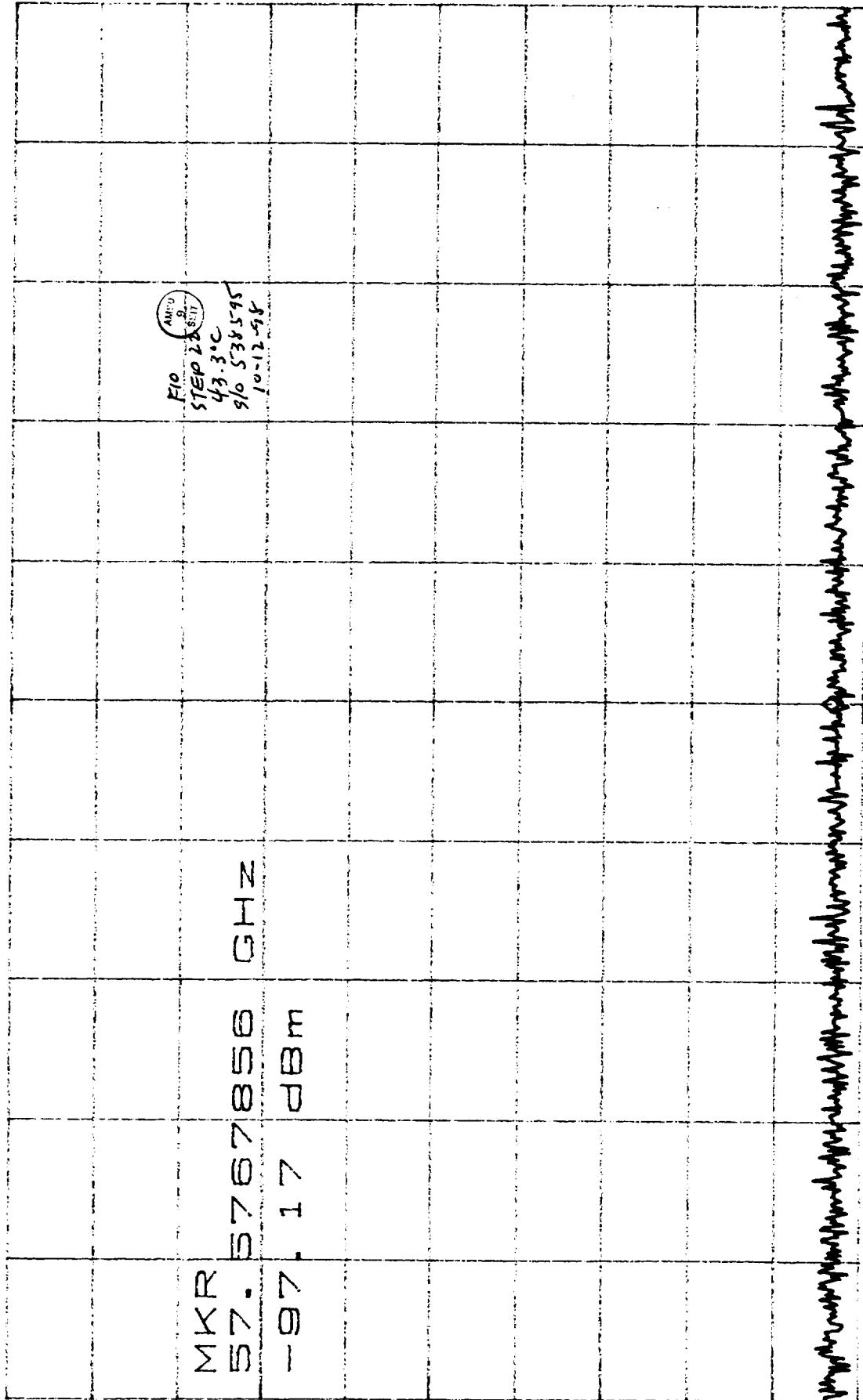
□

CENTER 57.4335597GHz \*RBW 1.0kHz \*VBW 1.0kHz  
\*SPAN 500.0kHz  
\*SWP 1.30sec

CL 30.0dB  
RL 0dBm

VAVG 3  
10dB/  
10dBm

MKR -97.17dBm  
57.5767856GHz

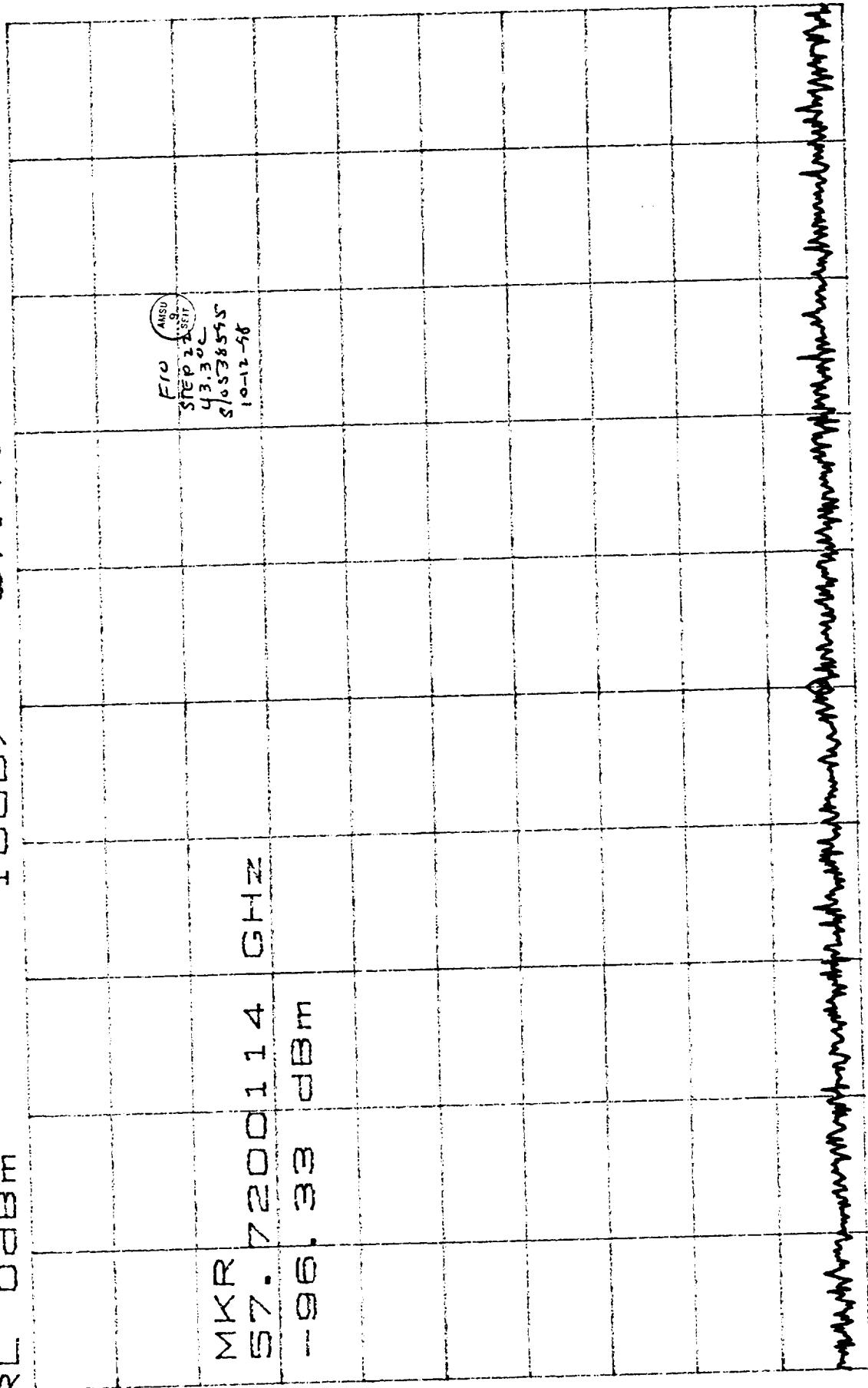


□

CENTER 57.5767856GHz \*VBW 1.0kHz  
\*RBW 1.0kHz SPAN 500.0kHz  
\*SWP 1.30sec

CL 30.0dB  
RL 0dBm

V A V G 4  
10dB/  
MKR -96. 33dBm



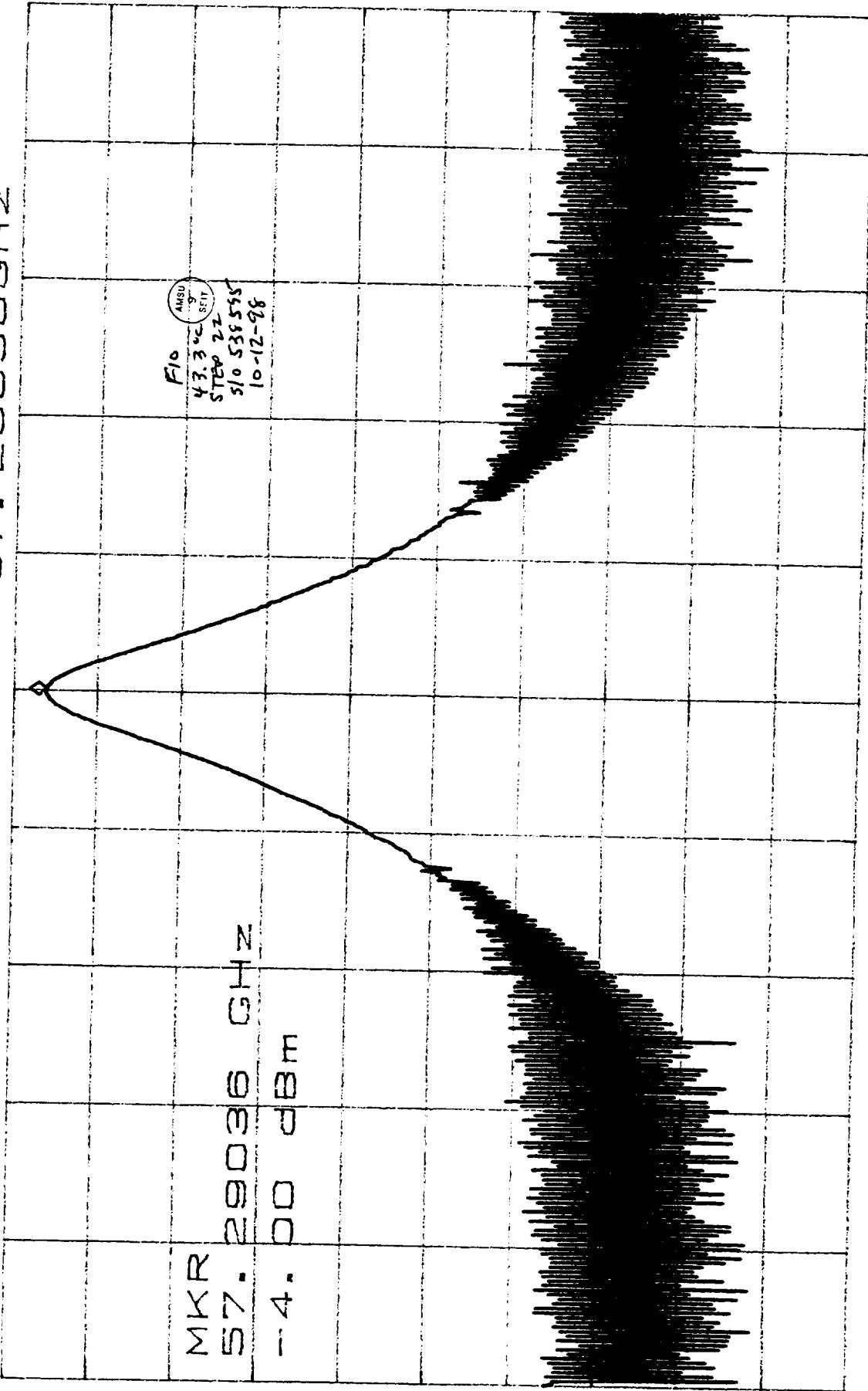
□

CENTER 57.7200114GHz \*RBW 1.0kHz  
\*RBW 1.0kHz SPAN 500.0kHz

\*SWP 1.30sec

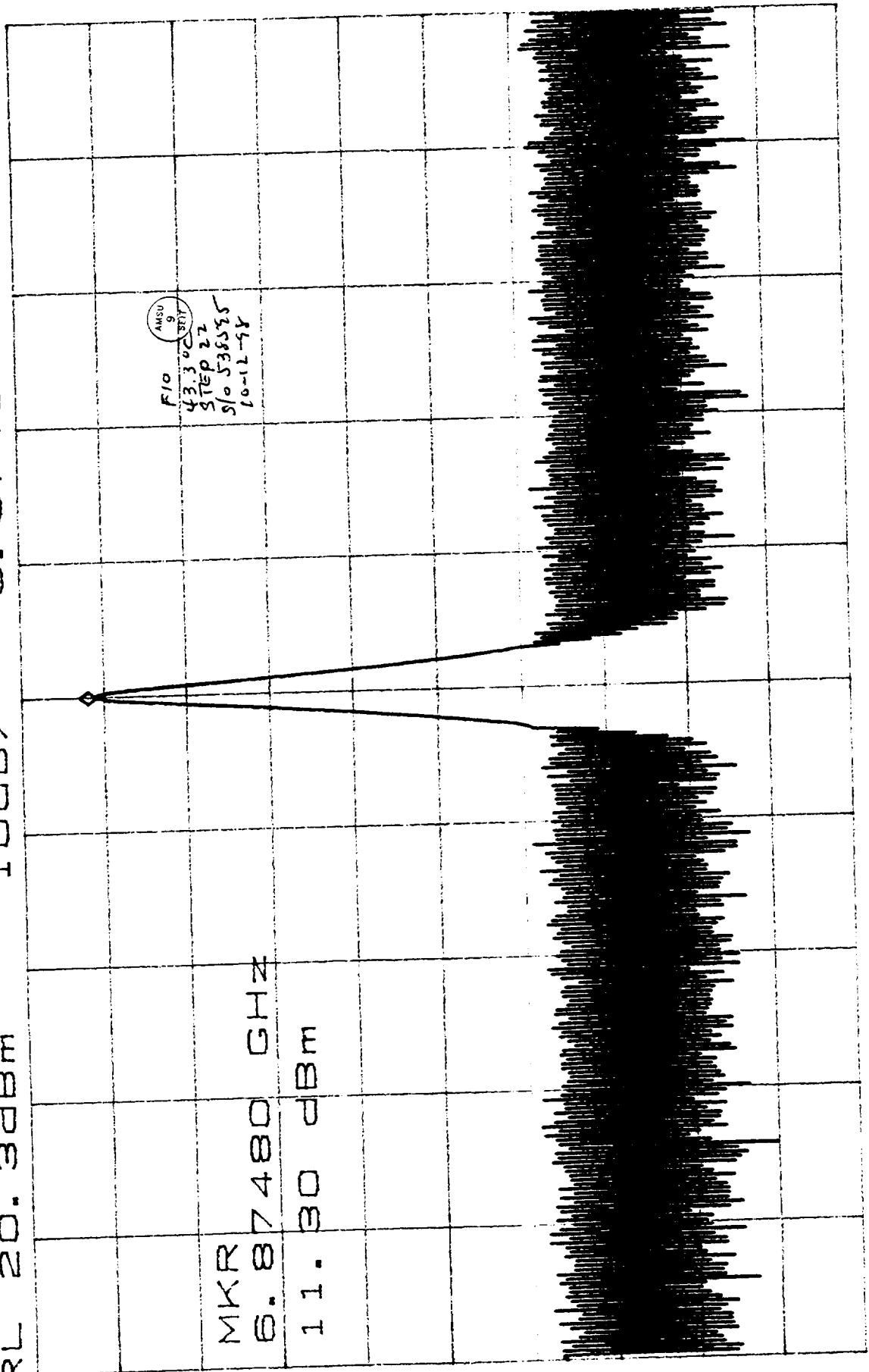
CL 30.0 dB  
RL 0 dBm

MKR -4.00 dBm  
57.29036 GHz



ATTEN 40dB  
RL 20. 3dBm

MKR 11. 30dBm  
6. 87480GHz

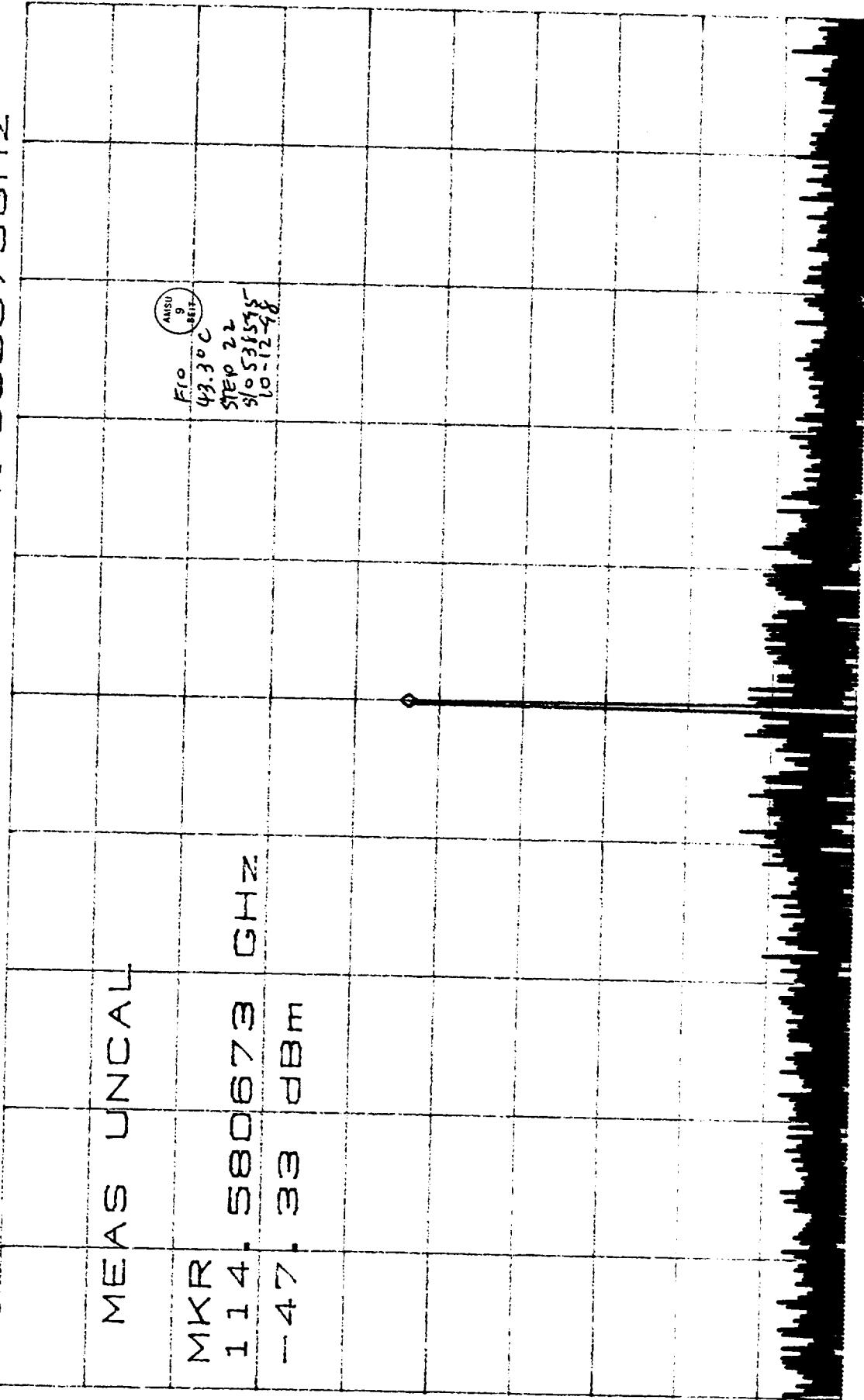


CENTER 6.87480GHz  
\*RBW 300KHz

SPAN 50.00MHz  
SWP 50.0ms

CL 30.0dB  
RL 0dBm

MKR -47.33dBm  
114.580673GHz



CENTER 114.580673GHz SPAN 1.000MHz  
\*RBW 300Hz \*VBW 1.0kHz \*\*SWP 2.80sec

TEST DATA SHEET 6A (Sheet 4 of 4)  
Functional Testing (Paragraph 4.2.1)

## Pre-Environmental CPT

## Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
22 (Cont)	Spurious and Sub	-200 to -90 dBc	<i>see plots</i>	<i>Pass</i>
	Power level of 114.58 GHz signal	<-10 dBm	<i>-47</i> dBm	<i>Pass</i>
<b>Load VSWR and Frequency Pulling</b>				
	2:1 mismatch over 1λ	N/A	Worst Case Freq = <i>5 Hz</i>	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = <i>-4</i> dB	N/A

Shop Order No.: 538595

Test Engineer: \_\_\_\_\_

Operation: O110Quality Control:  OCT 13 '98Unit Serial No.: F10Govt. Rep.: D. Duvvuri 10/23/98Date: 10-12-98



### Section 2A: Acceptance Level Vibration - F09

This section includes the data from the limited functional tests which take place before and throughout vibration, and the vibration-specific. The following table summarizes the results of the limited functional test.

Test	Expected Value	Post X axis	Post Y axis	Post Z axis
Output Frequency	57290344 ± 200 kHz	57290328 kHz	57290329 kHz	57290329 kHz
Output Power	18.5 dBm ± 1.5 dB	18.1 dBm	18.0 dBm	18.0 dBm

The following pages contain the raw data.



**TEST DATA SHEET 8B**  
Limited Functional Test (Paragraph 4.2.3)

Post X-Axis LPT

Test Setup Verified: D. Liles

Signature

Paragraph 4.2.3.2:

Step	Test		Required	Measurement	Pass/Fail
3	Potential Difference				
	From	To			
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	0.6 Vac	P
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	0.5 Vac	P
Step	Test	Expected	Measured	Pass/Fail	
8	Voltage Meter 1	+15 ± 0.1 V	+15.00 V	PASS	
	Voltage Meter 2	-15 ± 0.1 V	-15.03 V	PASS	
	Current Meter 1	600 mA max.	521 mA	PASS	
	Current Meter 2	100 mA max.	-64 mA	PASS	
9	Output Frequency	57.290344 ± .0001 GHz	57.290328 GHz	PASS	
10	Output Power	18.5 dBm ± 1.5 dB	18.07 dBm	PASS	

\* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

Shop Order No.: 538596

Operation: 0150

Unit Serial No.: F09

Date: 11/12/98

Test Engineer: D. Liles

Quality Control: QA 11/12/98

Govt. Rep.: J. Gallegas 11-12-98

11/12/98  
D. Liles  
QA 11/12/98

TEST DATA SHEET 8C  
Limited Functional Test (Paragraph 4.2.3)

Post Y-Axis LPT

Test Setup Verified: Dhruv  
Signature

Paragraph 4.2.3.2:

Step	Test		Required	Measurement	Pass/Fail
3	Potential Difference				
	From	To			
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	0.5 Vac	P
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	0.6 Vac	P

Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.00 V	P
	Voltage Meter 2	-15 ± 0.1 V	-15.03 V	P
	Current Meter 1	600 mA max.	522 mA	P
	Current Meter 2	100 mA max.	~64 mA	P
9	Output Frequency	57.290344 ± .0001 GHz	57.290329	P
10	Output Power	18.5 dBm ± 1.5 dB	18.02	P

\* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

11/12/98

Shop Order No.: 538596  
Operation: 0150  
Unit Serial No.: F09  
Date: 11/12/98

Test Engineer: Dhruv  
Quality Control: 7A 197 11/12/98  
Govt. Rep.: J. Gallagher 11-12-98

TEST DATA SHEET 8D  
Limited Functional Test (Paragraph 4.2.3)

Post Z-Axis LPT

Test Setup Verified: J. Holmes  
Signature

Paragraph 4.2.3.2:

Step	Test		Required	Measurement	Pass/Fail
3	Potential Difference				
	From	To			
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	0.5 Vac	P
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	0.5 Vac	P

Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.00 V	P
	Voltage Meter 2	-15 ± 0.1 V	-15.02 V	P
	Current Meter 1	600 mA max.	522 mA	P
	Current Meter 2	100 mA max.	-64 mA	P
9	Output Frequency	57.290344 ± .0001 GHz	57.290329	P
10	Output Power	18.5 dBm ± 1.5 dB	18.0	P

\* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

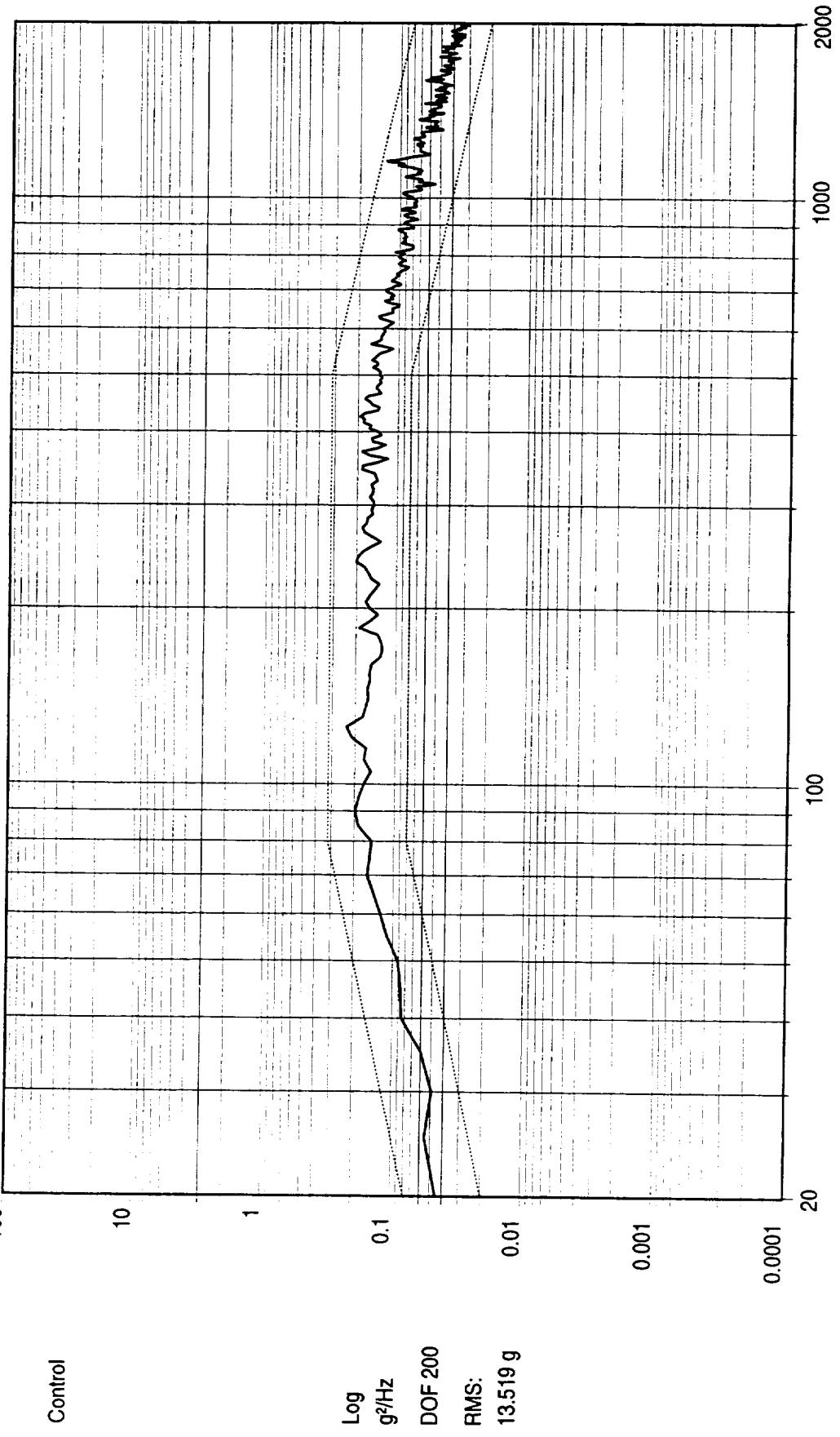
Shop Order No.: 538596  
Operation: 0150  
Unit Serial No.: F09  
Date: 11/12/98

Test Engineer: J. Holmes  
Quality Control: 7A 11/12/98  
Govt. Rep.: J. Holmes 11-12-98

Test Level: 0.000 dB  
Test Time: 0000:01:00

Reference RMS: 13.576  
Clipping: Off

**Test Range:** 20.000, 2000.000 Hz  
**Resolution:** 5.000 Hz



11:34:21  
12-Nov-1998

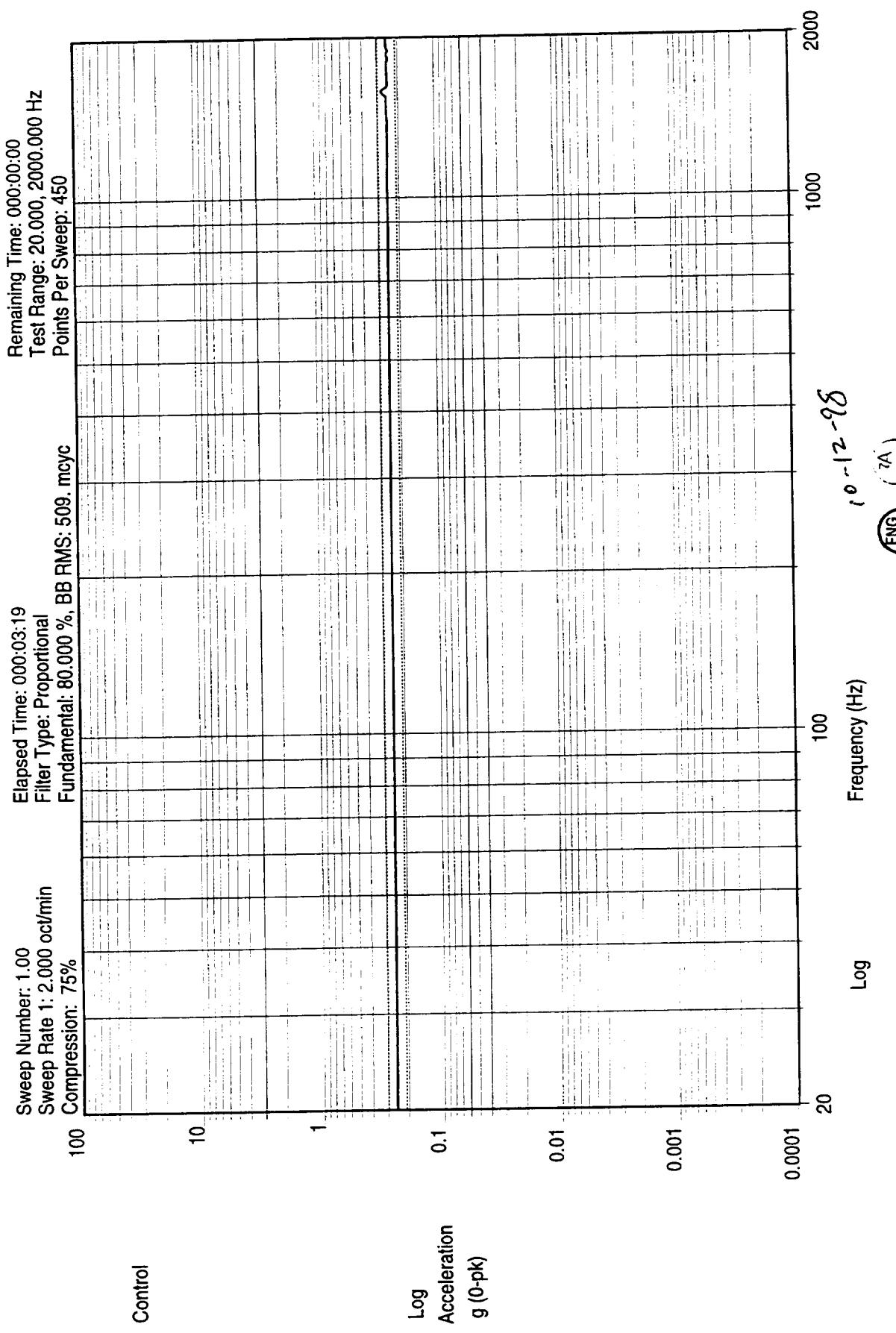
AMSU PHASE LOCK OSCILLATOR S/O538596-F09  
X AXIS SYSTEM CHECKOUT P/N 1348360-1 S/N F09



11-12-98

Frequency (Hz)

Log



11:51:43  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09  
X AXIS CHECKOUT P/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

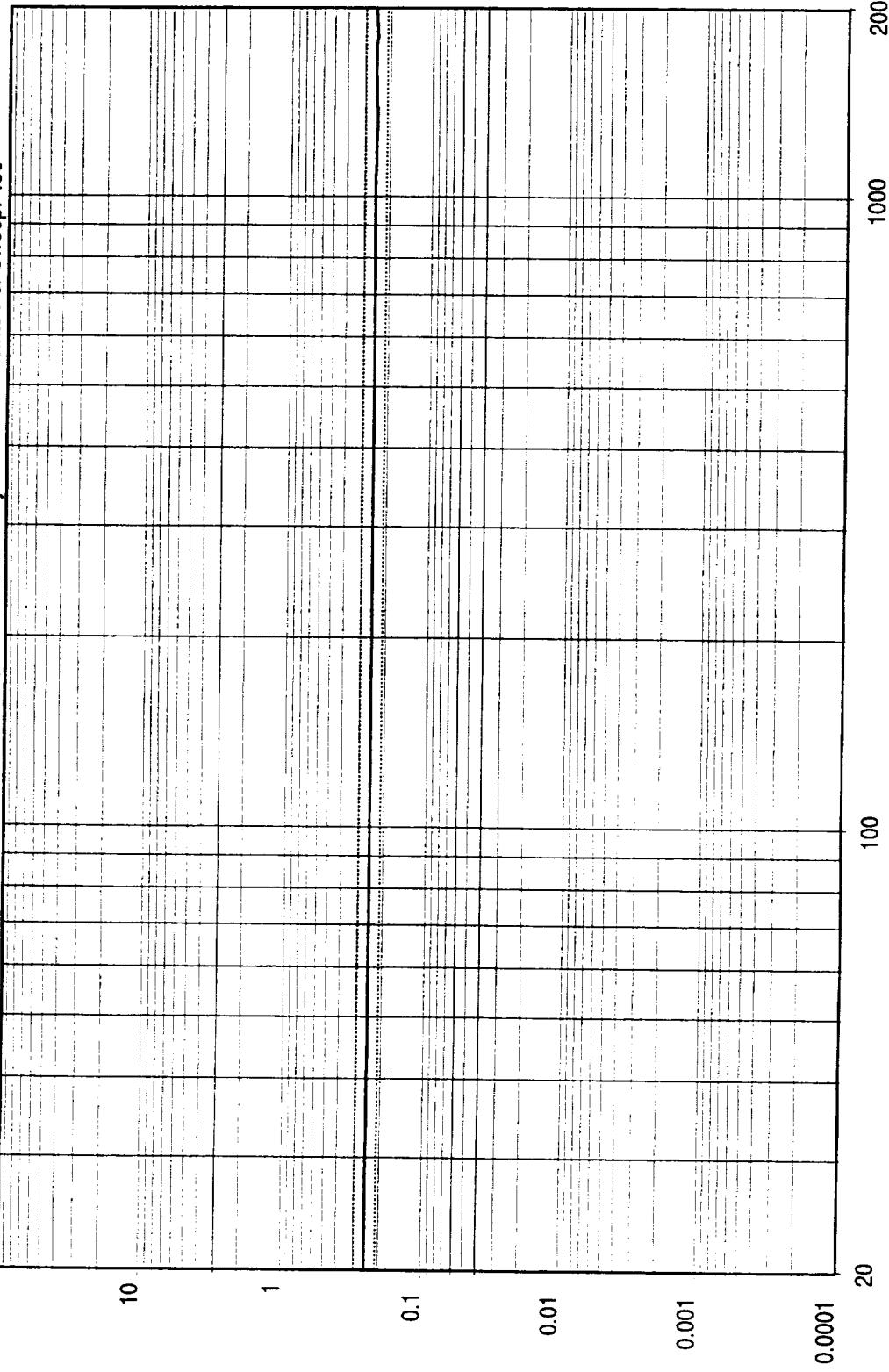
7A  
267

ENG  
217

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcy

Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450

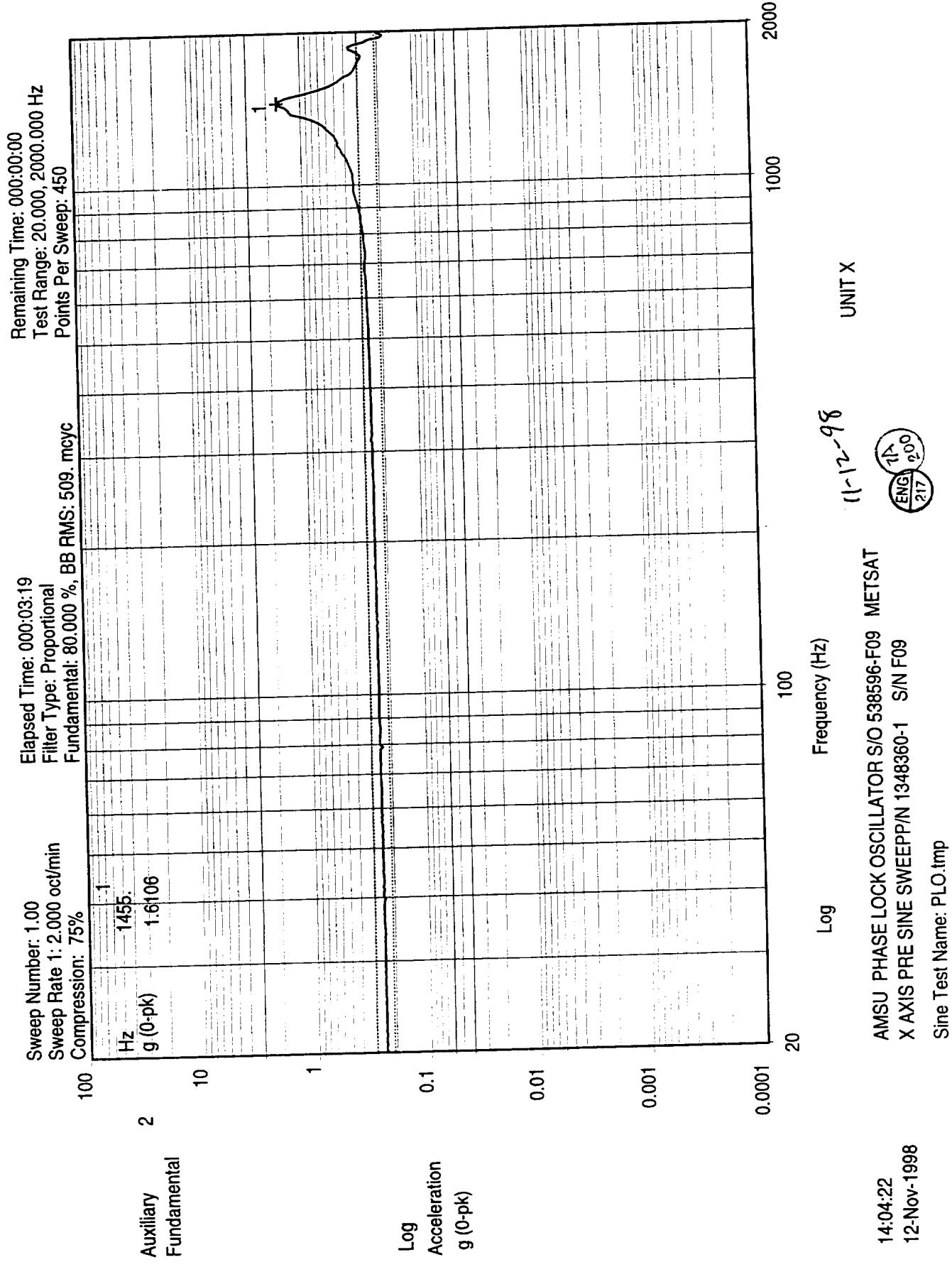


1Φ-12-98  
ENG 1A  
217 830

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT  
X AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

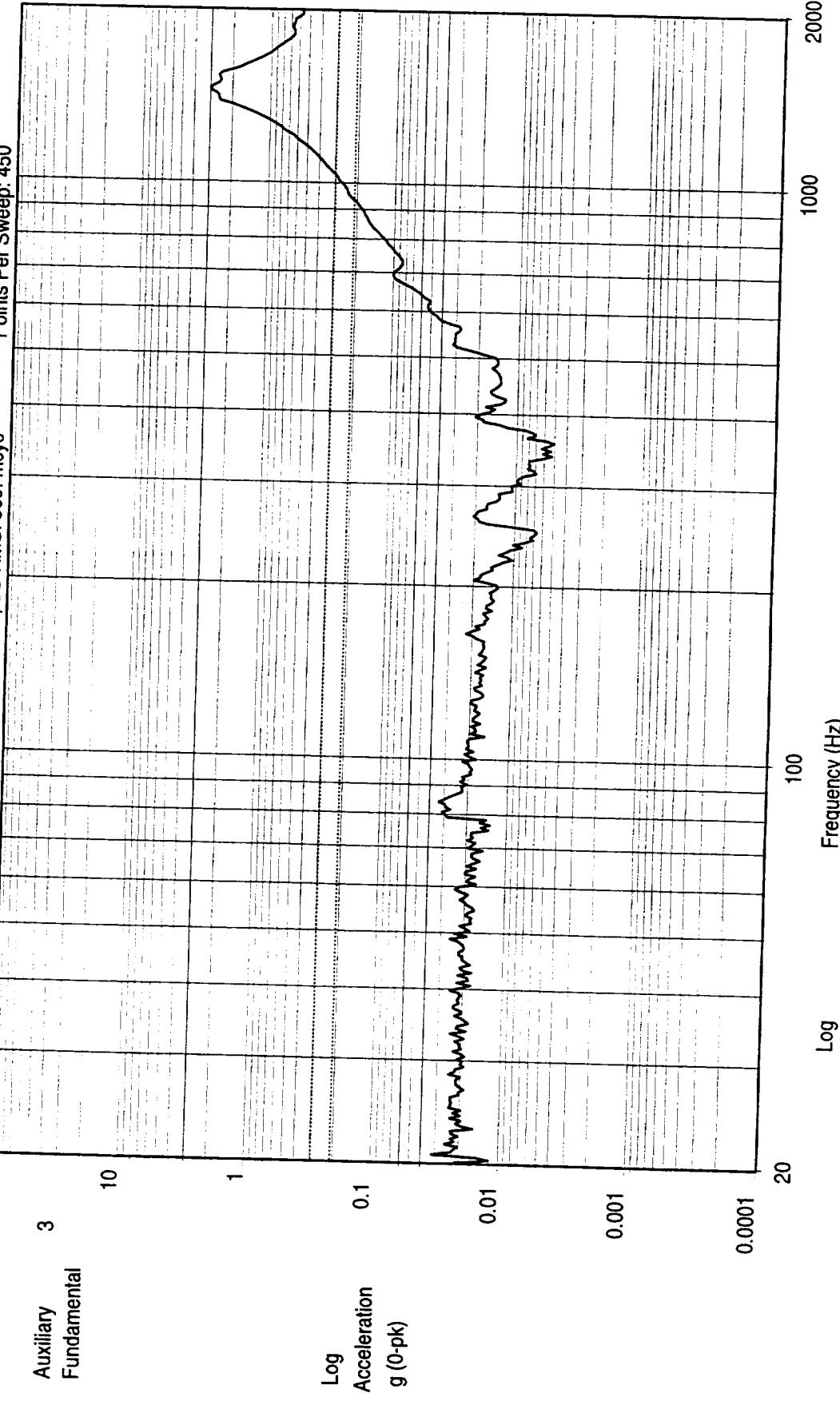
14:04:14  
12-Nov-1998



Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%  

---

Elapsed Time: 00:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, E

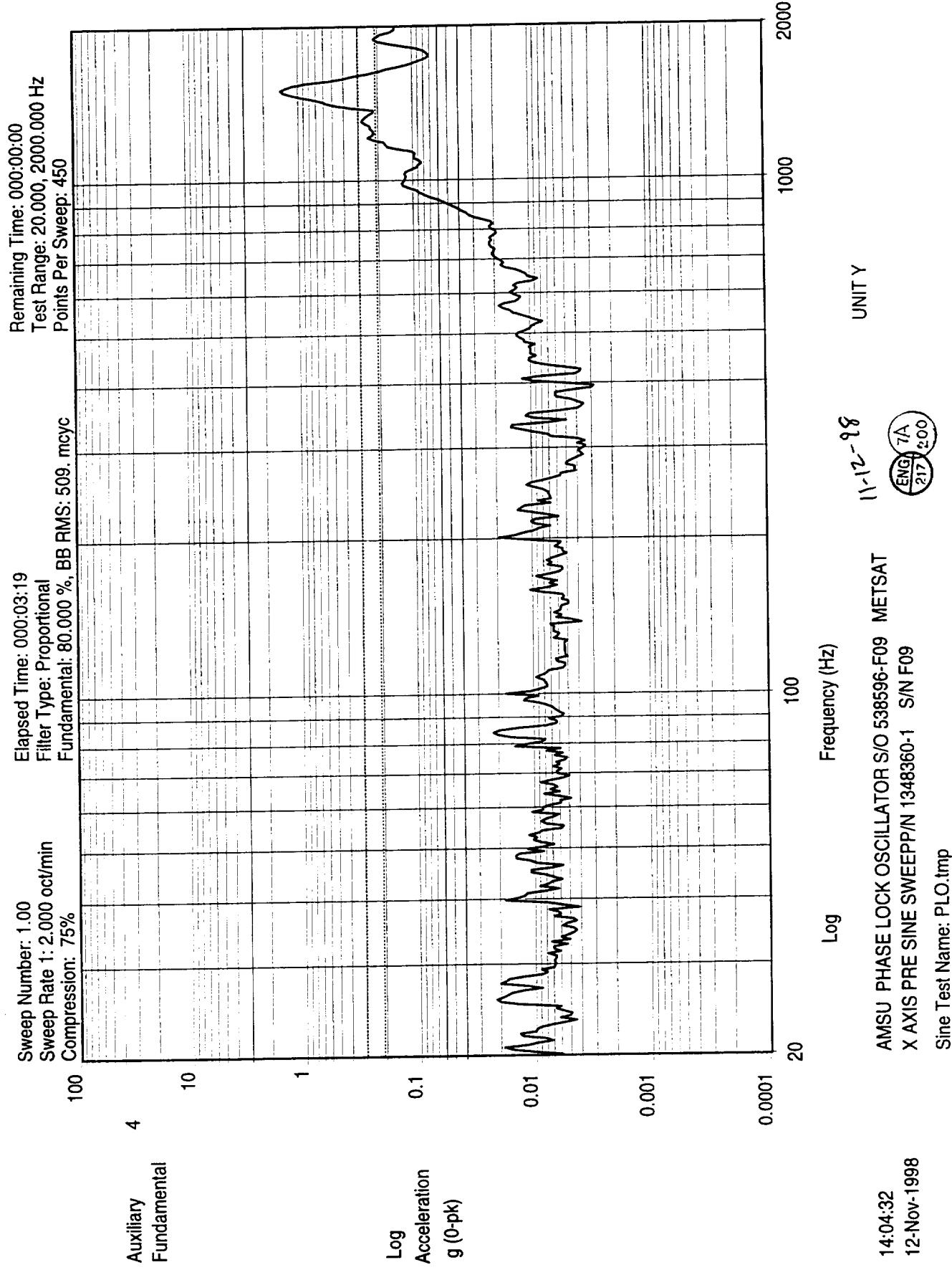


14:04:28  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT  
X AXIS PRE SINE SWEEP/P/N 1348360-1 S/N F09

Sine Test Name: PLO.tmp

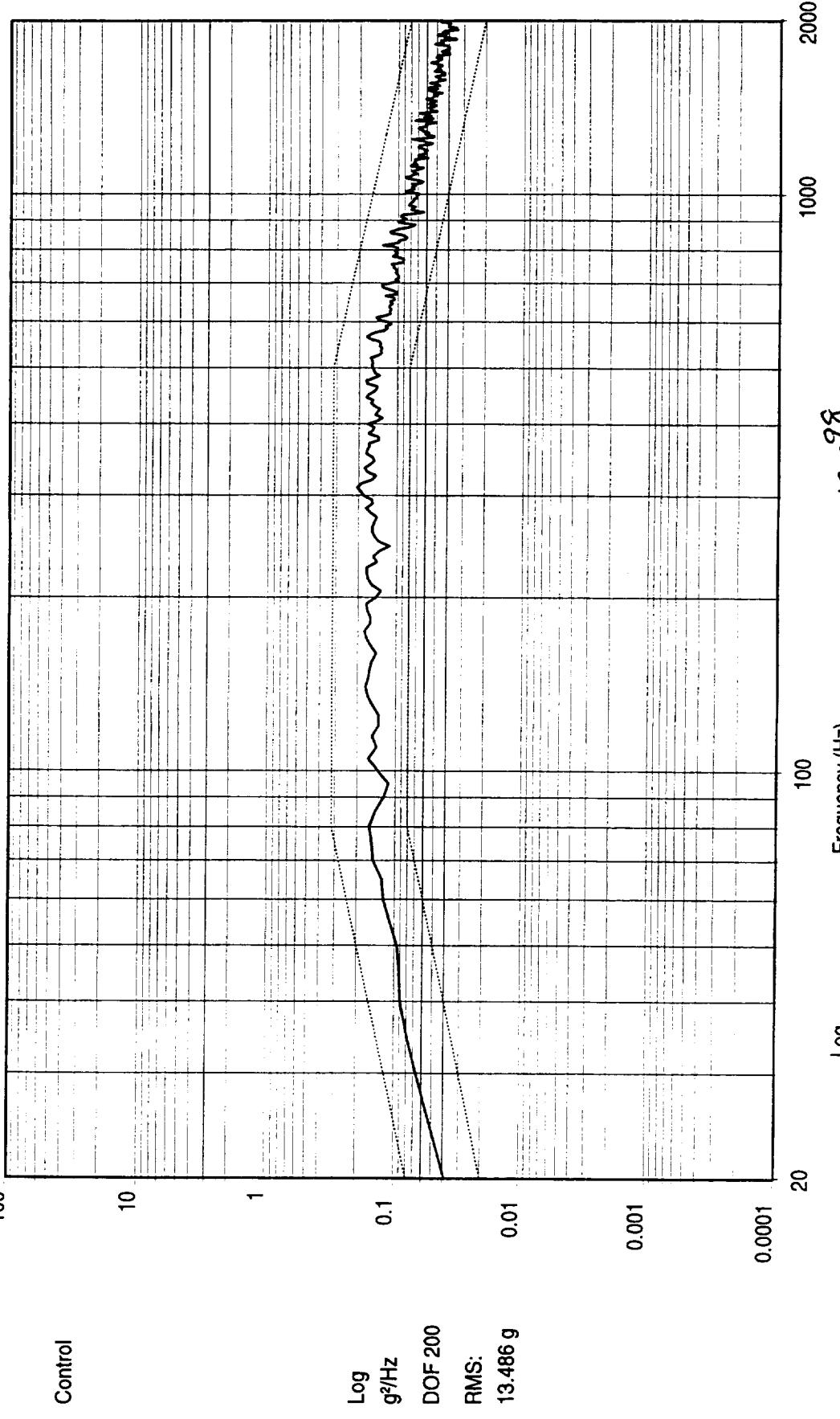
UNIZ



Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



14:22:27  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S10536596-F09 METSAT  
X AXIS TEST P/N 1348360-1 S/N ,F09

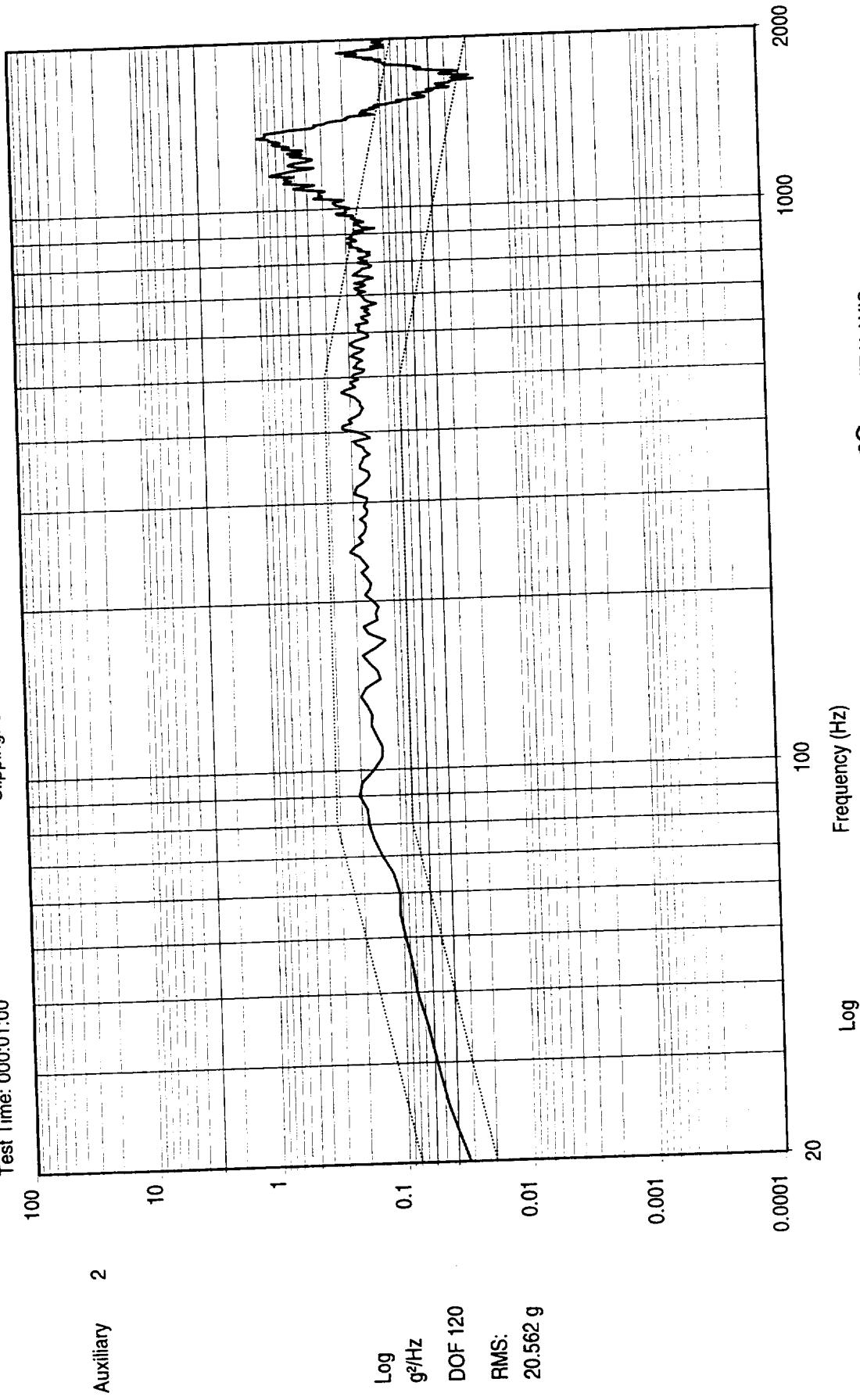
Test Name: PL0.tmp

FNG  
217002  
V12

Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



14:17:40  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S  
Y AXIS TEST P/N 1348360-1 S/N F09

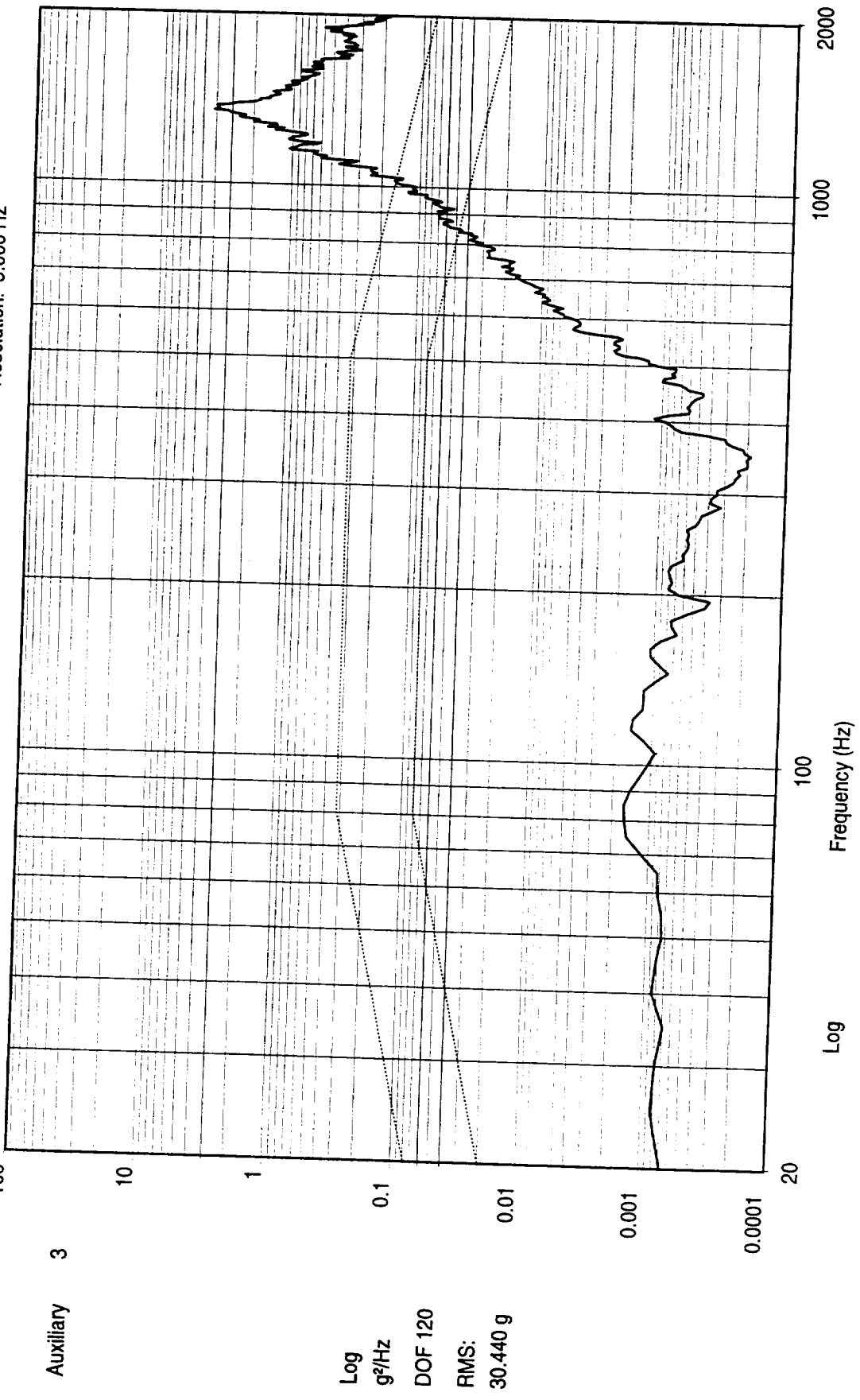
UNIT X AXIS

ENG  
217  
02

Test Name: PLOtmp

Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off  
Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



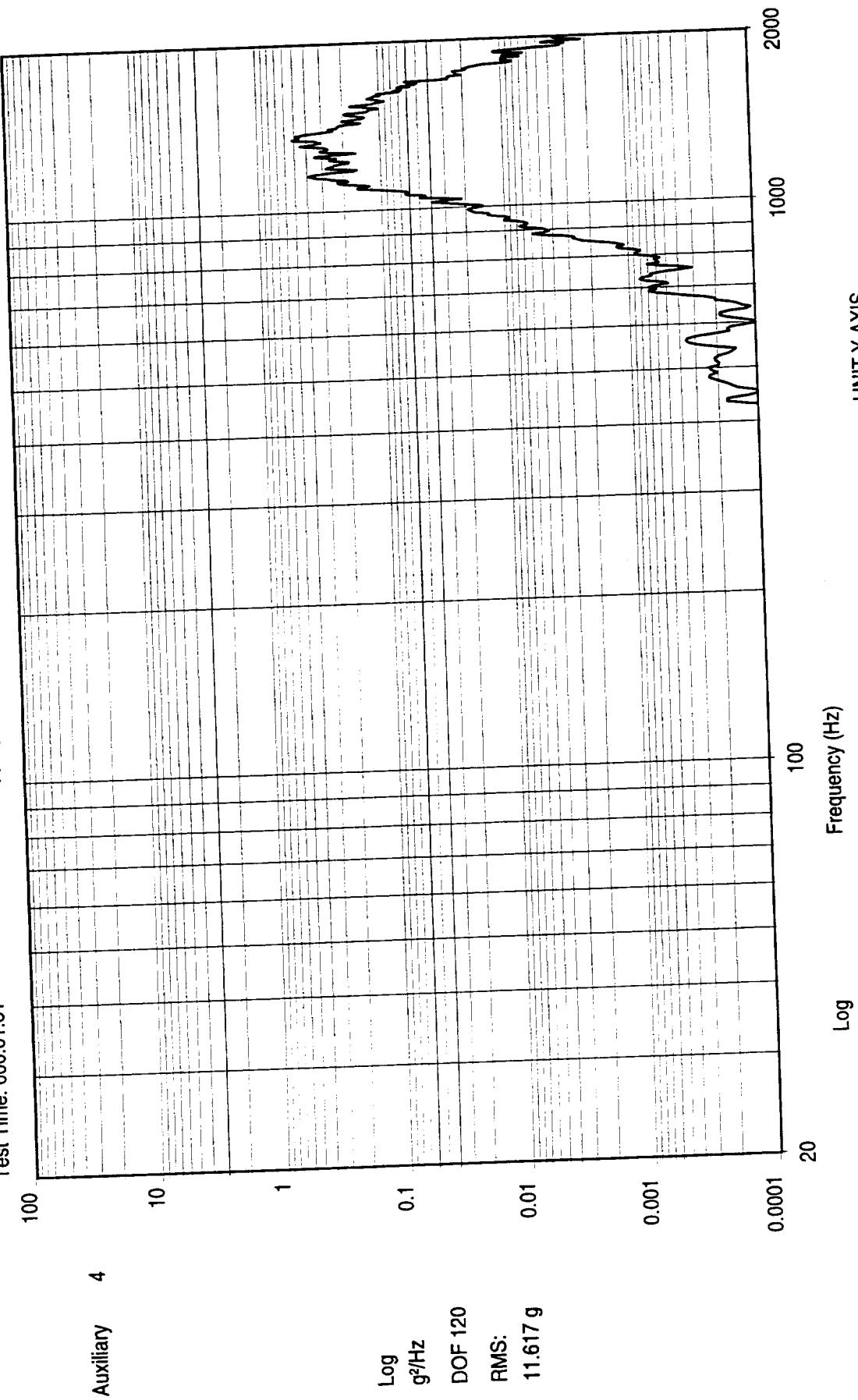
14:17:45  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/0538596-F09  
X AXIS TEST P/N 1348360-1 S/N F09  
METSAT  
Test Name: PL0.tmp

ENG 002  
2/17  
V1

Test Level: -18.000 dB  
Test Time: 000:01:31

Reference RMS: 13.576  
Clipping: Off  
Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



15:56:35  
12-Nov-1998

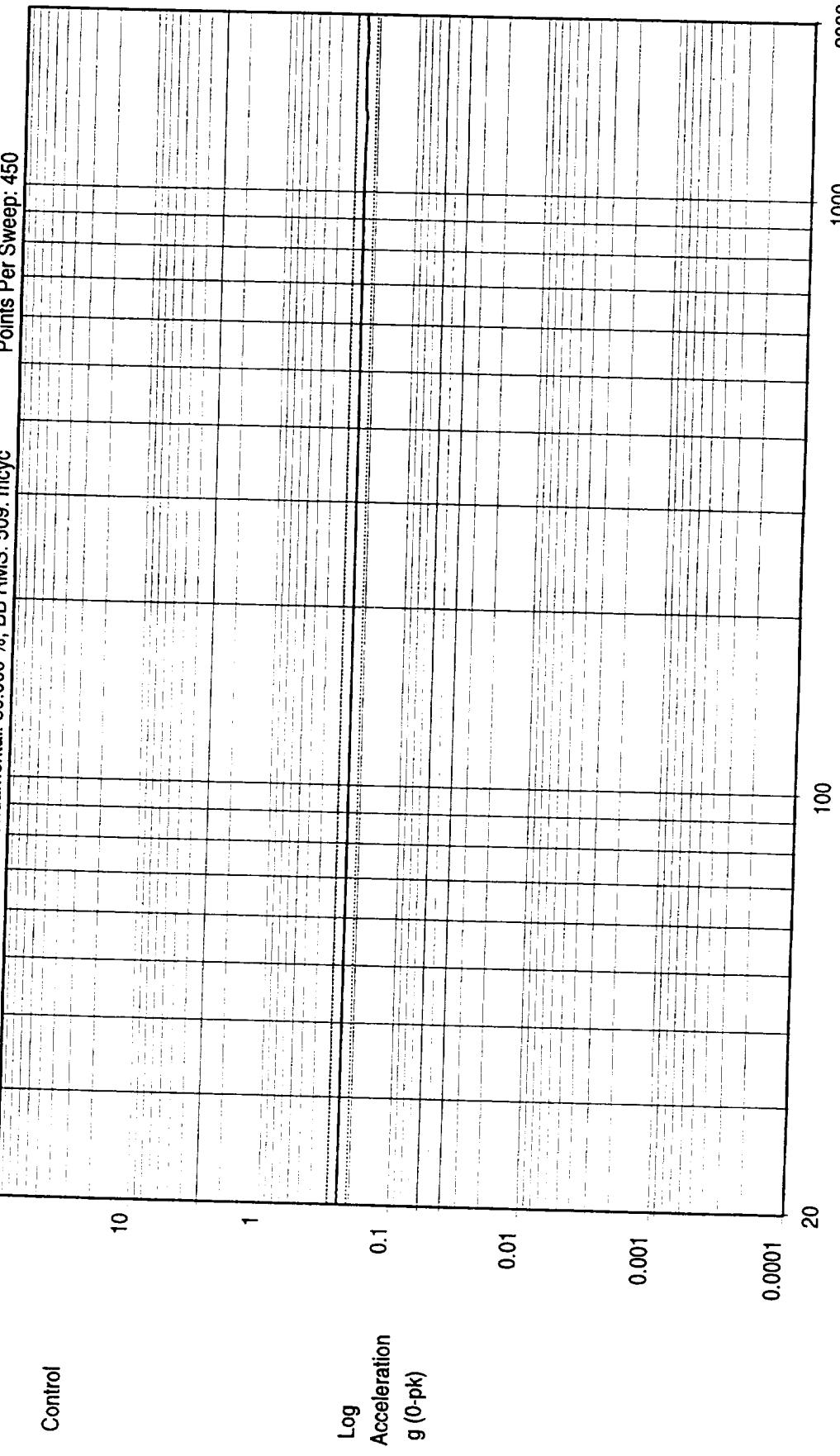
AMSU PHASE LOCK OSCILLATOR S/O538596-F09 METSAT  
X AXIS TEST P/N 1348360-1 S/N ,F09

11-12-98  
ENG 217  
COV

Test Name: PL0.tmp

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcy  
Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450

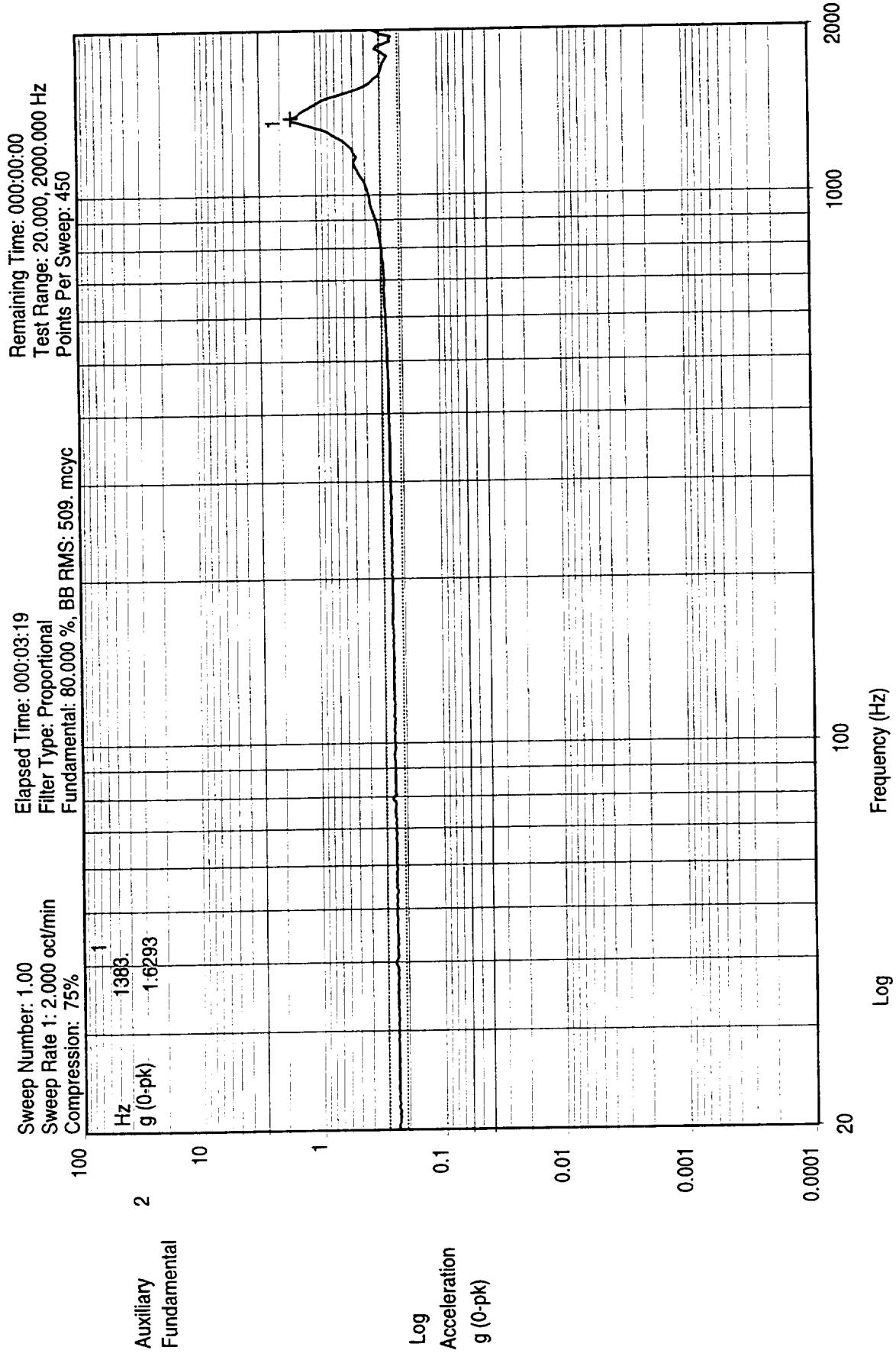


14:41:10  
12-Nov-1998

11-12-98  
ENG  
217  
200

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09  
X AXIS POST SINE SWEEP/N 1348360-1 S/N F09  
METSAT

Sine Test Name: PLO.tmp



14:40:56  
12-Nov-1998

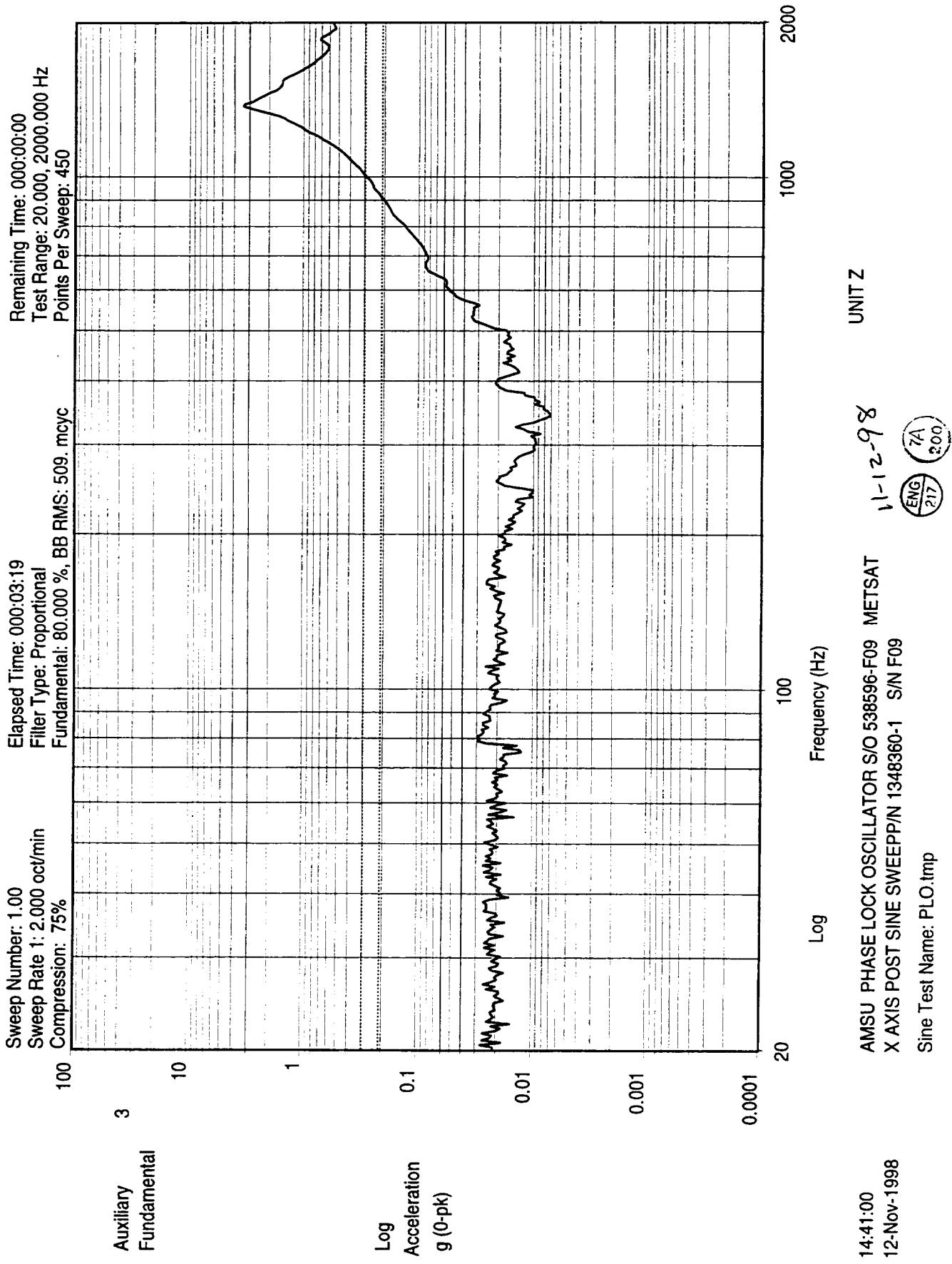
AMSU PHASE LOCK OSC  
X AXIS POST SINE SWEET  
Sine Test Name: PLO.Imp

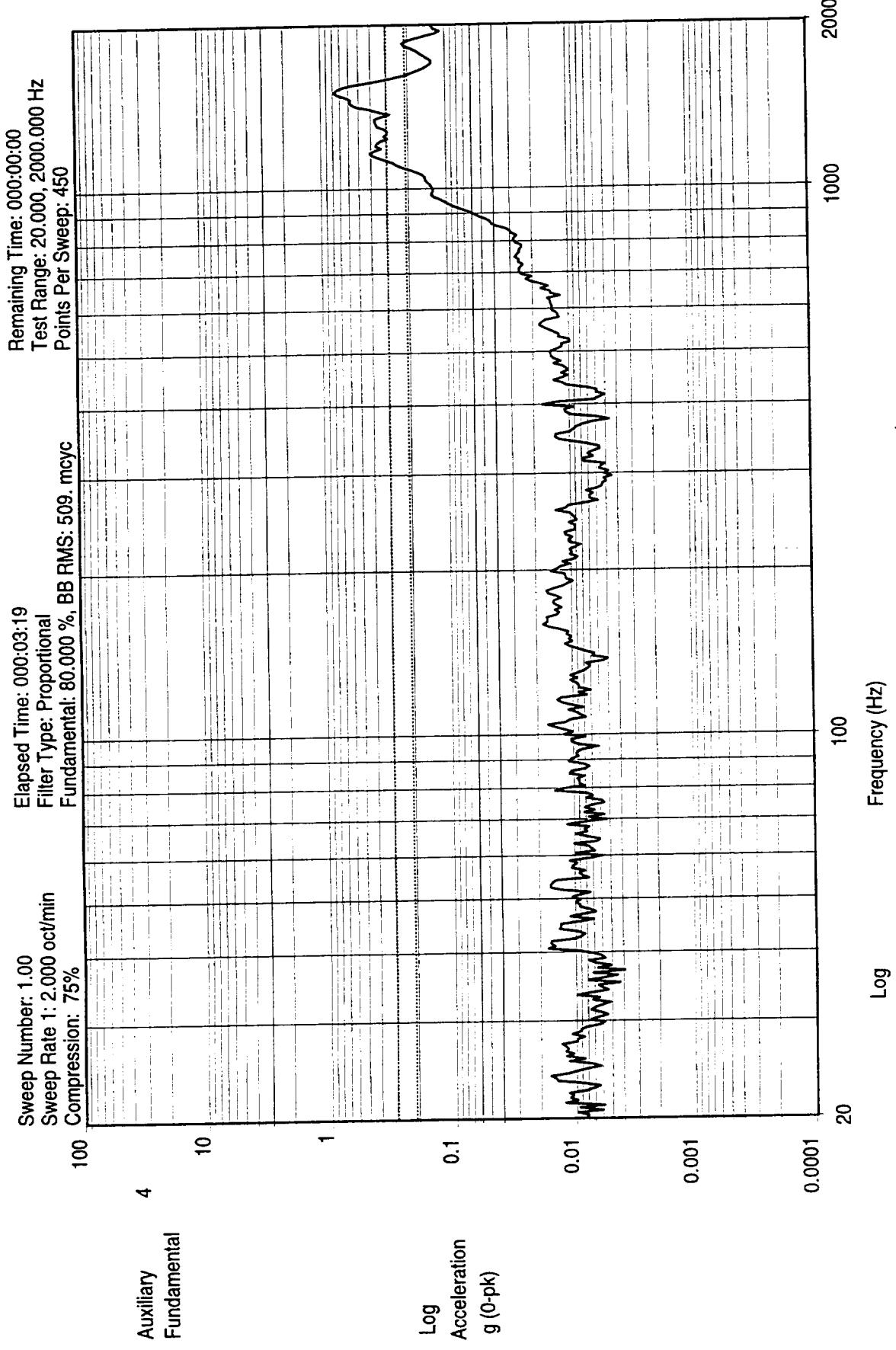
8596-F09 S/N F09 METS

UNIT X

11-12-98

7A  
200  
ENG  
217





14:41:04  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09  
X AXIS POST SINE SWEEP/PIN 1348360-1 SIN F09

Sine Test Name: PLO.1mp

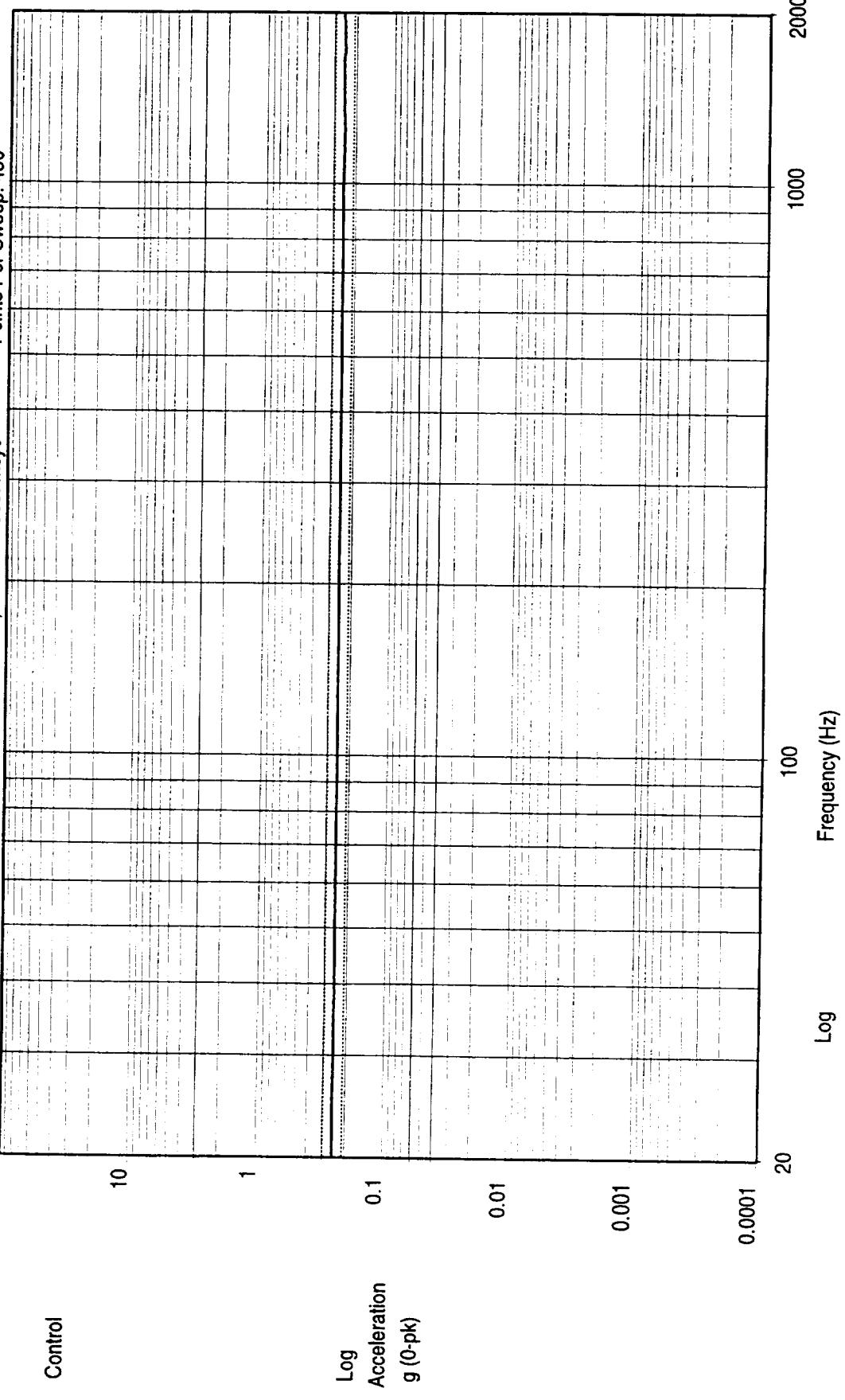
11-12-98

ENG 7A  
217 200

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 00:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, E

**Remaining Time:** 000:00:00  
**Test Range:** 20.000, 2000.000 Hz  
**Points Per Sweep:** 450

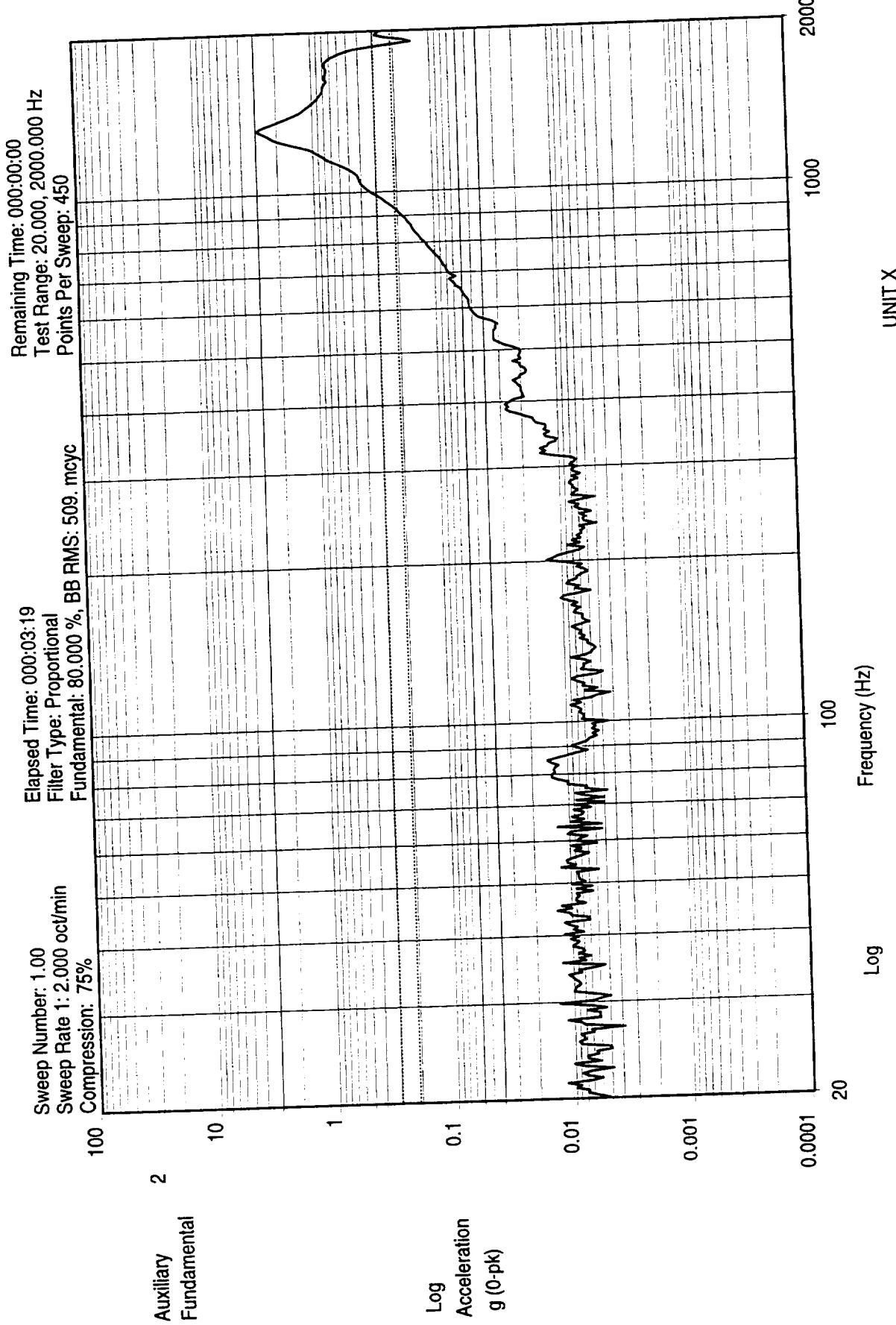


15:23:10  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09  
Y AXIS PRE SINE SWEEP P/N 1348360-1 S/N F09  
METSAT

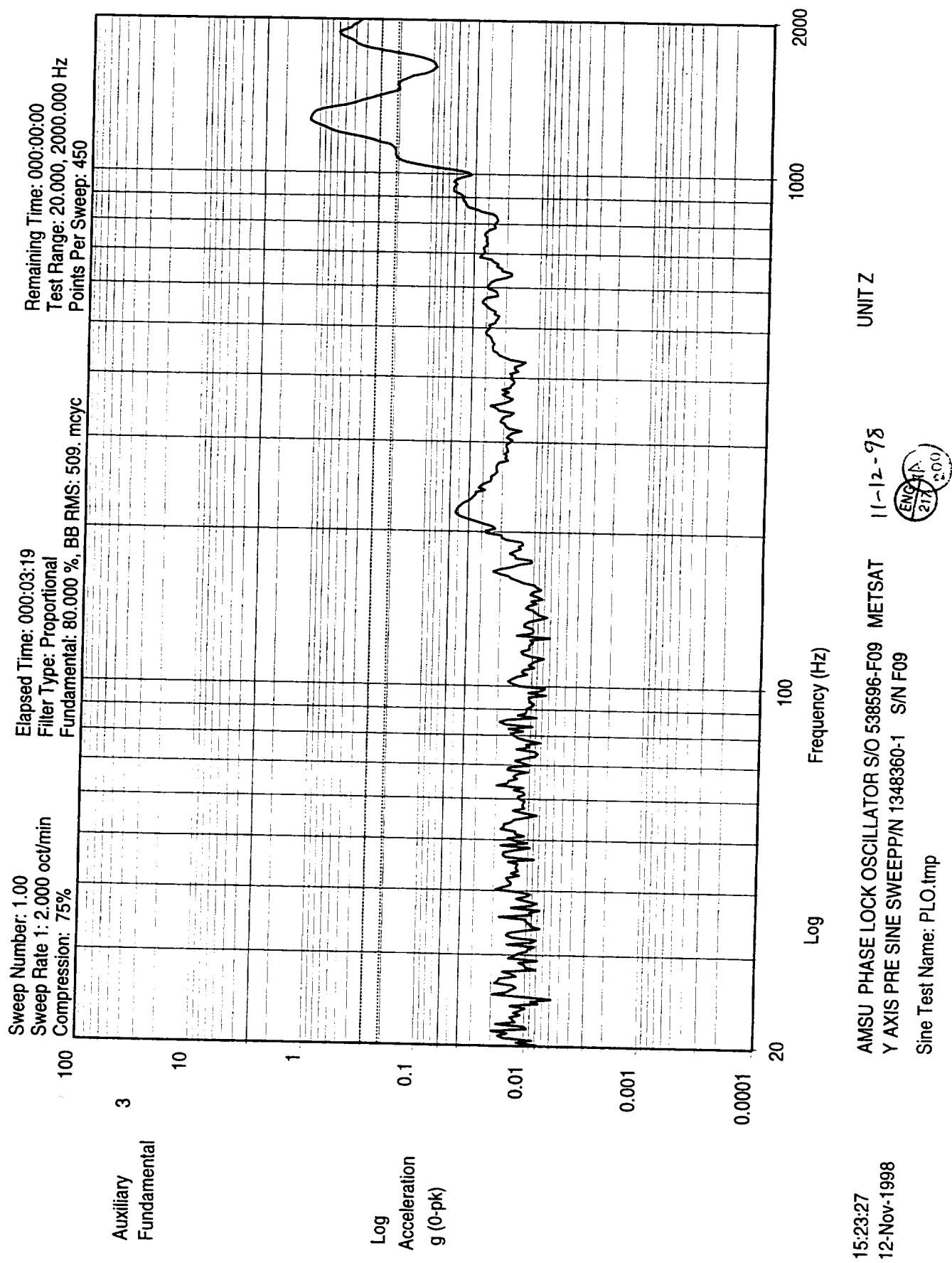
Sine Test Name: PLo,imp

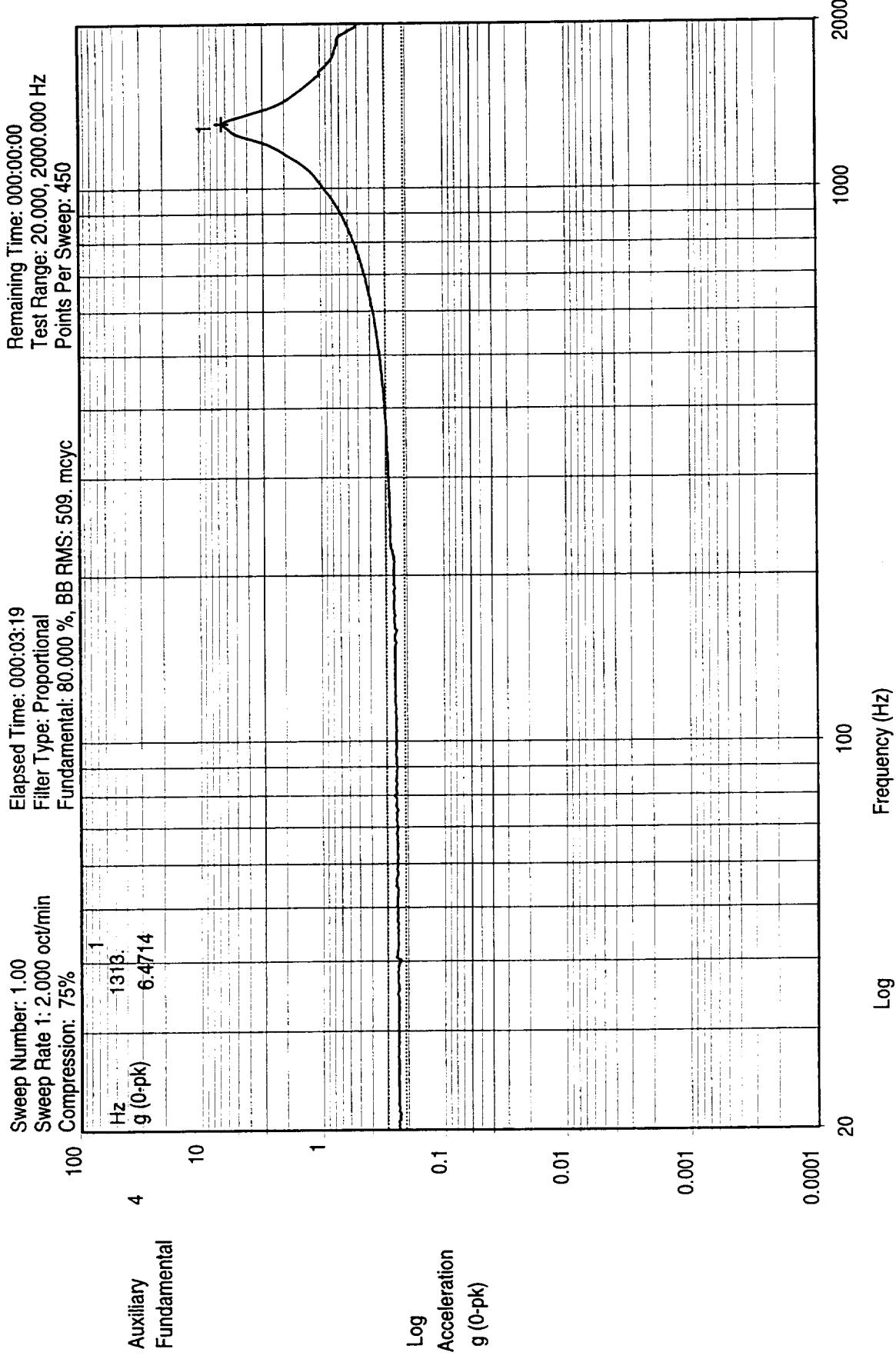
200  
7A  
217  
ENQ



15:23:23  
 12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT  
 Y AXIS PRE SINE SWEEPIN 1348360-1 S/N F09 11-12-98  
 Sine Test Name: PLO.tmp  
 ENG 7A  
 217 200





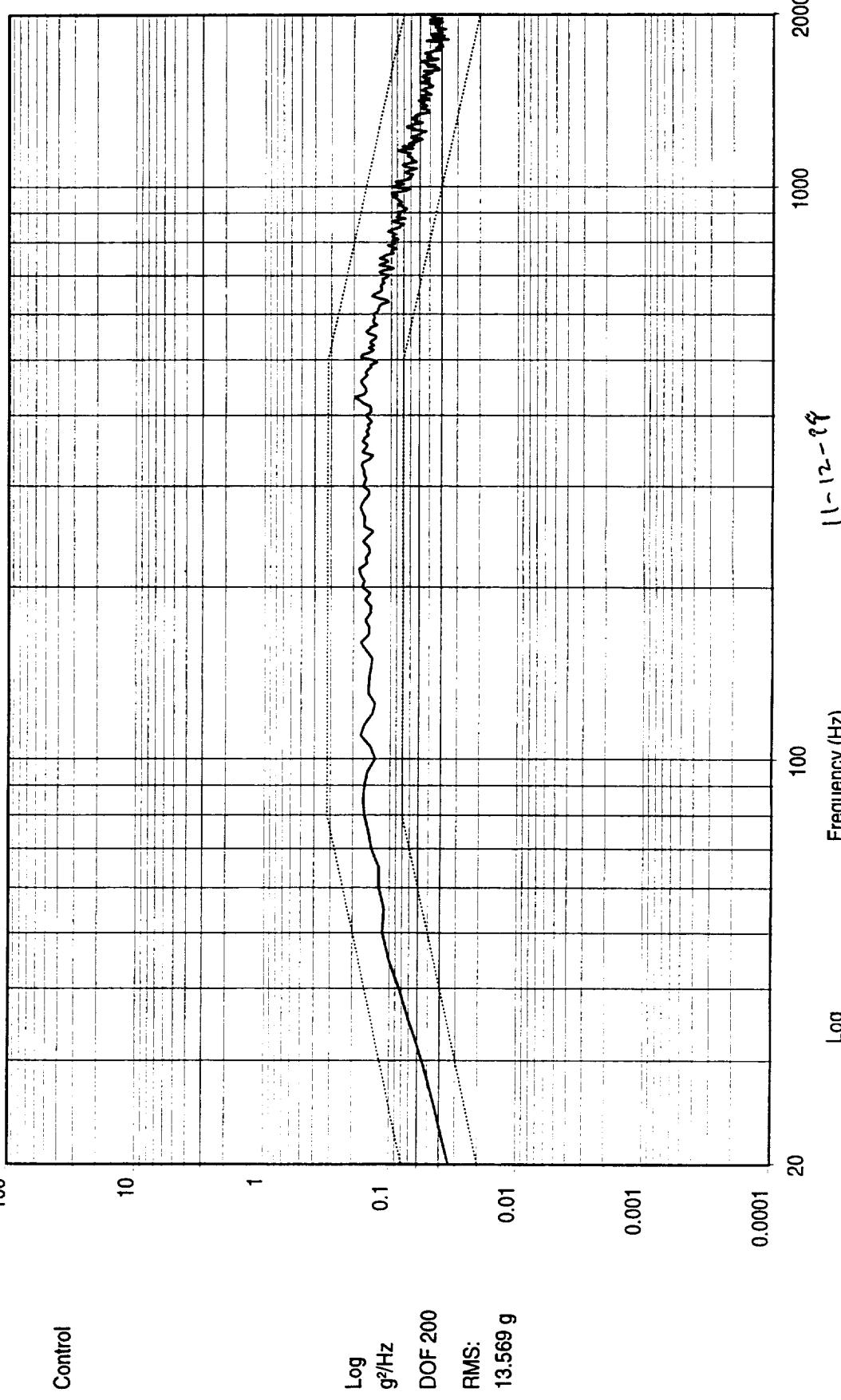
AMSU PHASE LOCK OSCILLATOR S/O 538596-F09      METSAT 11-12-98  
 Y AXIS PRE SINE SWEETPP/N 1348360-1      S/N F09  
 Sine Test Name: PLO.tmp  
 15:23:44  
 12-Nov-1998

ENG  
 217  
 100

Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



11-12-99  
12-11-99

ENG 1(A)  
217 200

AMSU PHASE LOCK OSCILLATOR S/0538596-F09 METSAT

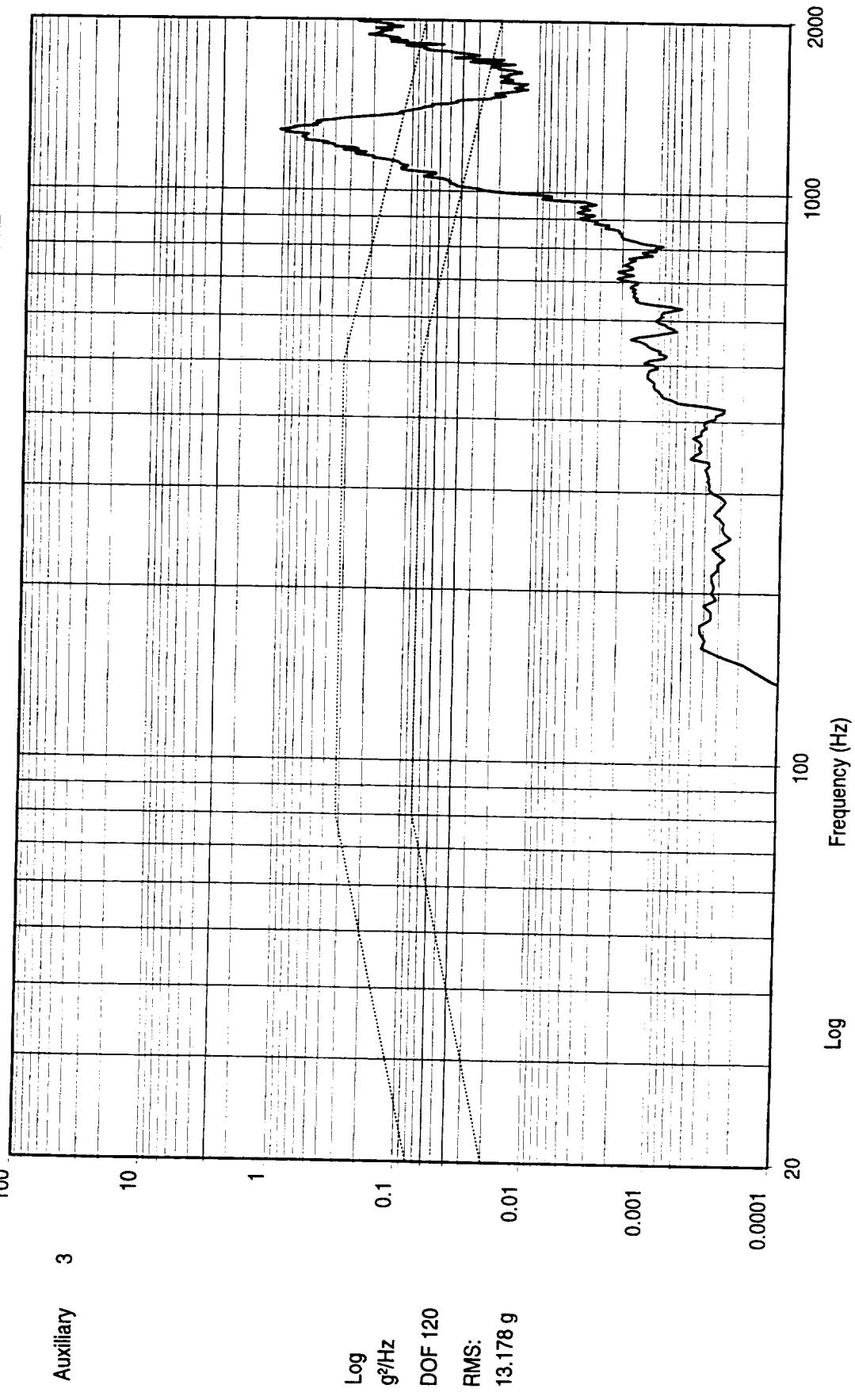
15:35:59  
12-Nov-1998

Y AXIS TEST P/N 1348360-1 SIN ,F09  
Test Name: PL0.Imp



Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off  
Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



15:36:15  
12-Nov-1998

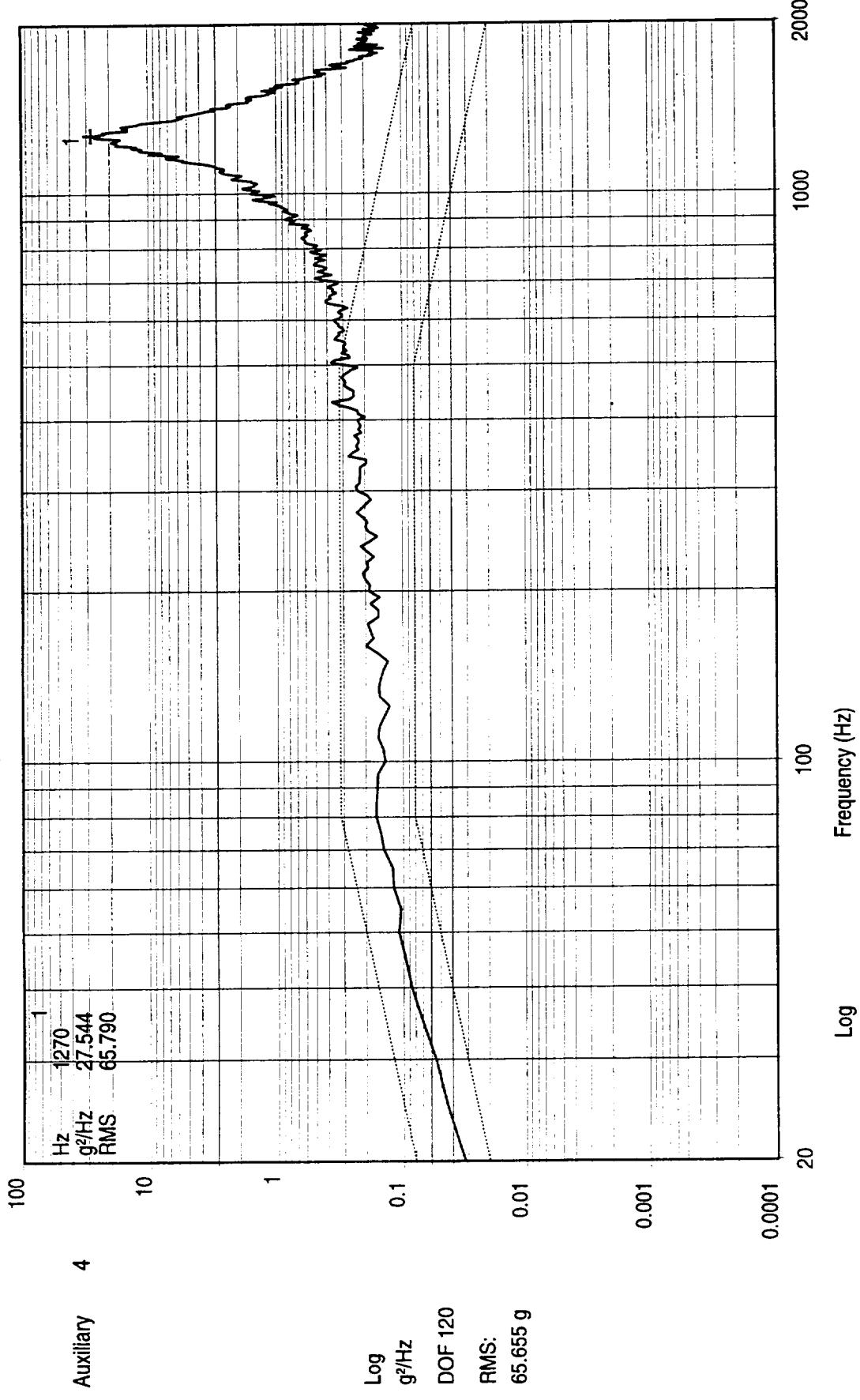
AMSU PHASE LOCK OSCILLATOR S/0538596-F09 METSAT 11-12-98 UNIT Z AXIS  
Y AXIS TEST P/N 1348360-1 S/N F09

ENCL 7A  
2/7/2000

Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



15:36:25  
12-Nov-1998

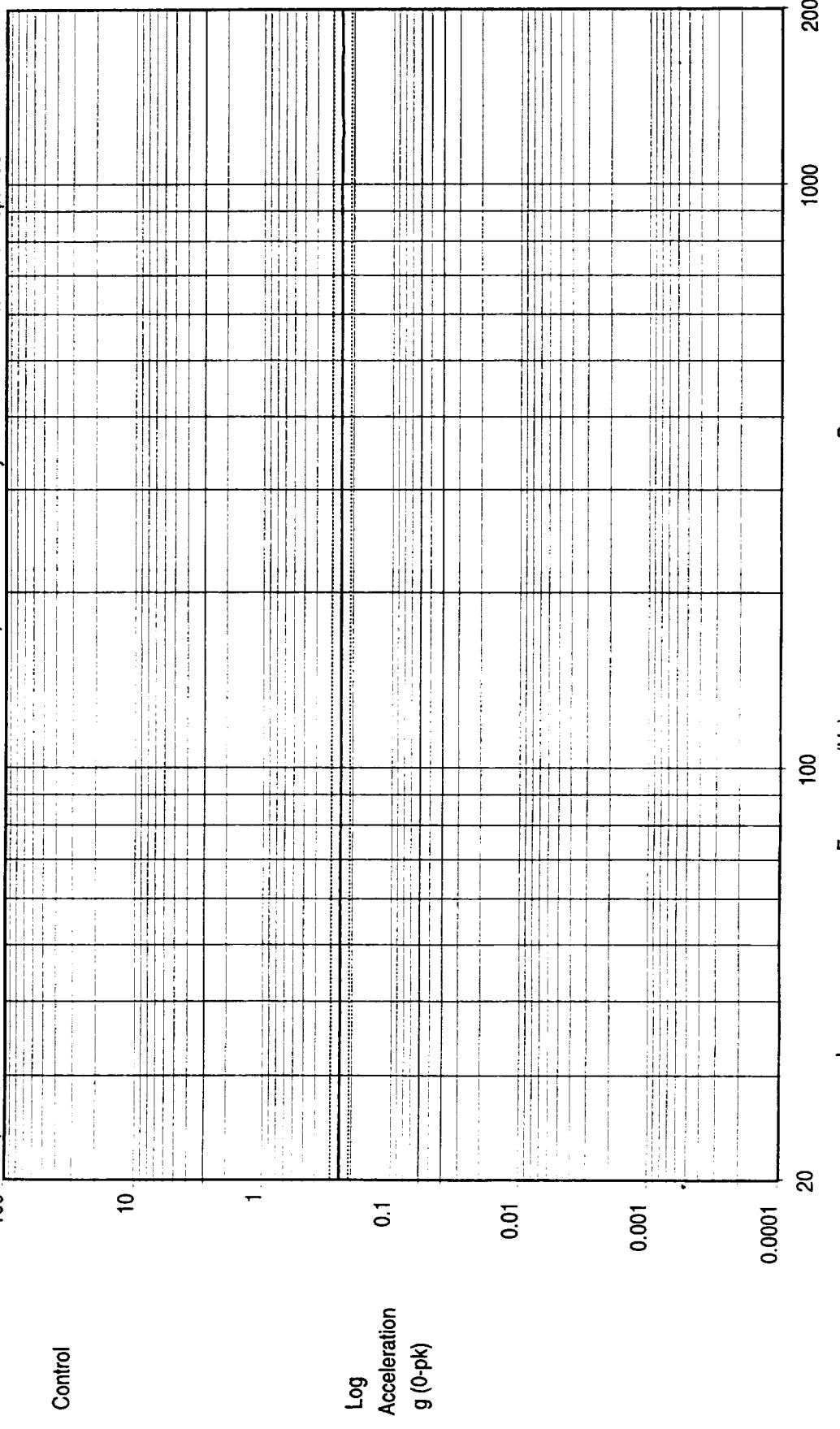
AMSU PHASE LOCK OSCILLATOR S/0538596-F09  
Y AXIS TEST P/N 1348360-1 S/N F09

Test Name: PLO.tmp

ENG 7A  
217 100

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcy

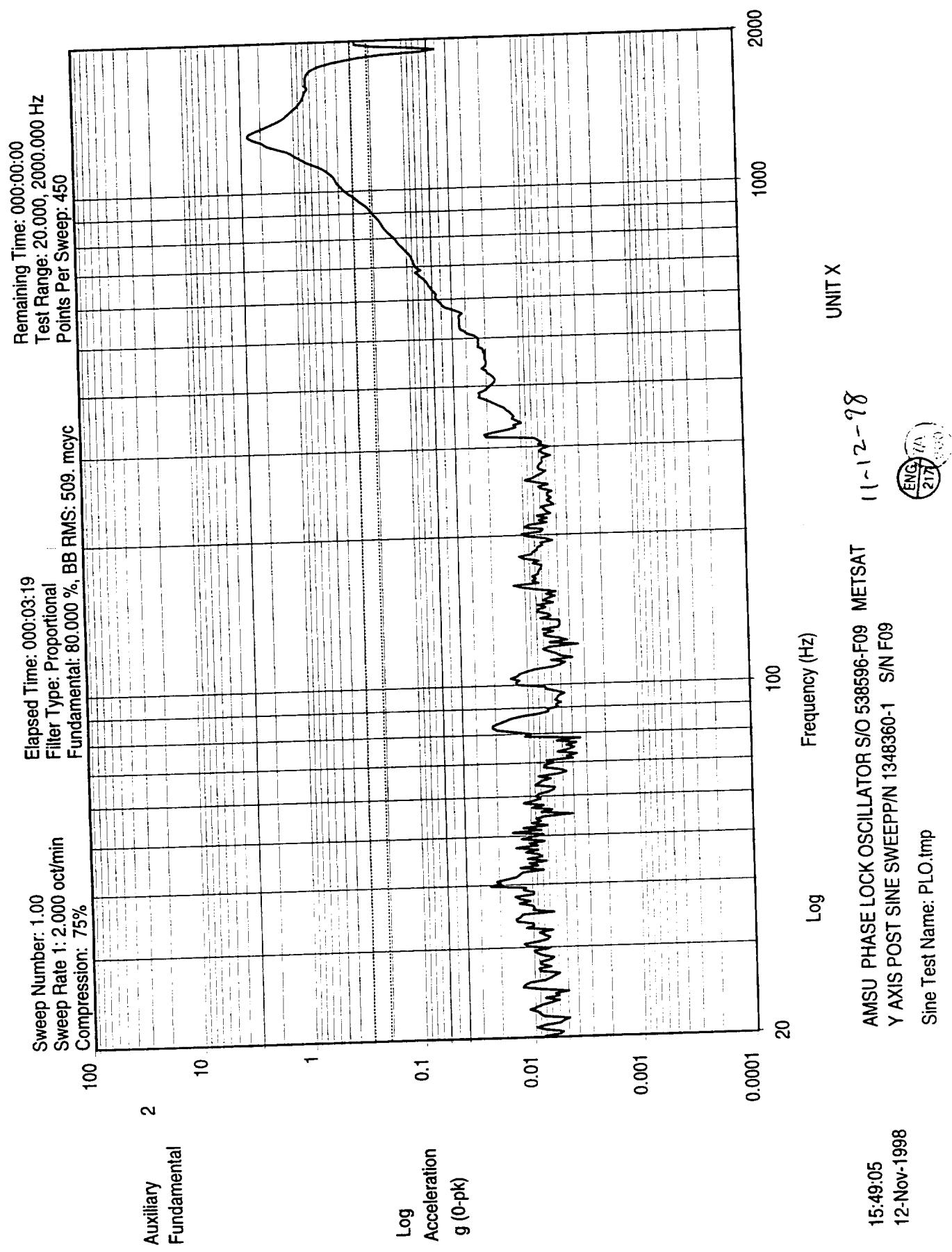


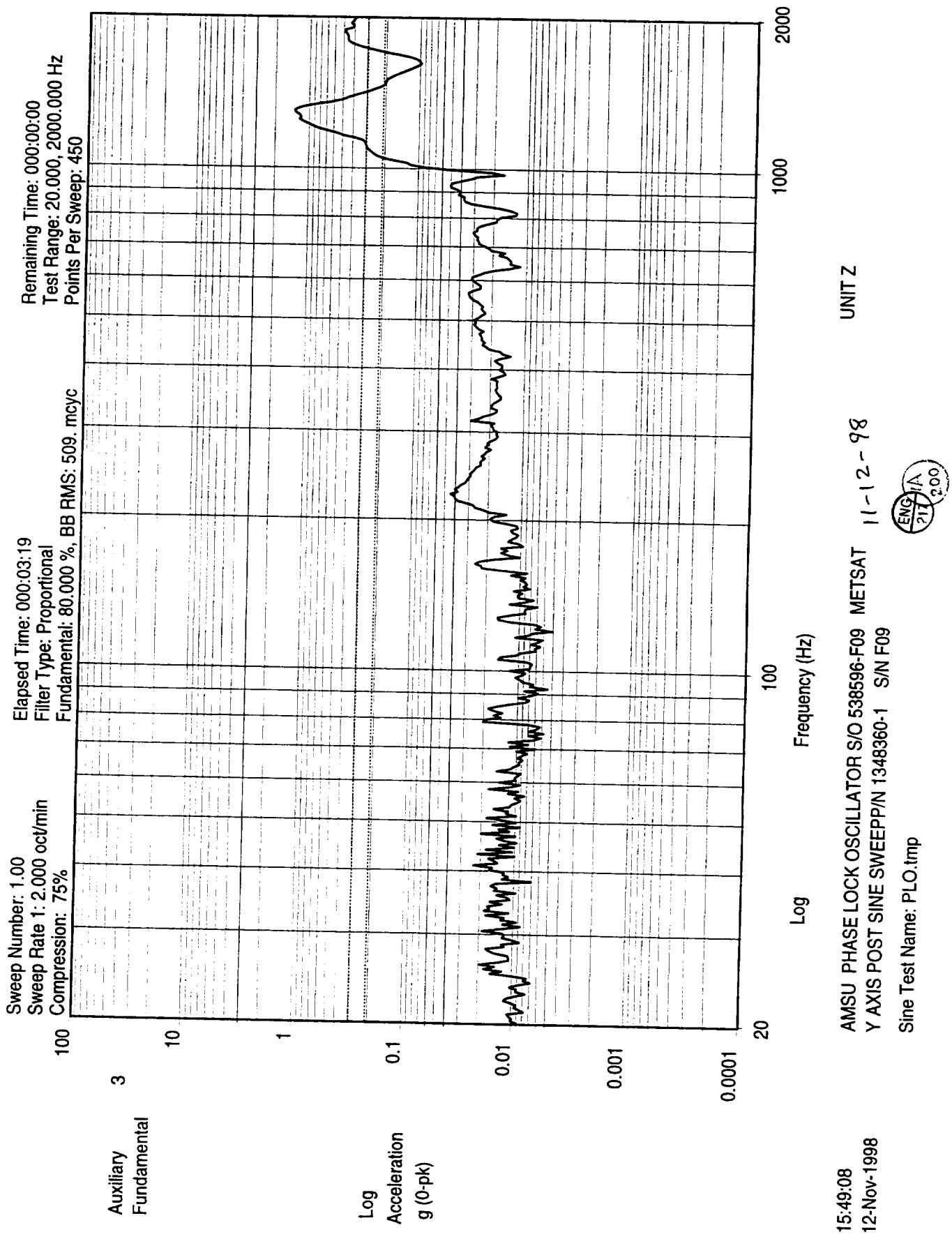
ENG  
11-12-98  
217

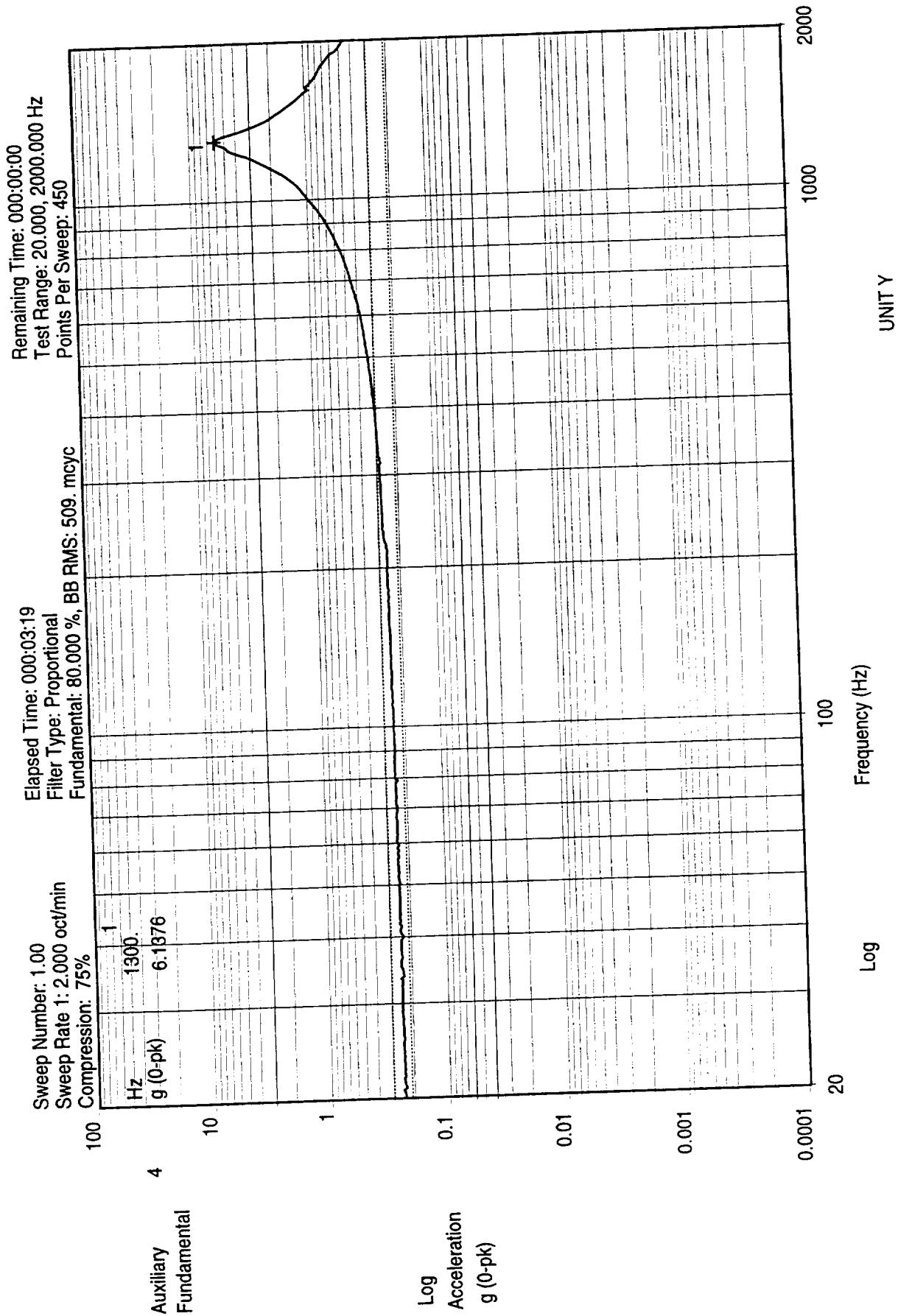
AMSU PHASE LOCK OSCILLATOR S/O 5338596-F09 METSAT  
Y AXIS POST SINE SWEETP/N 1348360-1 S/N F09

Sine Test Name: PLO.Imp

15:49:00  
12-Nov-1998





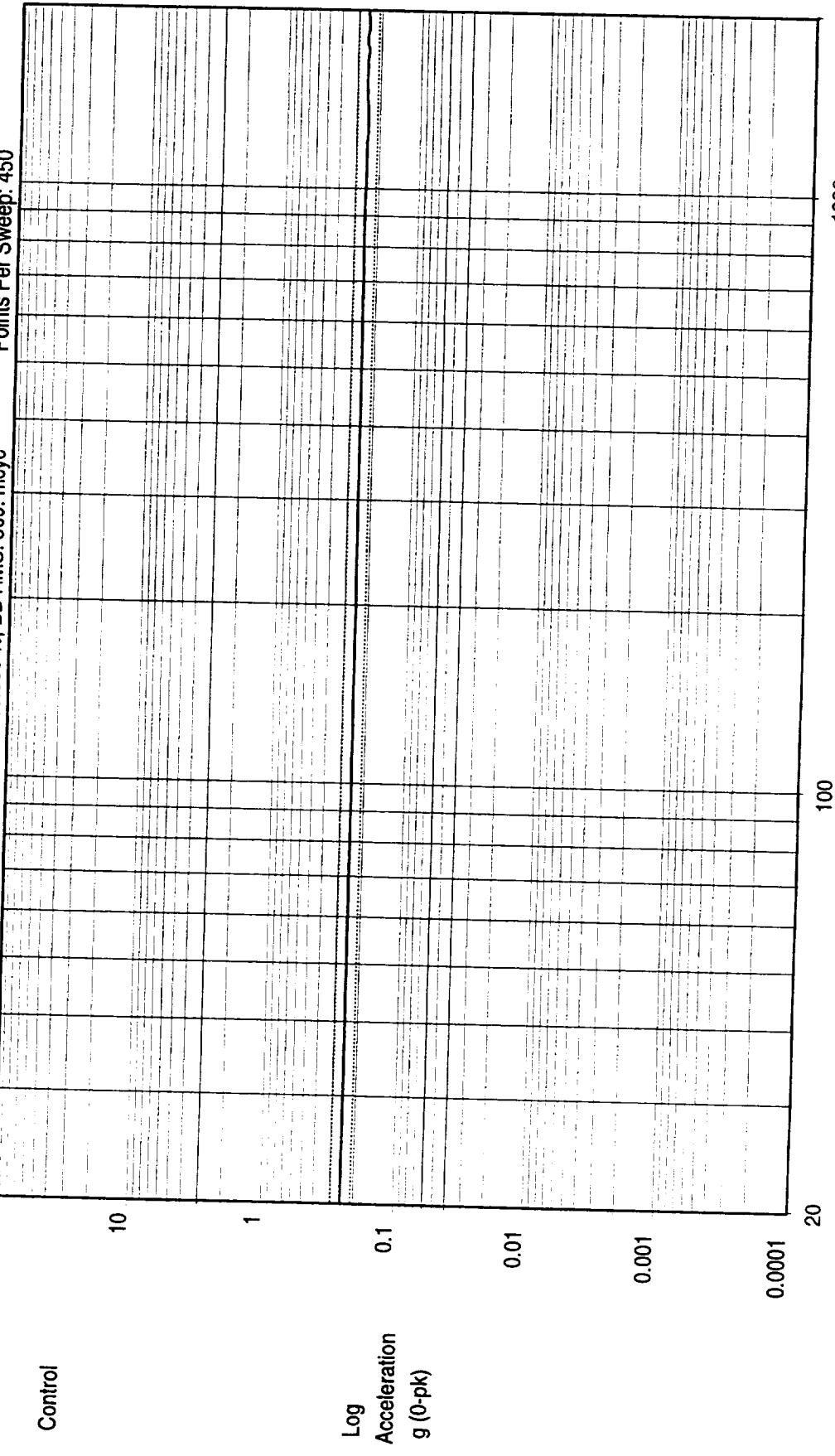


AMSU PHASE LOCK OSCILLATOR SIO 538596-F09 METSAT 11-12-98  
 Y AXIS POST SINE SWEEP/N 1348360-1 S/N F09  
 Sine Test Name: PLO.tmp  
 15:49:25  
 12-Nov-1998  
 ENG 7A  
 217 00

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcy

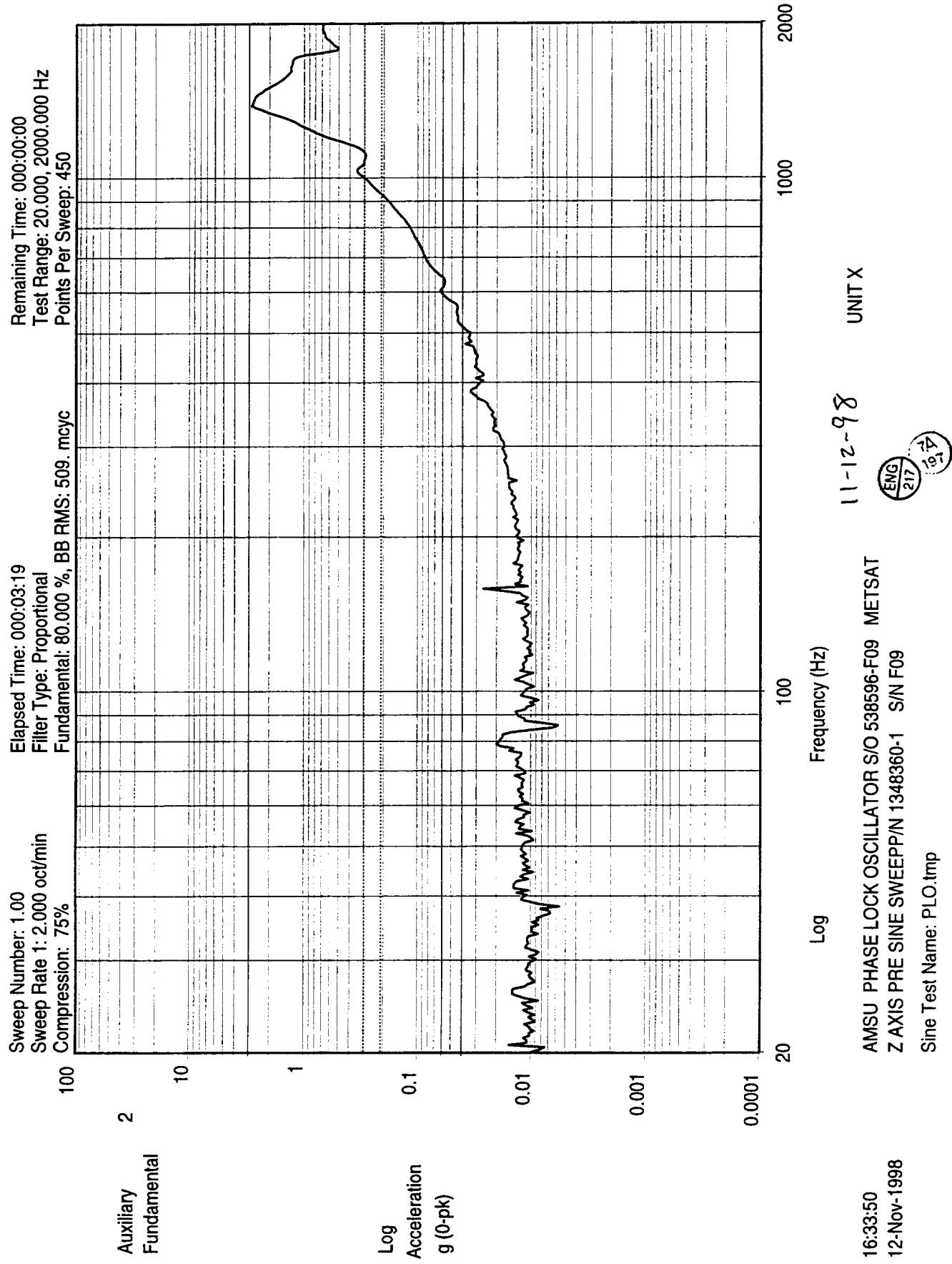
Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450



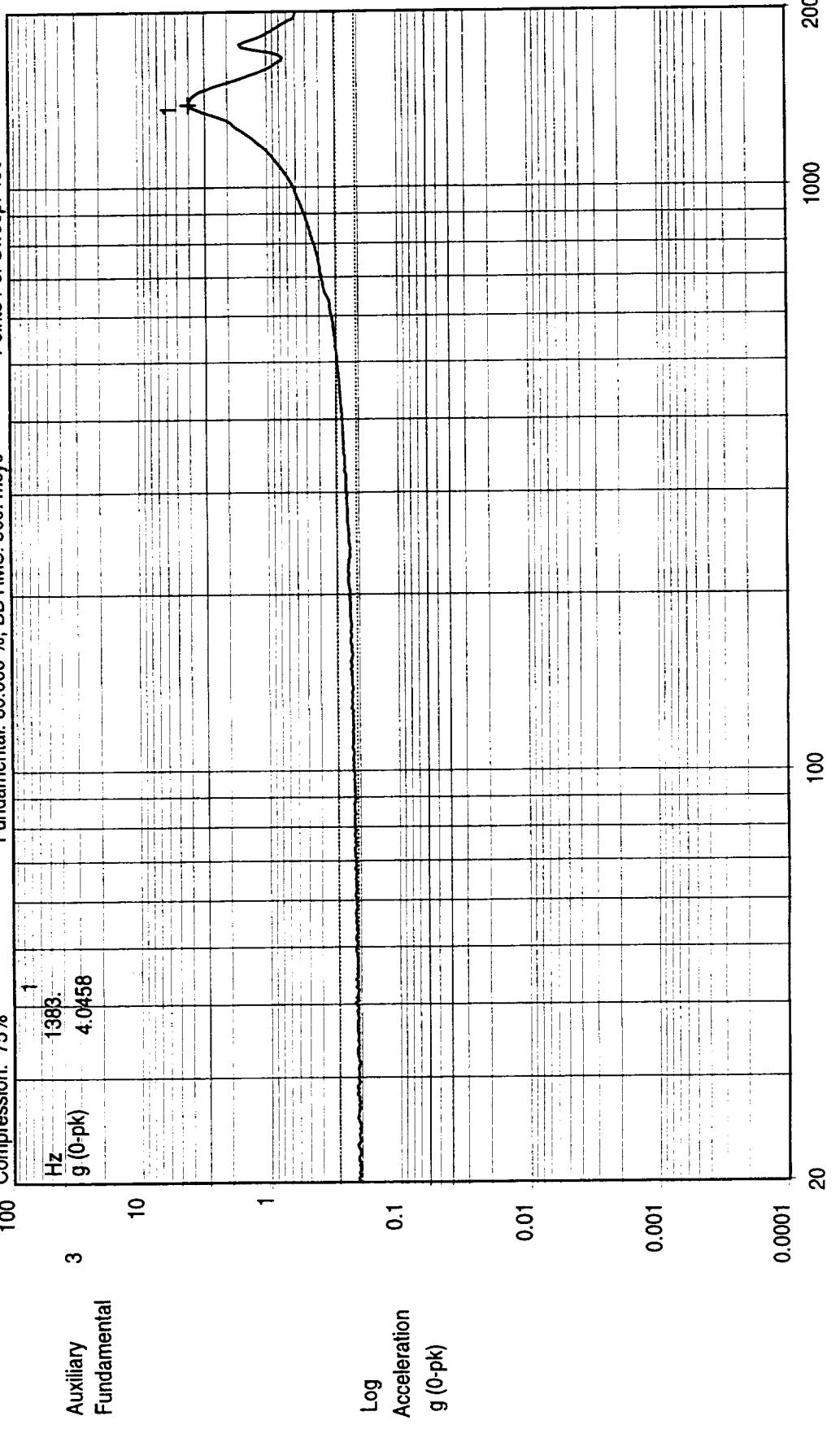
16:33:45  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09  
Z AXIS PRE SINE SWEEP/P/N 1348360-1 S/N F09  
Sine Test Name: PLO.lmp

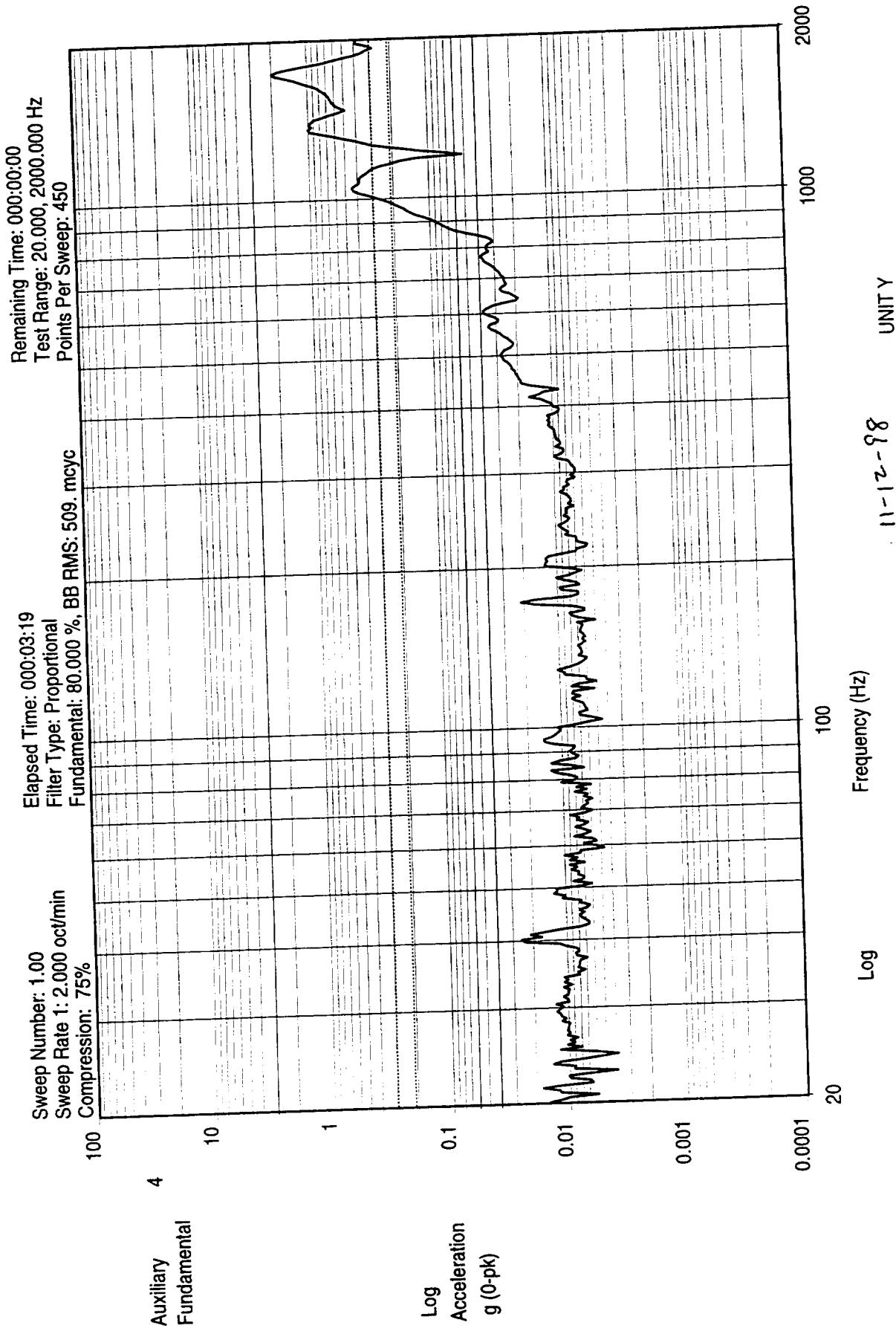
ENG  
217  
07  
11-12-98



Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%  
Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcyc



11-12-98  
UNIT Z  
ENG  
2/17/98  
AMSU PHASE LOCK OSCILLATOR S/O 538596-F09, METSAT  
Z AXIS PRE SINE SWEETP/N 1348360-1 S/N F09  
Sine Test Name: PLO.tmp  
16:34:10  
12-Nov-1998



AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT  
 Z AXIS PRE SINE SWEEP/N 1348360-1 S/N F09

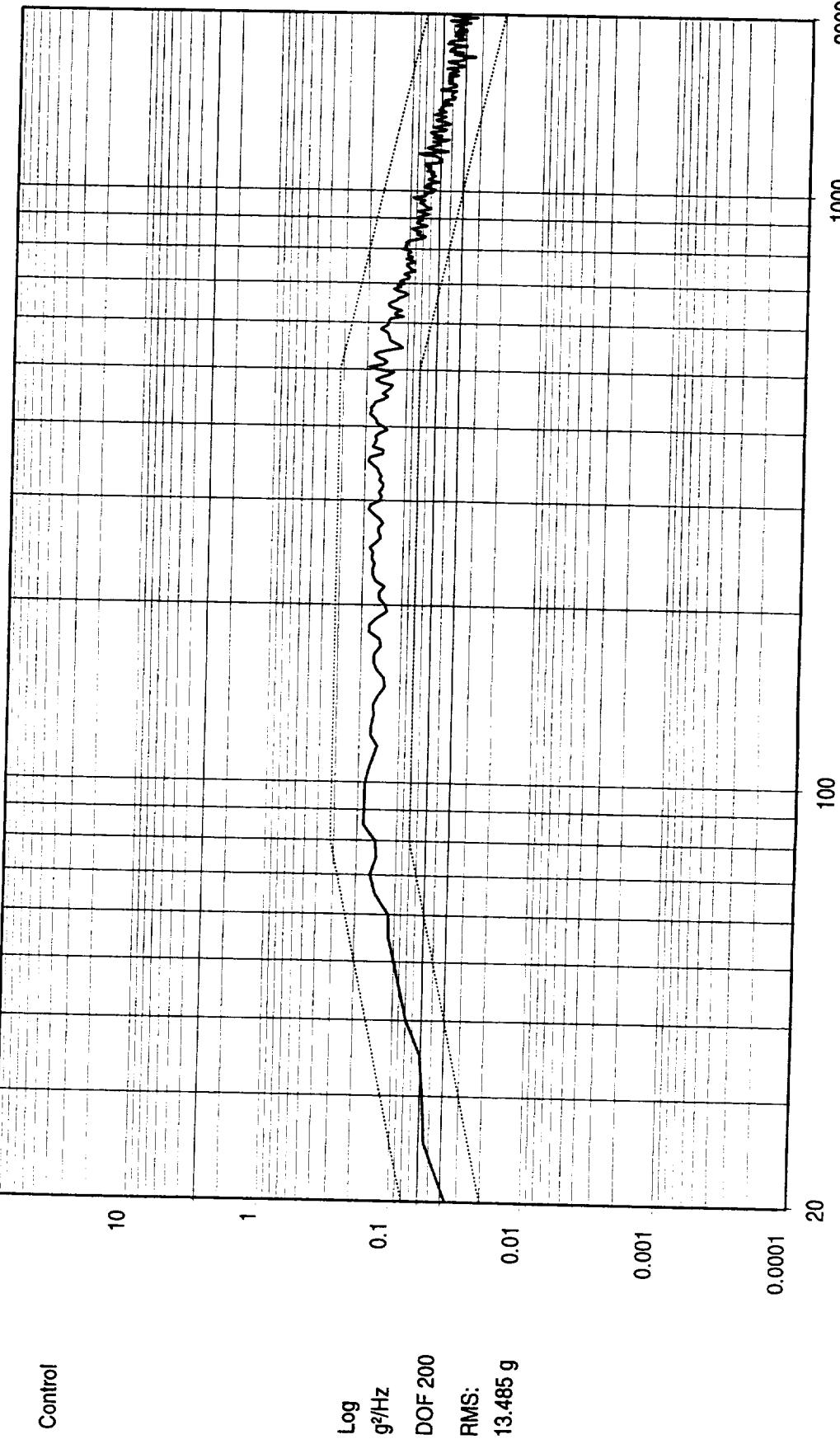
Sine Test Name: PLO.tmp

16:34:15  
 12-Nov-1998

Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



16:46:16  
12-Nov-1998

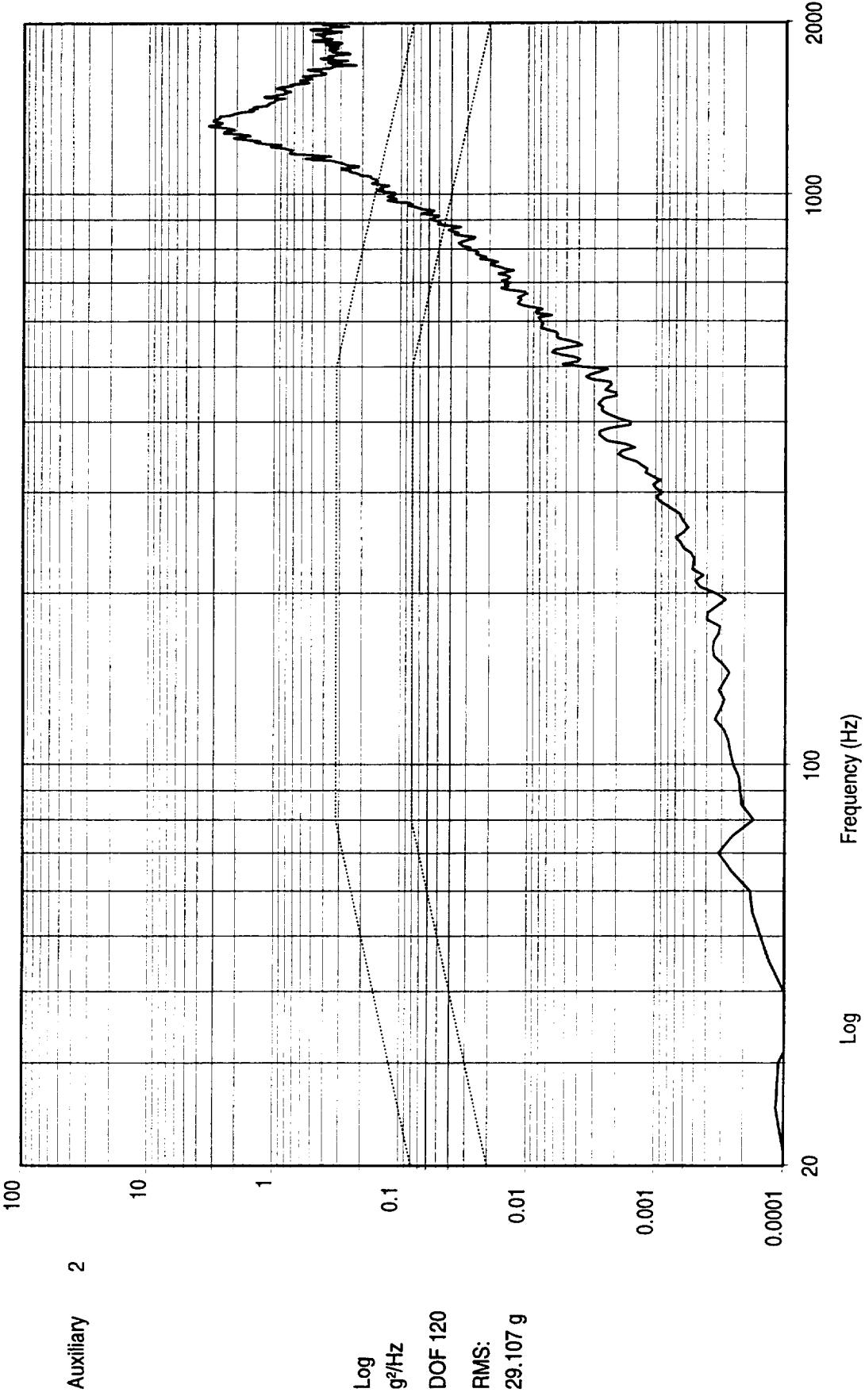
AMSU PHASE LOCK OSCILLATOR S/0538596-F09  
Z AXIS TEST P/N 1348360-1 S/N F09  
Test Name: PL0tmp

11-12-98  
ENG  
2/19/98

Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



16:46:20  
12-Nov-1998

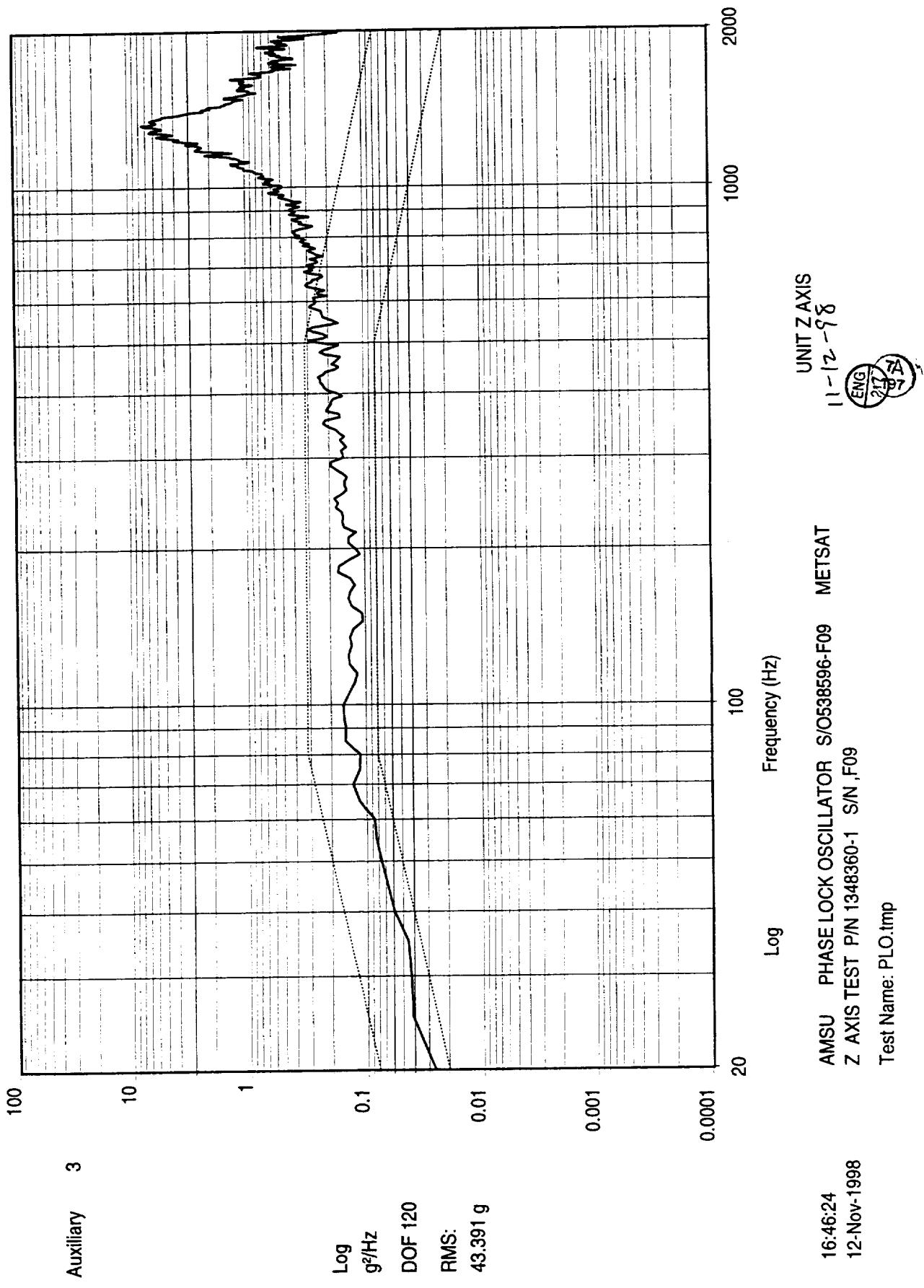
AMSU PHASE LOCK OSCILLATOR S/0538596-F09  
Z AXIS TEST P/N 1348360-1 SN ,F09  
Test Name: PL0.tmp

UNIT X AXIS  
11-12-78  
ENG  
217  
1997

Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



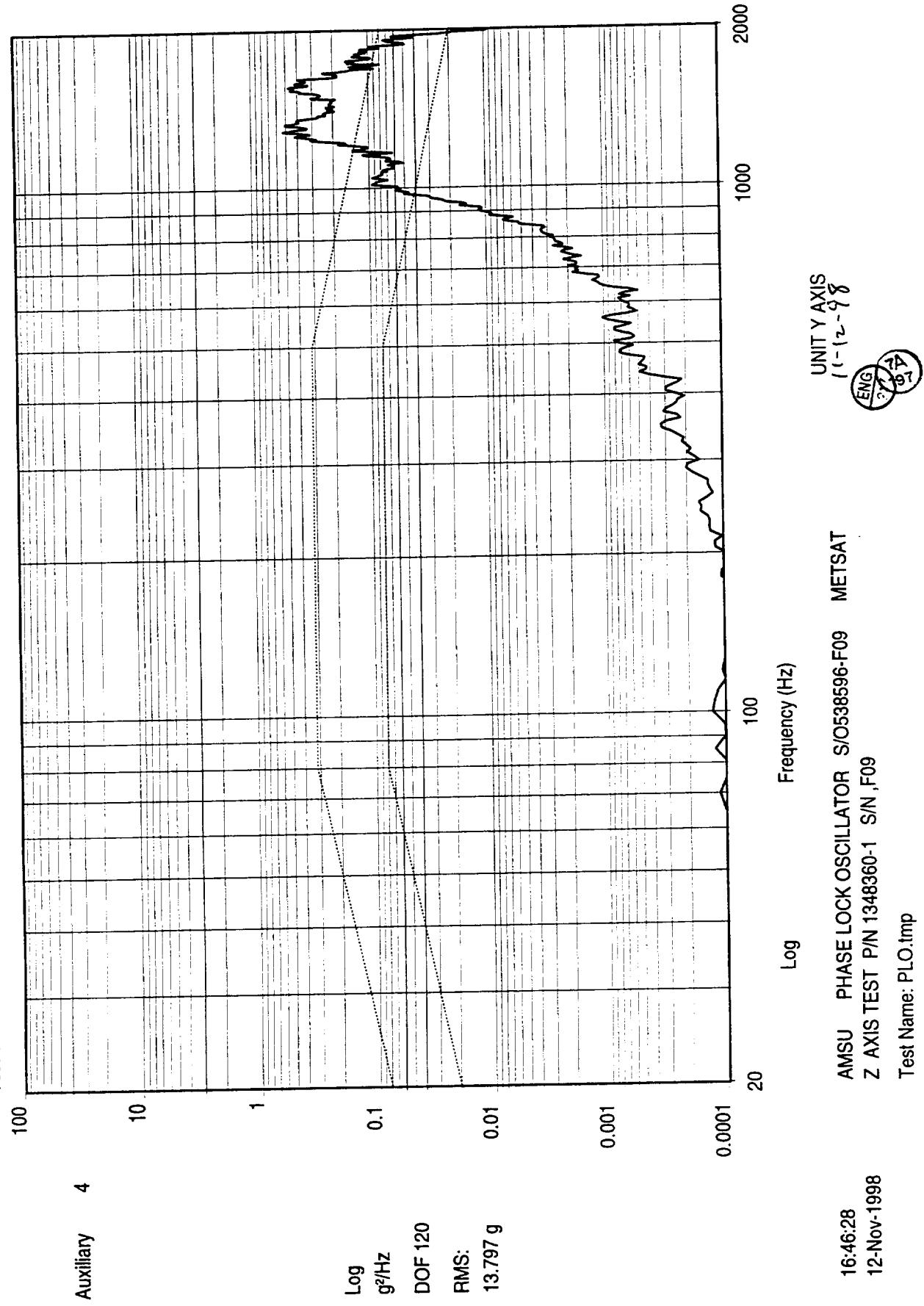
16:46:24  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/0538596-F09  
Z AXIS TEST P/N 1348360-1 S/N ,F09

Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off

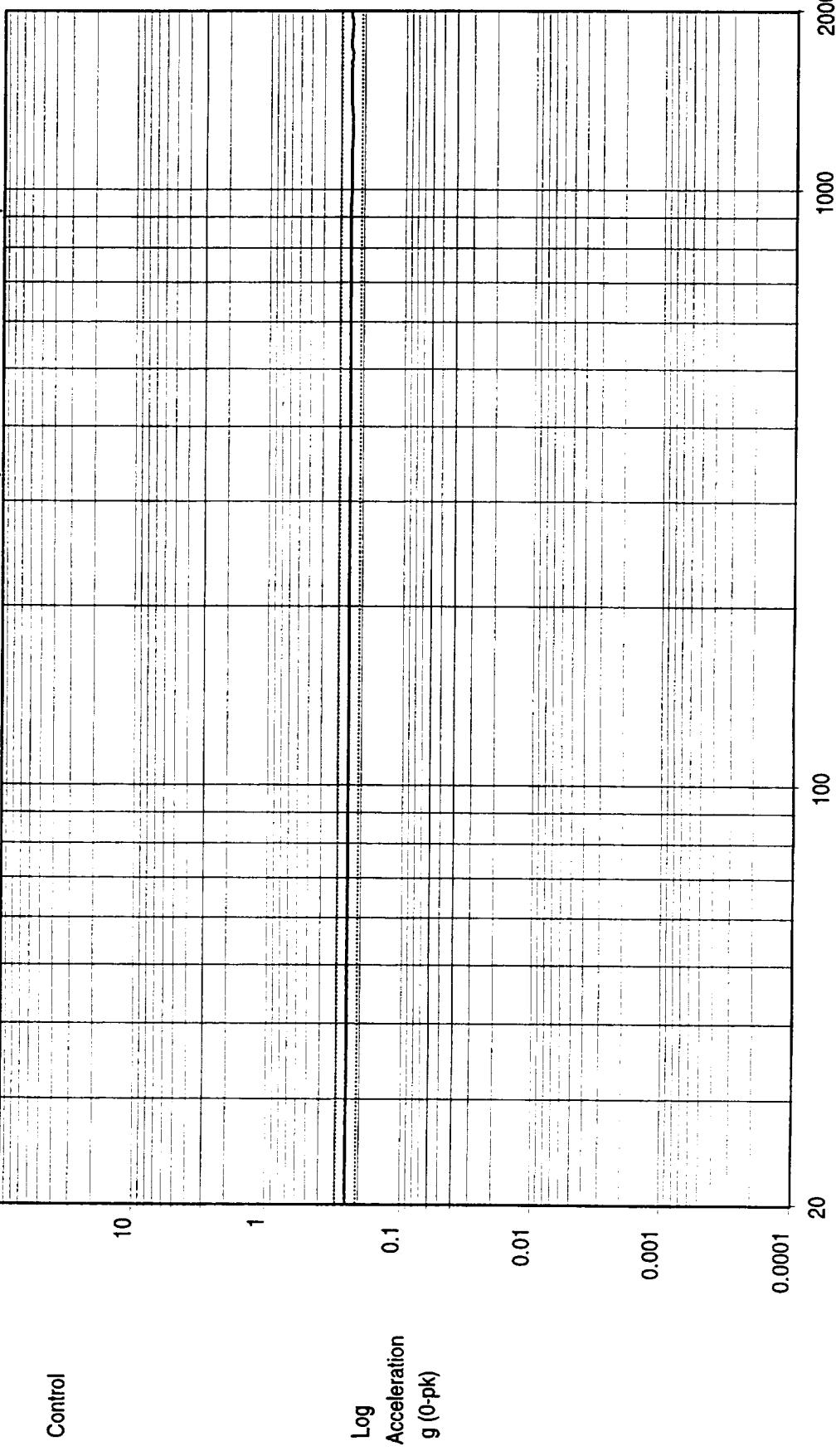
Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcy/c

Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450



20 100 1000 2000

20 100

Log

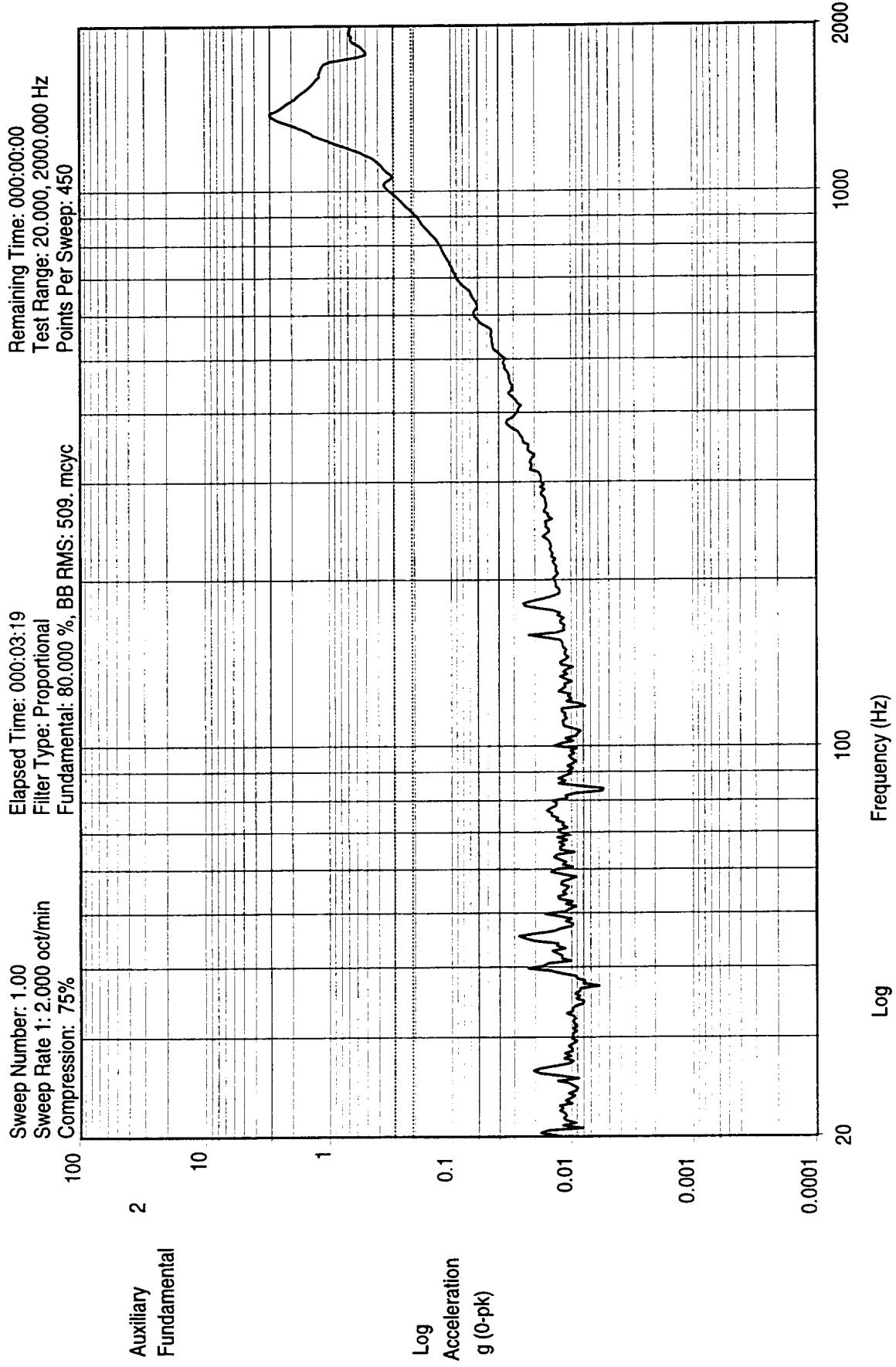
11-12-98

16:58:16  
12-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT  
Z AXIS POST SINE SWEPP/N 1348360-1 S/N F09

Sine Test Name: PLO.Imp

ENG 21/1997

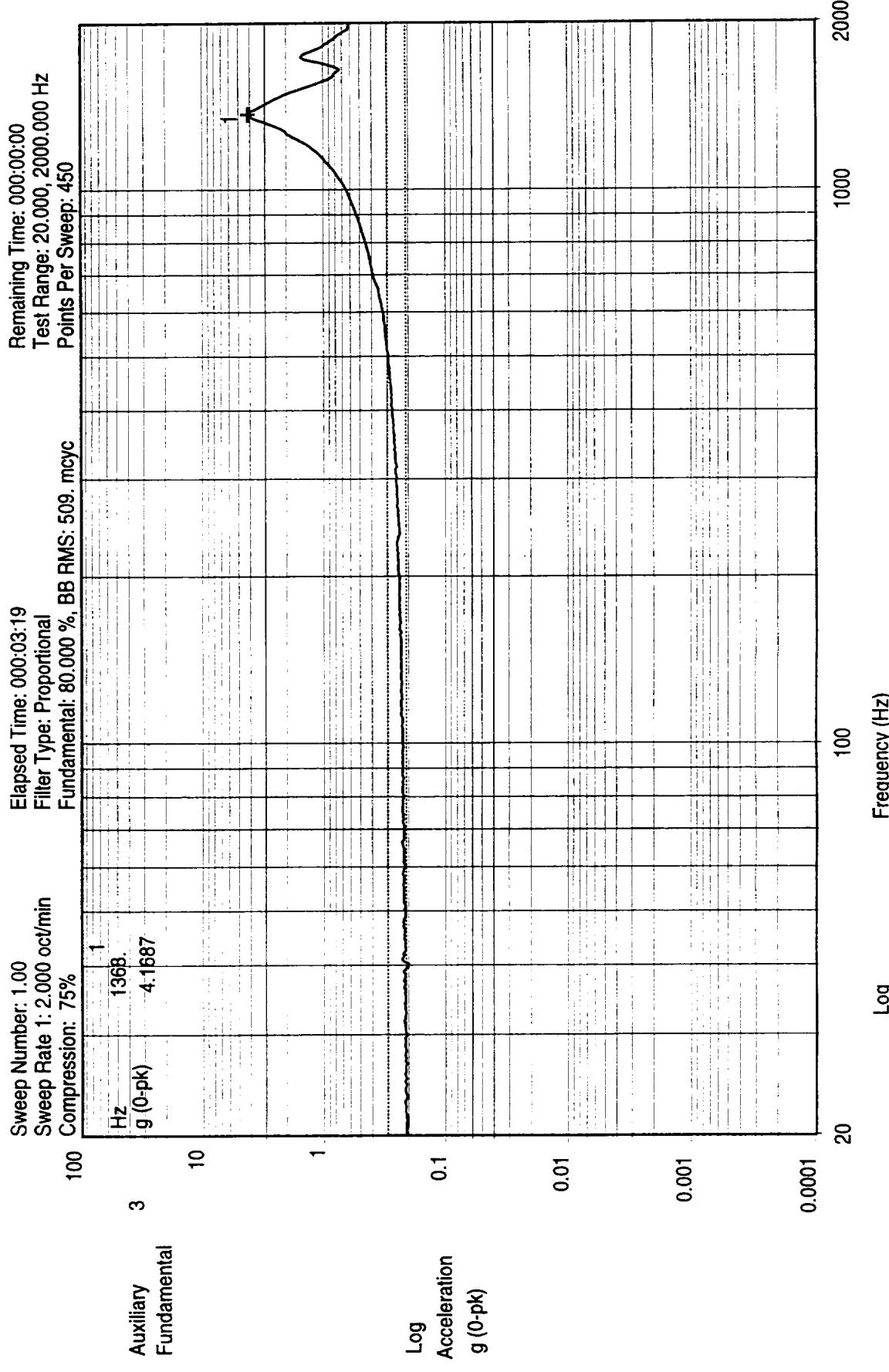


AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT 11-12-98  
 Z AXIS POST SINE SWEEP/N 1348360-1 S/N F09  
 Sine Test Name: PLO.tmp

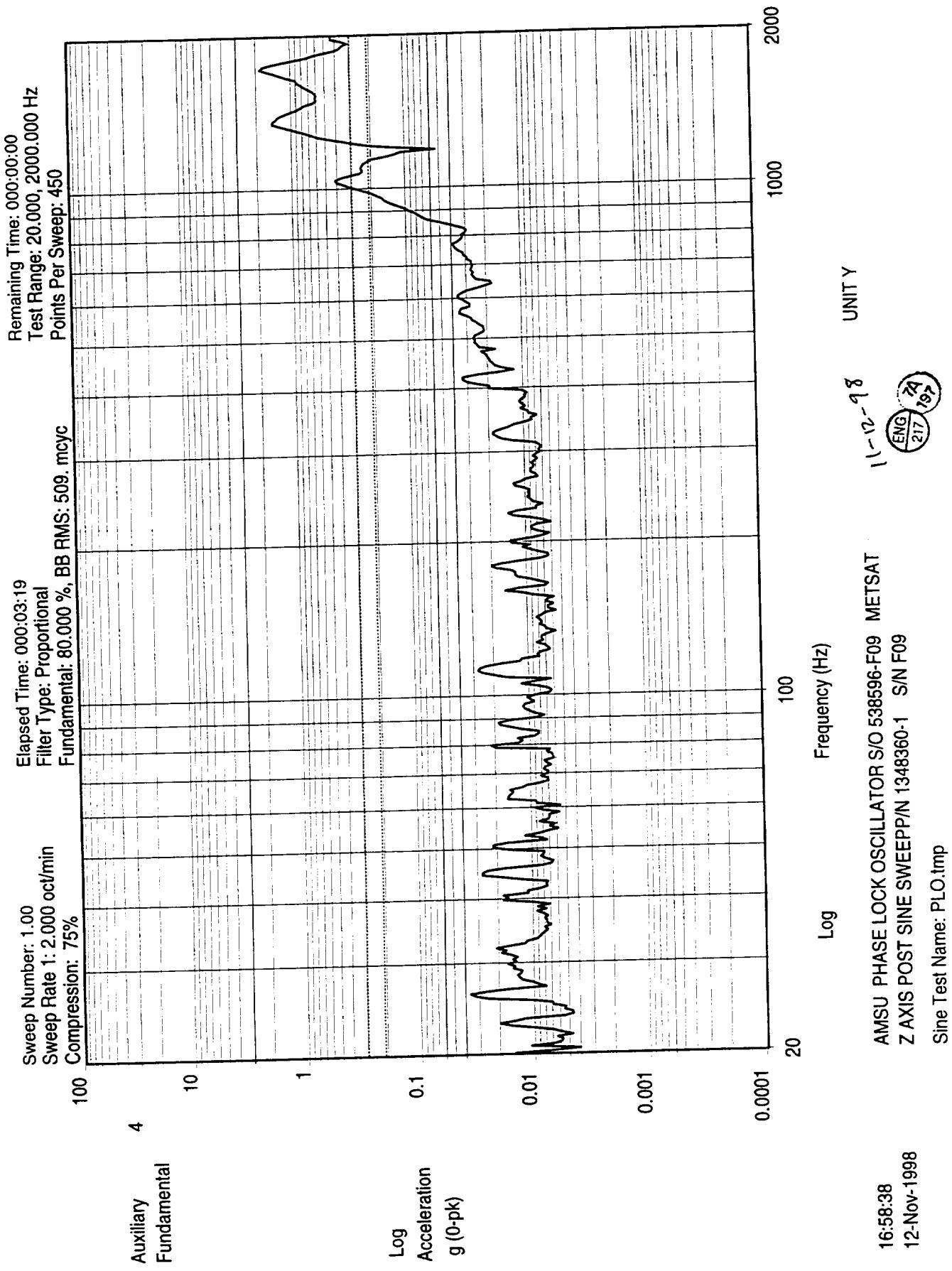
ENCL 24  
 2/17 1998

16:58:21  
 12-Nov-1998

**Remaining Time:** 000:00:00  
**Test Range:** 20.000, 2000.000 Hz  
**Points Per Sweep:** 450



11-12-98  
ENCL A  
2178  
Sine Test Name: PL0.tmp  
Z AXIS POST SINE SWEEP/N 1348360-1 S/N F09  
AMSU PHASE LOCK OSCILLATOR S/O 538596-F09 METSAT





### Section 2B: Acceptance Level Vibration - F10

This section includes the data from the limited functional tests which take place before and throughout vibration, and the vibration-specific. The following table summarizes the results of the limited functional test.

<b>Test</b>	<b>Expected Value</b>	<b>Post X axis</b>	<b>Post Y axis</b>	<b>Post Z axis</b>
Output Frequency	57290344 ± 200 kHz	57290339 kHz	57290360 kHz	57290376 kHz
Output Power	18.5 dBm ± 1.5 dB	17.9 dBm	17.9 dBm	17.3 dBm

The following pages contain the raw data.



TEST DATA SHEET 8B  
Limited Functional Test (Paragraph 4.2.3)  
Post X-Axis LPT

Test Setup Verified: O Pines  
Signature

Paragraph 4.2.3.2:

Step	Test		Required	Measurement	Pass/Fail
3	Potential Difference				
	From	To			
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	1mVac	PASS
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	1mVac	PASS

Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.00 V	PASS
	Voltage Meter 2	-15 ± 0.1 V	-15.02 V	PASS
	Current Meter 1	600 mA max.	534 mA	PASS
	Current Meter 2	100 mA max.	-70 mA	PASS
9	Output Frequency	57.290344 ± .0001 GHz	57.290339	PASS
10	Output Power	18.5 dBm ± 1.5 dB	17.89 dBm	PASS

92 (45/1) 11/4/98

\* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

11/4/98

(45/1)

Shop Order No.: 538595  
Operation: Q150  
Unit Serial No.: F10  
Date: 11/4/98

Test Engineer: O Pines  
Quality Control: TA 11/4/98  
Govt. Rep.: 11/4/98



SHEET 82 OF 11 June 1998  
ECN NO. 1956TEST DATA SHEET 8C  
Limited Functional Test (Paragraph 4.2.3)

Post Y-Axis LPT

Test Setup Verified: O. Perez  
Signature

Paragraph 4.2.3.2:

Step	Test		Required	Measurement	Pass/Fail
3	Potential Difference				
	From	To			
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	1m Vac	Pass
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	1m Vac	Pass

Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.00 V	Pass
	Voltage Meter 2	-15 ± 0.1 V	-15.08 V	Pass
	Current Meter 1	600 mA max.	535 mA	Pass
	Current Meter 2	100 mA max.	-70 mA	Pass
9	Output Frequency	57.290344 ± .0001 GHz	57.2903360	Pass
10	Output Power	18.5 dBm ± 1.5 dB	17.89 dBm	Pass

\* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

Shop Order No.: 538595Operation: 0150Unit Serial No.: F10Date: 11/4/98Test Engineer: O. PerezQuality Control: 11/4/98Govt. Rep.: Dorothy Lee11/4/98  
45/1



TEST DATA SHEET 8D  
Limited Functional Test (Paragraph 4.2.3)

Post Z-Axis LFT

Test Setup Verified: D. Hines  
Signature

Paragraph 4.2.3.2:

Step	Test		Required	Measurement	Pass/Fail
3	Potential Difference				
	From	To			
	Power Supply RTN	Test Platform *	< 1.0 Vac	N/A	N/A
	Power Supply RTN	Frequency Counter Chassis	< 1.0 Vac	1m Vac	PASS
	Power Supply RTN	Power Meter Chassis	< 1.0 Vac	1m Vac	PASS

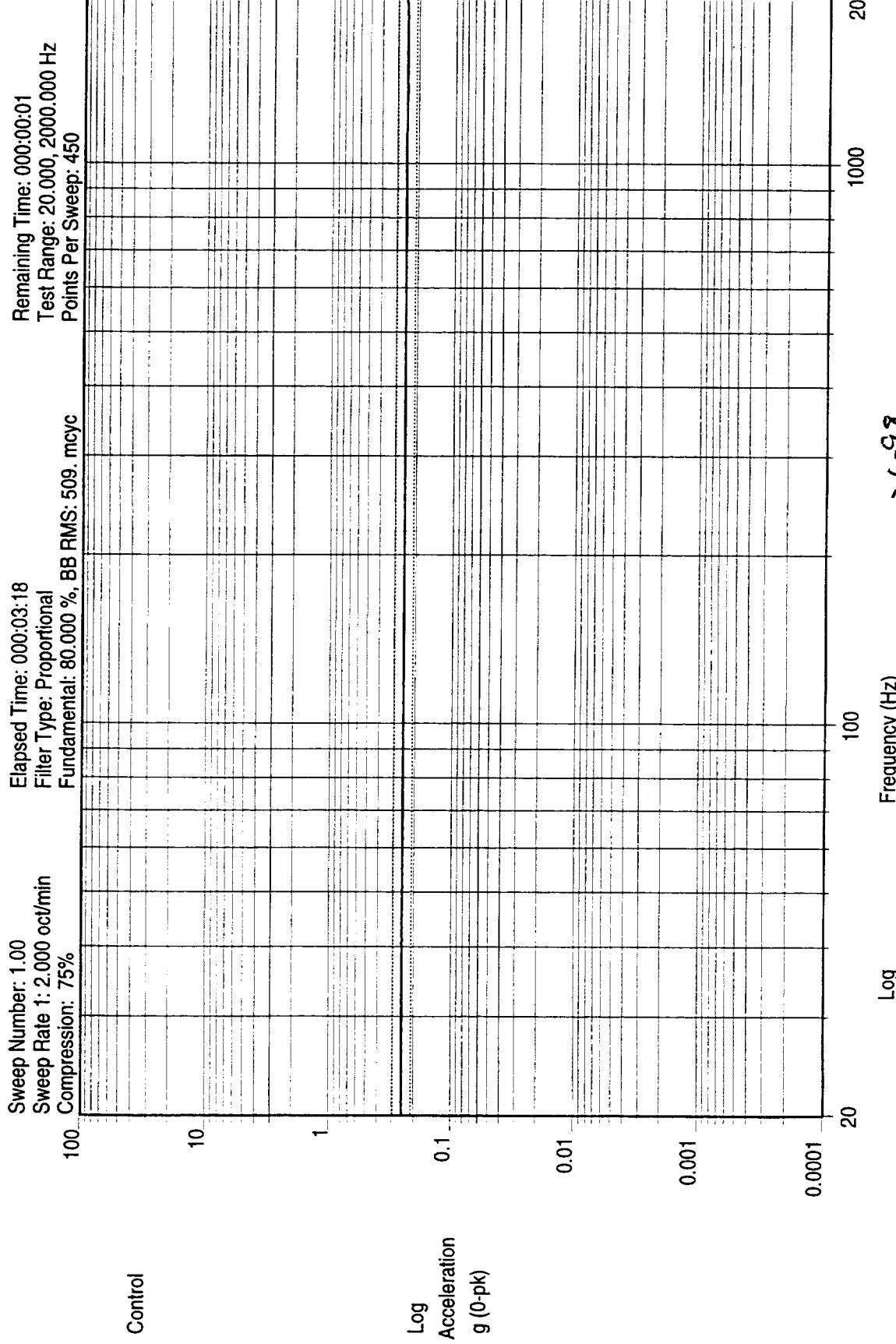
Step	Test	Expected	Measured	Pass/Fail
8	Voltage Meter 1	+15 ± 0.1 V	15.01 V	PASS
	Voltage Meter 2	-15 ± 0.1 V	-15.05 V	PASS
	Current Meter 1	600 mA max.	535 mA	PASS
	Current Meter 2	100 mA max.	70 mA	PASS
9	Output Frequency	57.290344 ± .0001 GHz	57.2903376 GHz	PASS
10	Output Power	18.5 dBm ± 1.5 dB	17.26 dBm	PASS

\* If used. N/A this line entry if not used in test. Example: If PLO is to be vibrated and unit tested "in-place" after each axis, check potential difference between shaker table and power supply RTN.

11/4/98  


Shop Order No.: 538595  
Operation: O150  
Unit Serial No.: F10  
Date: 11/4/98

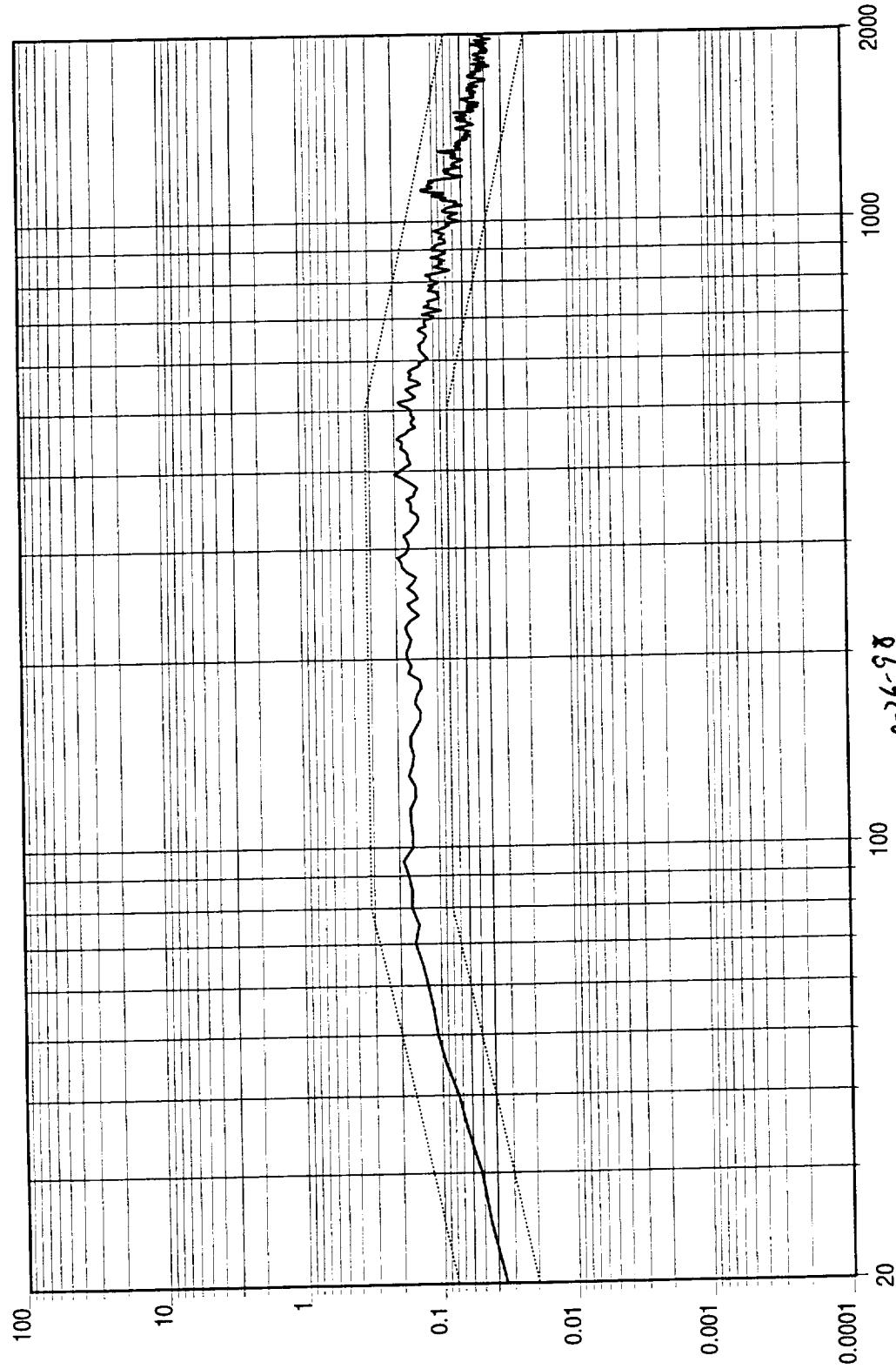
Test Engineer: D. Hines  
Quality Control: 24 11/4/98  
Govt. Rep.: H. Hines 11/5/98



AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
 Y AXIS SYSTEM CHECKOUT P/N 1348360-1 S/N F10  
 Sine Test Name: PLO.tmp

10:09:36  
 26-Oct-1998

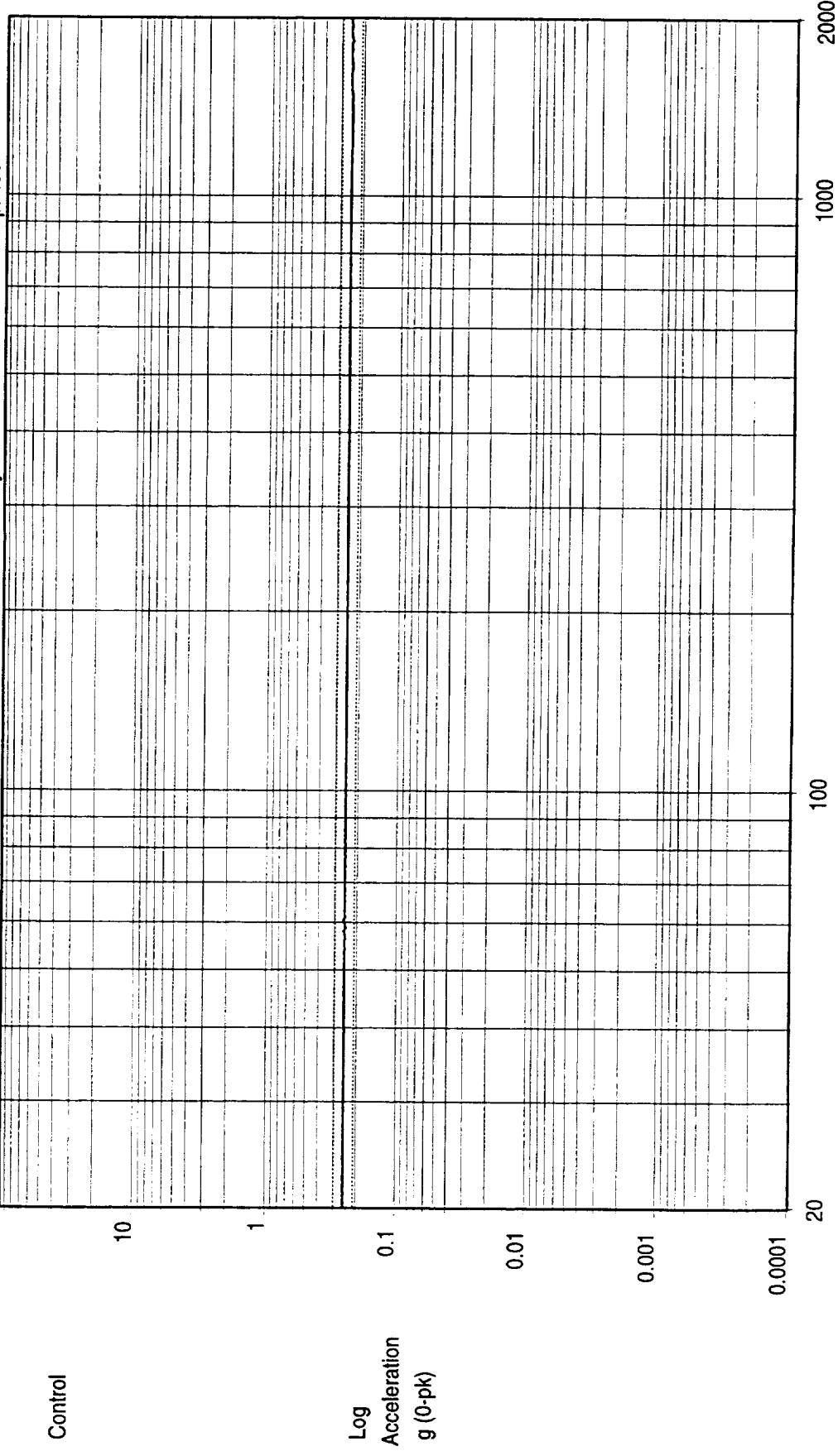
Test Level: 0.000 dB  
Test Time: 000:01:13  
Reference RMS: 13.576  
Clipping: Off



AMSU PHASE LOCK OSCILLATOR S/0584921, 53854922  
Y AXIS SYSTEM CHECKOUT P/N 1348360-1 SN-F08, F10  
Test Name: PLO.lmp  
09:59:42 26-Oct-1998  
ENG 217  
ENG 217  
EOT  
e62  
10-26-98

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 00:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcyc

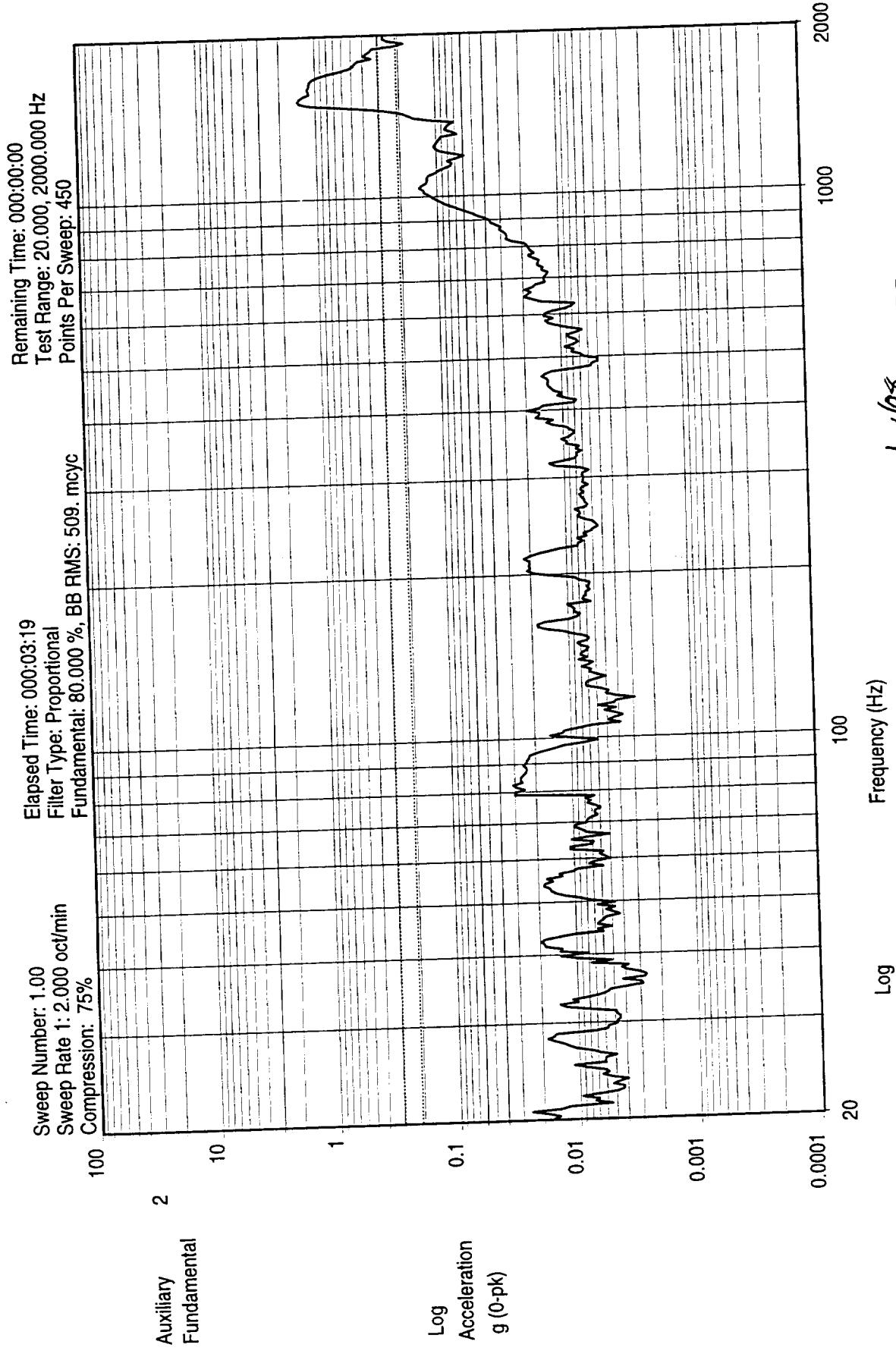


11:32:04  
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
PRE Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

ENG 217 E.O.I 10/24/98



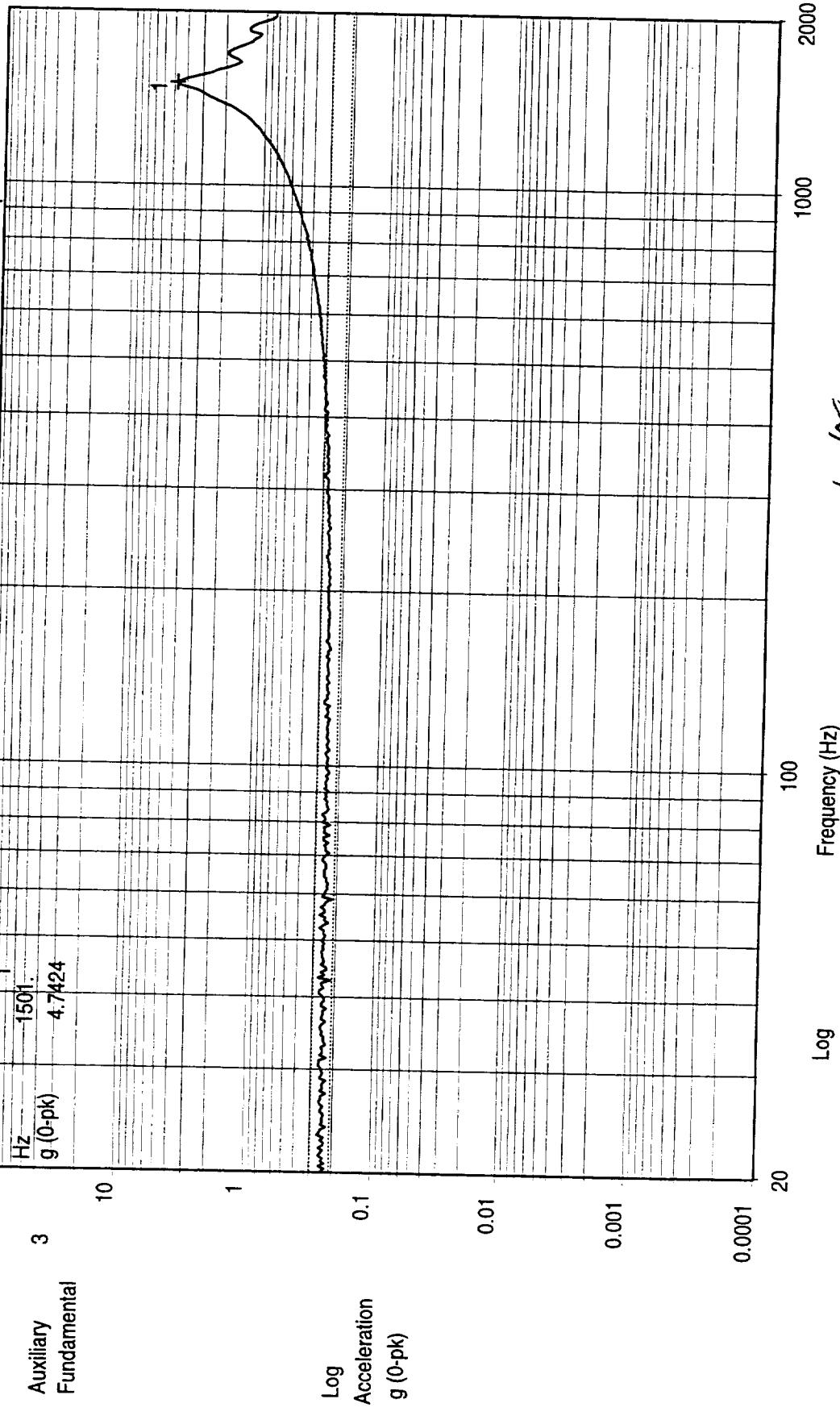
11:32:09  
 26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
 PRE Y AXIS SINE SWEEP TEST P/N 1348360-1 SIN F10  
 Sine Test Name: PLOtmp

10/26/98 UNIT Z  
 ENG 217  
 E.O.I.  
 24  
 267

Elapsed Time: 00:00  
 Filter Type: Propo  
 Fundamental: 80.0  
 Sweep Number: 1.00  
 Sweep Rate 1: 2.000 oct/min  
 Compression: 75%  
 Hz  
 g (0-pk)  
 1  
 -1501.  
 4.7424  
 100  
 3  
 Auxiliary  
 Fundamental

Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450

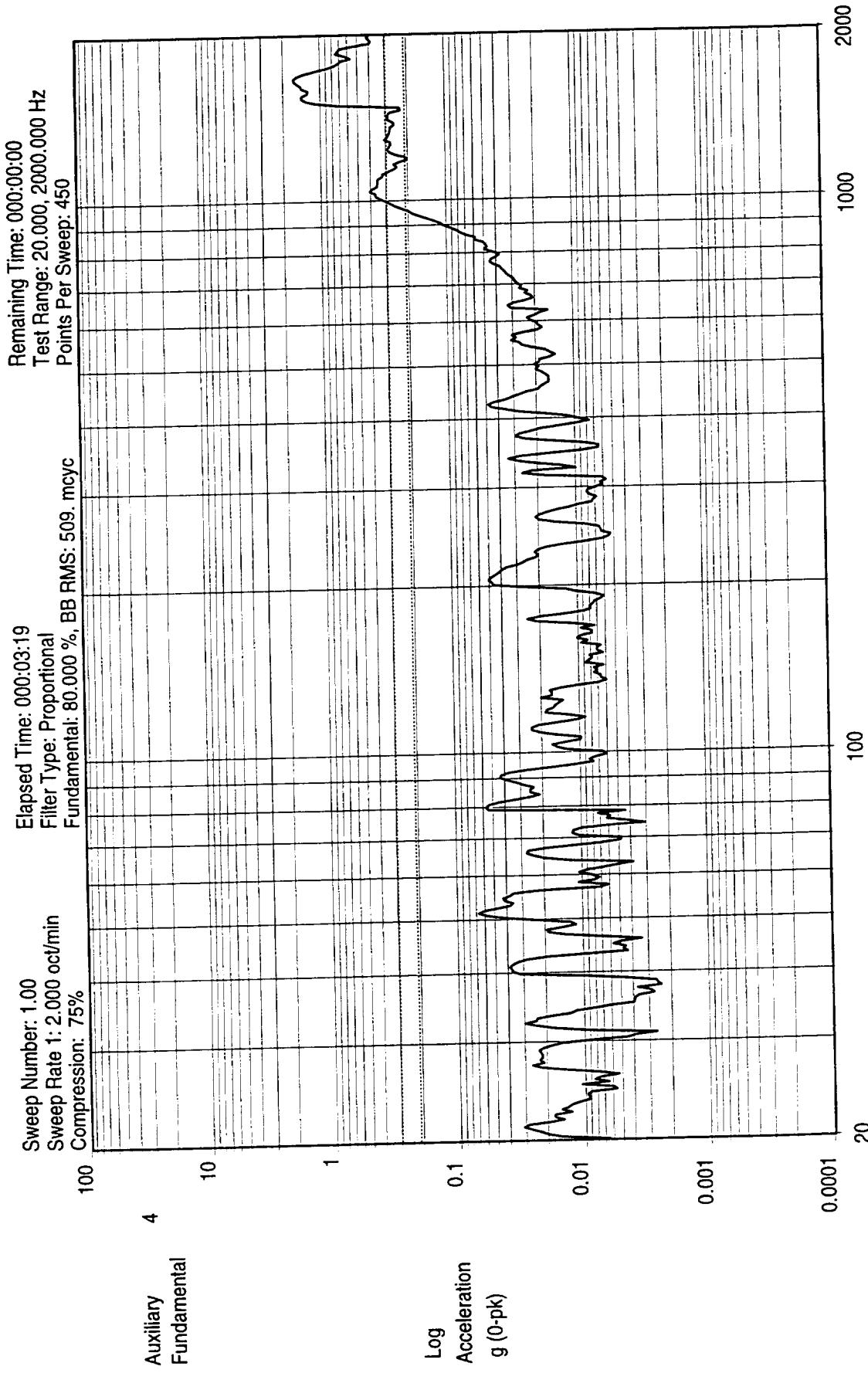


11:34:15  
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
PRE Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

UNITY  
EOT  
ENG  
217



10/26/98 UNIT X  
 AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
 PRE Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10  
 Sine Test Name: PLO.tmp

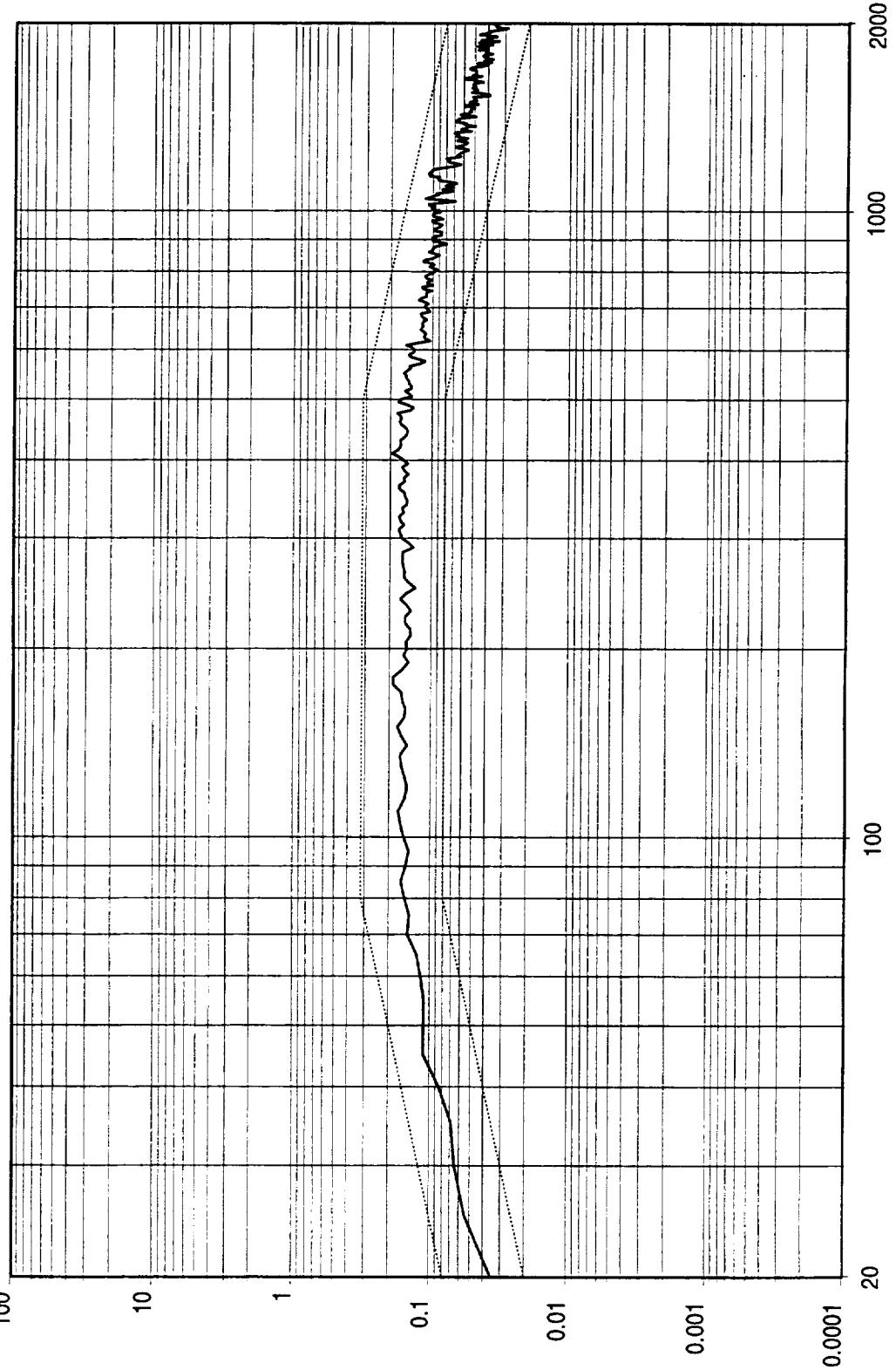
11:32:54  
 26-Oct-1998

EOT  
 7A  
 267  
 ENG  
 217

Test Level: 0.000 dB  
Test Time: 000:01:00

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz

Reference RMS: 13.576  
Clipping: Off

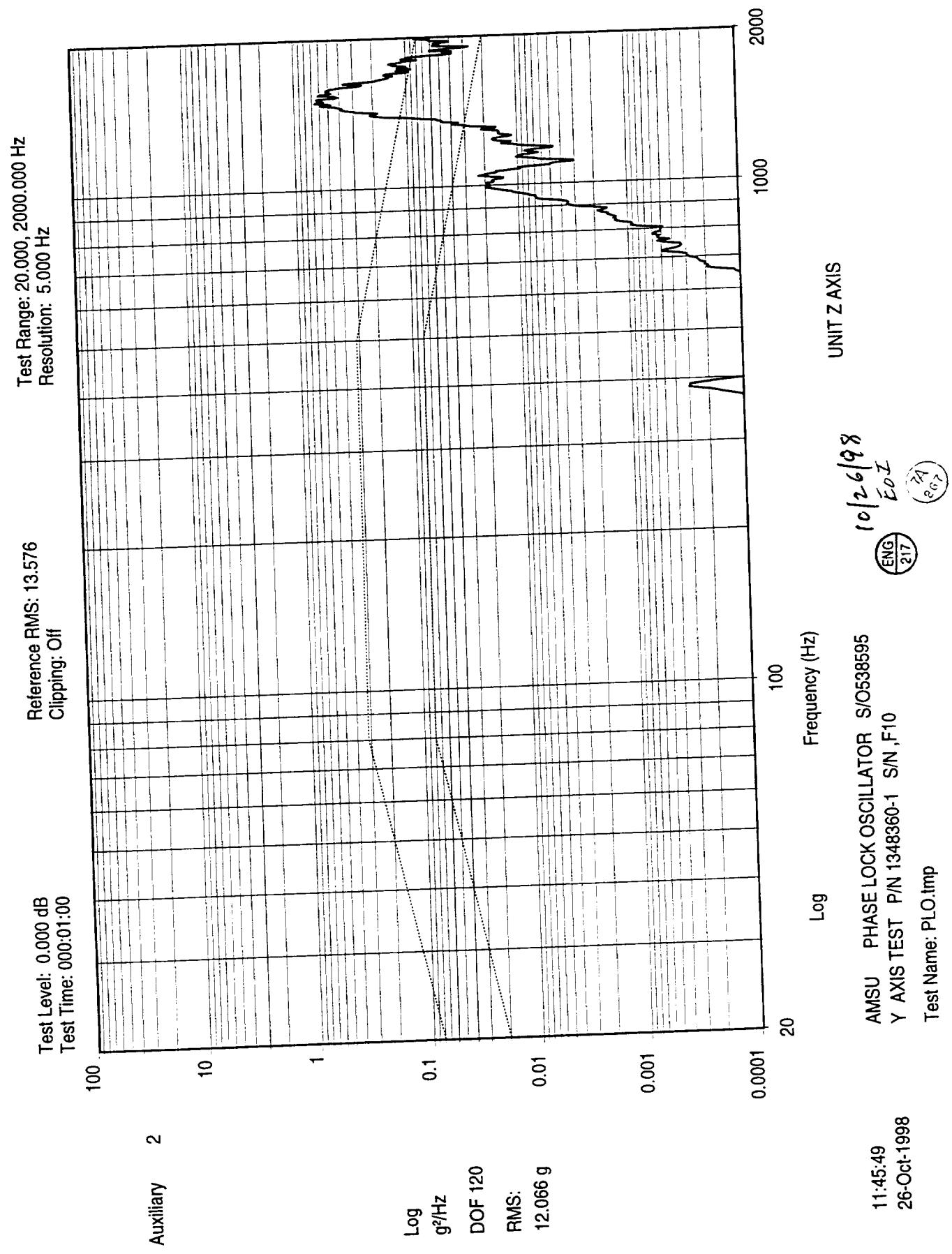


10/26/98  
EOT  
217  
267

AMSU PHASE LOCK OSCILLATOR S/0538595  
Y AXIS TEST P/N 1340360-1 S/N, F10

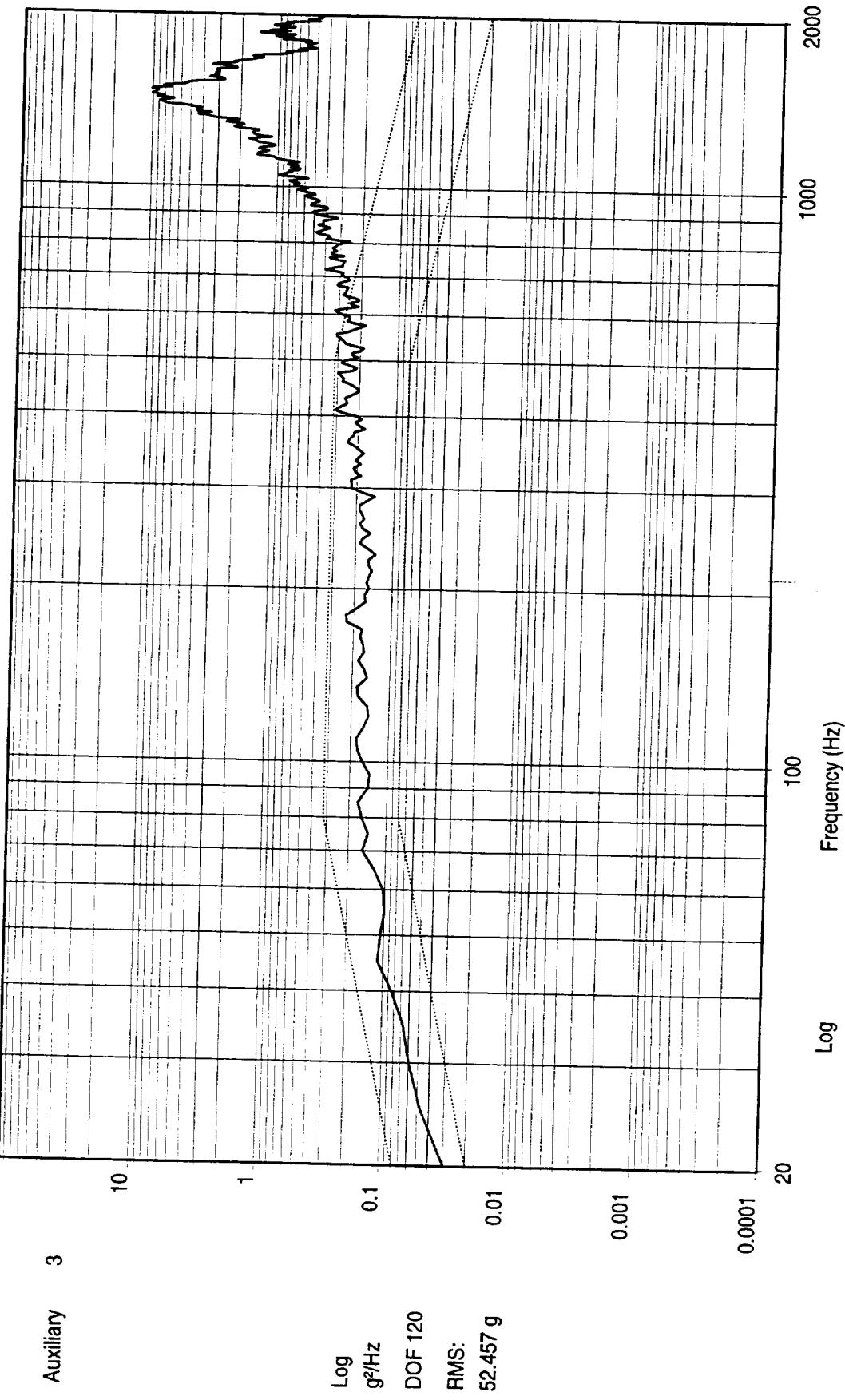
Test Name: PL0.tmp

11:45:44  
26-Oct-1998



Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off



11:45:53  
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/0538595  
Y AXIS TEST P/N 1348360-1 S/N F10  
Test Name: PL0.tmp

UNIT Y AXIS

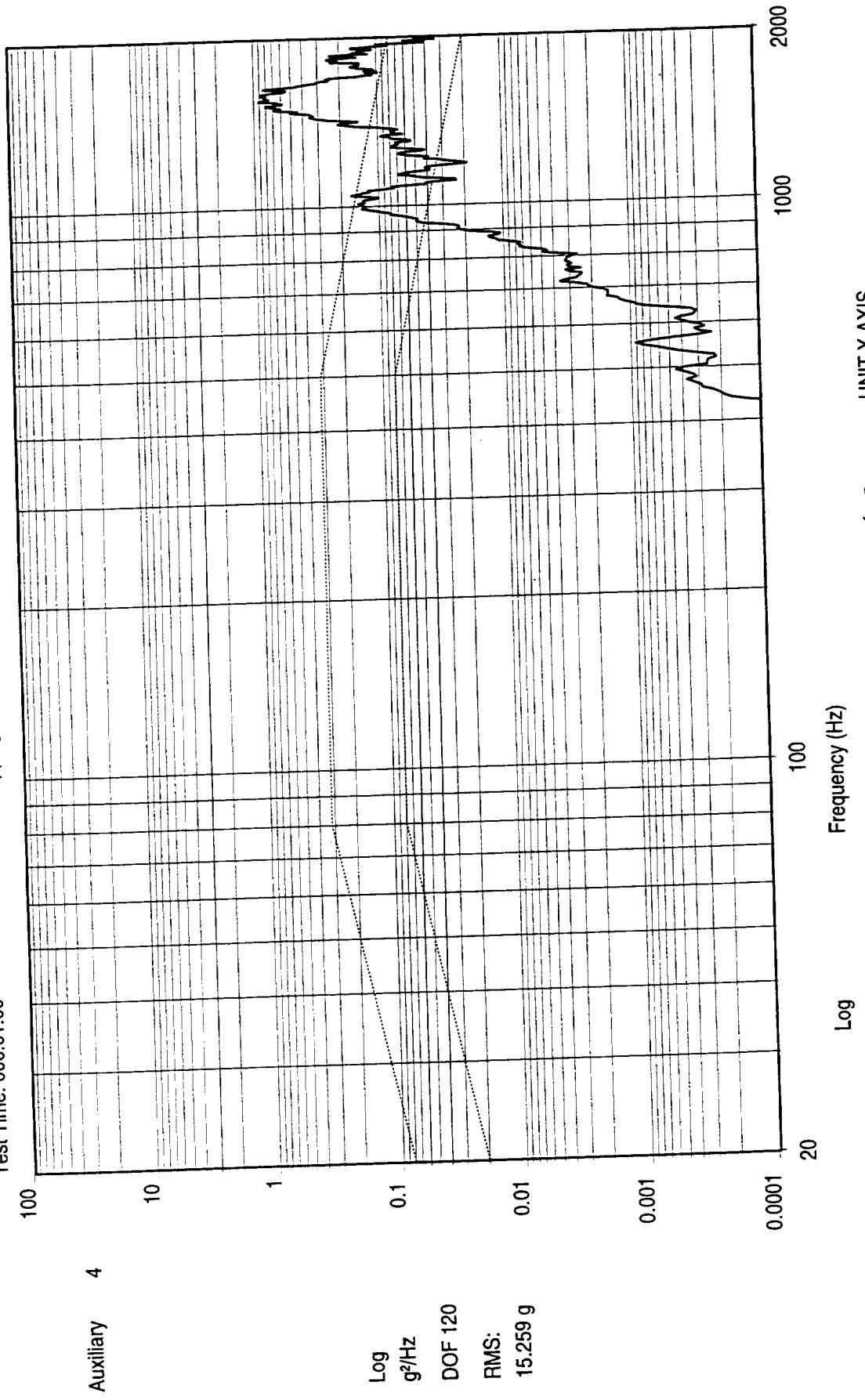
10 $^{1/2}$  (PSS)  
E0Z  
217

AMSU PHASE LOCK OSCILLATOR S/0538595  
Y AXIS TEST P/N 1348360-1 S/N F10  
Test Name: PL0.tmp

Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



11:45:57  
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O538595  
Y AXIS TEST P/N 1348360-1 S/N ,F10

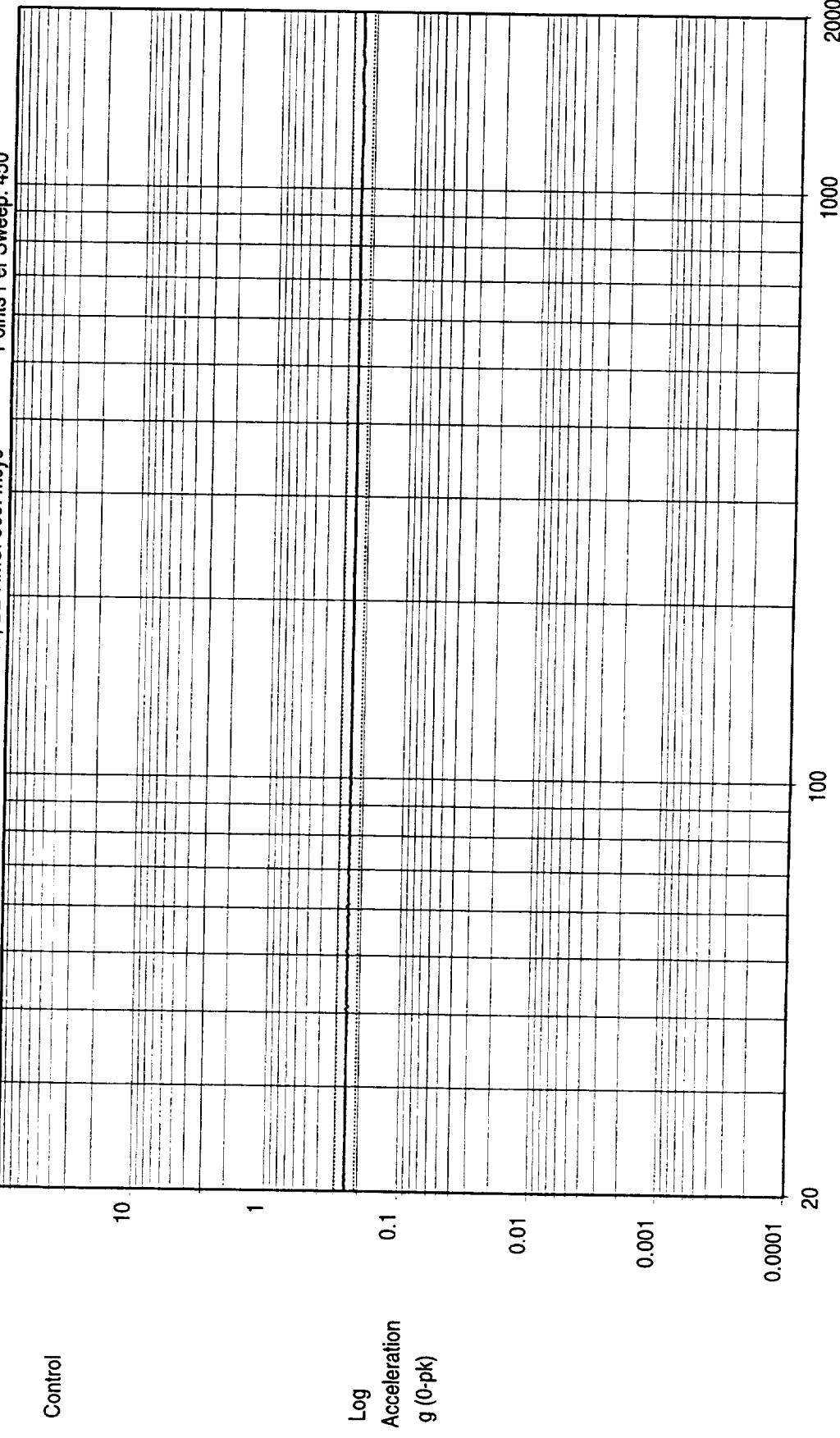
UNIT X AXIS

26/98  
EOT  
7A  
26/1

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcy

Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450

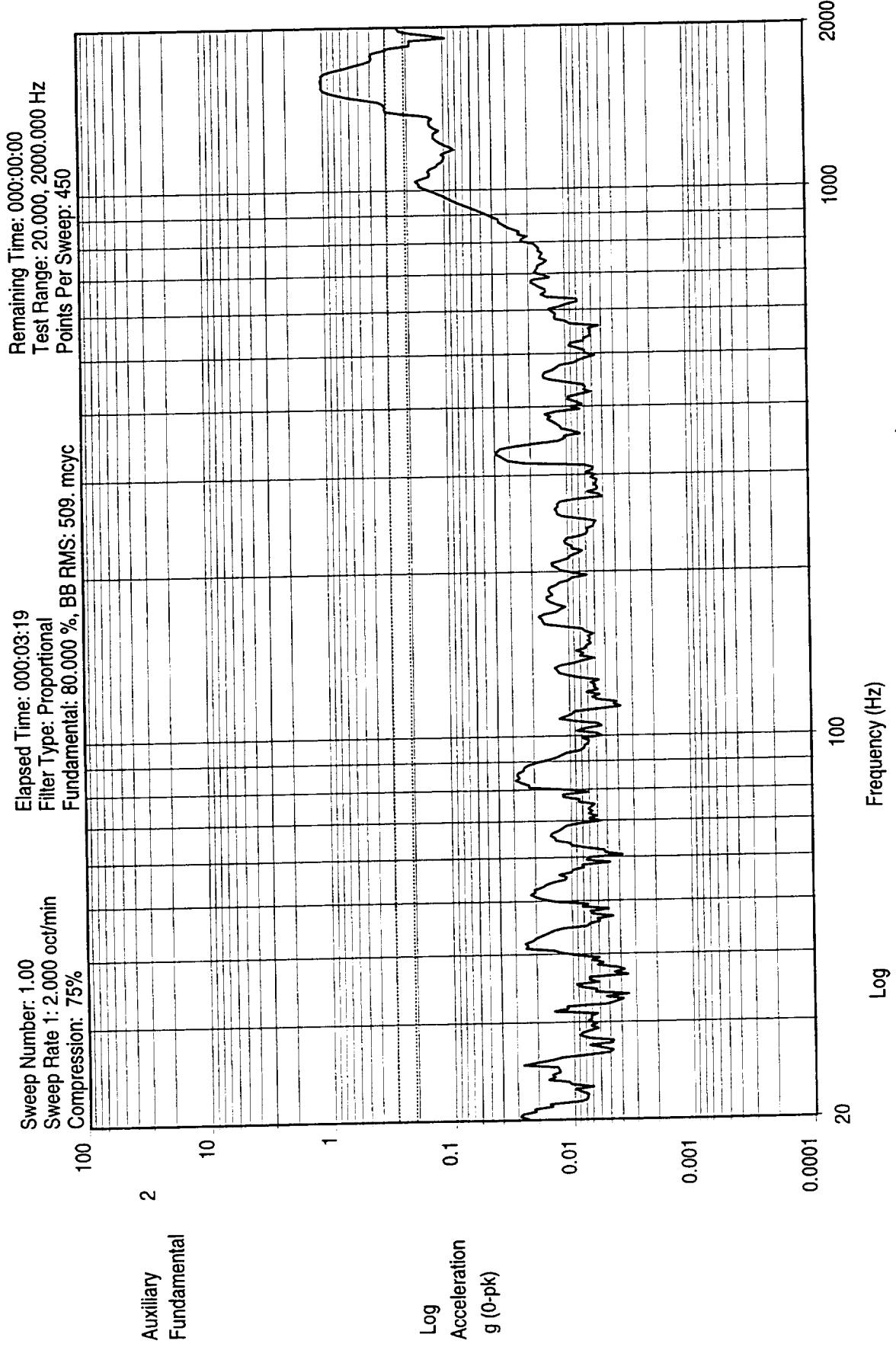


11:55:30  
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
POST Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

10/26/98  
ENCL 217  
2A  
e67



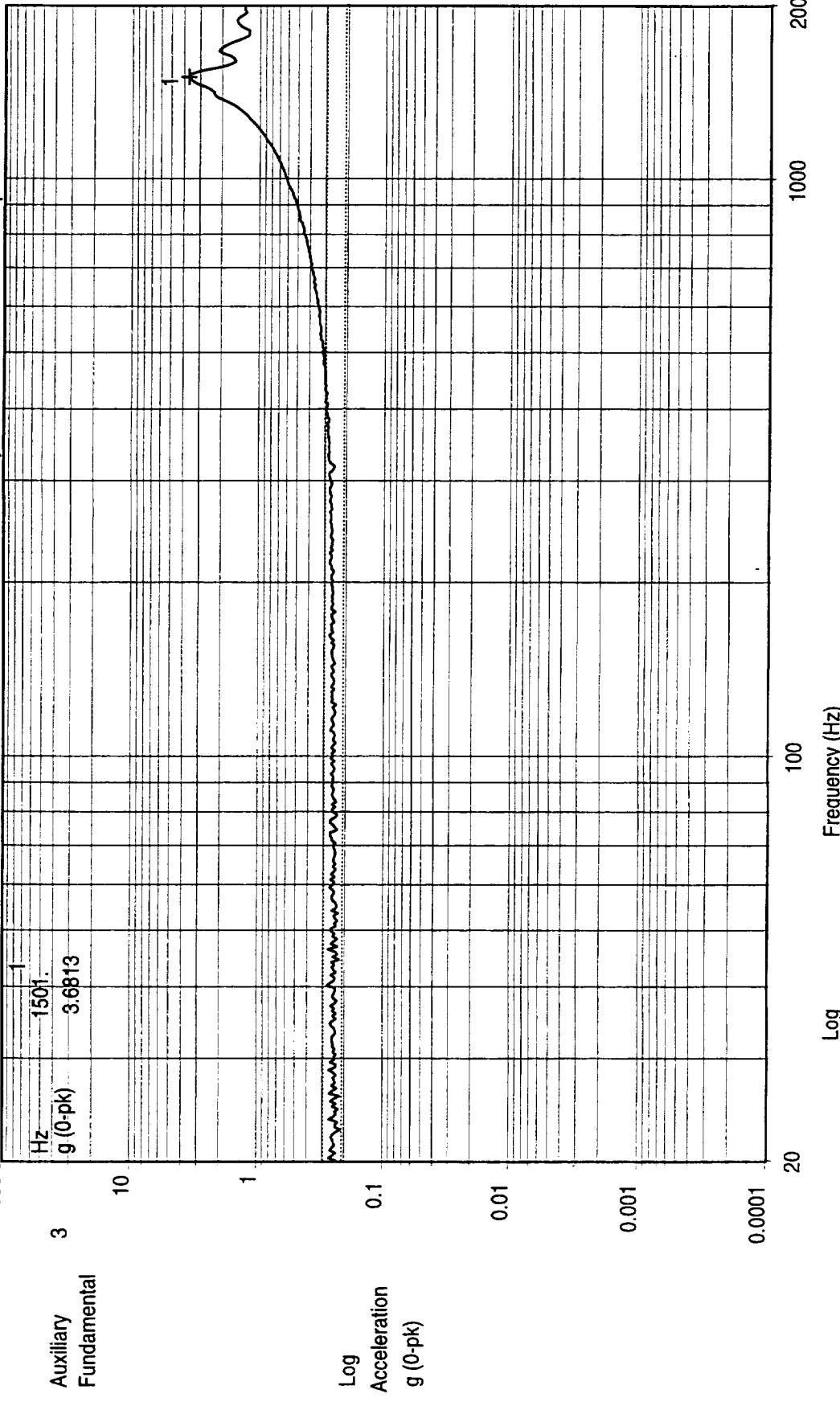
11:55:34  
26-Oct-1998

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
POST Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10  
Sine Test Name: PLO.ltmp

10/26/98 UNIT Z  
ENG EOT  
24  
267

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

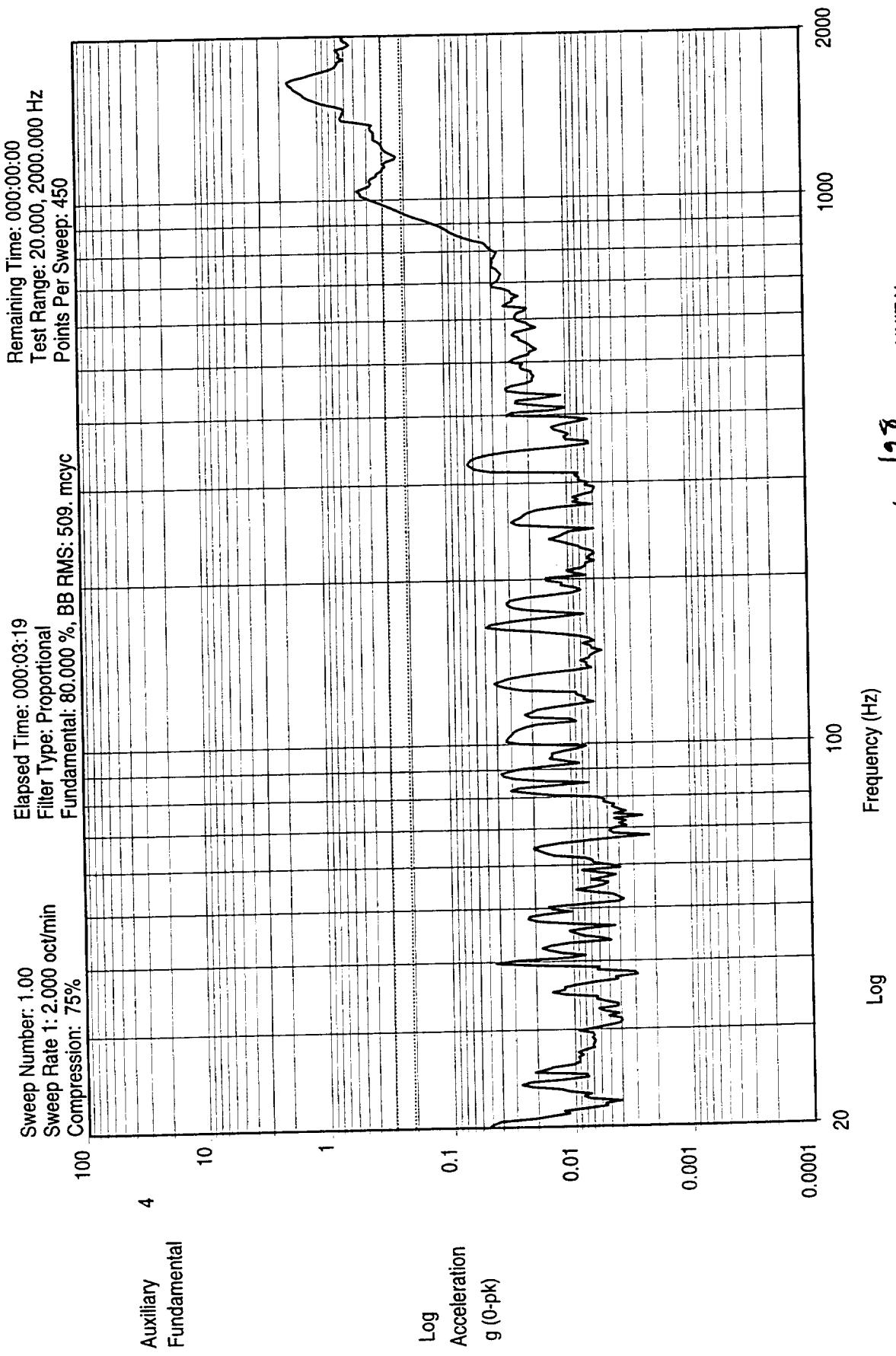
Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. m/s/c



10/26/98 UNIT Y  
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
POST Y AXIS SINE SWEEP TEST P/N 1343360-1 S/N F10  
Sine Test Name: PLO.tmp

11:57:50  
26-Oct-1998

ENG 217 267



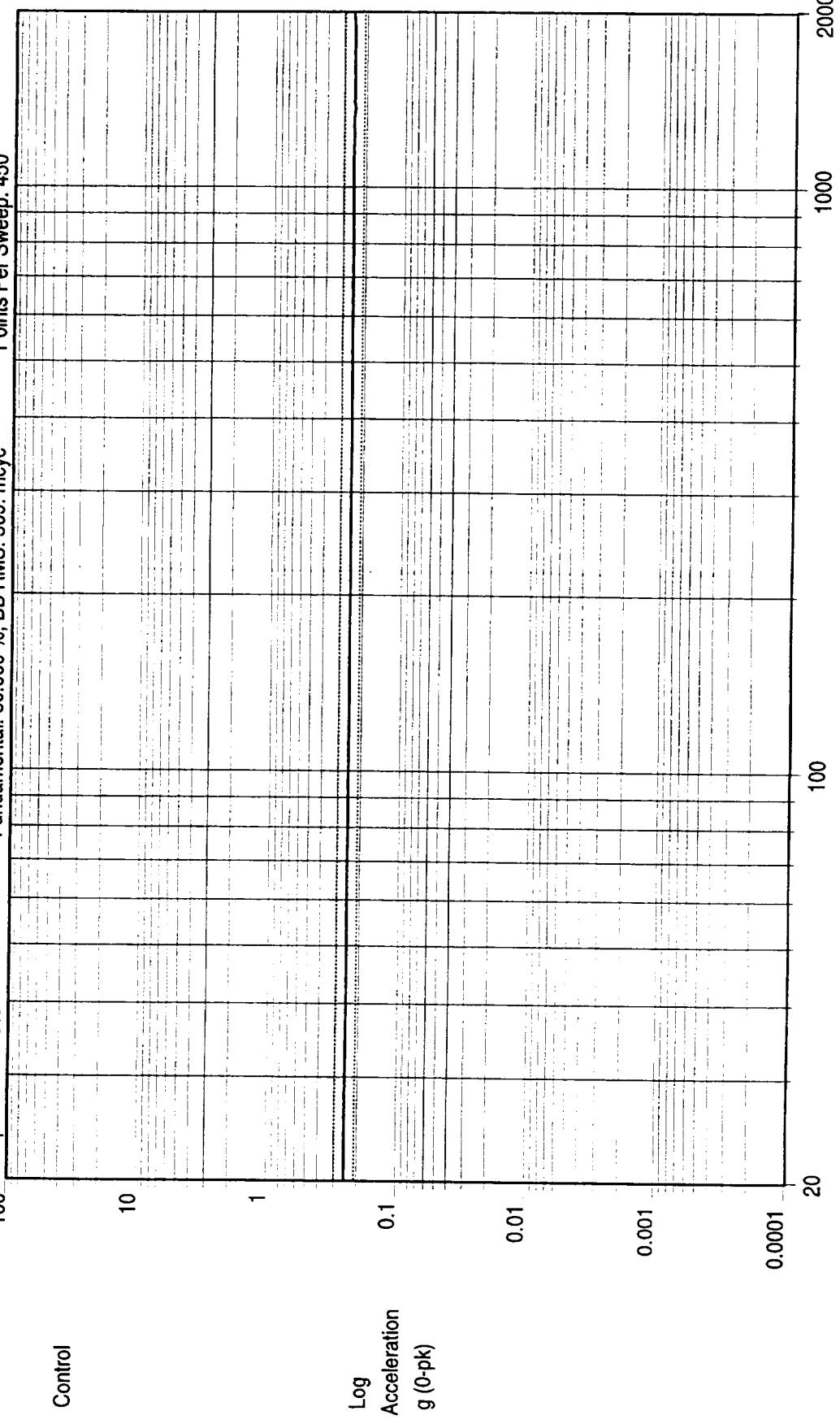
10/26/98 UNIT X  
 AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
 POST Y AXIS SINE SWEEP TEST P/N 1348360-1 S/N F10  
 Sine Test Name: PLO.tmp

11:55:42  
 26-Oct-1998

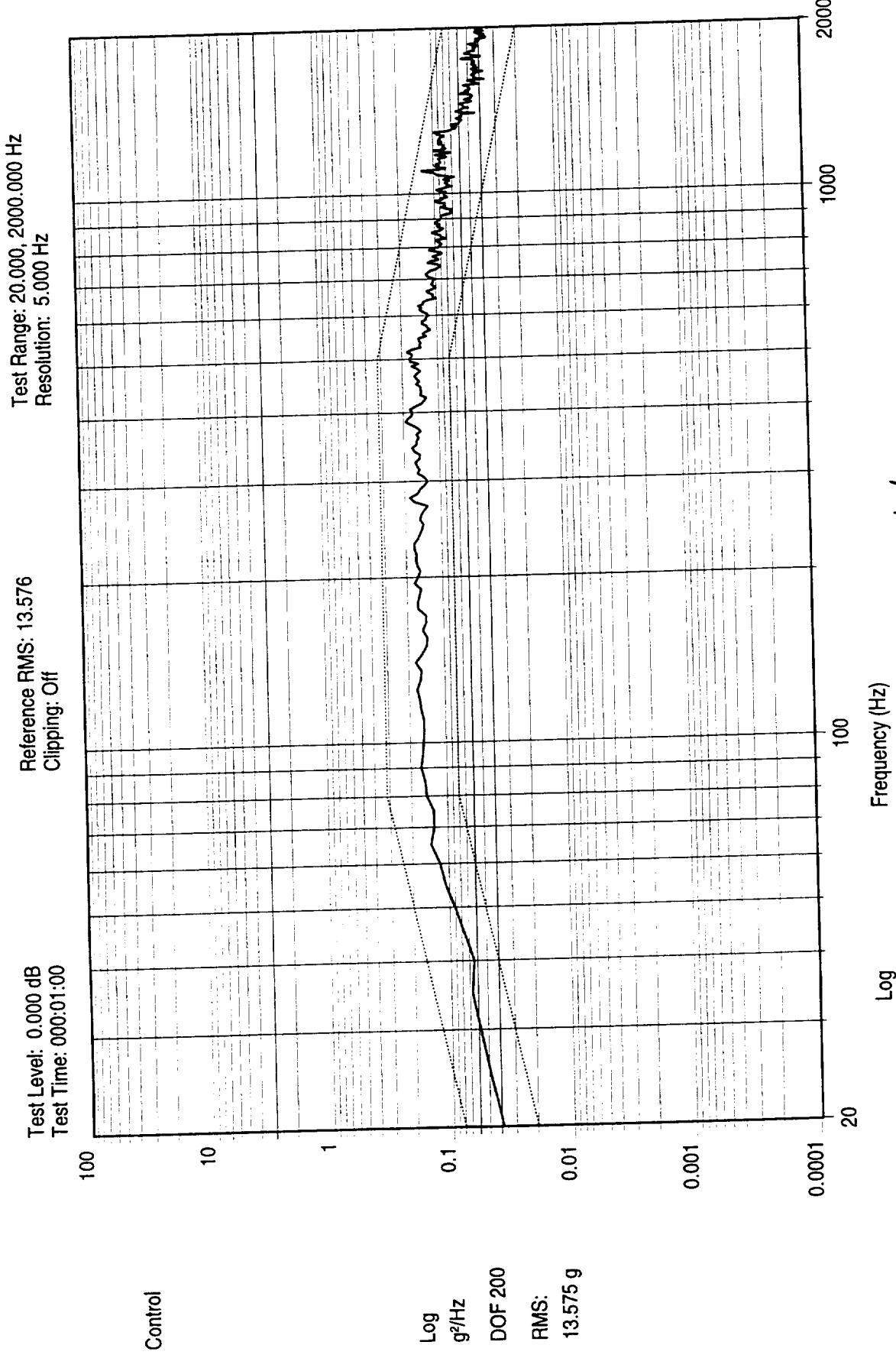
ENIG  
 261  
 27

Remaining Time: 000:00:00  
Elapsed Time: 000:03:19  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%  
Control



11(4)(98)  
10:47:55  
04-Nov-1998  
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
Y AXIS SYSTEM CHECKOUT P/N 1348360-1 S/N F10  
Sine Test Name: PLO.tmp  
ENG 7A  
217 267



10:56:02  
 04-Nov-1998

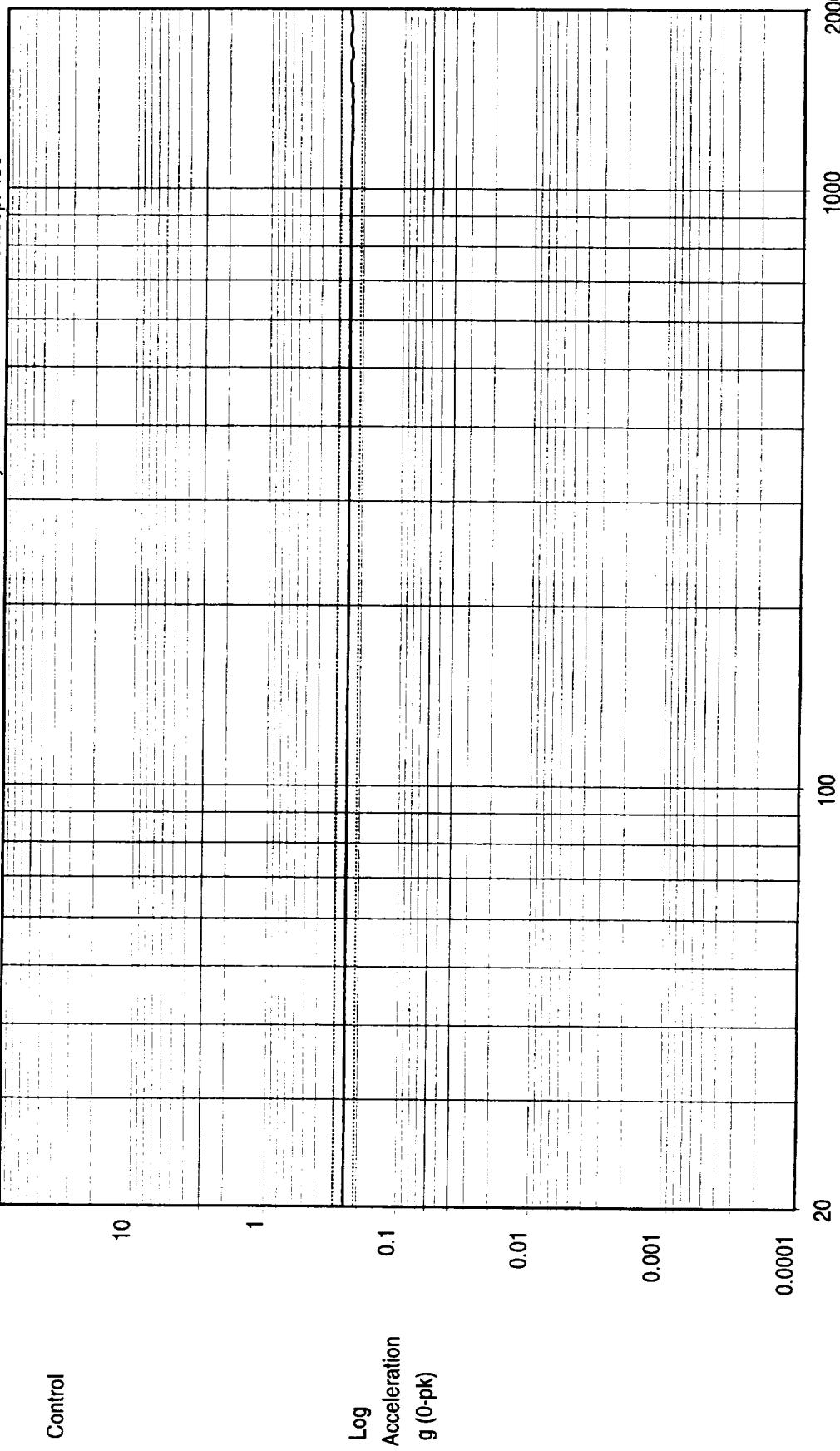
AMSU PHASE LOCK OSCILLATOR S/O538595  
 Y AXIS SYSTEM CHECKOUT P/N 1348360-1 S/N F10

Test Name: PLO.tmp

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mvc

Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450



11/4/98

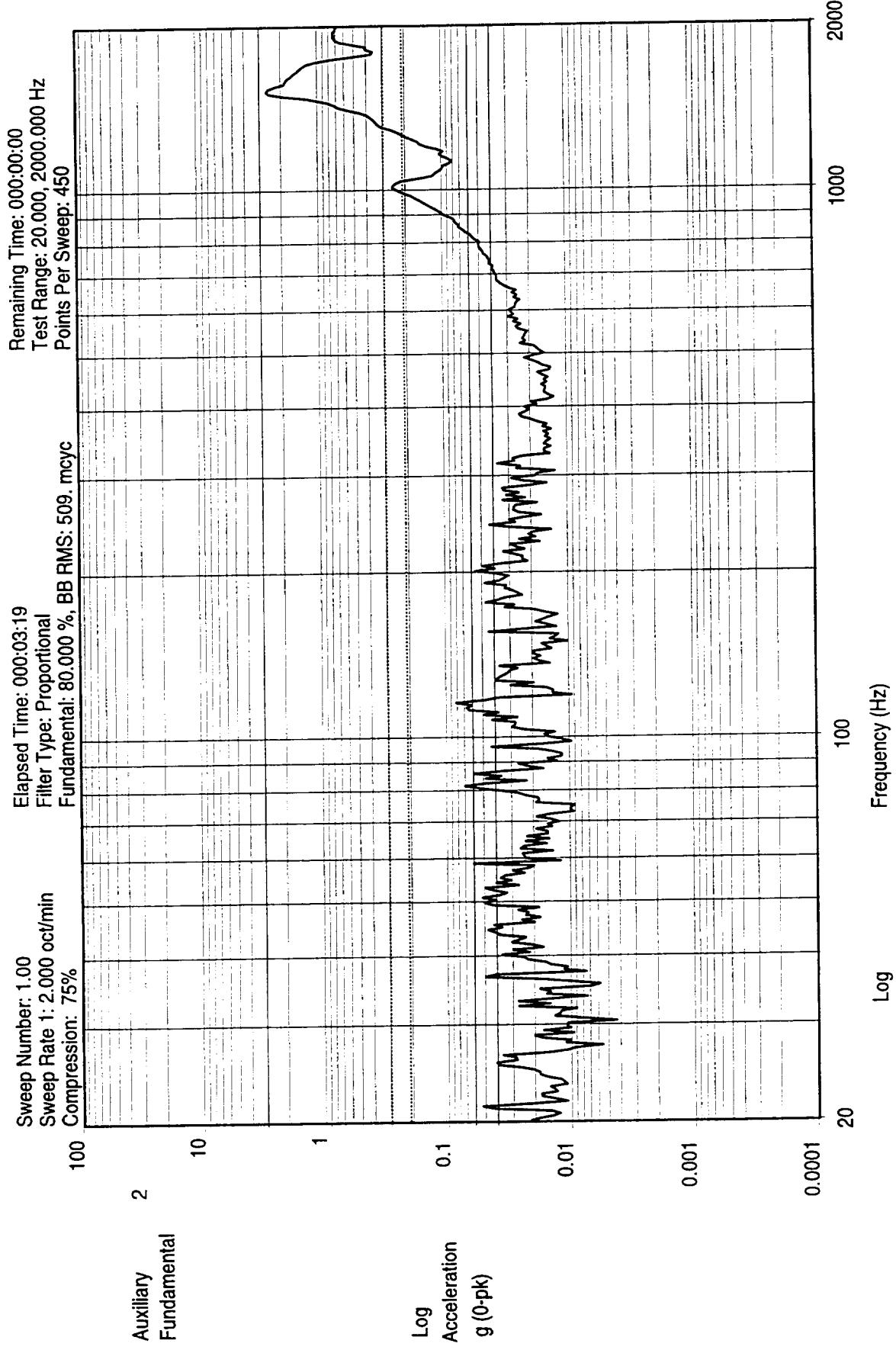
1A  
267

ENG  
217

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
Y AXIS TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

14:22:27  
04-Nov-1998



UNIT Z

11-4-98  
 1A  
 ENG  
 217  
 261

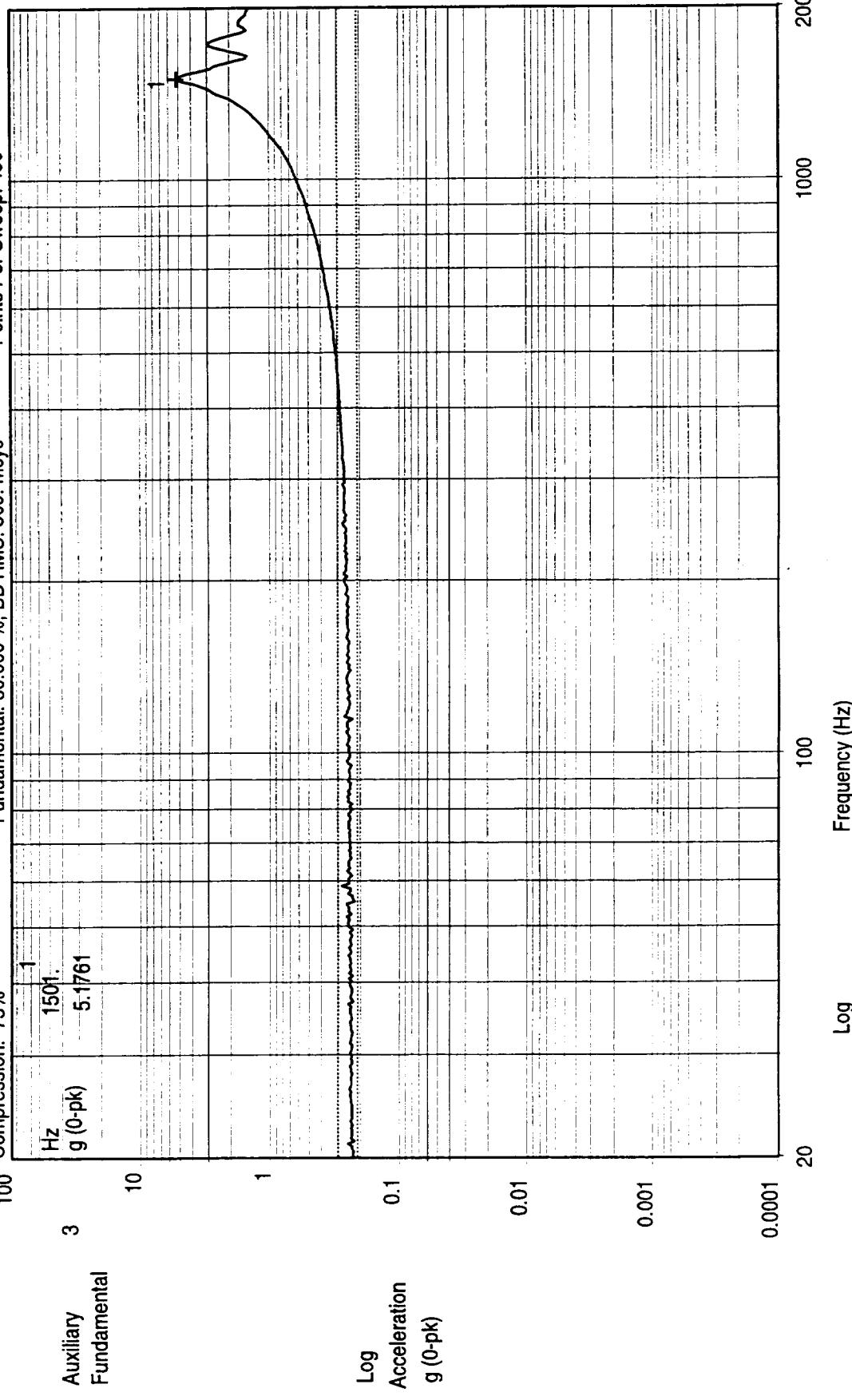
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
 Y AXIS TEST P/N 1348360-1 SIN F10

Sine Test Name: PLO.tmp

14:22:32  
 04-Nov-1998

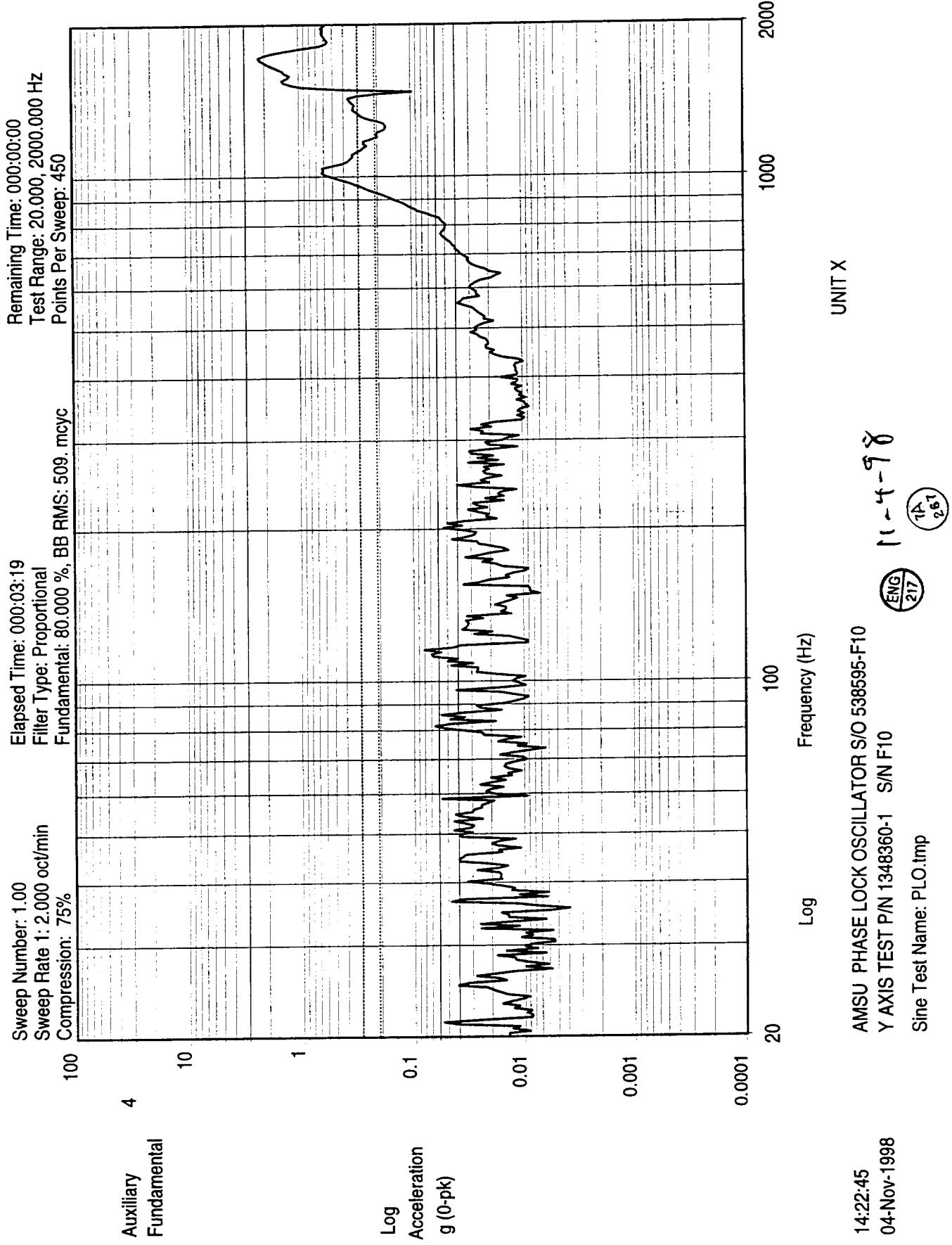
Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Remaining Time: 000:00:00  
Test Range: 20,000, 2000.000 Hz  
Points Per Sweep: 450



14:22:41  
04-Nov-1998

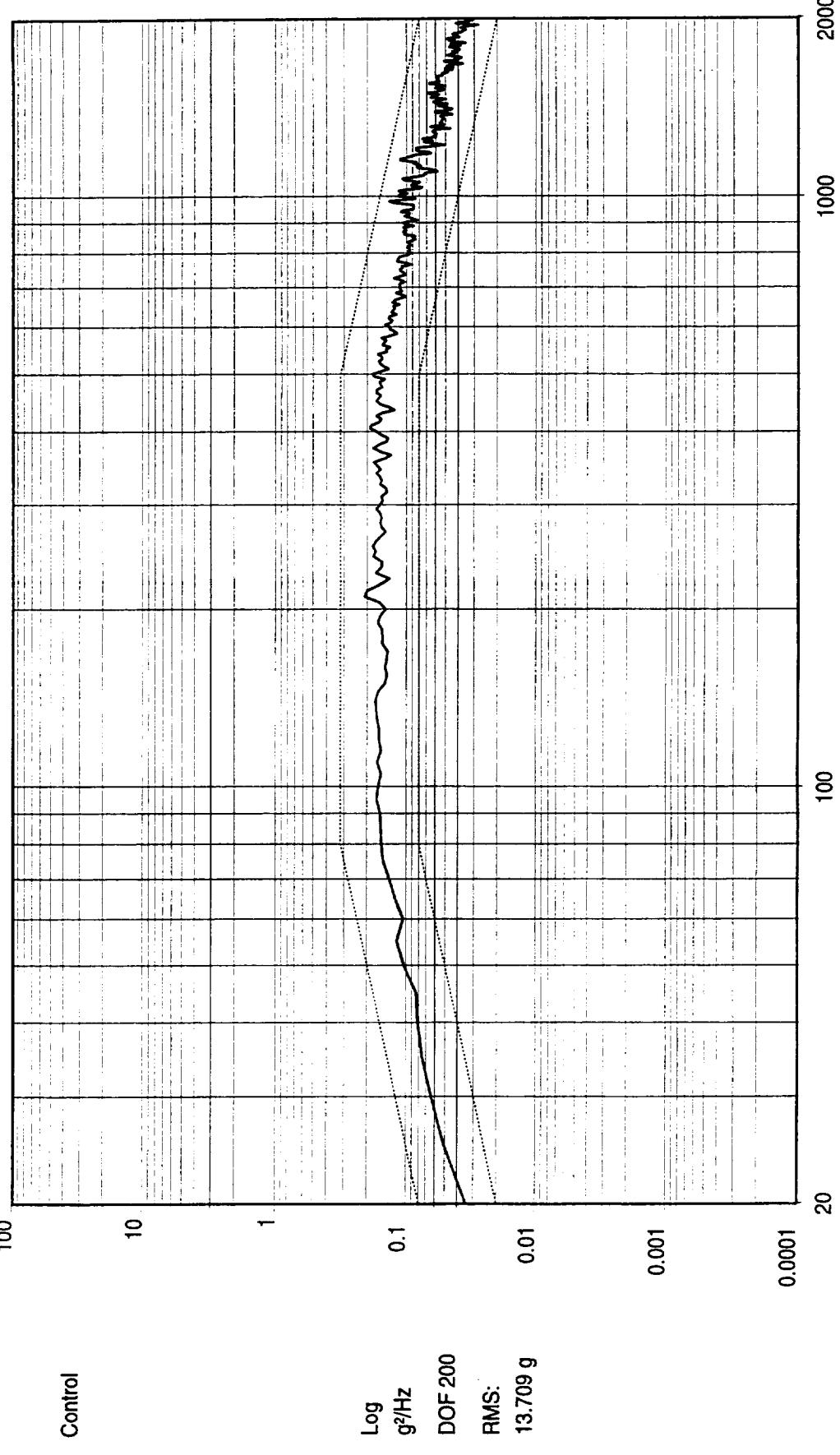
AMSU PHASE LOCK OSCILLATOR S10 538595-F10  
Y AXIS TEST P/N 1348360-1 S/N F10  
Sine Test Name: PLO.tmp  
11-4-98  
WESI



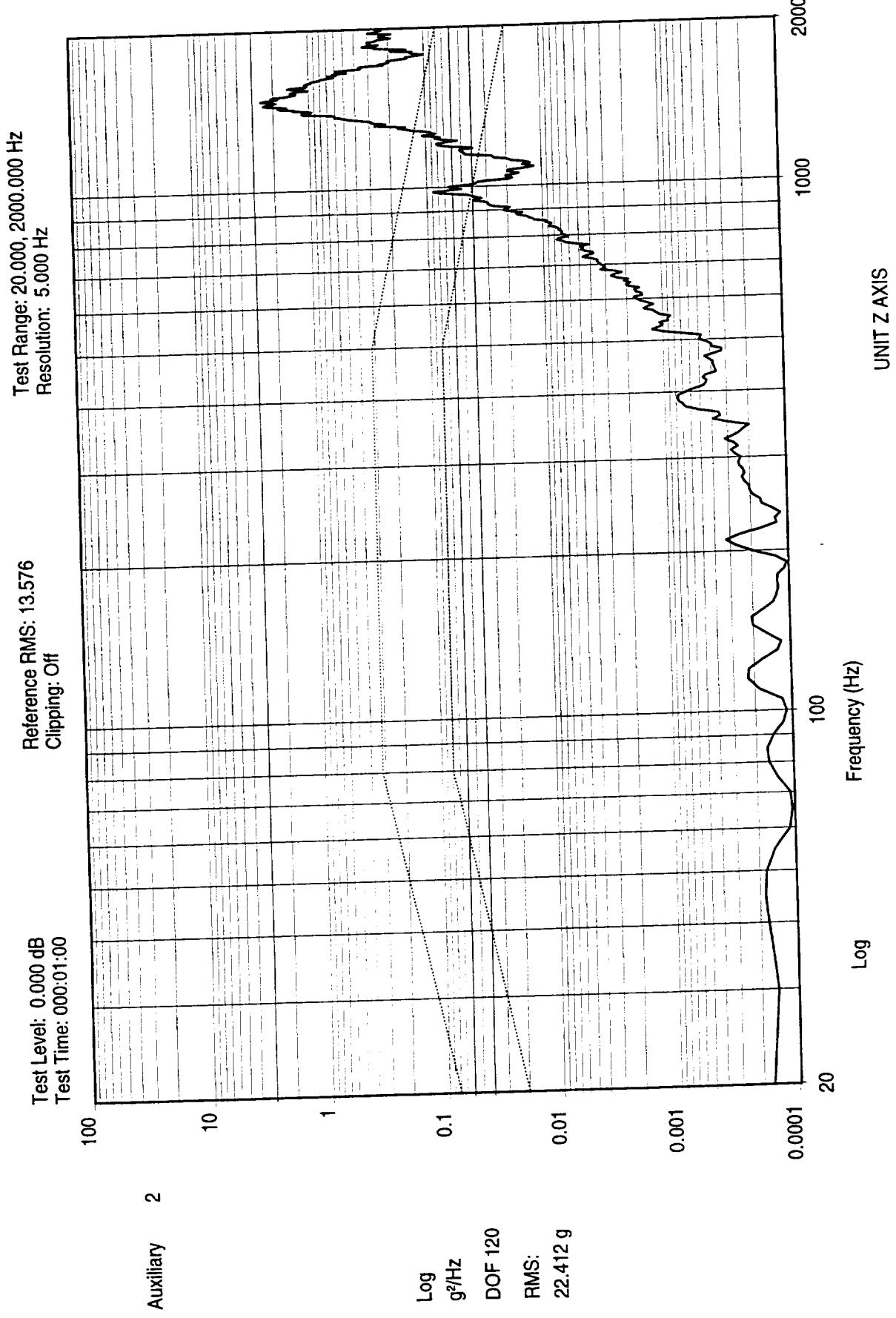
Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz

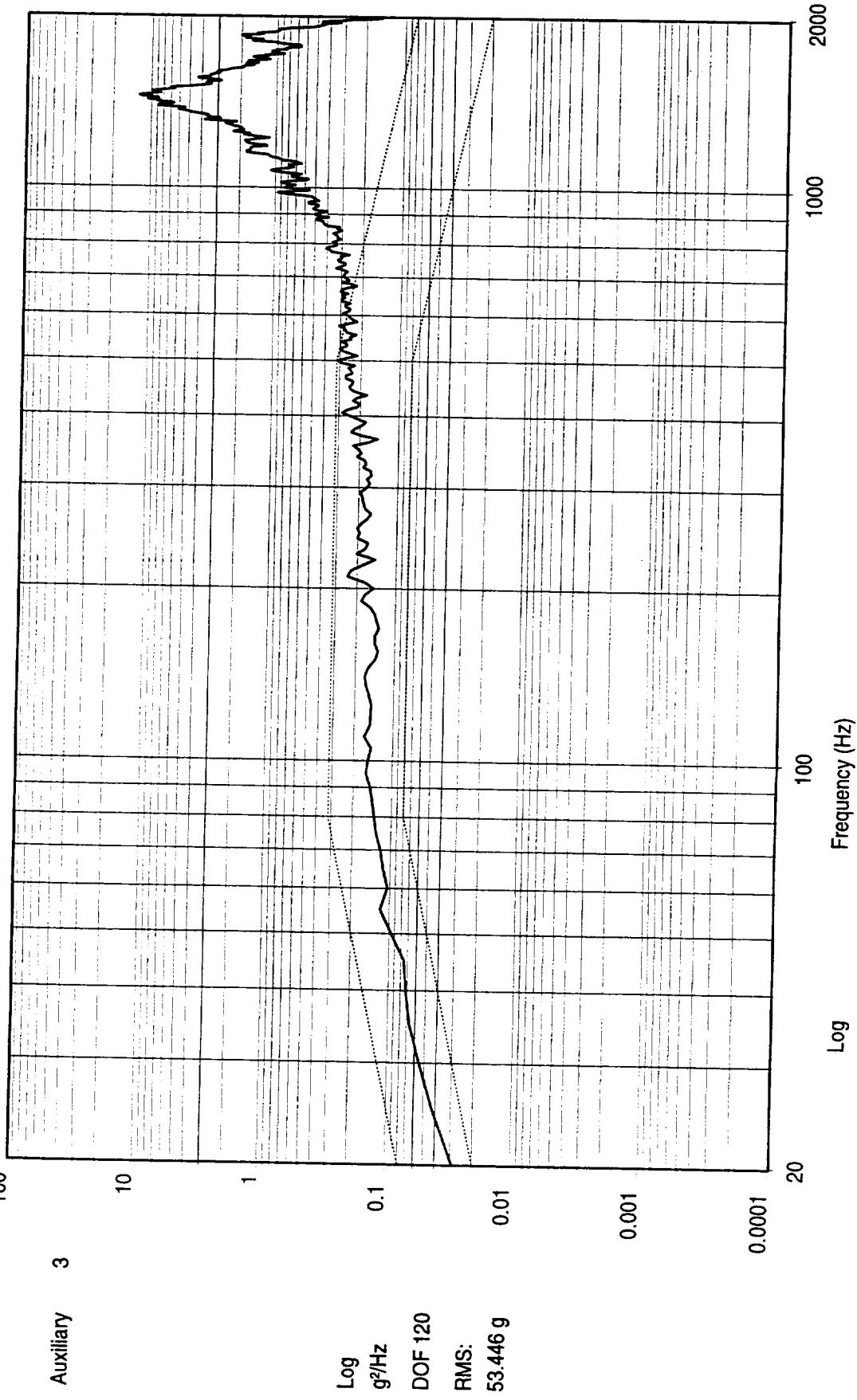


14:41:59  
04-Nov-1998  
AMSU PHASE LOCK OSCILLATOR S/0538595  
Y AXIS TEST P/N 1348360-1 S/N ,F10  
Test Name: PL0.Imp  
11-4-98  
ENG 217  
TA 261



Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off  
Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



14:42:08  
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/0538595  
Y AXIS TEST P/N 1348360-1 S/N ,F10  
Test Name: PL0.tmp

UNIT Y AXIS

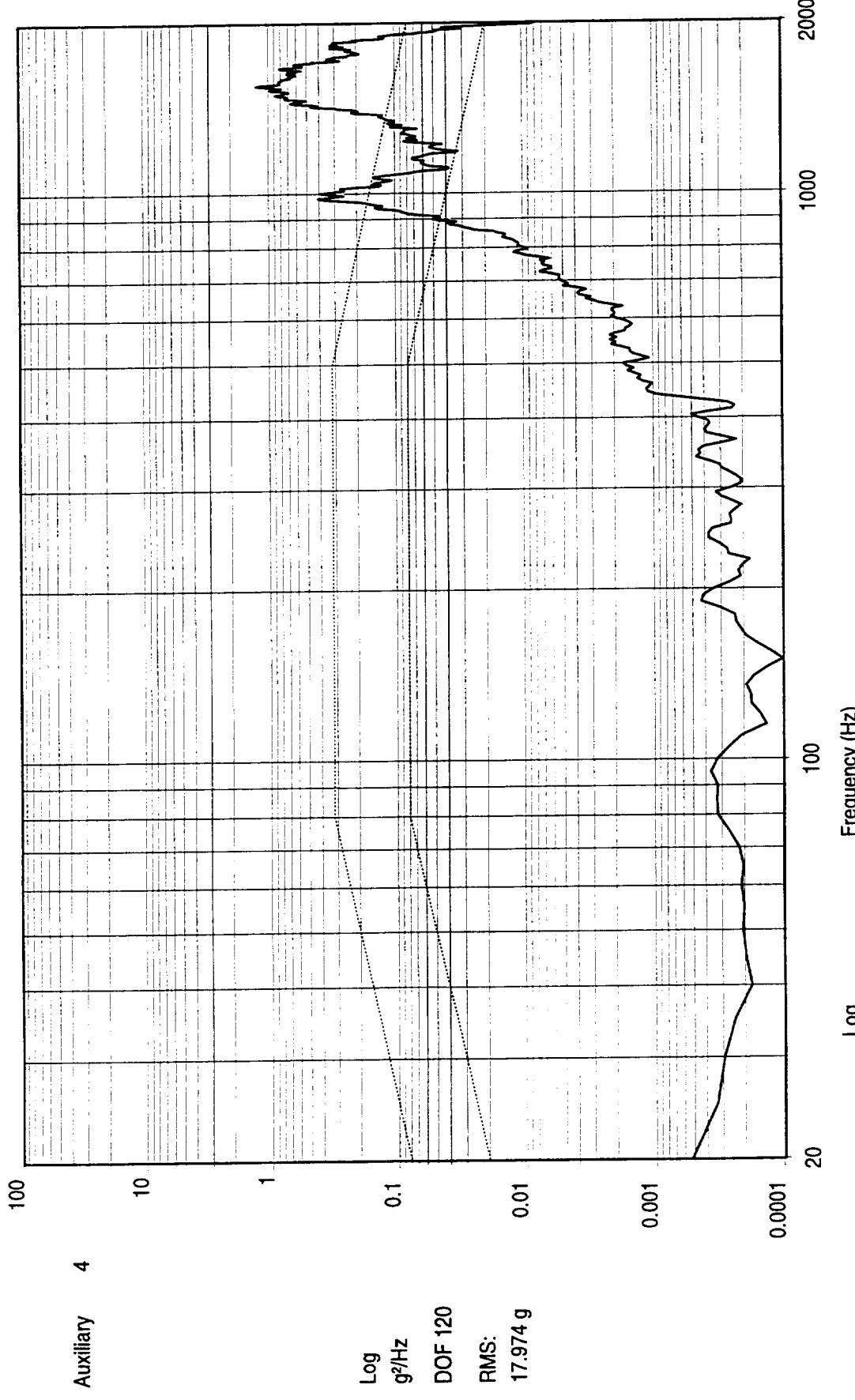
11-4-98

ENG  
217  
263

Test Level: 0.000 dB  
Test Time: 000:01:00

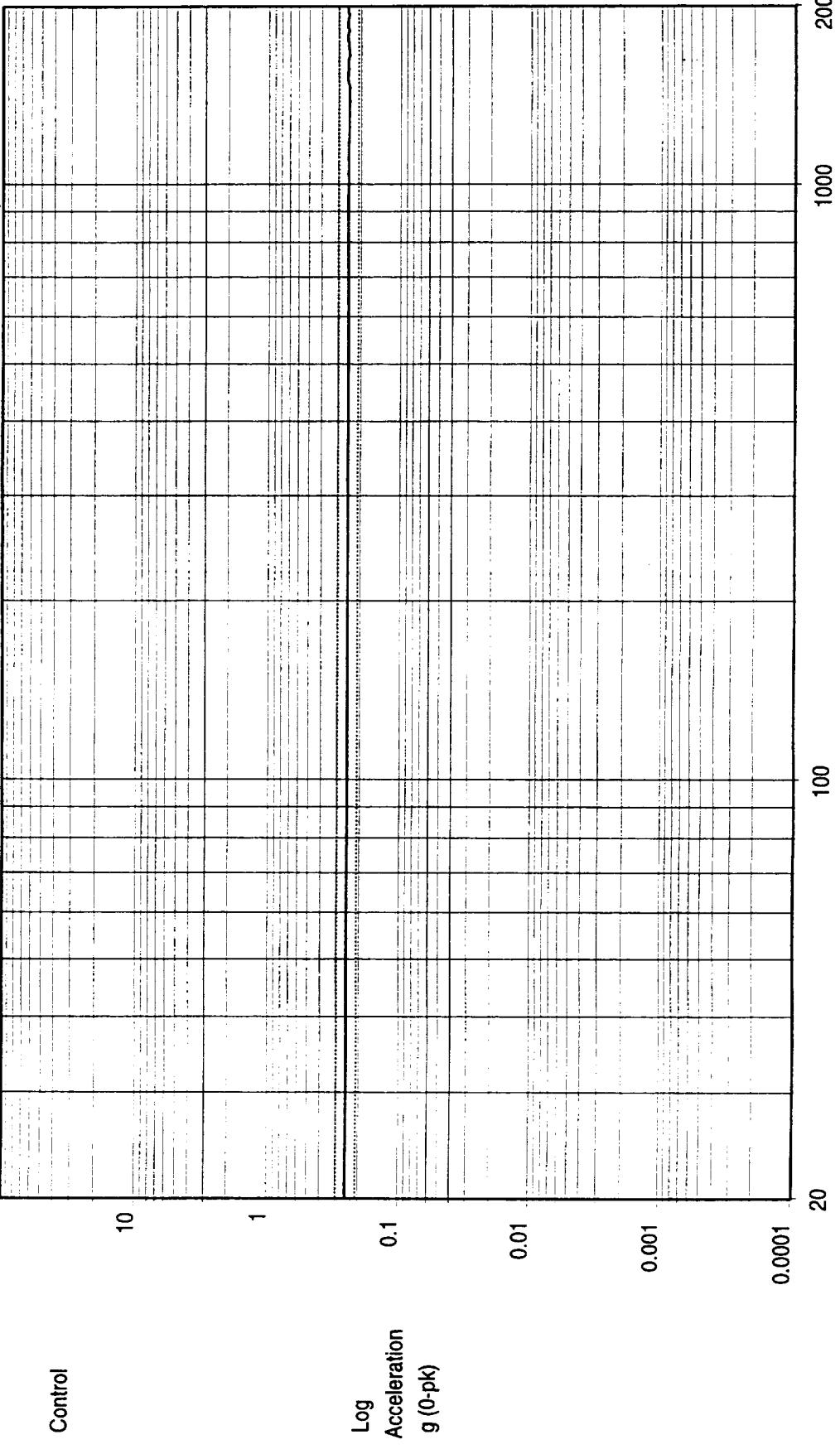
Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz

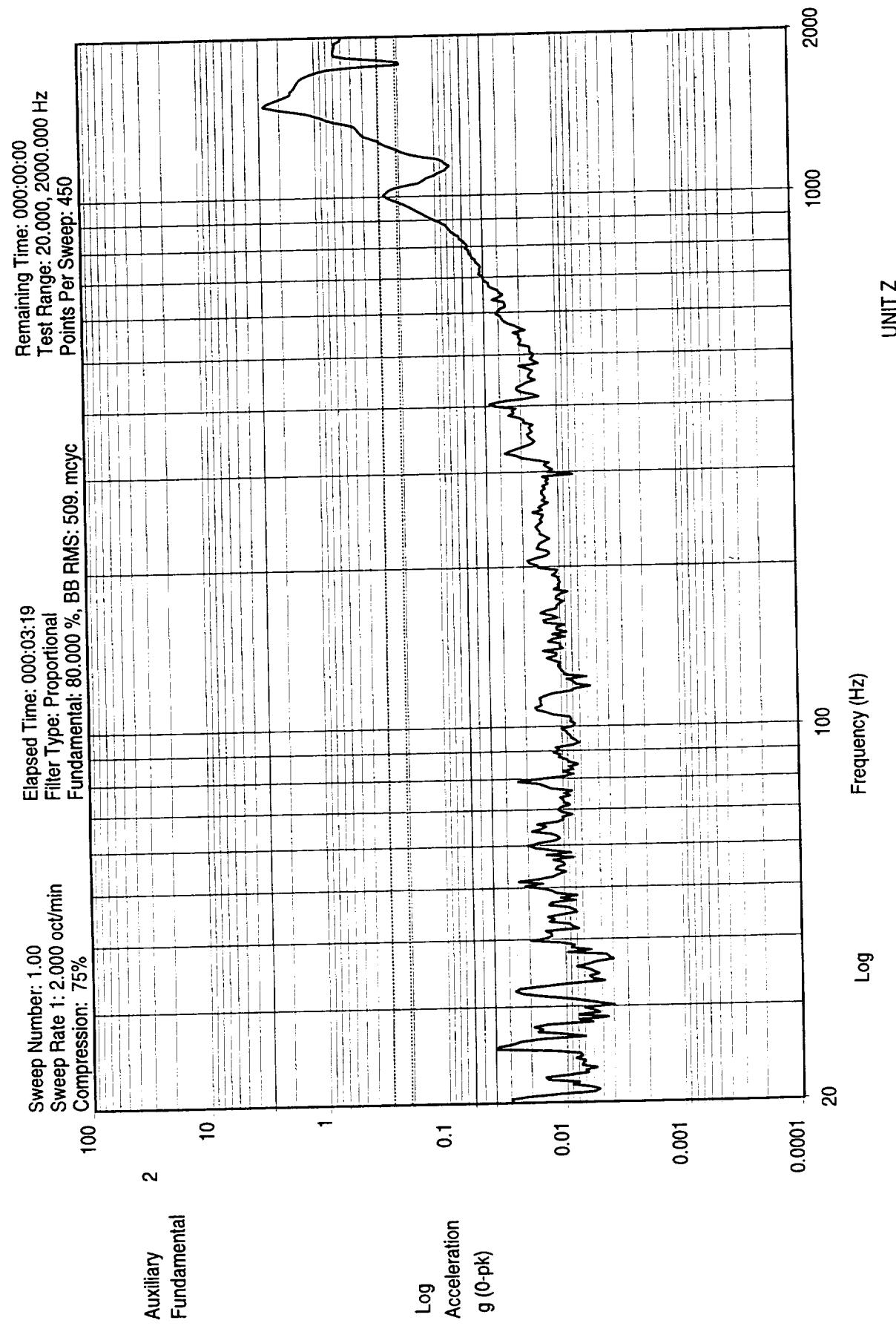


Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcyc  
Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450



14:55:56  
04-Nov-1998  
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
Y AXIS POST SINE TEST P/N 1348360-1 S/N F10  
Sine Test Name: PLO.tmp  
11-4-98  
ENG 217 261

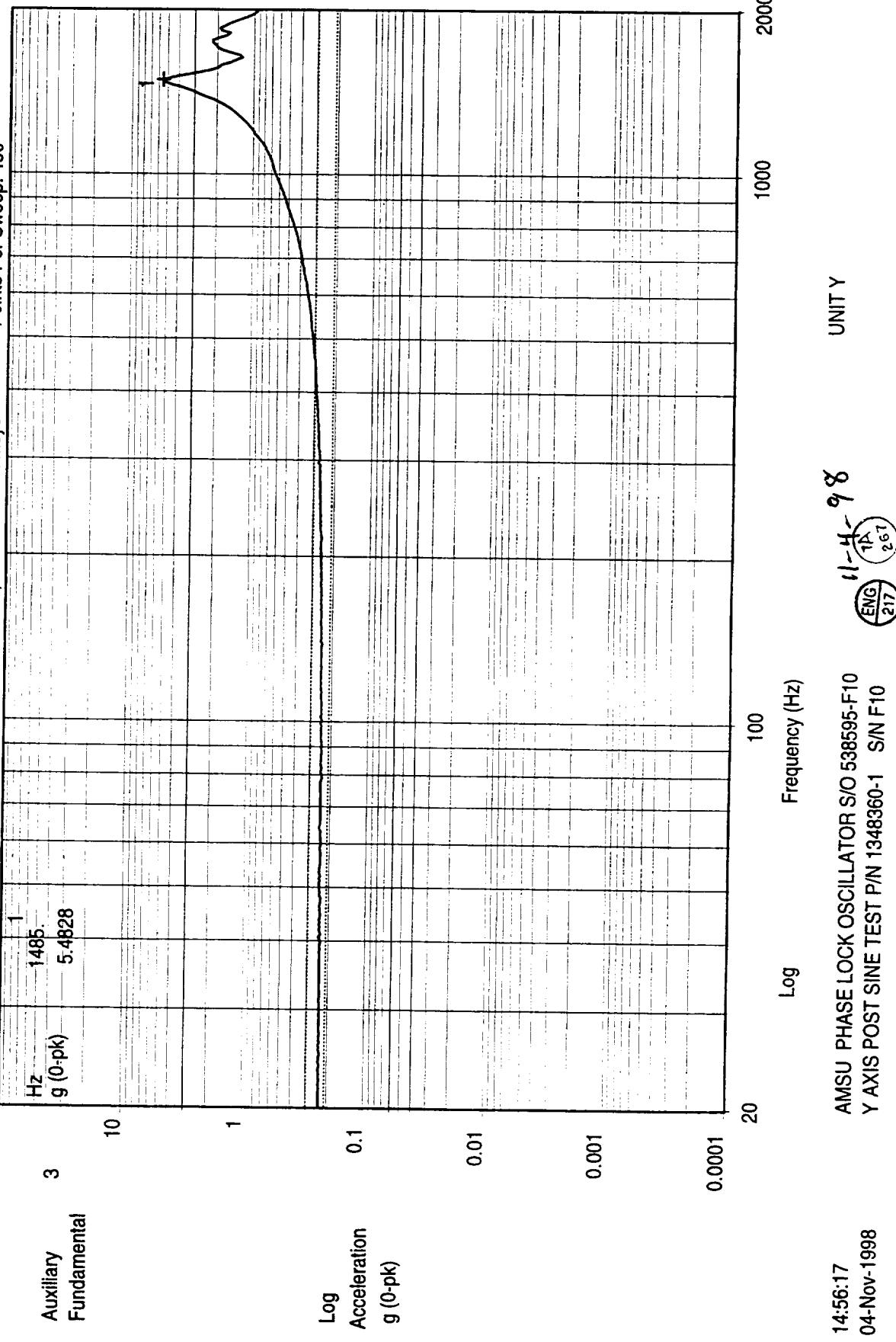


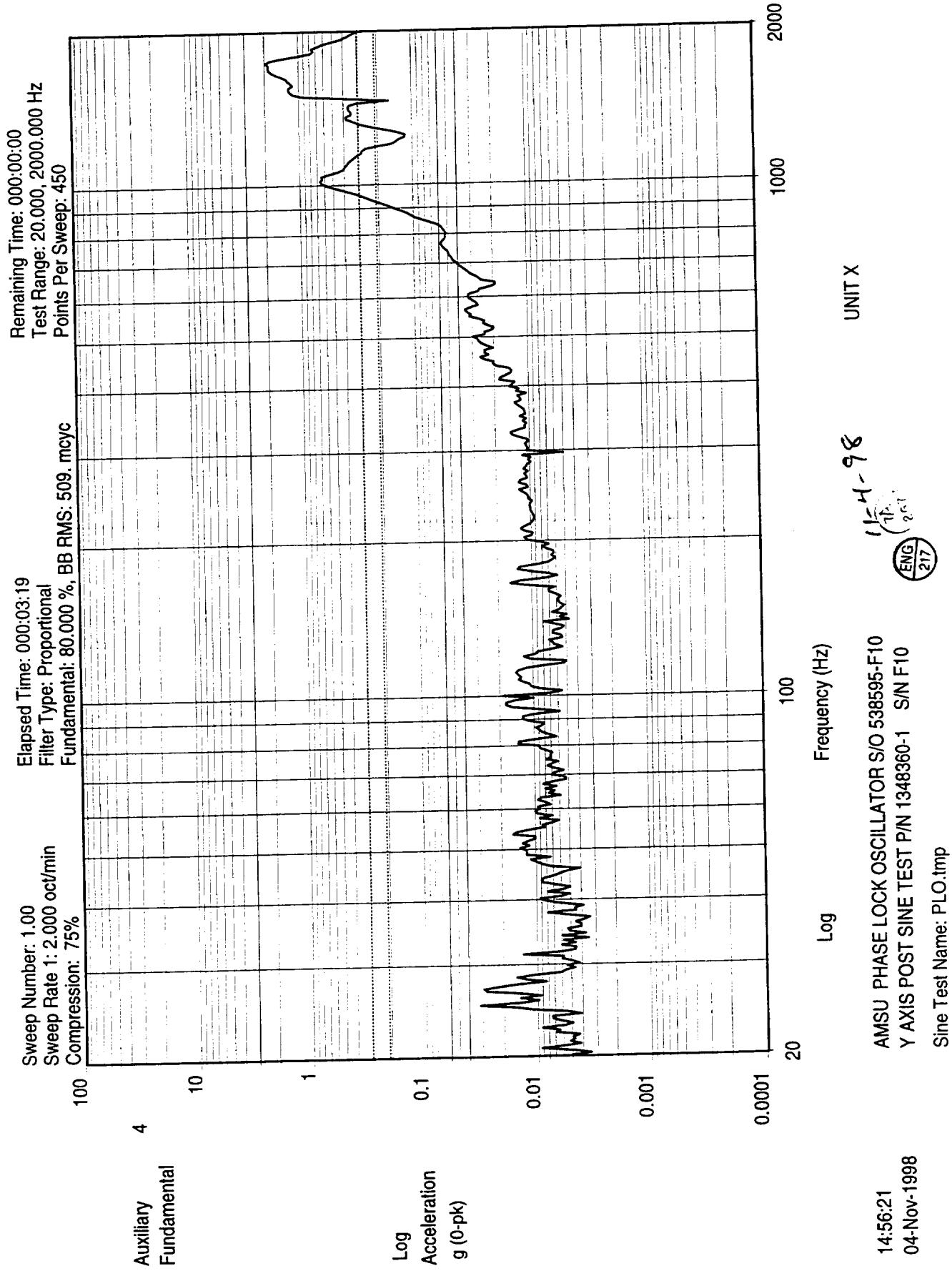
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
 Y AXIS POST SINE TEST P/N 1348360-1 SIN F10  
 11-4-98  
 Sine Test Name: PLO:tmp  
 04-Nov-1998  
 14:56:02  
 ENG 1A  
 217 267

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcy

Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450

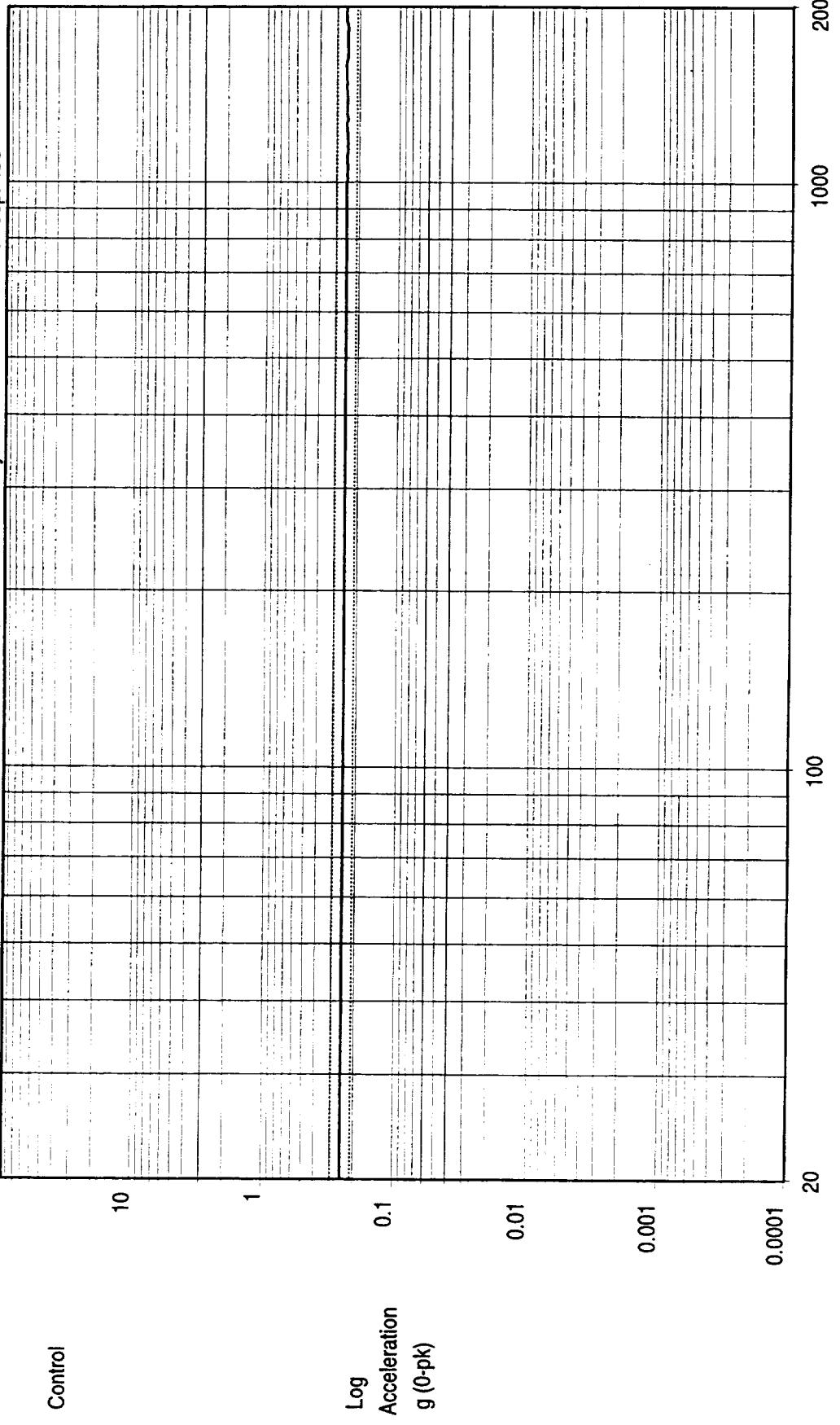




Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcyc

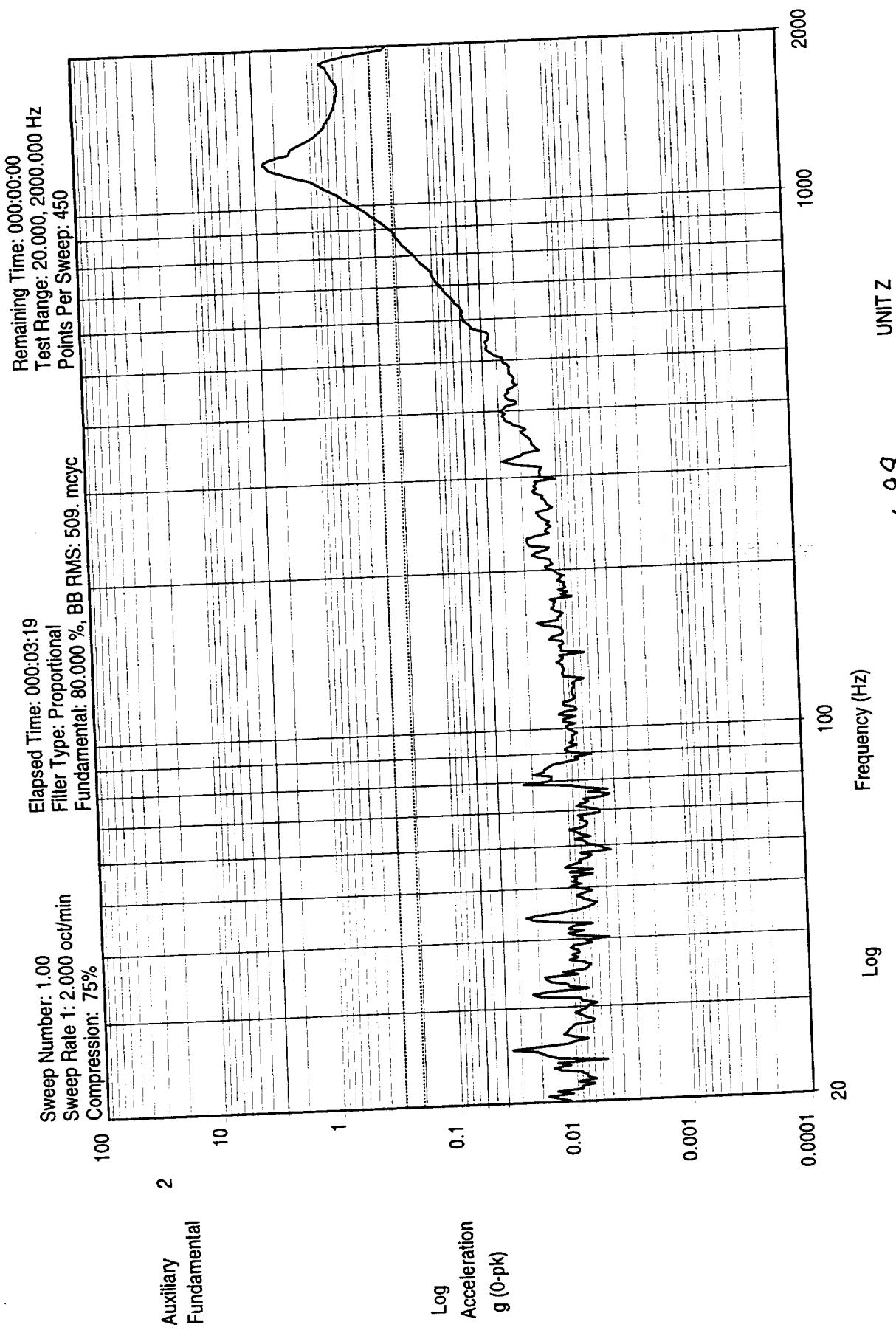
Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450



15:37:11  
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S10 538595-F10  
X AXIS SINE TEST P/N 1348360-1 S/N F10  
Sine Test Name: PL0.tmp

11-4-98  
11 261  
ENG 217

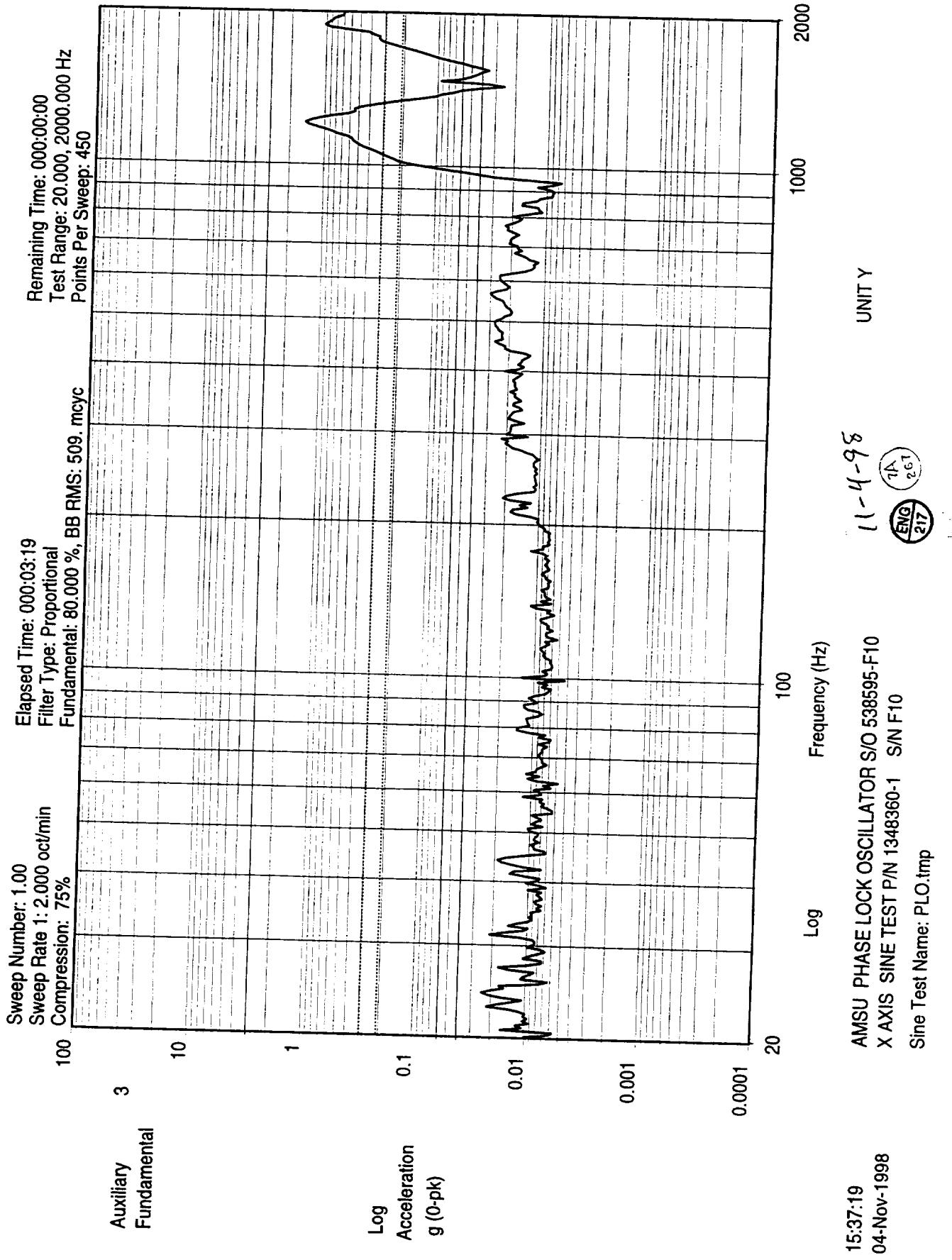


1A  
261  
217

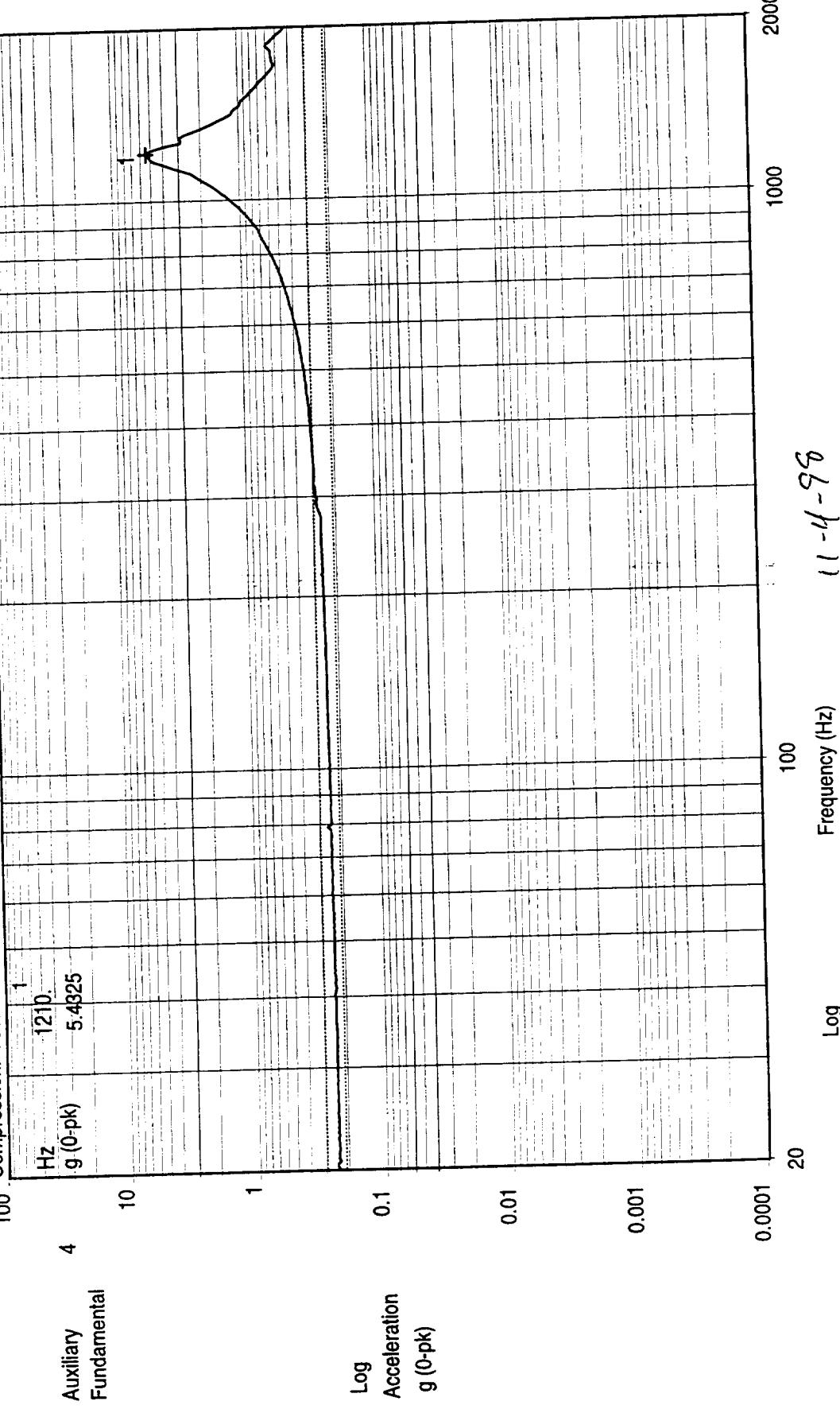
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
X AXIS SINE TEST P/N 1348360-1 S/N F10

Sine Test Name: PLO.tmp

15:37:15  
04-Nov-1998



Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%  
Elapsed Time: 00:03:19  
Test Range: 20.000, 2000.000 Hz  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcy



UNIT X



11-11-98

AMSU PHASE LOCK OSCILLATOR S10 538595-F10  
X AXIS SINE TEST P/N 1348360-1 S/N F10

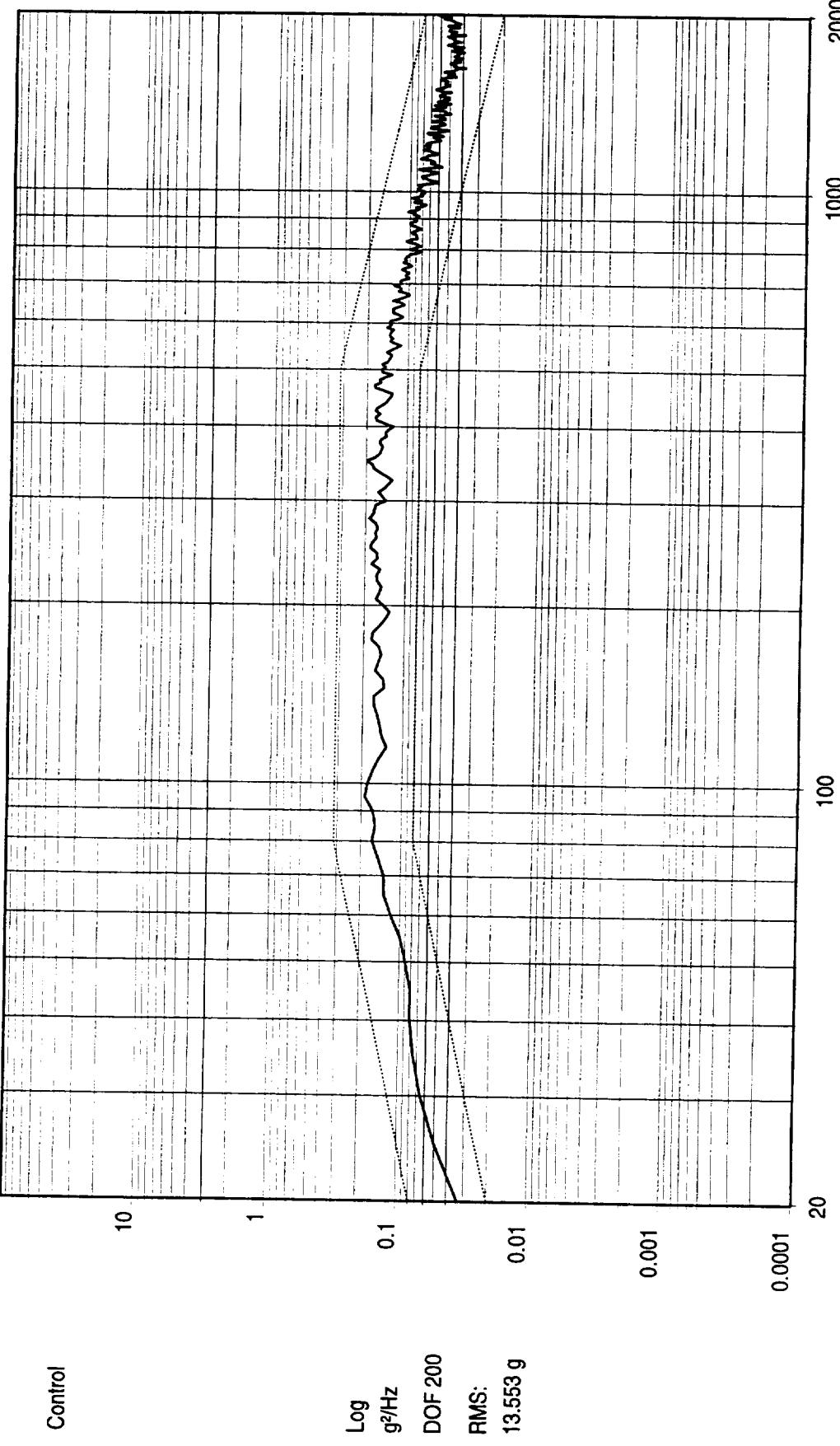
Sine Test Name: PL0.tmp

15:37:36  
04-Nov-1998

Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off

**Test Range:** 20.000, 2000.000 Hz  
**Resolution:** 5.000 Hz



15:51:48  
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/0538595  
X AXIS TEST P/N 1348360-1 S/N F10

Test Name: PLO;tmp

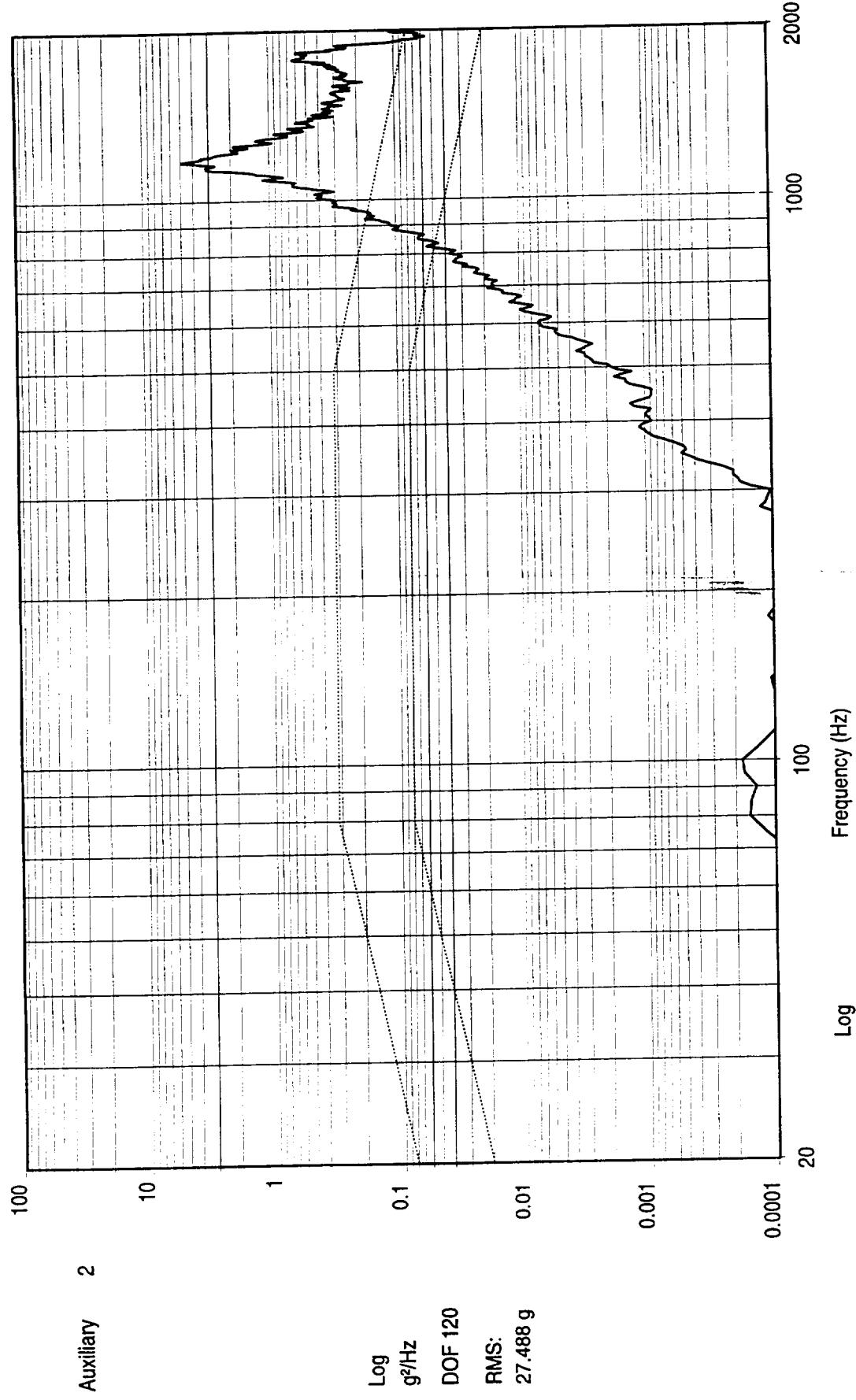
161  
217

11-4-98

Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 20000.000 Hz  
Resolution: 5.000 Hz



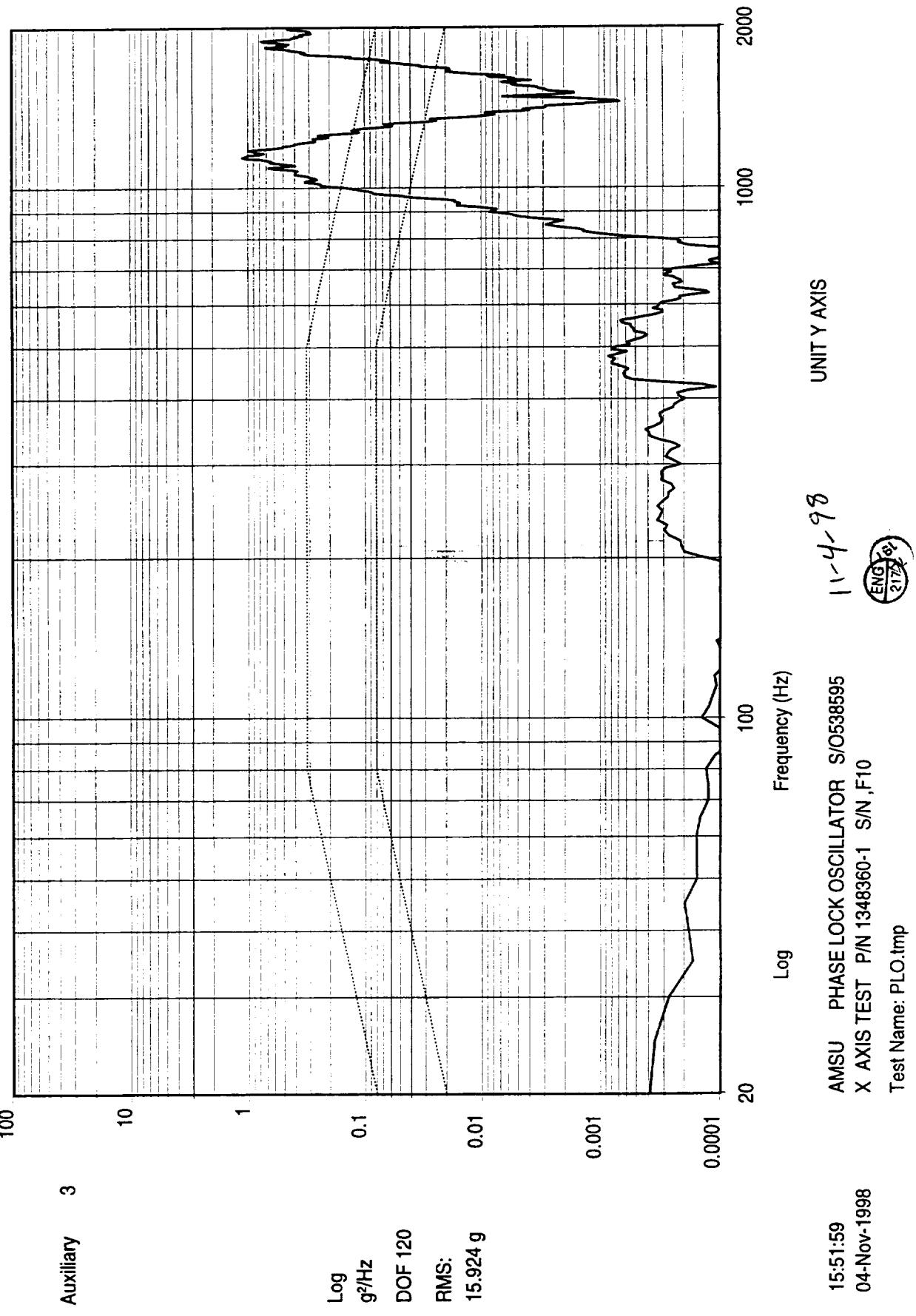
15:51:55  
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/0538595  
X AXIS TEST P/N 1348360-1 S/N ,F10  
Test Name: PLO.tmp

ENG  $\frac{<6}{217}$

Test Level: 0.000 dB  
Test Time: 00:01:00

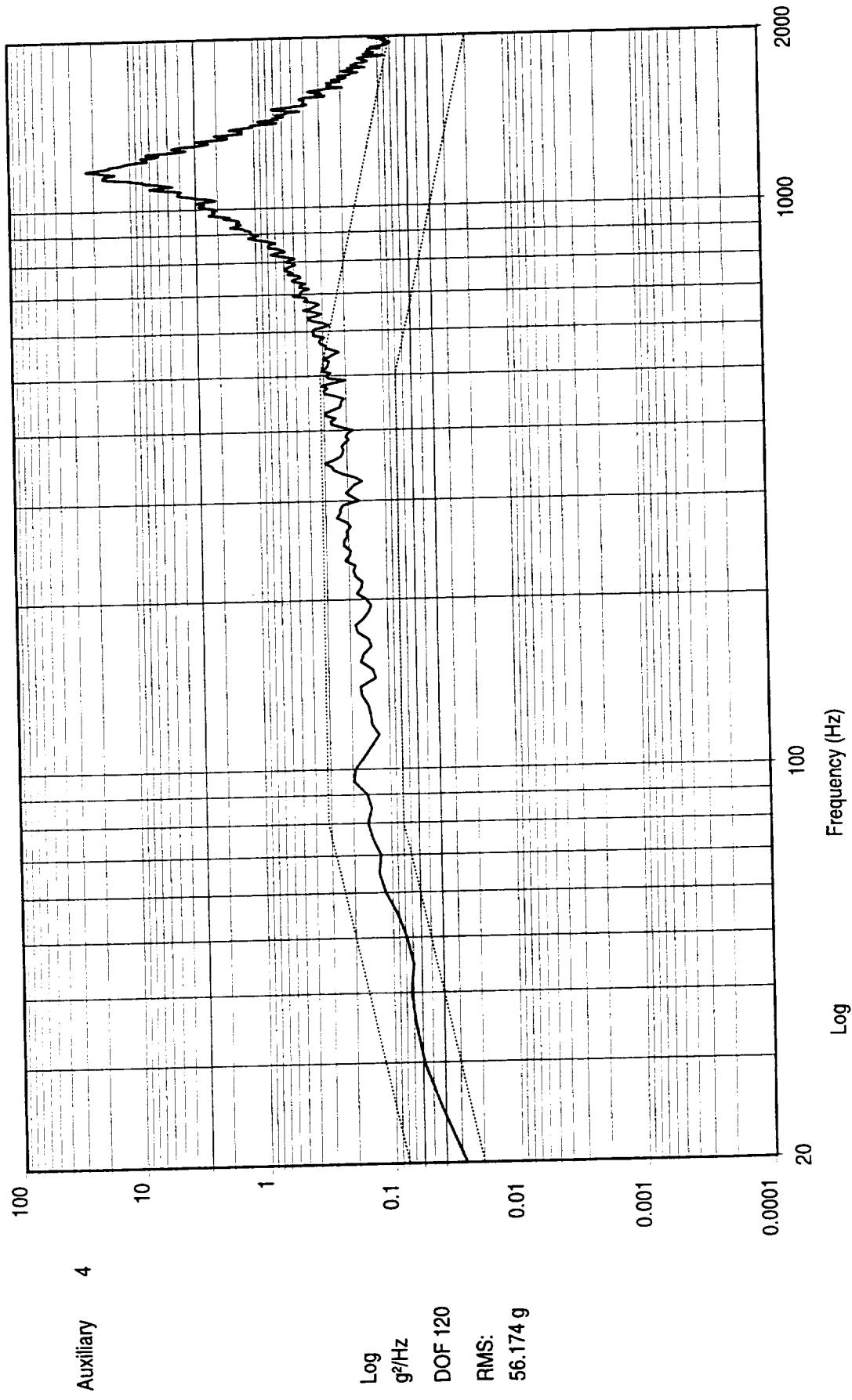
Reference RMS: 13.576  
Resolution: 5.000 Hz



Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



15:52:05  
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538595  
X AXIS TEST P/N 1348360-1 S/N F10  
Test Name: PLO.tmp

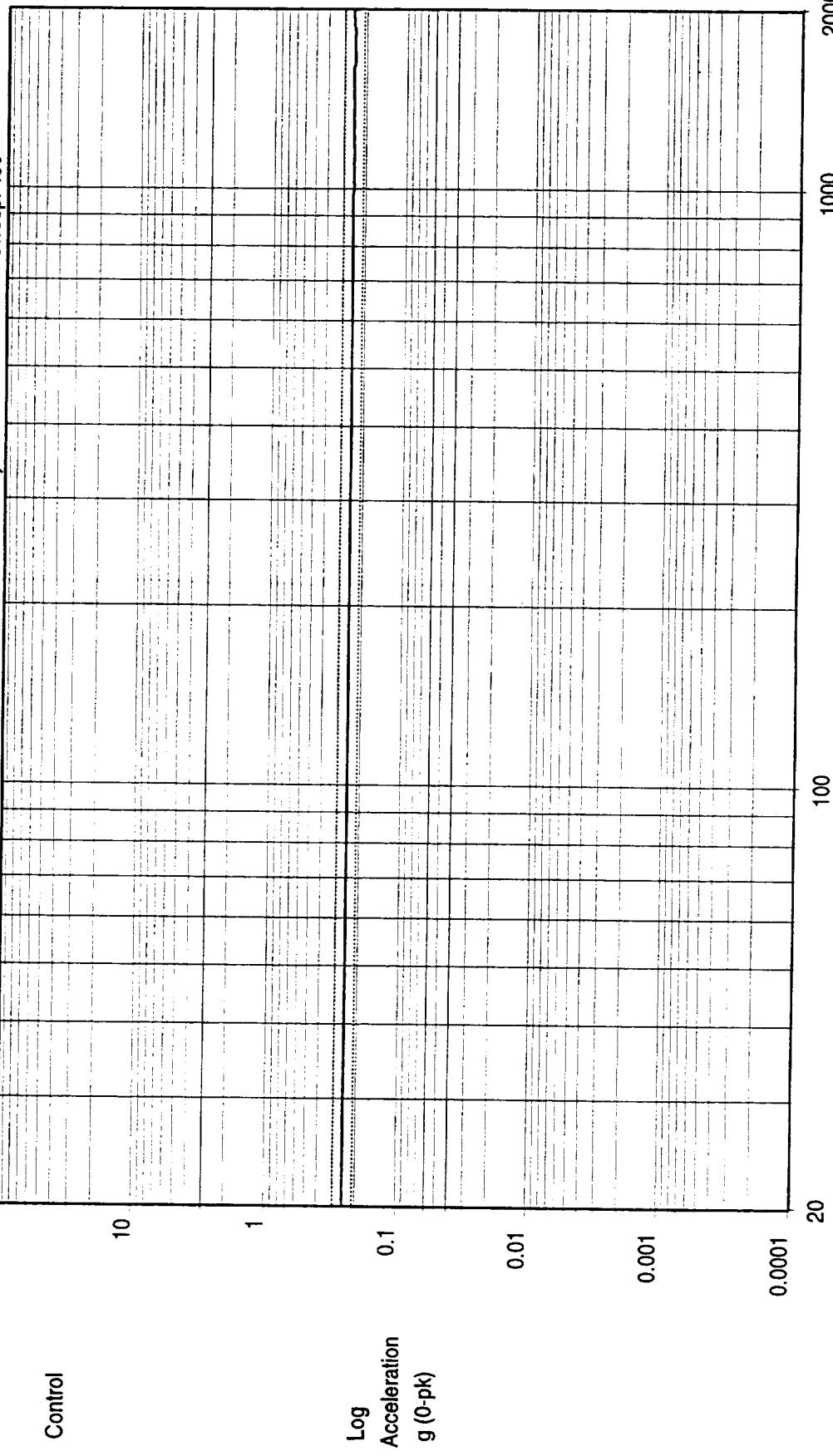
UNIT X AXIS

11-4-98

ENG 16  
217

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcyc



2000  
1000  
100  
20

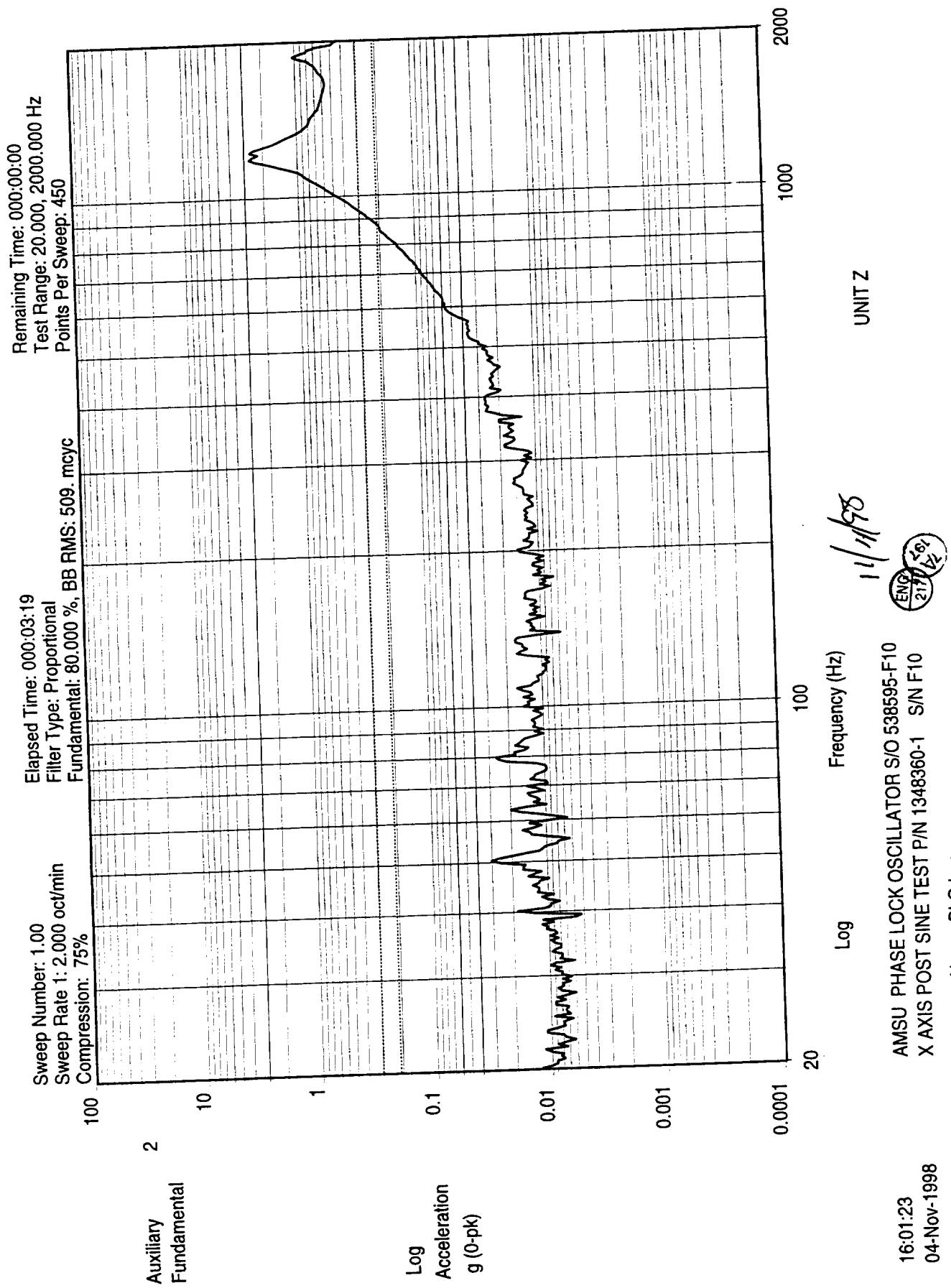
11/4/98

AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
X AXIS POST SINE TEST P/N 1348360-1 SN F10

Sine Test Name: PLO.tmp

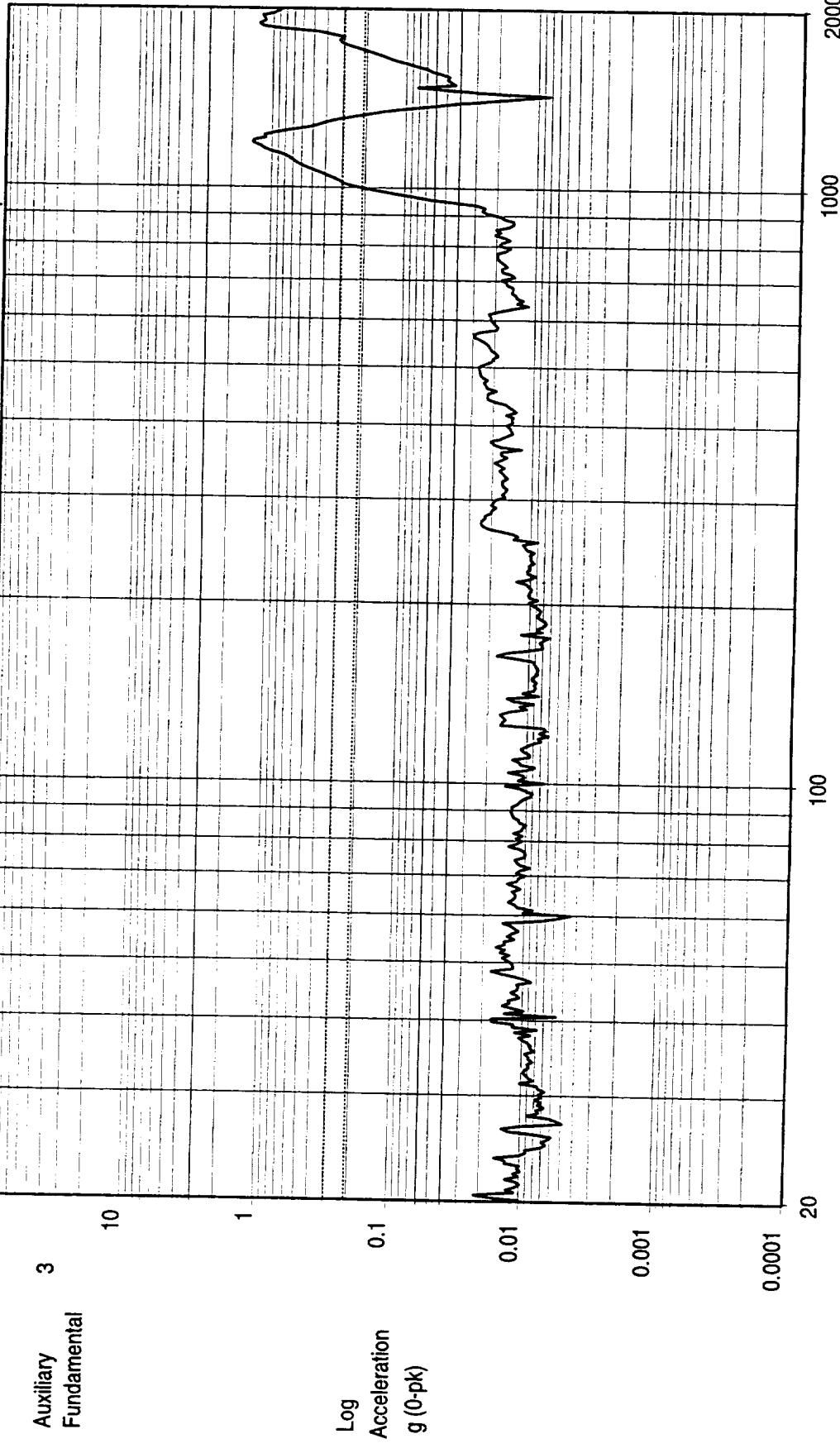
16:01:18  
04-Nov-1998

ENG  
L3I  
42  
217



Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%

Elapsed Time: 000:03:19  
Filter Type: Proportional  
Fundamental: 80.000 %, BB RMS: 509. mcyc



16:01:27  
04-Nov-1998

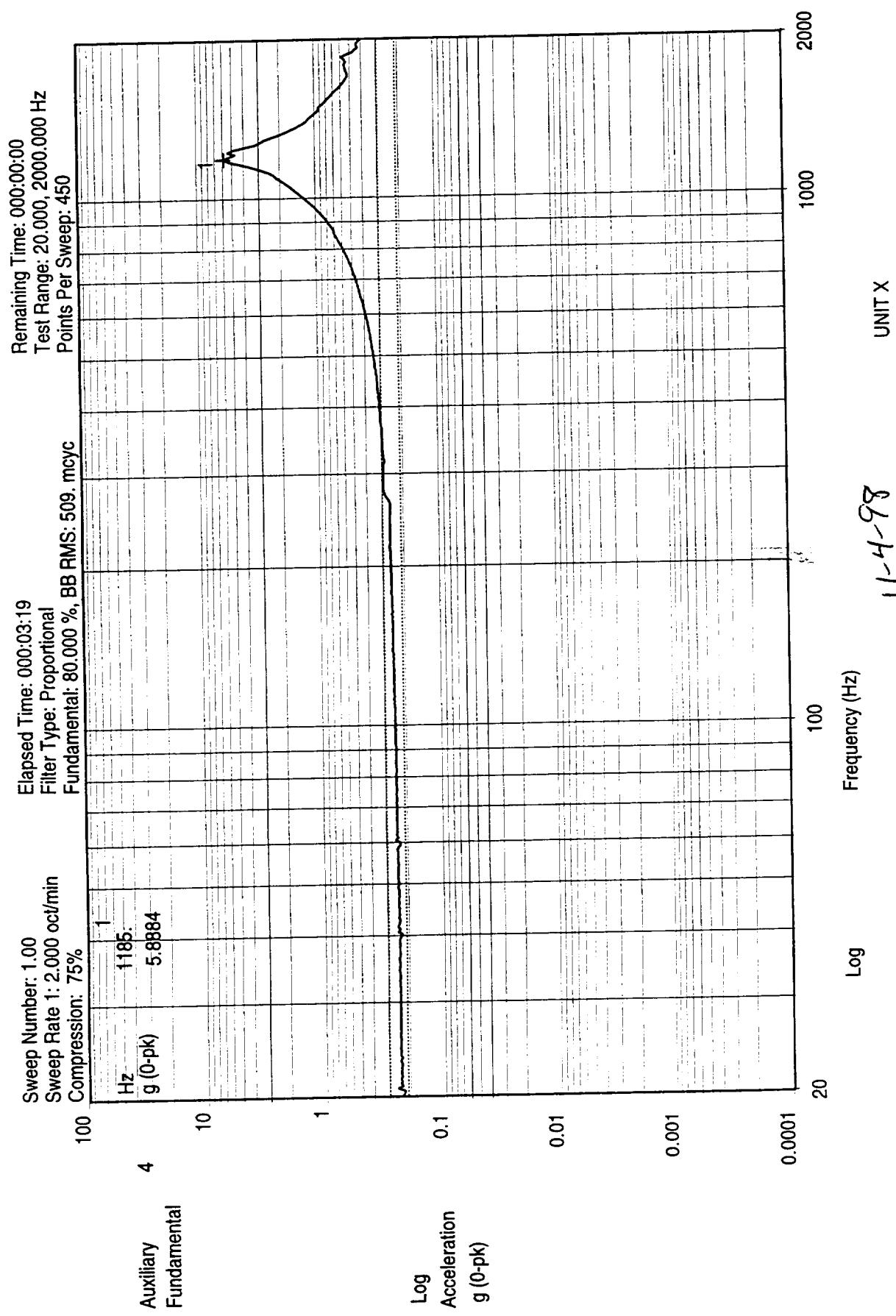
AMSU PHASE LOCK OSCILLATOR S/I 538595-F10  
X AXIS POST SINE TEST P/N 1348360-1 SN F10  
Sine Test Name: PLO.Imp

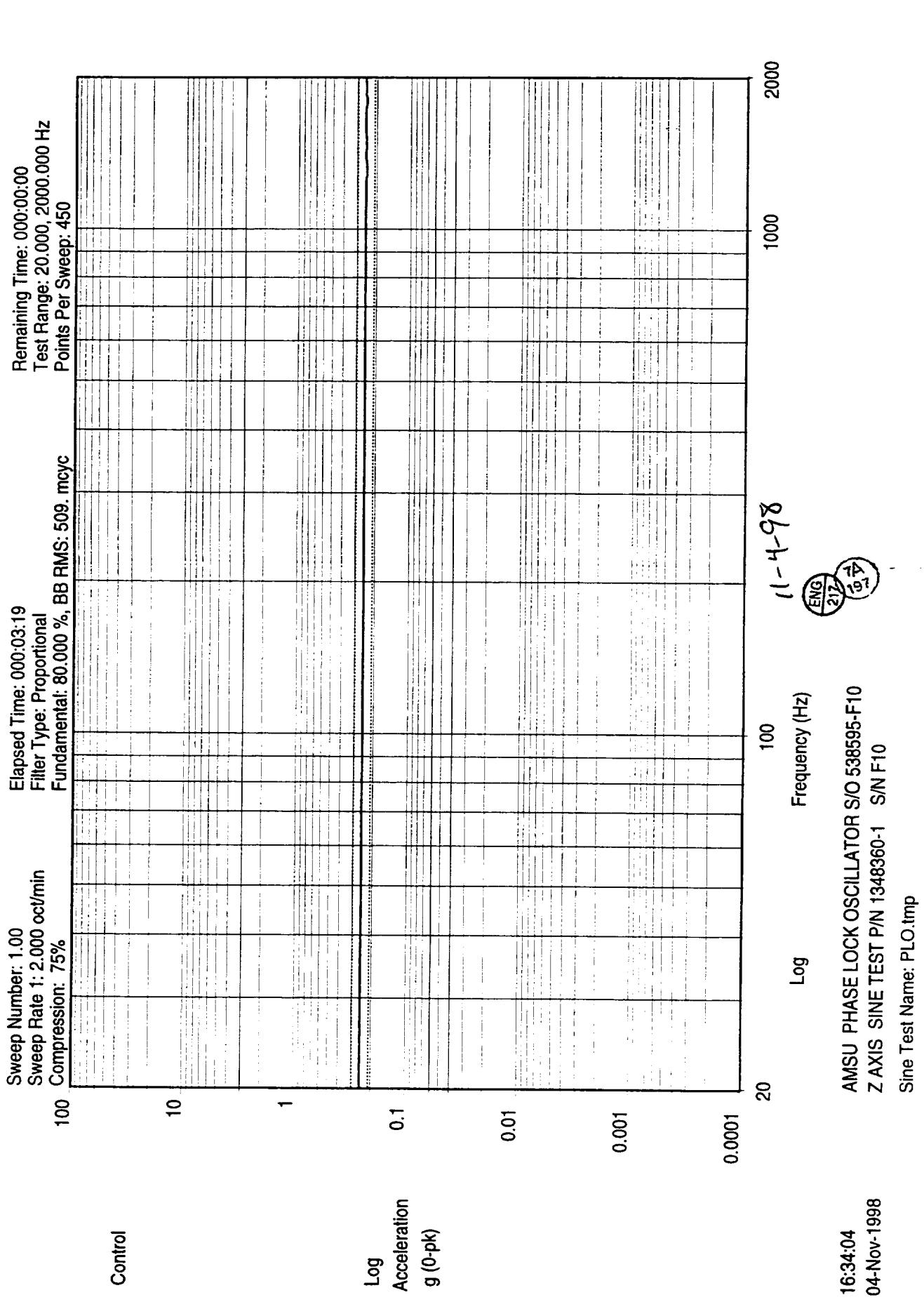
UNIT Y

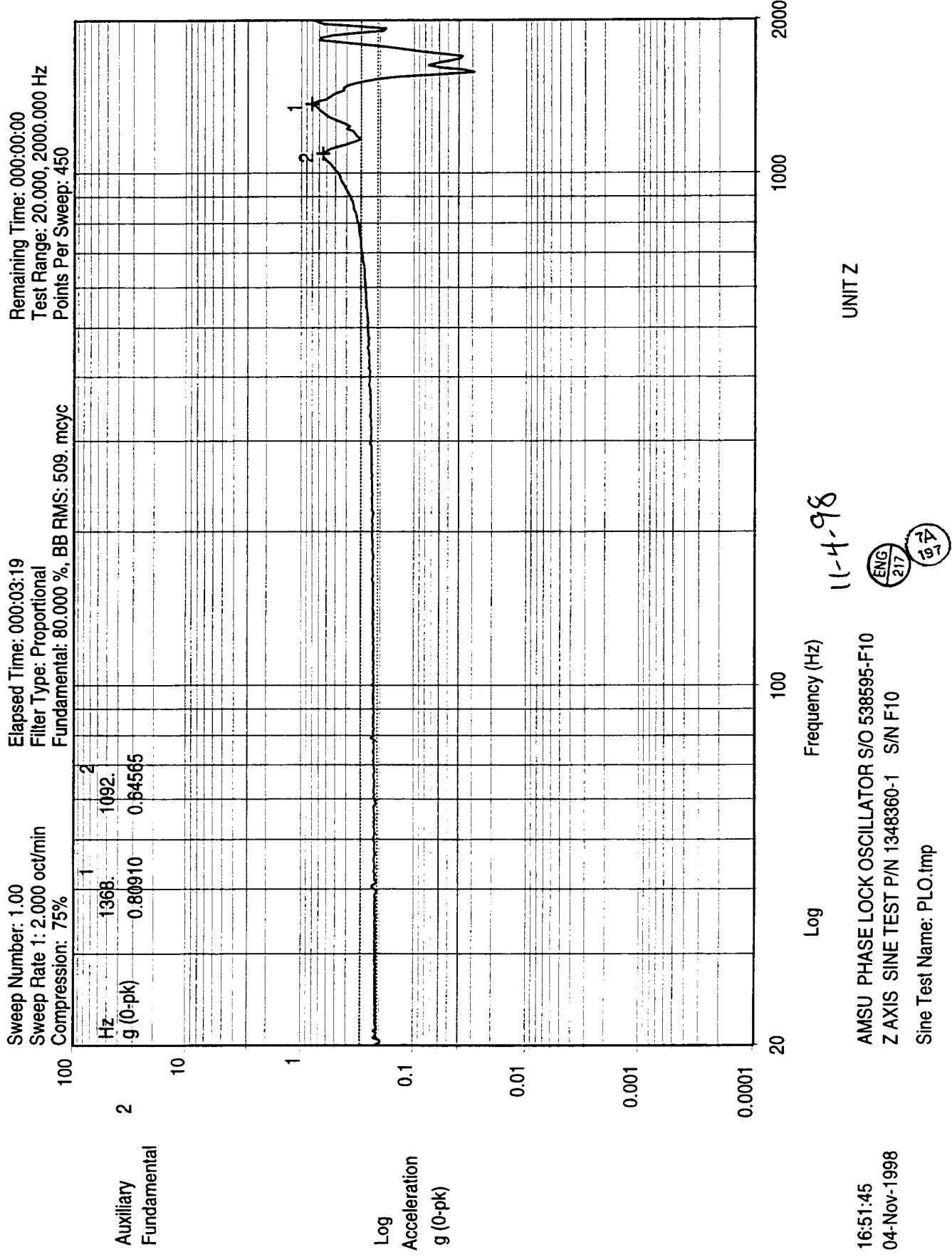
1/4/98

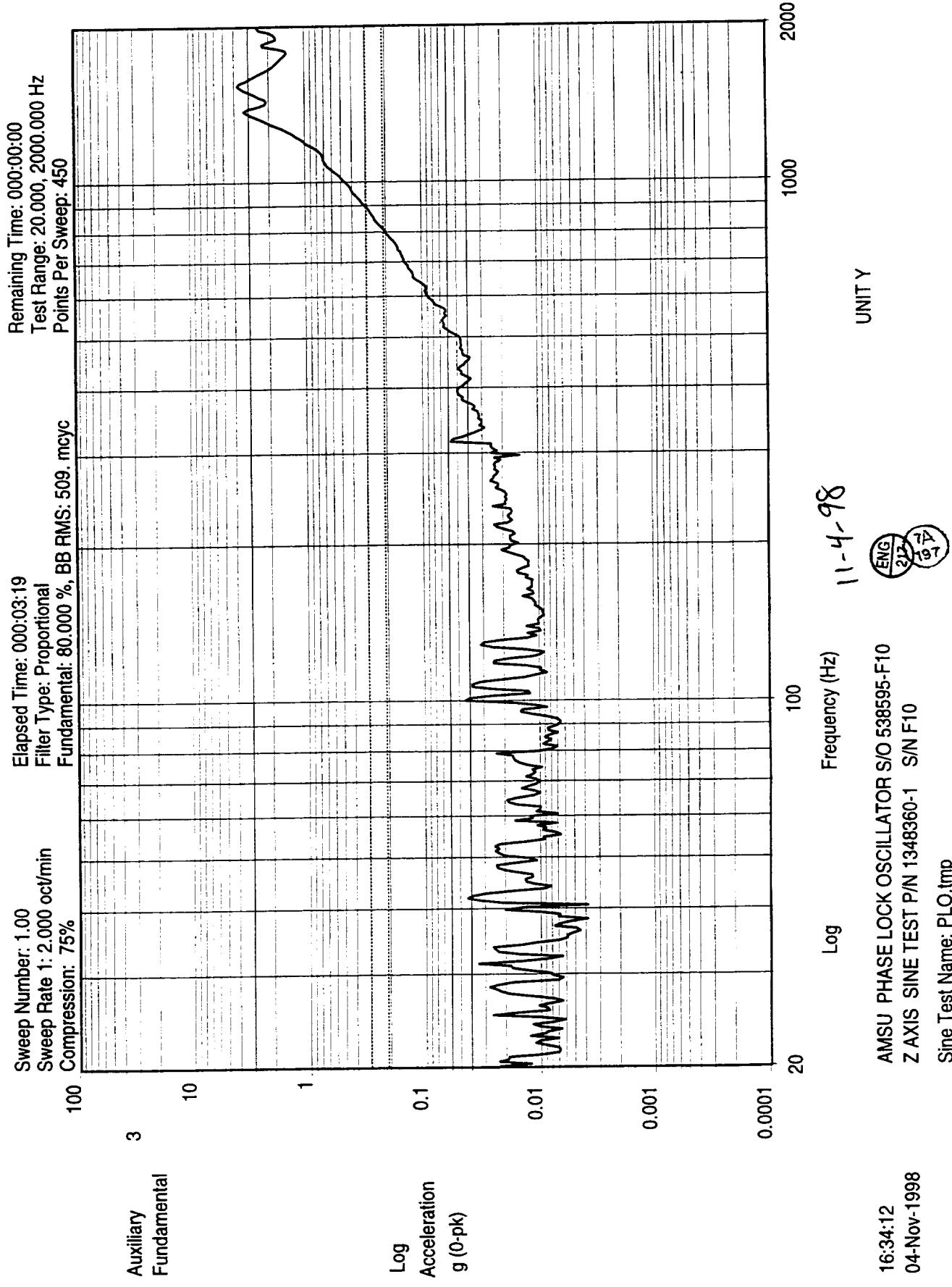
16  
217

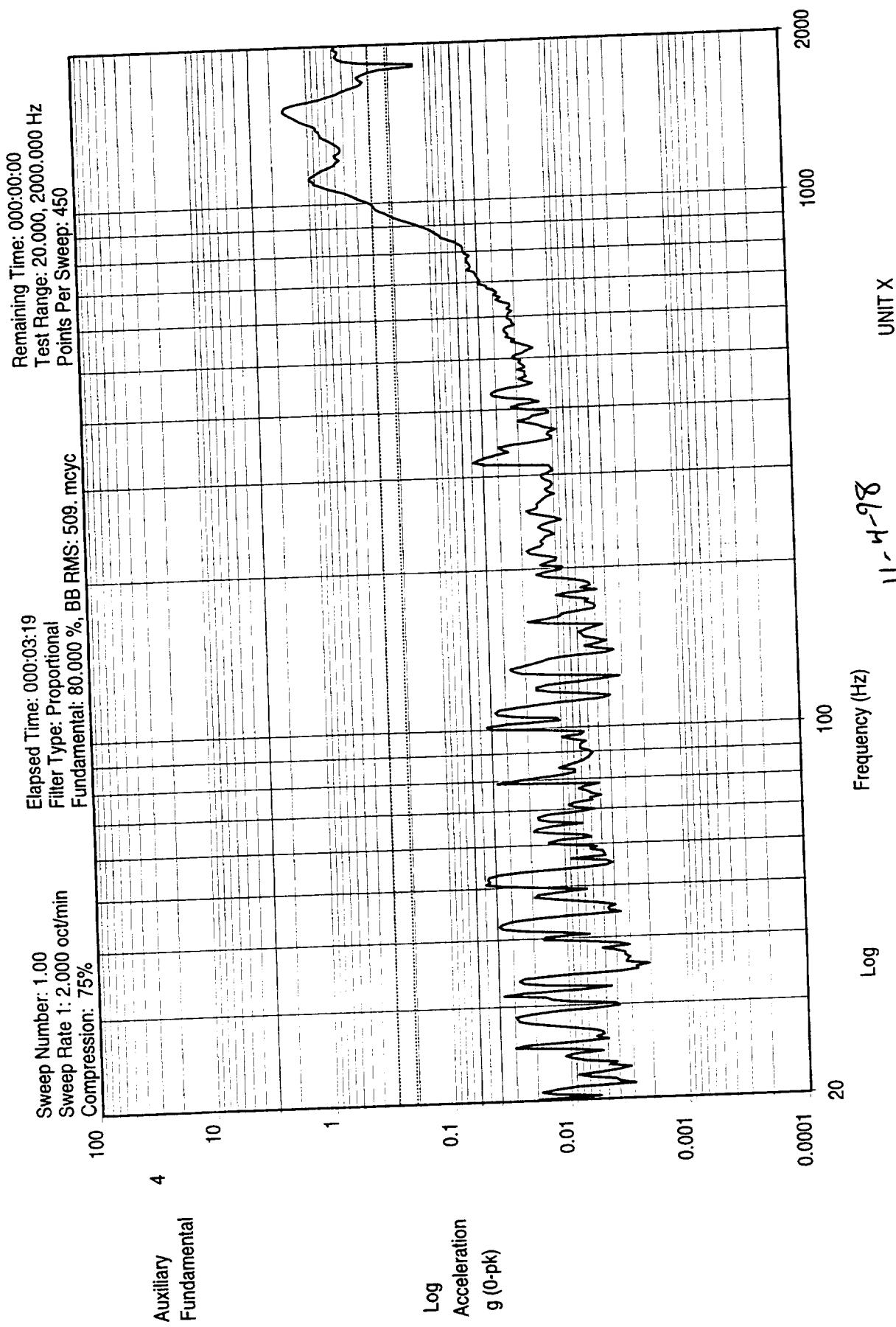
1/4/98









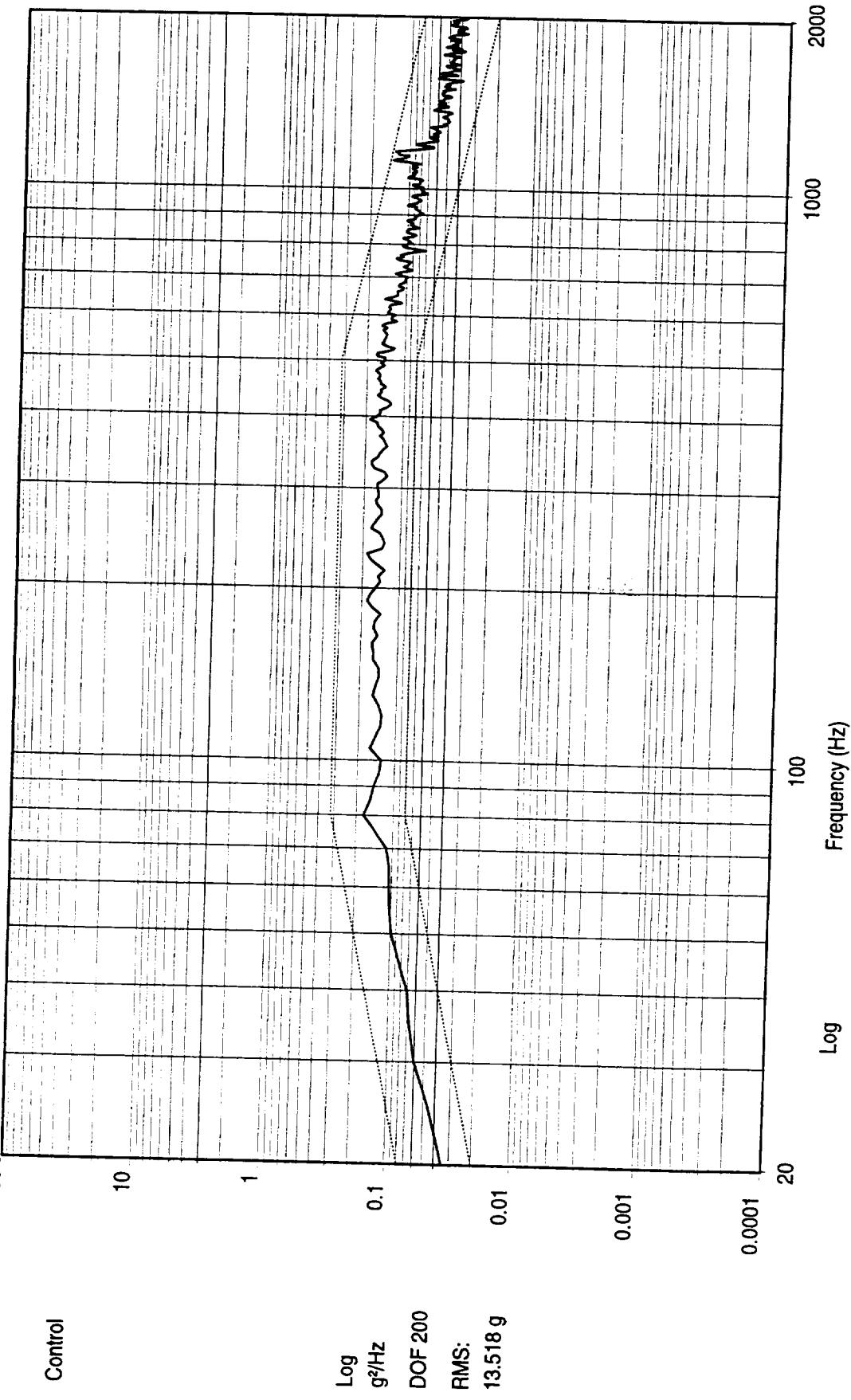


16:34:17  
 04-Nov-1998

Test Level: 0.000 dB  
Test Time: 00:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



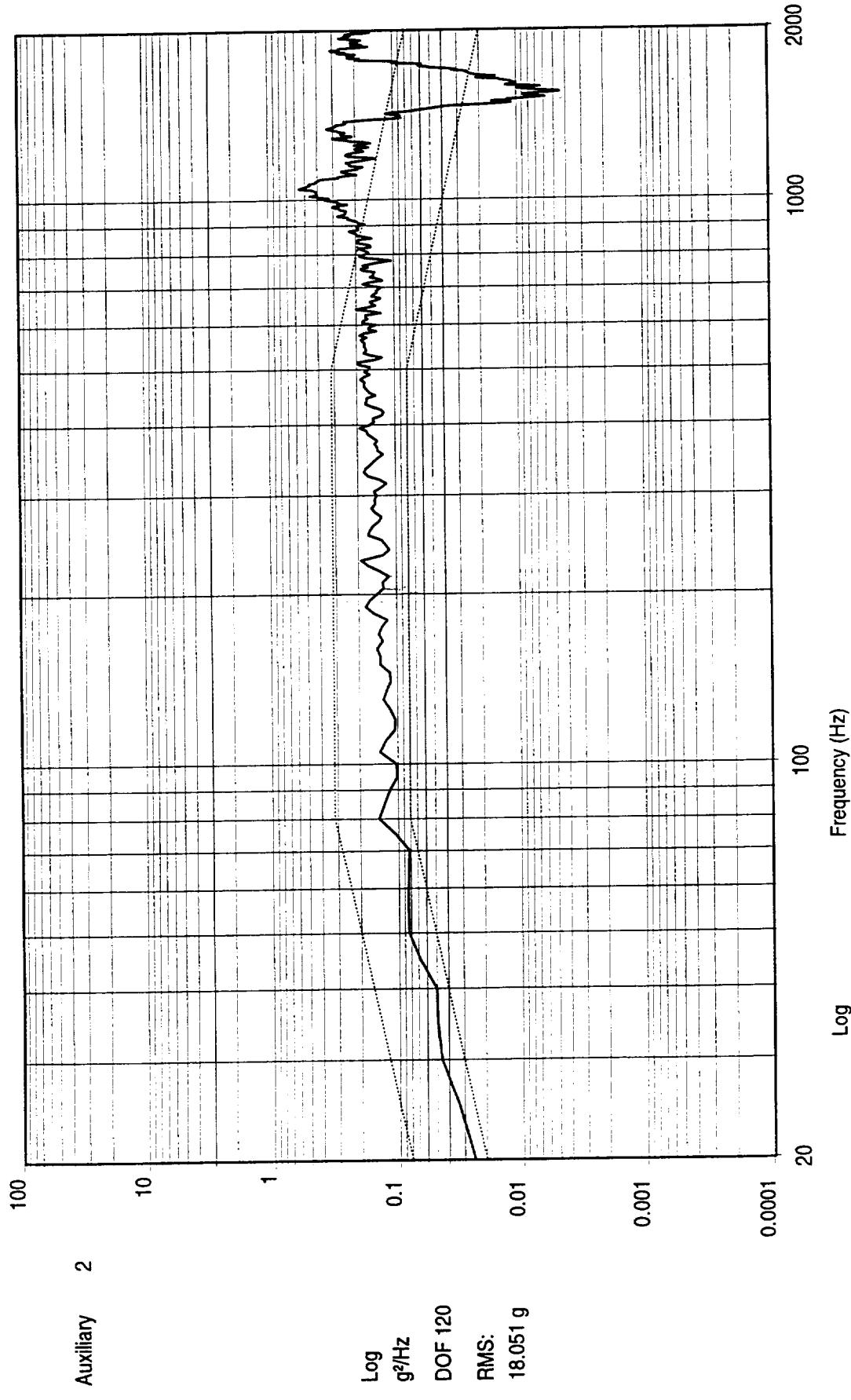
17:13:00  
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/O538595  
Z AXIS TEST P/N 1348360-1 S/N, F10

Test Name: PL0.tmp

ENG  
217  
197  
148

Test Level: 0.000 dB  
Test Time: 000:01:00  
Reference RMS: 13.576  
Clipping: Off



17:13:07  
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/0538595  
Z AXIS TEST P/N 1348360-1 SIN\_F10  
Test Name: PLO.tmp

ENG  
217

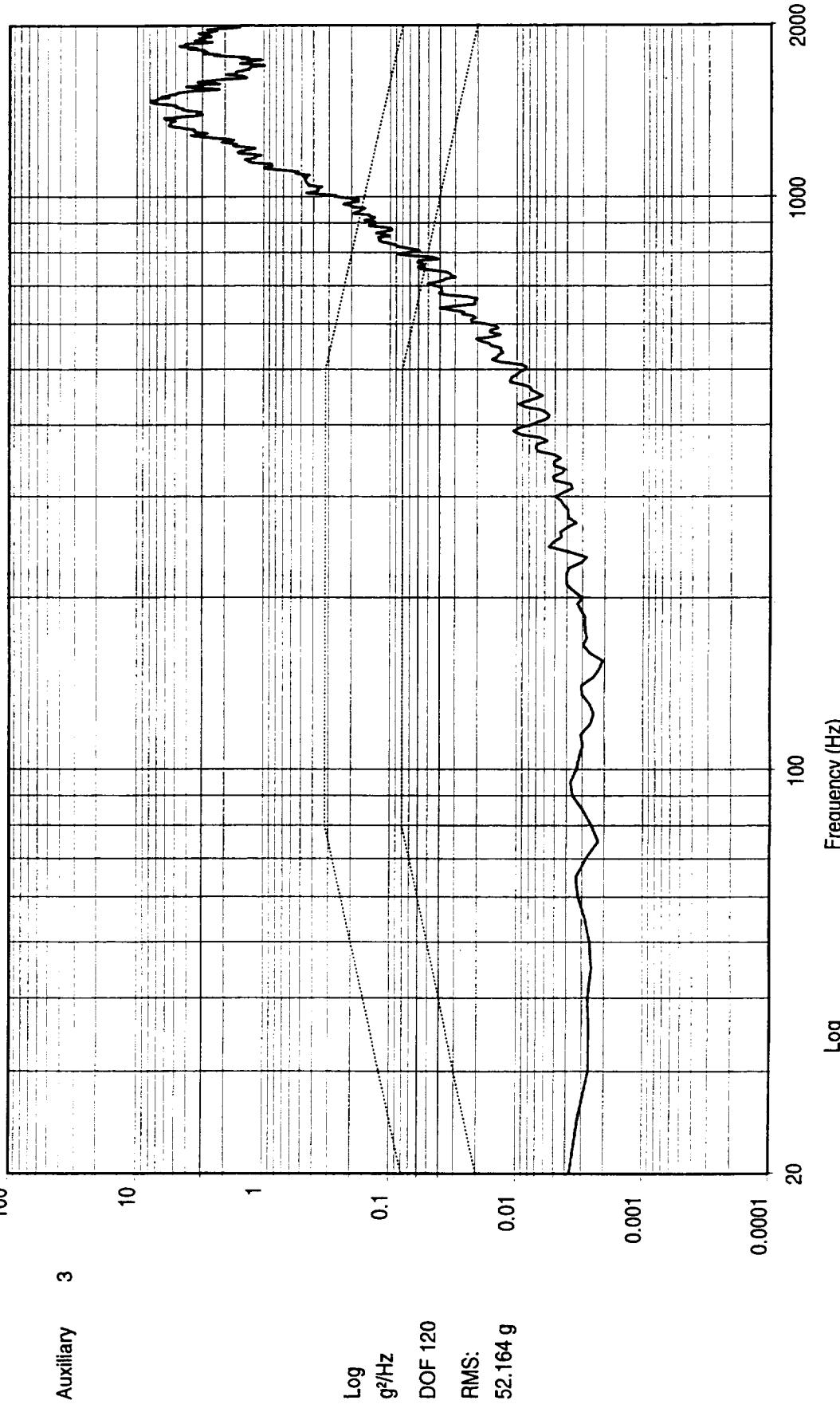
18.051

0.0001

Test Level: 0.000 dB  
Test Time: 000:01:00

Reference RMS: 13.576  
Clipping: Off

Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



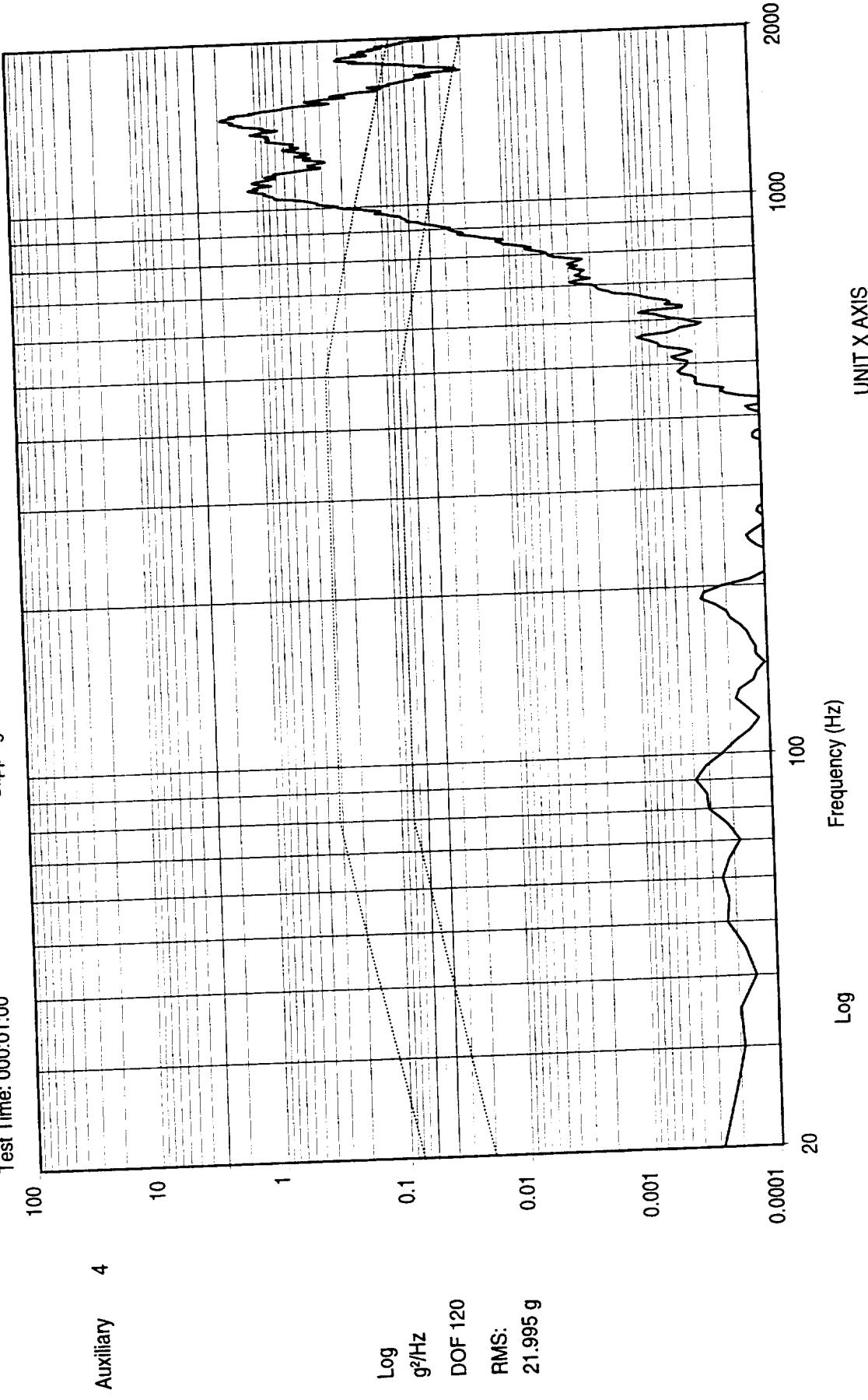
17:13:11  
04-Nov-1998

AMSU PHASE LOCK OSCILLATOR S/0538595  
Z AXIS TEST P/N 1348360-1 S/N ,F10

Test Name: PL0.Imp

ENG  
217  
1974  
 $\mu\text{-}\mathcal{F}_c$

Test Level: 0.000 dB  
Test Time: 000:01:00  
Reference RMS: 13.576  
Clipping: Off  
Test Range: 20.000, 2000.000 Hz  
Resolution: 5.000 Hz



17:13:15  
04-Nov-1998

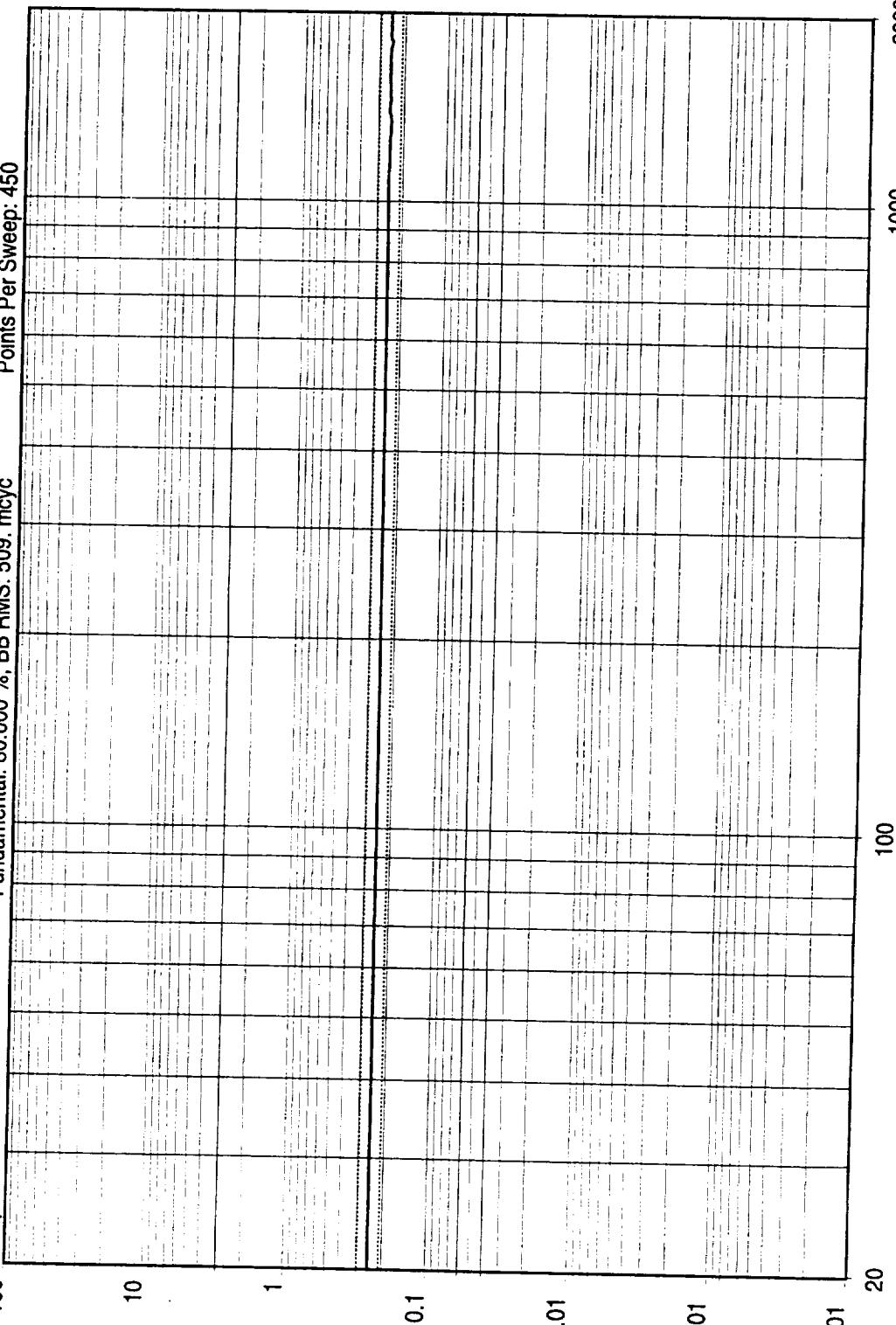
AMSU PHASE LOCK OSCILLATOR S/0538595  
Z AXIS TEST PN 1348360-1 SIN.F10  
Test Name: PLO.tmp

ENG  
217  
197

CL-X.G.

Test Report

Sweep Number: 1.00  
Sweep Rate 1: 2.000 oct/min  
Compression: 75%



Control

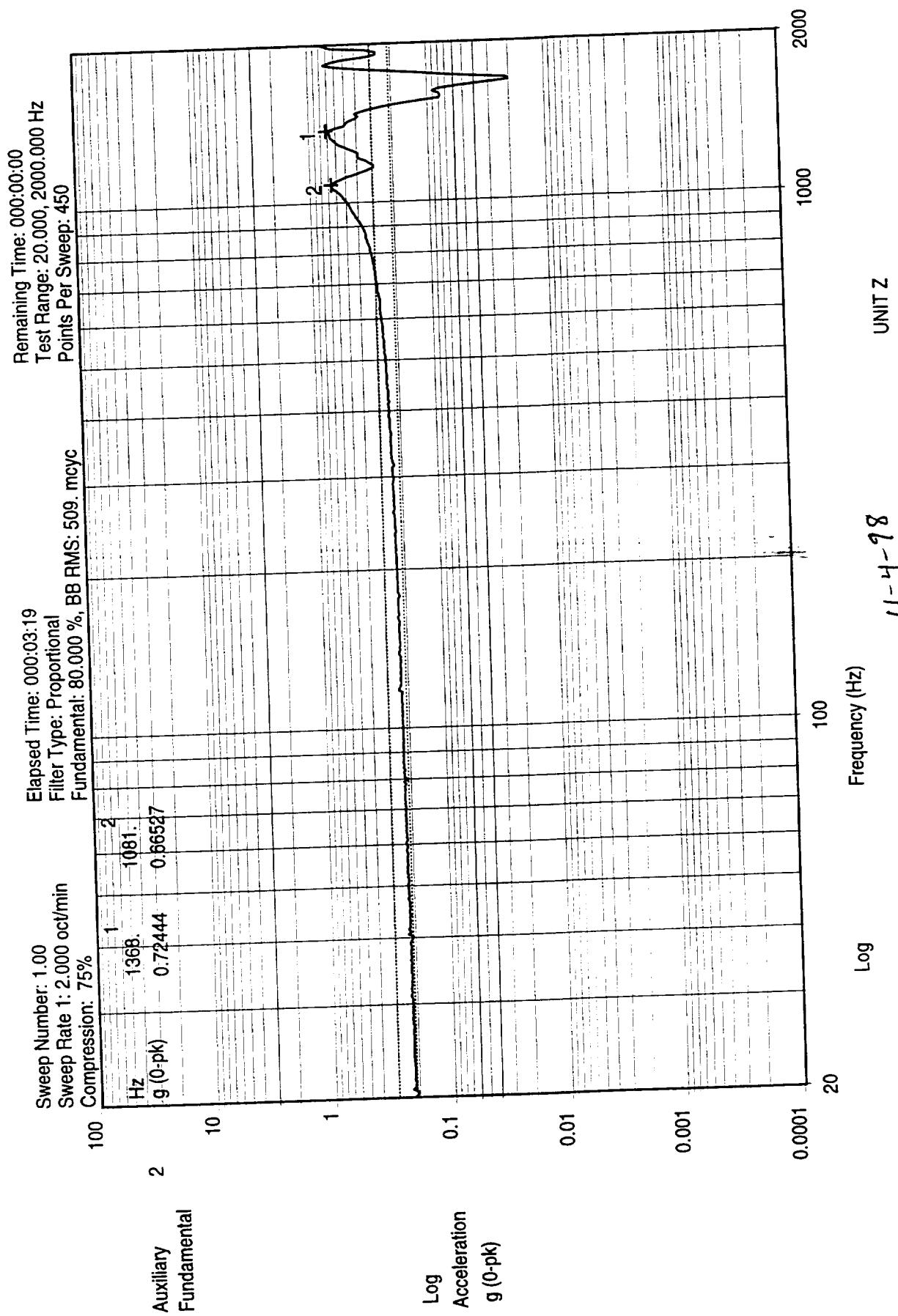
Elapsed Time: 000:03:19  
Remaining Time: 000:00:00  
Test Range: 20.000, 2000.000 Hz  
Points Per Sweep: 450

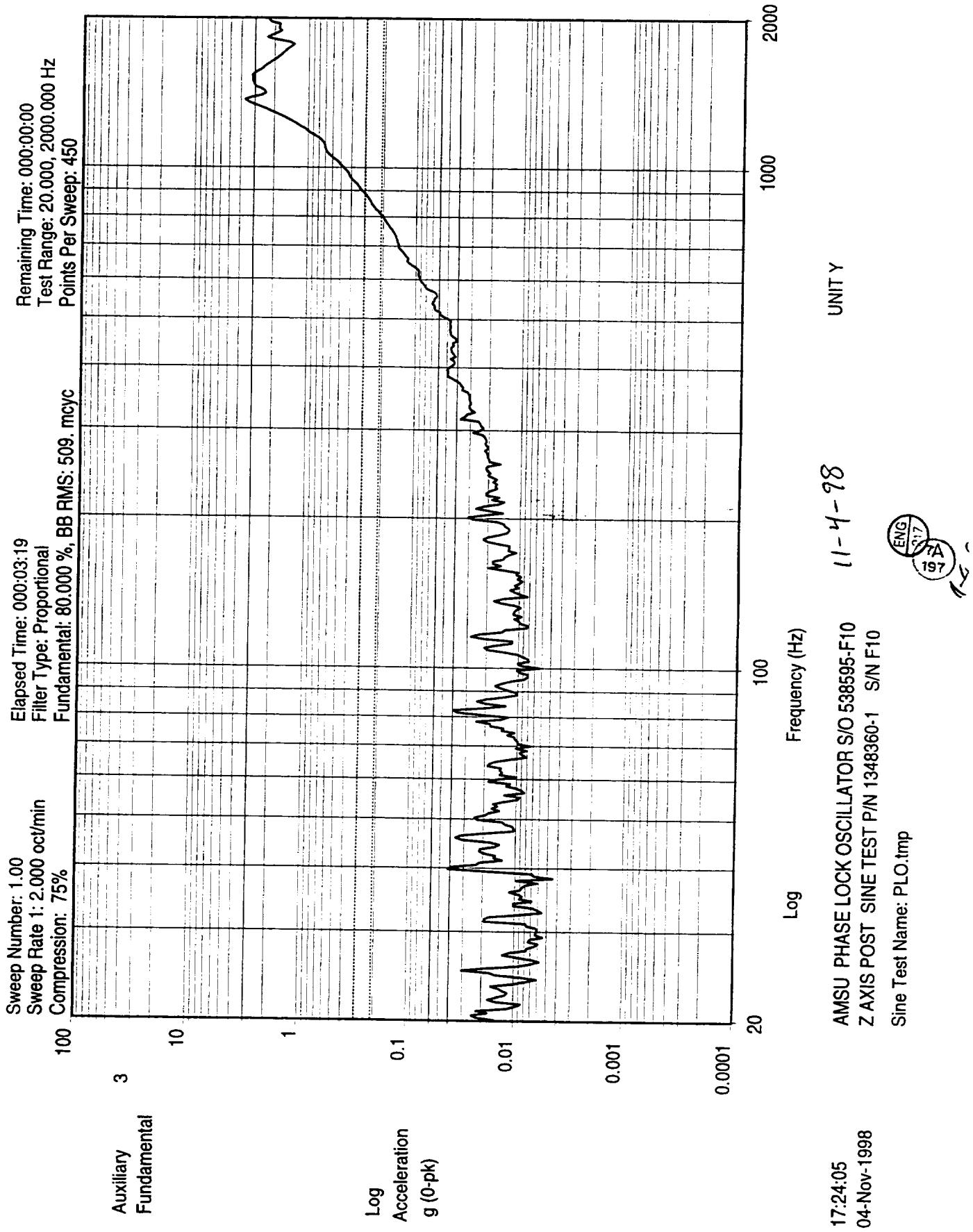
17:23:25  
04-Nov-1998

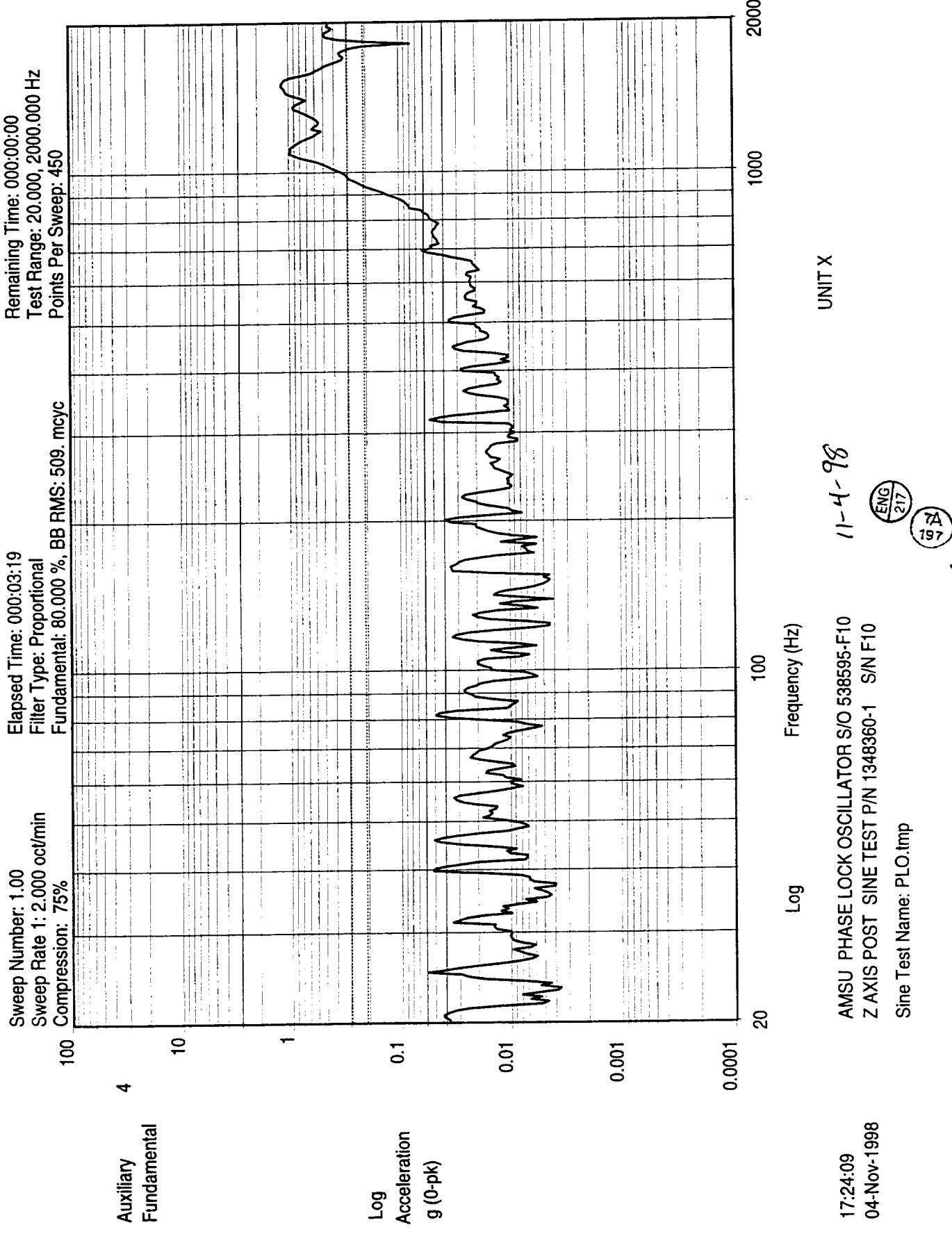
AMSU PHASE LOCK OSCILLATOR S/O 538595-F10  
Z AXIS POST SINE TEST P/N 1348360-1 S/N F10  
Sine Test Name: PLO.tmp

11-4-98

ENG  
217  
7A  
197



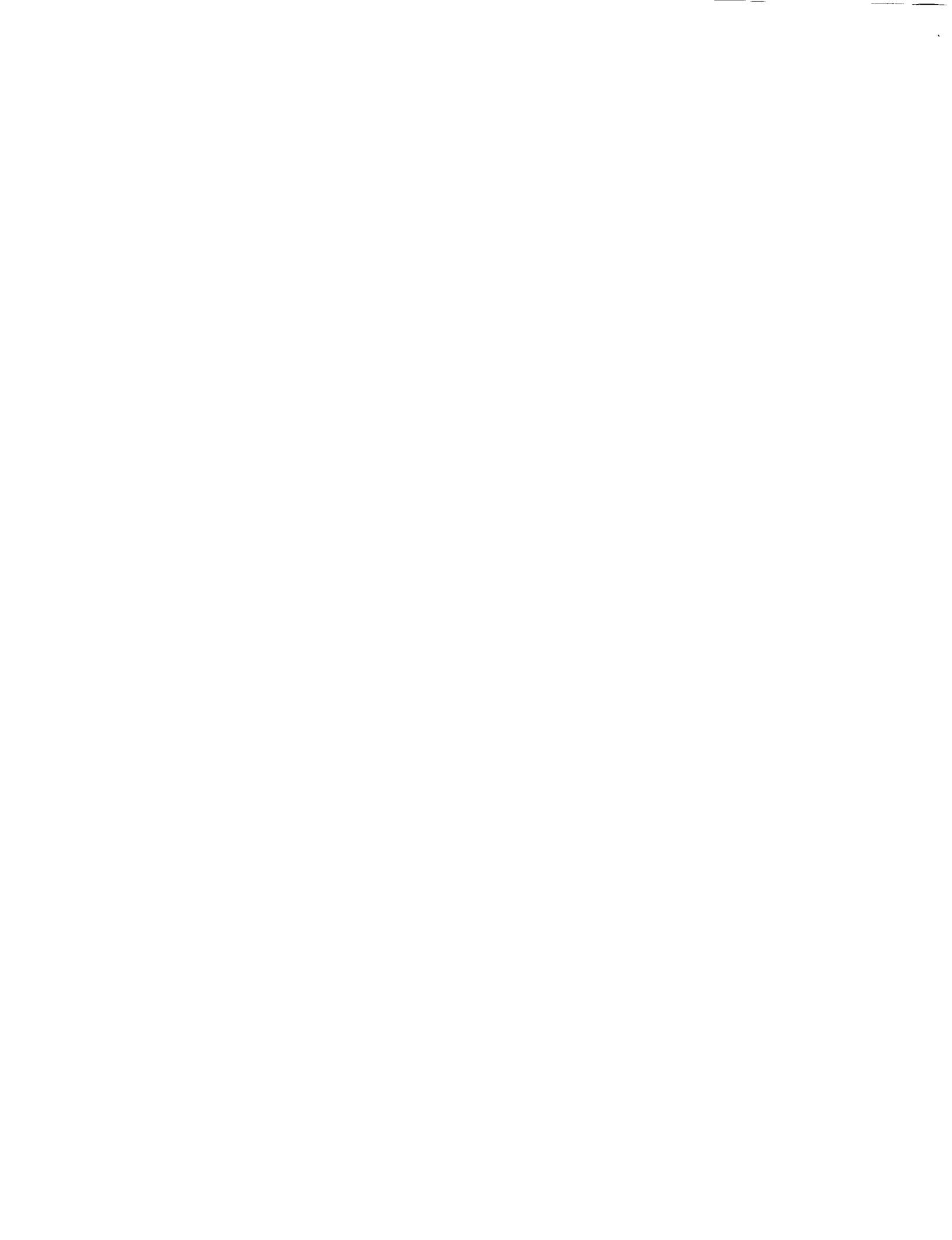






### Section 3A: Frequency and Power Hysteresis - F09

Worst case frequency and power hysteresis at 22°C for S/N F09 are 11 kHz and approximately 0.4 dBm, respectively.



TEST DATA SHEET 7 (Sheet 1 of 3)  
Temperature Cycling (Paragraph 4.2.2)

Test Setup Verified: *John Auger / J. Auger*  
Signature

Temperature Cycle	Cycle 1	Cycle 2	Cycle 3	Cycle 4	Cycle 5	Cycle 6
Frequency 57.290344 GHz $\pm 200$ kHz	57.290327 490 GHz	57.290328 285 GHz	57.290330 856 GHz		N	
Output Power 17 to 20 dBm	17.95 dBm	17.8 dBm	17.59 dBm		A	17.85 dBm 11/18/98
Frequency 57.290344 GHz $\pm 200$ kHz	57.290335 074 GHz	57.290335 877 GHz	57.290338 062 GHz			
Output Power 17 to 20 dBm	18.03 dBm	18.05 dBm	17.85 dBm			

ambient →

	Beginning of cycle 3
freq	= 57.290330050 GHz
P <sub>o</sub>	= 17.7 dBm

ambient →

	freq = 57.290338062
P <sub>o</sub>	= 17.85 dBm

Shop Order No.: 538596  
Operation: 0170  
Unit Serial No.: F09  
Date: 11-13-98

Test Engineer: *John Auger*  
Quality Control: *2A* *NOV 18 '98*  
Govt. Rep.: *M. Am. docc 11/18/98*



Section 3B: Frequency and Power Hysteresis - F10

Worst case frequency and power hysteresis at 22°C for S/N F10 are 12 kHz and approximately 0.1 dBm, respectively.



TEST DATA SHEET 7 (Sheet 1 of 3)  
Temperature Cycling (Paragraph 4.2.2)

Test Setup Verified: John Ruyngs  
Signature

Temperature Cycle	Cycle 1	Cycle 2	Cycle 3	Cycle 4	Cycle 5	Cycle 6
Frequency 57.290344 GHz ±200 kHz	57.290338 986 GHz	57.290336 775 GHz	57.290343 942 GHz			
Output Power 17 to 20 dBm	17.85 dBm	17.8 dBm	17.8 dBm		NJP John Ruyngs 11-5-98	
Frequency 57.290344 GHz ±200 kHz	57.290343 GHz	57.290347 GHz	57.290348 725 GHz			
Output Power 17 to 20 dBm	17.80 dBm	17.83 dBm	17.9 dBm			

Shop Order No.: 538595

Test Engineer: John Ruyngs

Operation: 0170

Quality Control: 268 NOV 10 '98

Unit Serial No.: F10

Govt. Rep.: 11/11/98

Date: 11-5-98



Section 4A: EMI/RE02 - F09

Not required. Qualification Testing done on S/N's F01, F02.



Section 4B: EMI/RE02 - F10

Not required. Qualification Testing done on S/N's F01, F02.



Section 5A: Final Functional Testing - F09

This section contains the results of a full functional test over temperature taken after PLO  
F09 endured thermal cycling. All tests passed.



TEST DATA SHEET 6C (Sheet 1 of 4)  
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Test Setup Verified:

*[Signature]*  
Signature

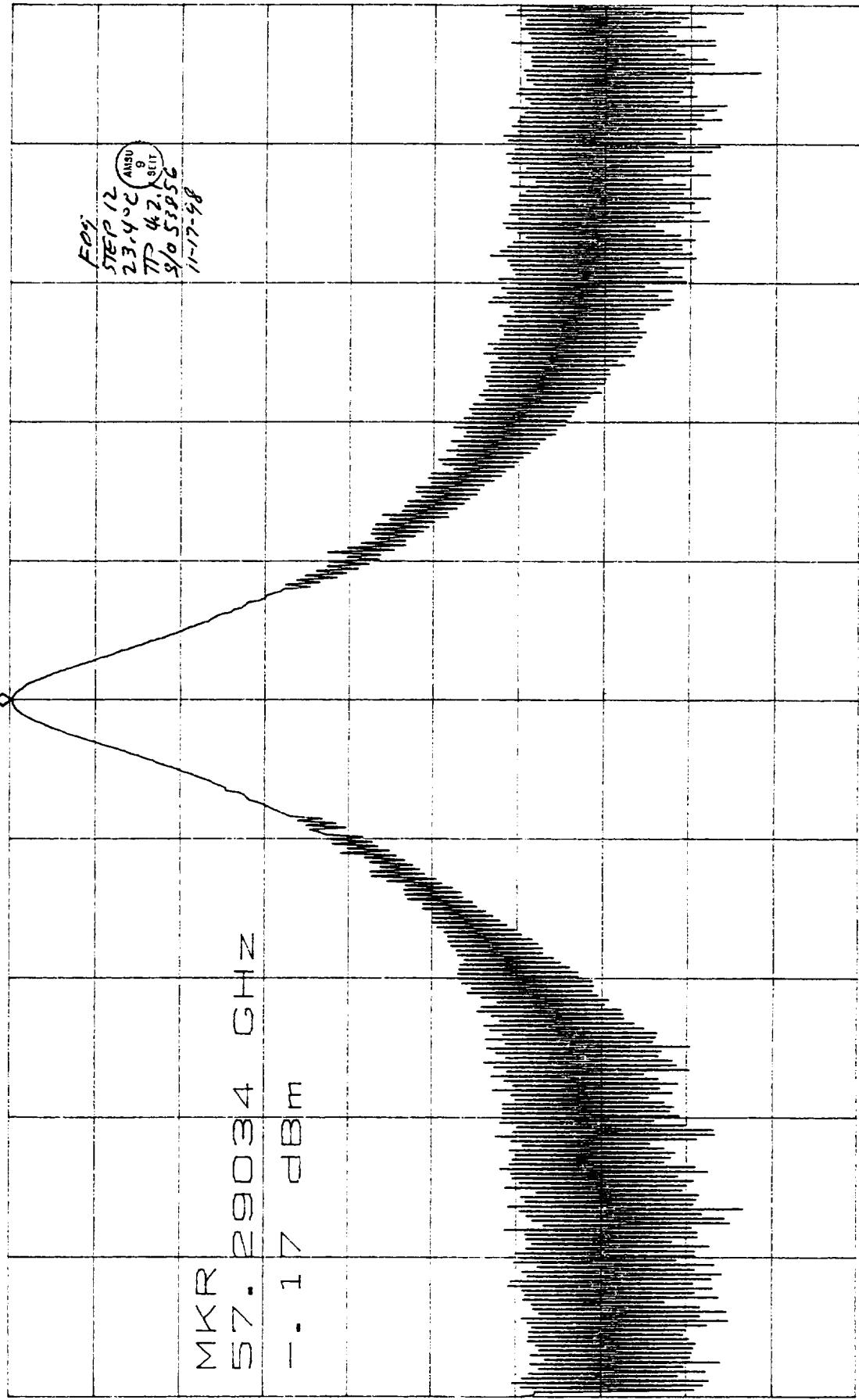
Paragraph 4.2.1.3, Functional Testing:

Step	Test	Expected	Measured	Pass/ Fail
1	Potential Difference from $\pm 15$ V RTN to:			
	PLO Base Plate	< 1.0 Vac	0.03 Vac	Pass
	Spectrum Analyzer	< 1.0 Vac	0.02 Vac	Pass
	Frequency Counter Chassis	< 1.0 Vac	0.1 Vac	Pass
	Power Meter Chassis	< 1.0 Vac	0.07 Vac	Pass
4	Evacuate vacuum chamber and record pressure	$< 10^{-2}$ torr	Pressure = <i>10<sup>-2</sup> 9.999999999999999</i>	* <i>N/A</i>
5	Thermal couple readings	TC1 = $22 \pm 2$ °C	TC1 = <u>24.0</u> °C	Pass
			TC2 = <u>23.9</u> °C	N/A
			TC3 = <u>23.1</u> °C	N/A
6	DRO L/A	0 to 1V	DRO L/A = <u>87 mV</u>	Pass
	PLO L/A	S/N: F06, F08 = $14.6 \pm 0.4$ V S/N: F07 = 0 to 1V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.53</u> V	Pass
	Is PLO locked?	Yes	Yes <u>yes</u>	Pass
		No _____		
7	PLO Frequency	$57.290344 \pm .0002$ GHz	Freq. = <u>57.29033910</u> GHz	
	PLO Power	17 to 20 dBm	P = <u>18.11</u> dBm	Pass
8	Input Voltage and Current			<i>11-17-98</i>
	VM1 Voltage	$+15 \pm 0.1$ V	VM1 = <u>+15.19</u> V	Pass
	VM2 Voltage	$-15 \pm 0.1$ V	VM2 = <u>-15.14</u> V	Pass
	IM1 Current	600 mA max.	IM1 = <u>522</u> mA	Pass
	IM2 Current	100 mA max.	IM2 = <u>-63.4</u> mA	Pass
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>86.6 mV</u>	Pass
	PLO L/A Voltage	S/N: F06, F07, F08 = $14.6 \pm 0.4$ V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.53</u> V	Pass
12	RF Output Power and Frequency	17 to 20 dBm	P = <u>18.11</u> dBm	Pass
		$57.290344 \pm .0002$ GHz	Freq. = <u>57.29033910</u> GHz	Pass
	Baseplate Temp. (TC1)	TC1 = $22 \pm 2$ °C	TC1 = <u>23.4</u> °C	Pass

\*Record data only if performing test under vacuum

CL 30.0 dB  
RL 0 dBm

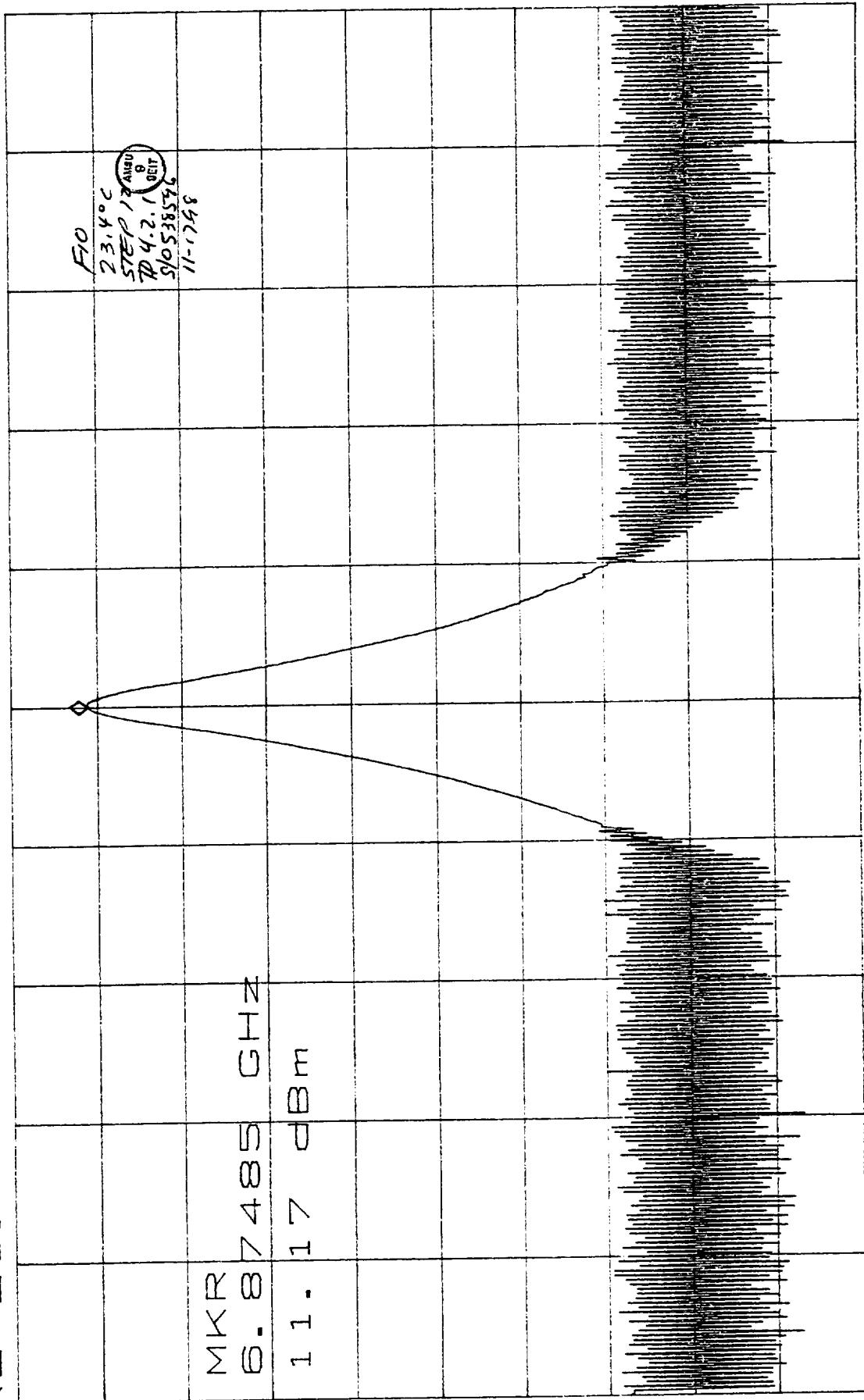
MKR -17 dBm  
57.29034 GHz



CENTER 57.29034 GHz  
\*RBW 300KHz VBW 300KHz  
SPAN 10.00MHz  
\*SWP 50.0ms

\*ATTEN 30dB  
RL 20.0dBm

MKR 11.17dBm  
10dB / 6.87485GHz

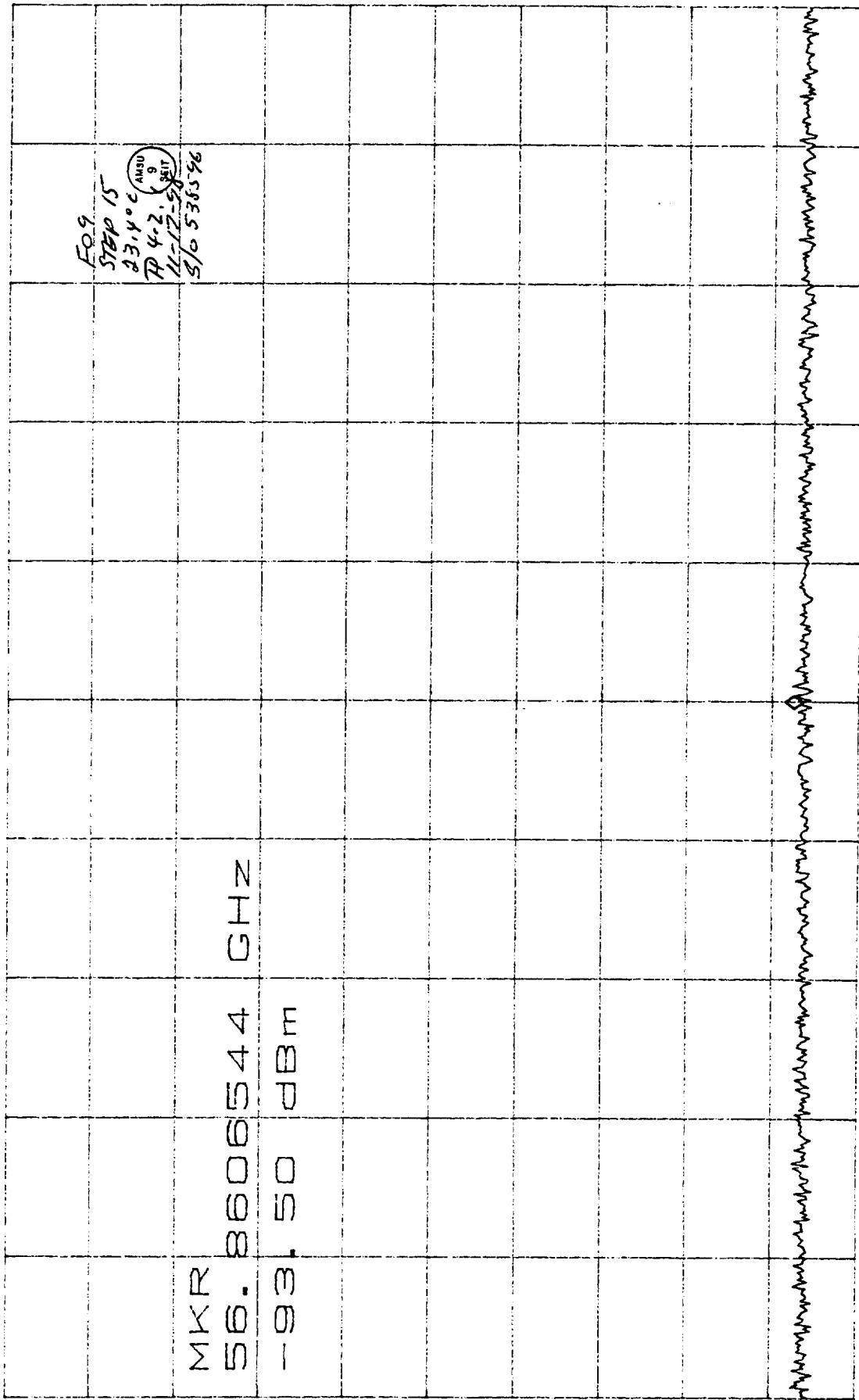


CENTER 6.87485GHz  
\*RBW 300kHz VBW 300kHz  
SPAN 20.00MHz SWP 50.0ms

SPAN 20.00MHz  
SWP 50.0ms

CL 30.0dB V AVG 10  
RL 0dBm

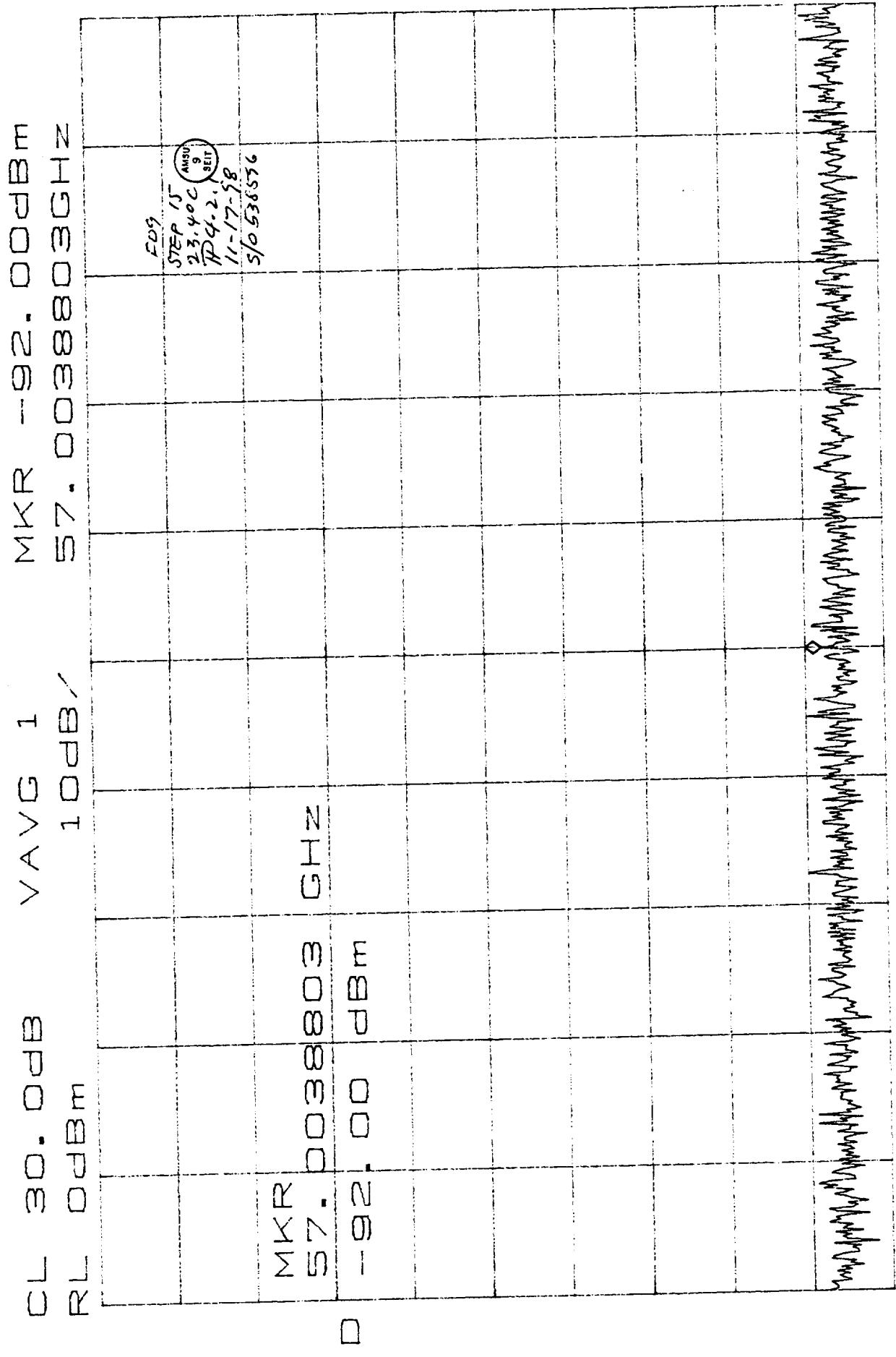
MKR -93.50dBm  
56.8606544GHz



□

Fo.9  
3780.15  
23.4°C  
AMSU  
P 4.2  
9  
II-12-28  
3/0 5333.96

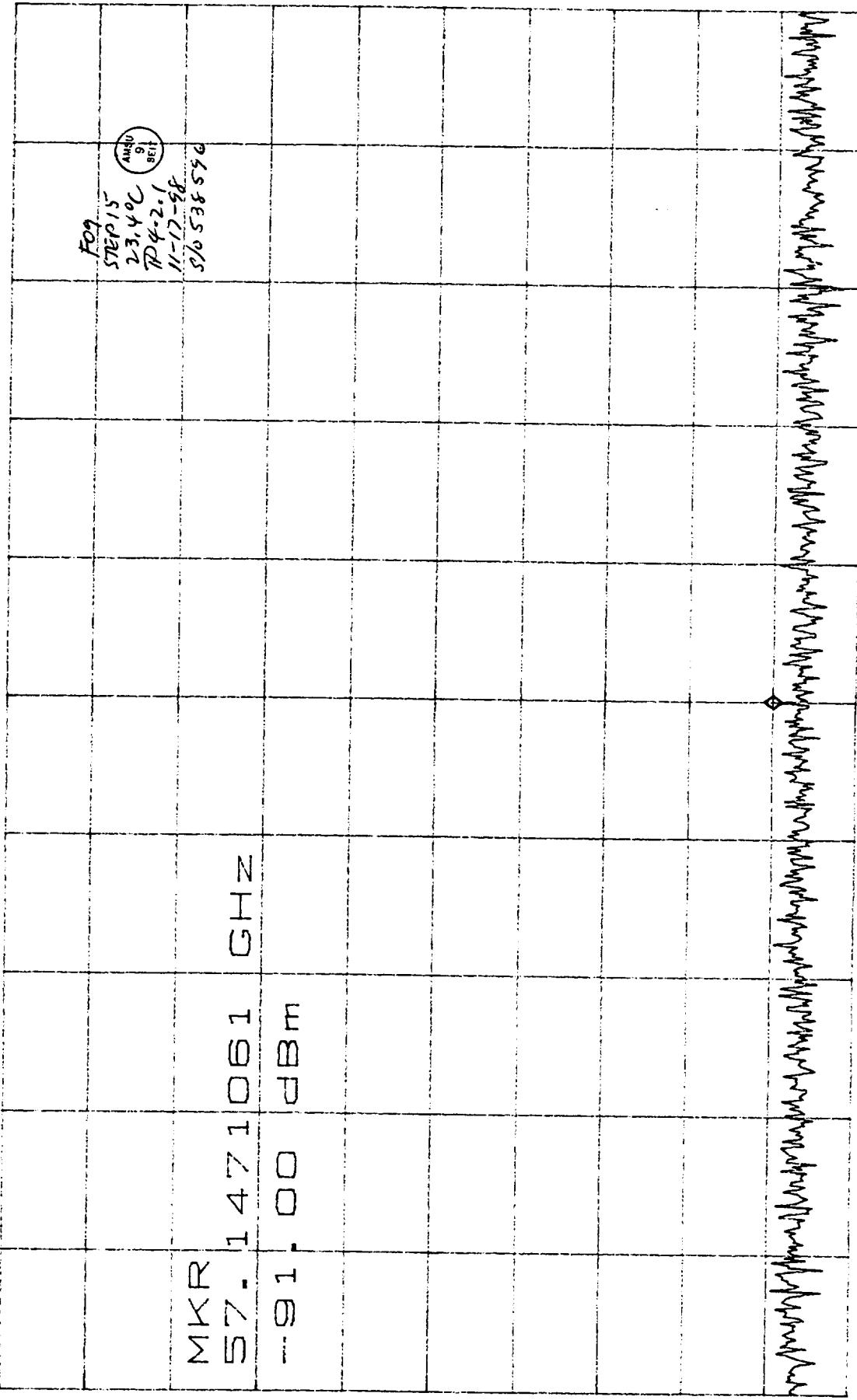
CENTER 56.8606544GHz  
RBW 3.0kHz \*V BW 1.0kHz  
SPAN 500.0kHz  
\*SWP 2.00sec



CL 30. 0dB  
RL 0dBm

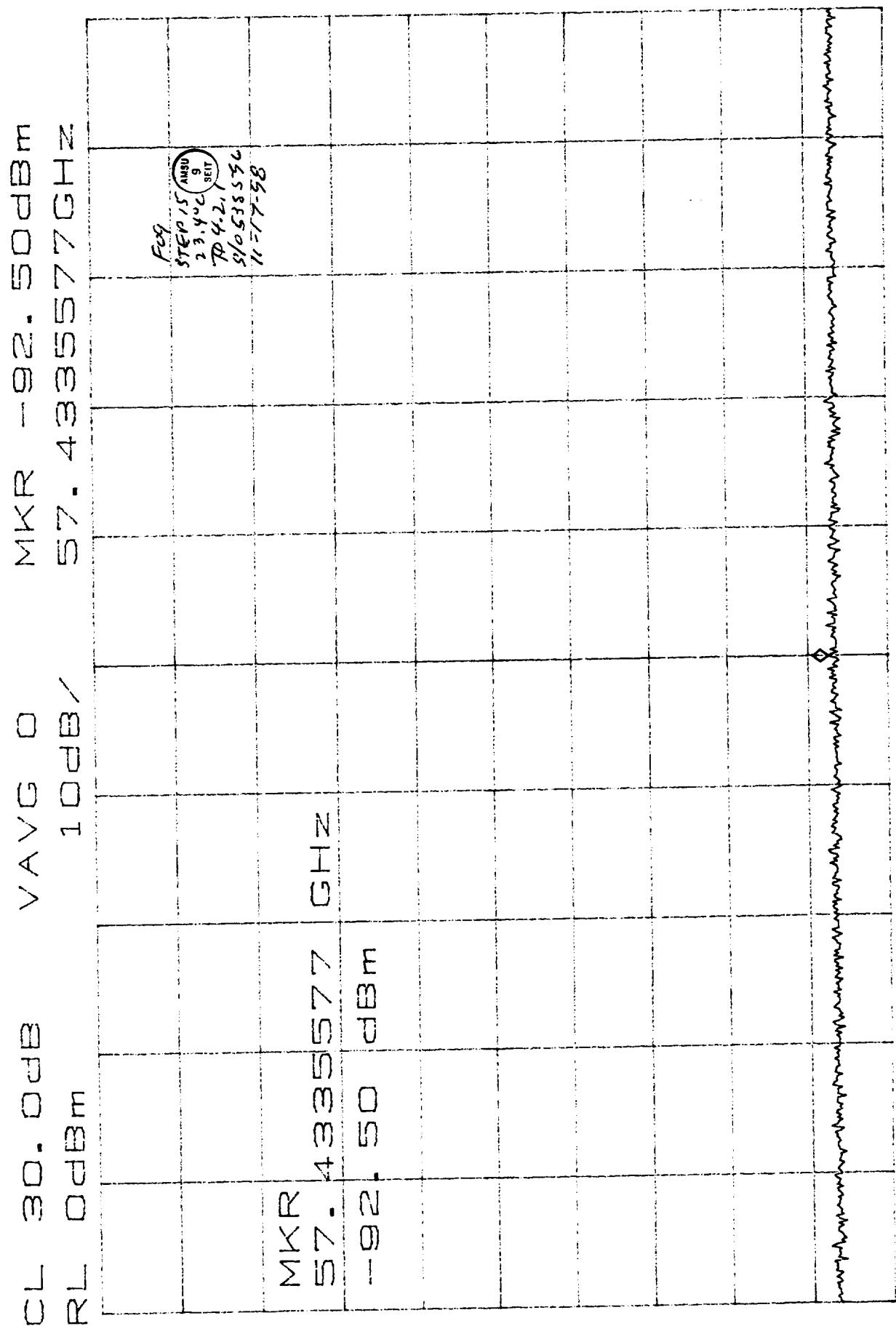
V AVG 1  
10dB/  
57. 1471061GHz

MKR -91. 00dBm  
57. 1471061GHz



□

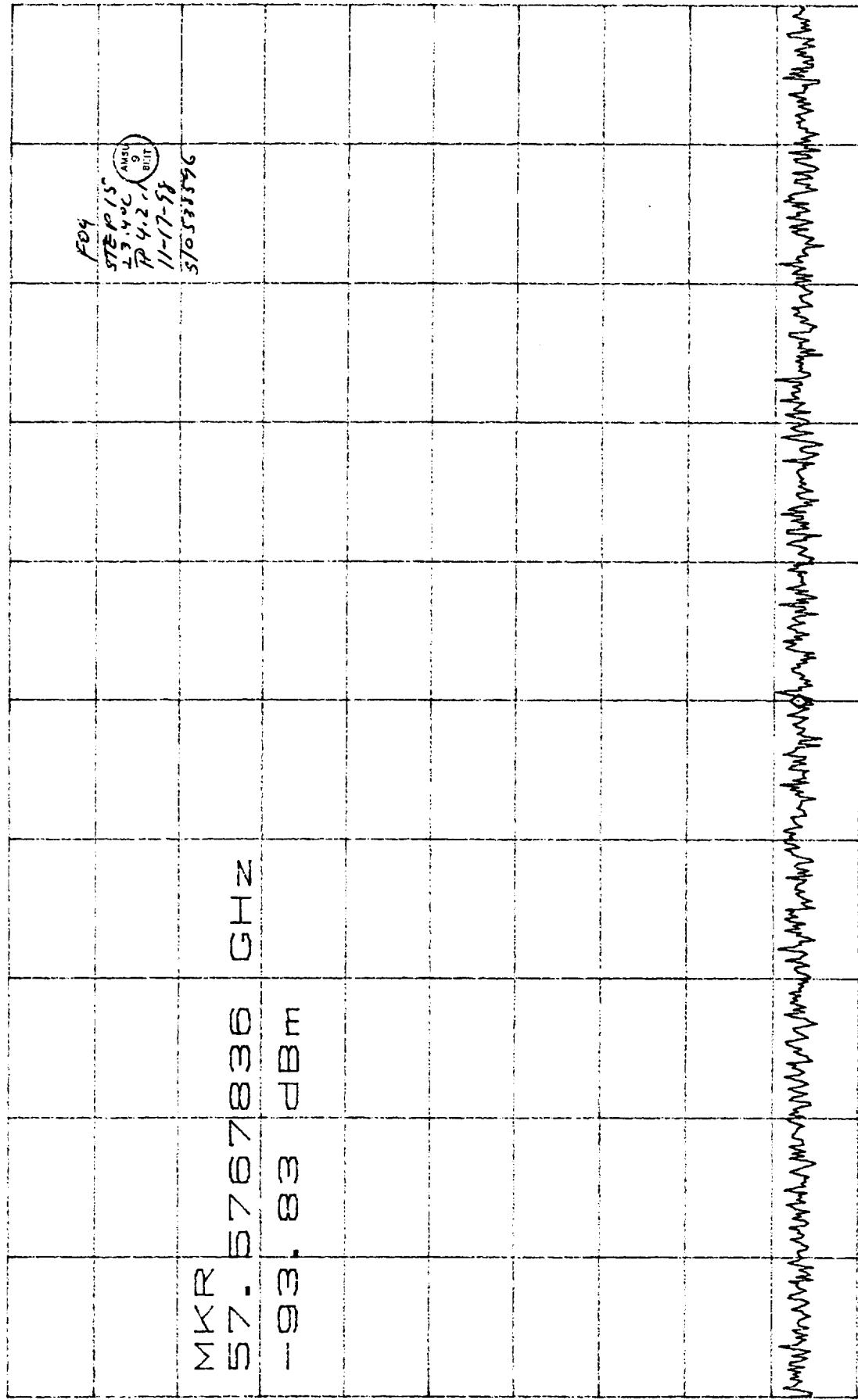
CENTER 57. 1471061GHz  
RBW 3. 0kHz \*V BW 1. 0kHz \*SPAN 500. 0kHz  
\*SWP 2. 00sec



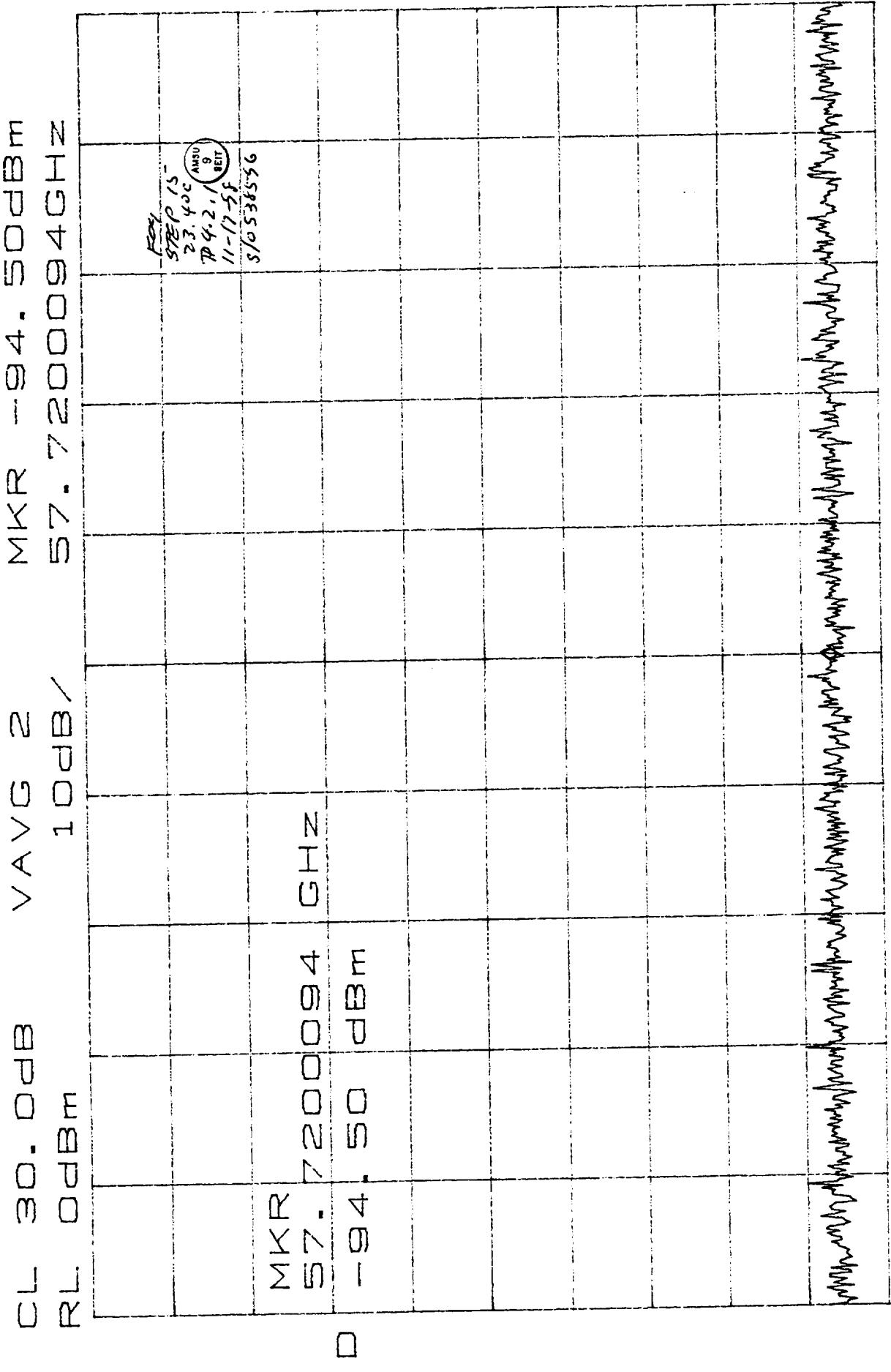
CL 30.0dB  
RL 0dBm

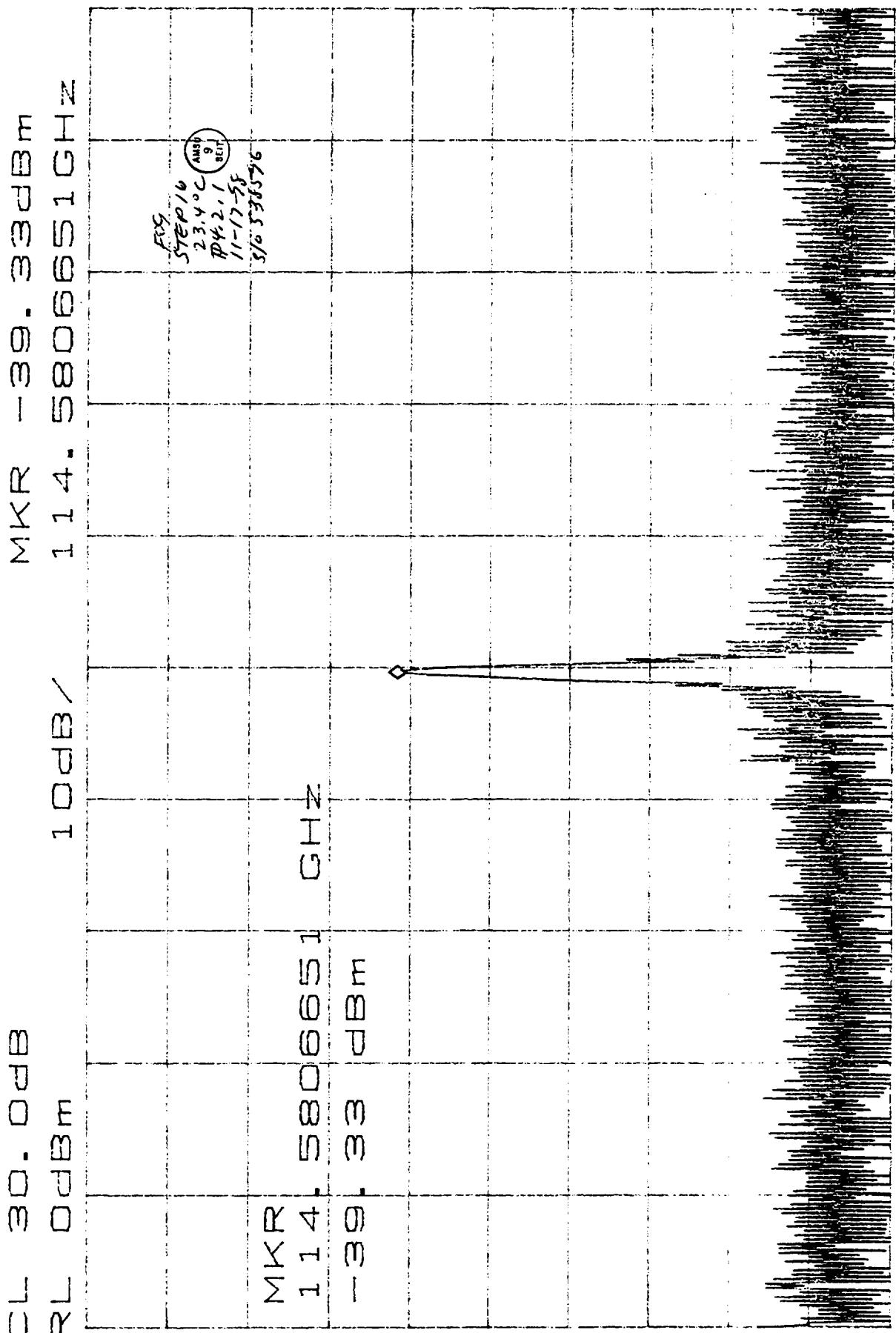
V AVG 3  
10dB/  
/

MKR -93.83dBm  
57.5767836GHz



CENTER 57.5767836GHz \*VBW 1.0kHz  
RBW 3.0kHz \*SWP 2.00sec





CENTER 114.5806655 GHz \*VBW 1.0 kHz  
 RBW 300 Hz \*SWP 2.80 sec  
 SPAN 100.0 kHz

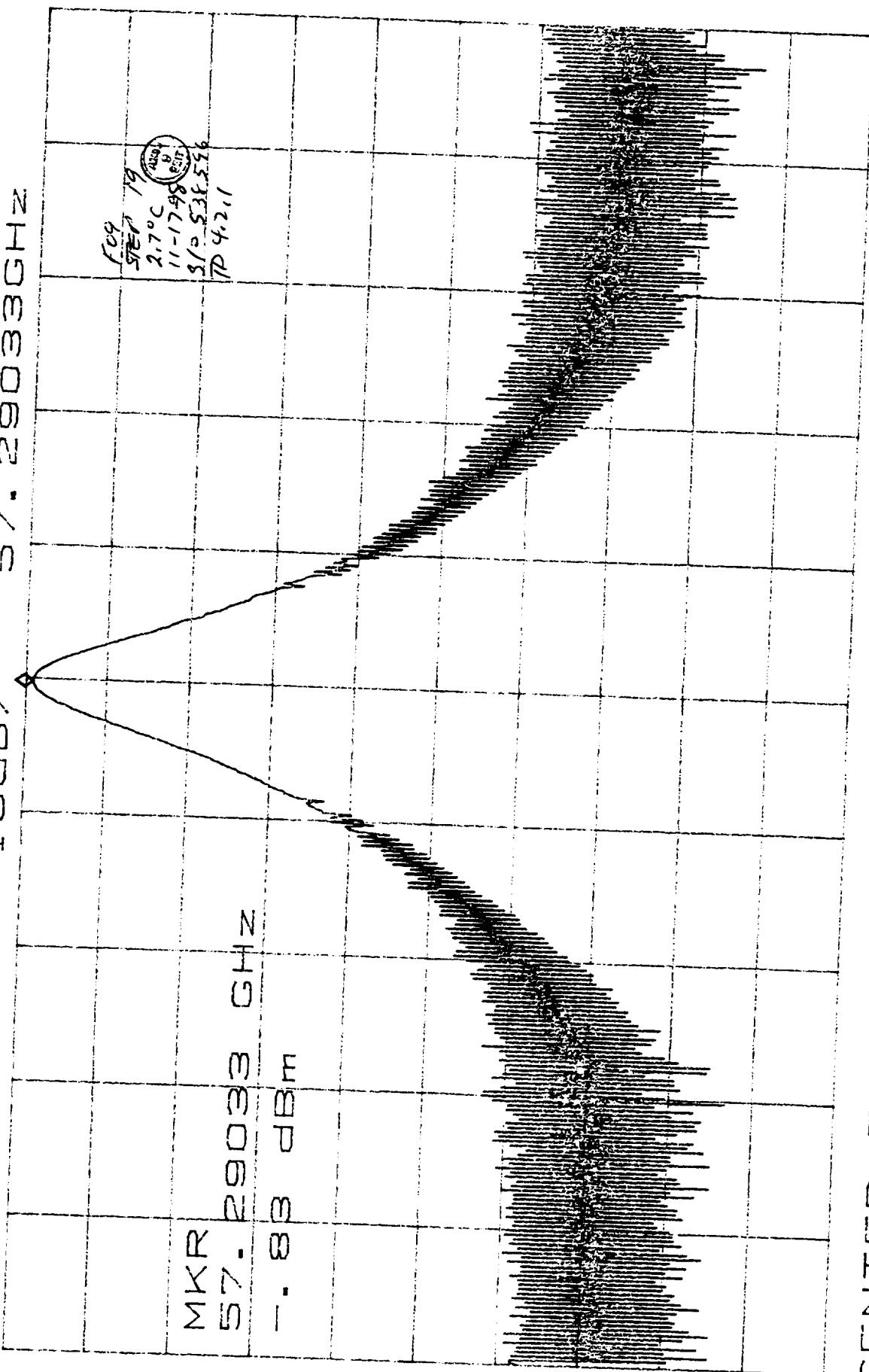
TEST DATA SHEET 6C (Sheet 2 of 4)  
Functional Testing (Paragraph 4.2.1)  
Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/ Fail
13	Frequency vs. Voltage			
	$\pm 15$ V Supplies	$+15.2 \pm 0.05$ V	+Voltage = <u>15.2</u> V	Pass
		$-15.2 \pm 0.05$ V	-Voltage = <u>-15.2</u> V	✓
		$57.290344 \pm .0002$ GHz	Freq. = <u>57.290344</u> GHz	
		17 to 20 dBm	P = <u>18.15</u> dBm	
14	Frequency vs. Voltage			
	$\pm 15$ V Supplies	$+14.8 \pm 0.05$ V	+Voltage = <u>14.8</u> V	
		$-14.8 \pm 0.05$ V	-Voltage = <u>-14.8</u> V	
		$57.290344 \pm .0002$ GHz	Freq. = <u>57.290344</u> GHz	
		17 to 20 dBm	P = <u>18.18</u> dBm	
15	Spurious and Sub	-200 to -90 dBc	<u>see plots</u>	✓
16	Power level of 114.58 GHz signal	<-10 dBm	<u>-39.33</u> dBm	Pass
17	Load VSWR and Frequency Pulling			
	2:1 mismatch over $1\lambda$	N/A	Worst Case Freq = <u>7</u> Hz	N/A
	2:1 mismatch over $1\lambda$	N/A	Worst Case Power = <u>1.0</u> dB Peak	N/A
18	Operating Temperature @ $1^\circ\text{C}$ baseplate	TC1 = $1 \pm 2^\circ\text{C}$	TC1 = <u>2.7</u> $^\circ\text{C}$	Pass
			TC2 = <u>2.3</u> $^\circ\text{C}$	N/A
			TC3 = <u>1.9</u> $^\circ\text{C}$	N/A
		0 - 1V	DRO L/A = <u>71.8</u> mV	Pass
		S/N: F06, F07, F08 = $14.6 \pm 0.4$ V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.53</u> V	Pass
19	Input Voltage and Current			
		VM1 Voltage	VM1 = <u>15.0</u> V	
		VM2 Voltage	VM2 = <u>-15.0</u> V	
		IM1 Current	IM1 = <u>508</u> mA	
		IM2 Current	IM2 = <u>62</u> mA	
		DRO L/A Voltage	DRO L/A = <u>71.8</u> mV	
		PLO L/A Voltage	PLO L/A = <u>4.53</u> V	
		RF Output Power	Power = <u>19.09</u> dBm	
	Frequency	57.290344 $\pm .0002$ GHz	Freq. = <u>57.290344</u> GHz	Pass

CL 30. Odd  
RL Odd

MKR - 83DBE  
57-29033GHN



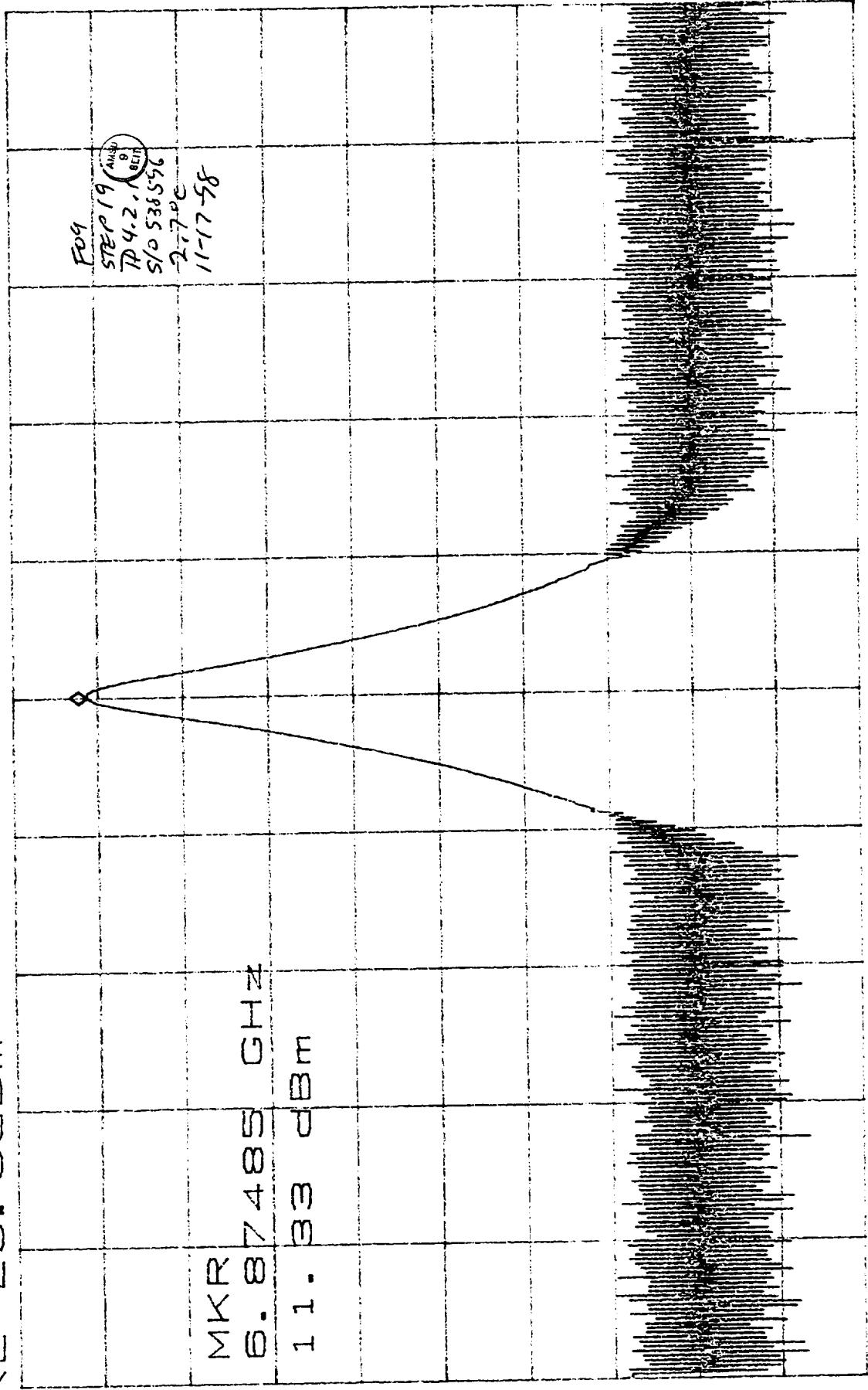
CENTER 57.29034GHz  
RBW 300kHz \*VBW 31

ATTEN 30dB  
RL 20. 0dBm

MKR 11. 33dBm

6. 87485GHz

10dB/  
RL

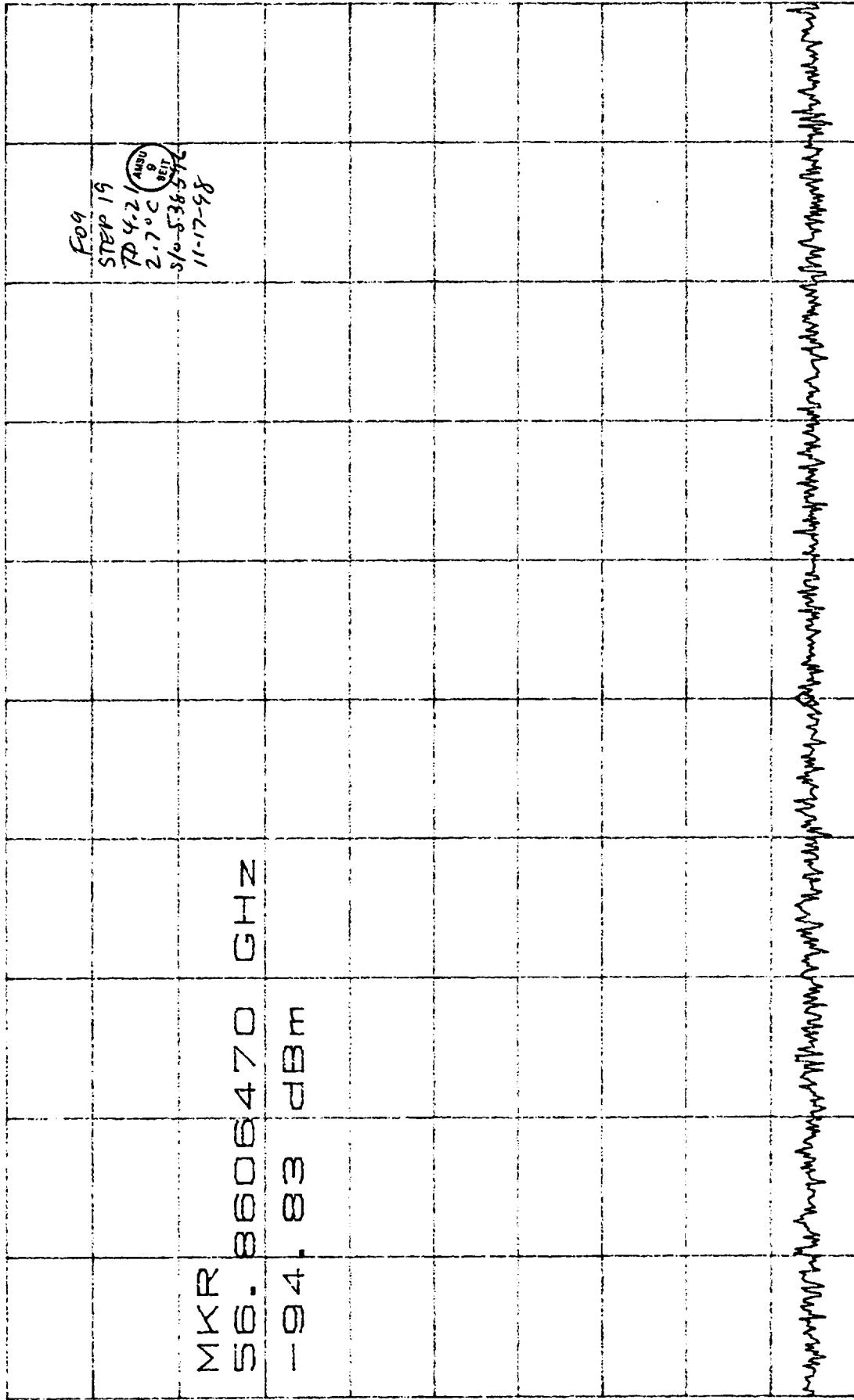


CENTER 6. 87485GHz  
\*RBW 300KHz VBW 300KHz

SPAN 20. 00MHz SWP 50. 0ms

CL 30.0dB V AVG 3  
RL 0dB / 10dB

MKR -94.83dBm  
56.8606470GHz



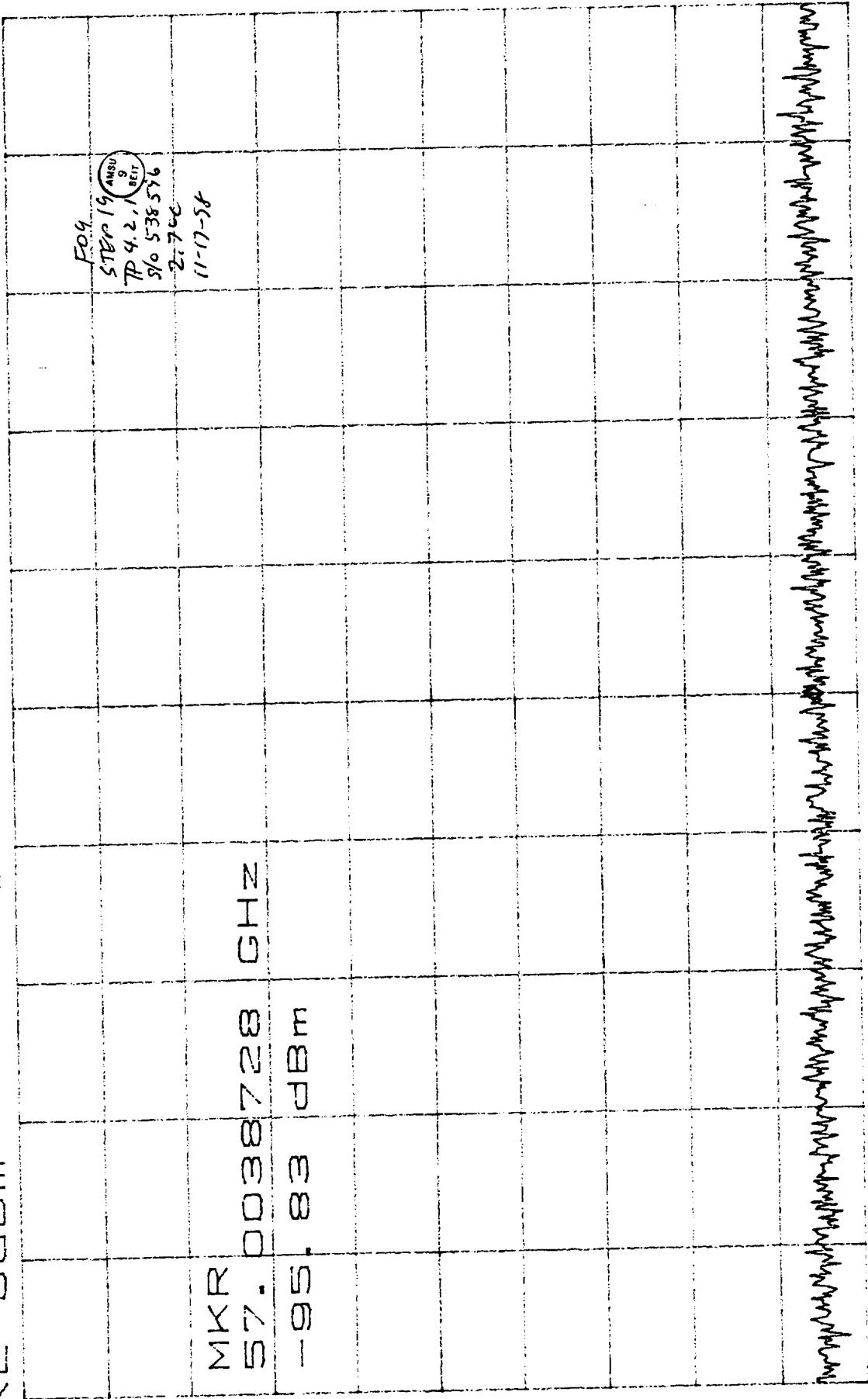
CENTER 56.8606470GHz \*VBW 1.0kHz  
\*RBW 3.0kHz \*SWP 2.00sec

SPAN 500.0kHz

CL 30.0dB  
RL 0dBm

VAVG 2  
10dB/  
RL 0dBm

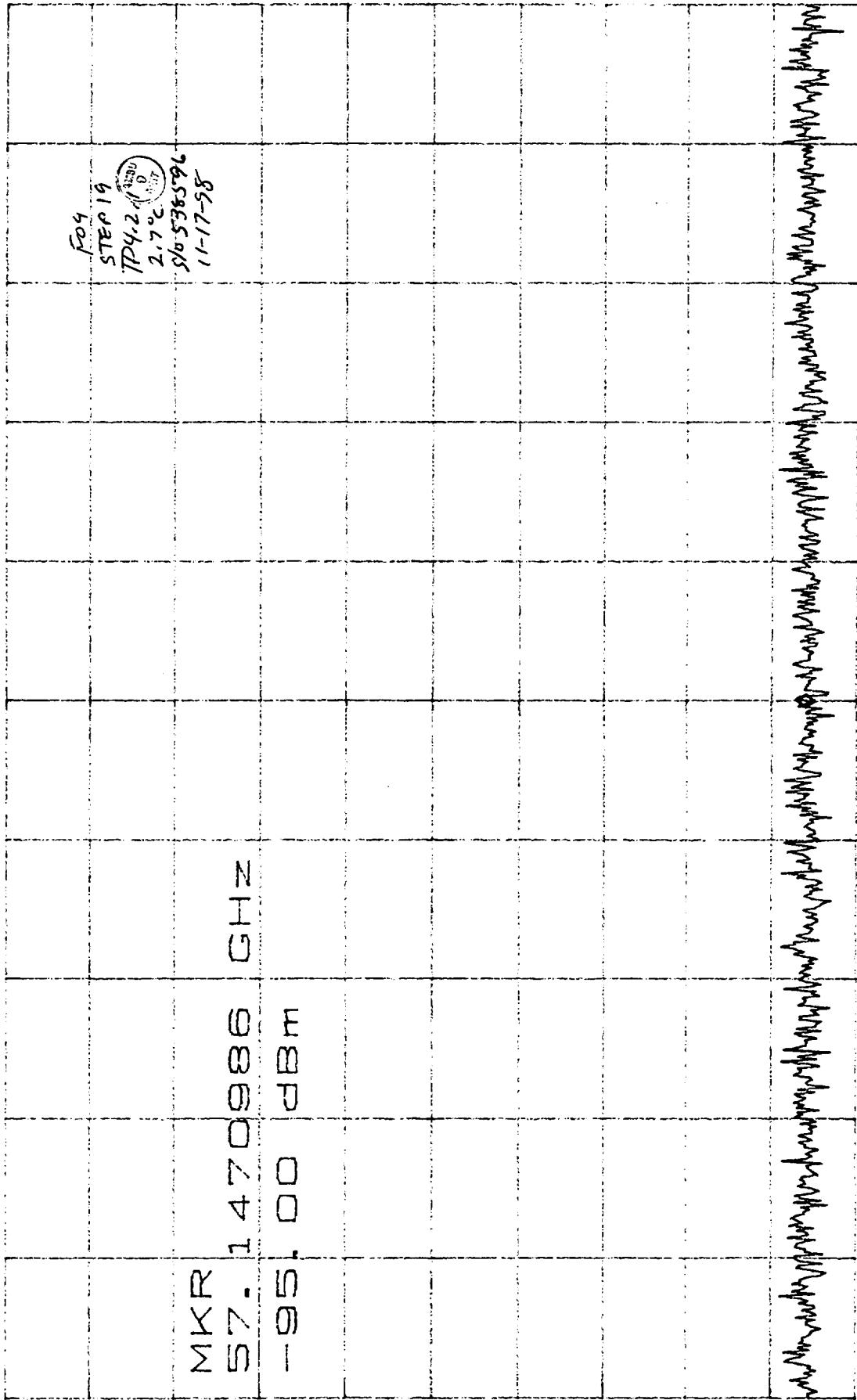
MKR -95.83dBm  
57.0038728GHz



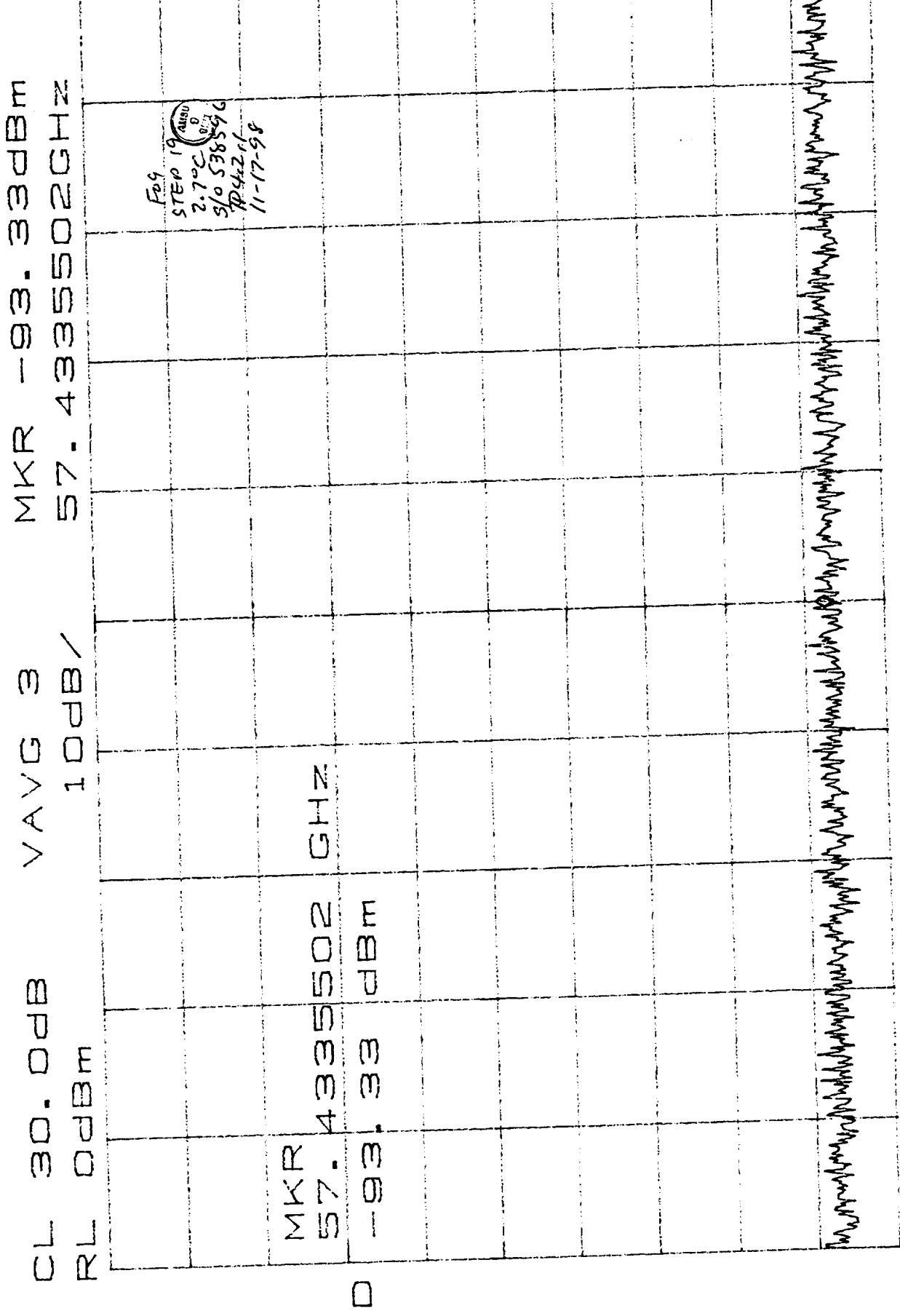
CENTER 57.0038728GHz \*VBW 1.0kHz  
\*RBW 3.0kHz \*SPAN 500.0kHz  
\*SWP 2.00sec

CL 30.0dB VAVG 2  
RL 0dBm

MKR -95.00dBm  
57.1470986GHz



CENTER 57.1470986GHz  
\*RBW 3.0KHz \*VBW 1.0KHz  
SPAN 500.0KHz  
\*SWP 2.00sec

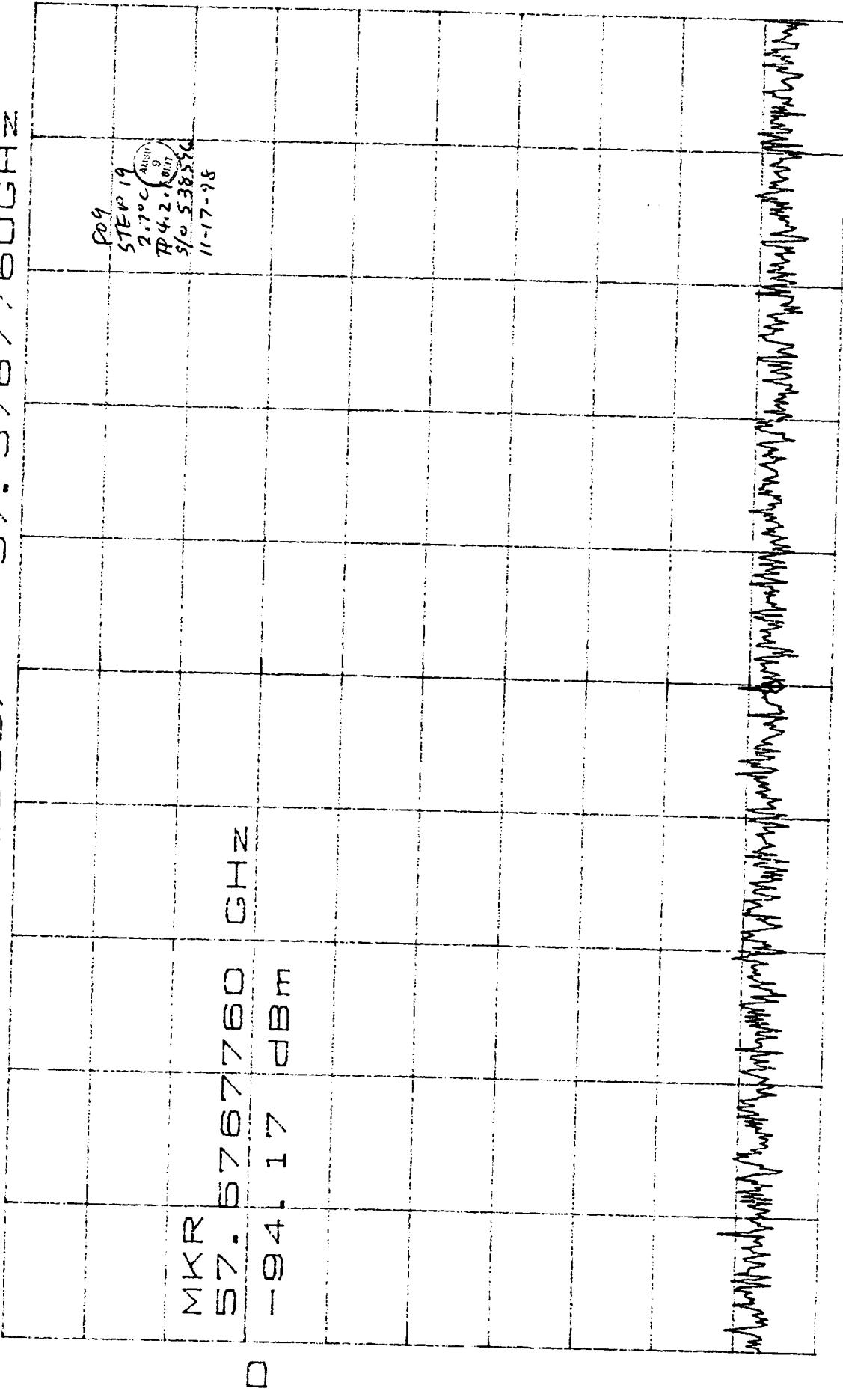


SPAN 500. 0kHz  
 CENTER 57. 4335502GHz \*RBW 3. 0kHz \*SWP 2. 00sec  
 \*RBW 3. 0kHz \*VBW 1. 0kHz

CL 30.0dB  
RL 0dBm

VAVG 2  
10dB/

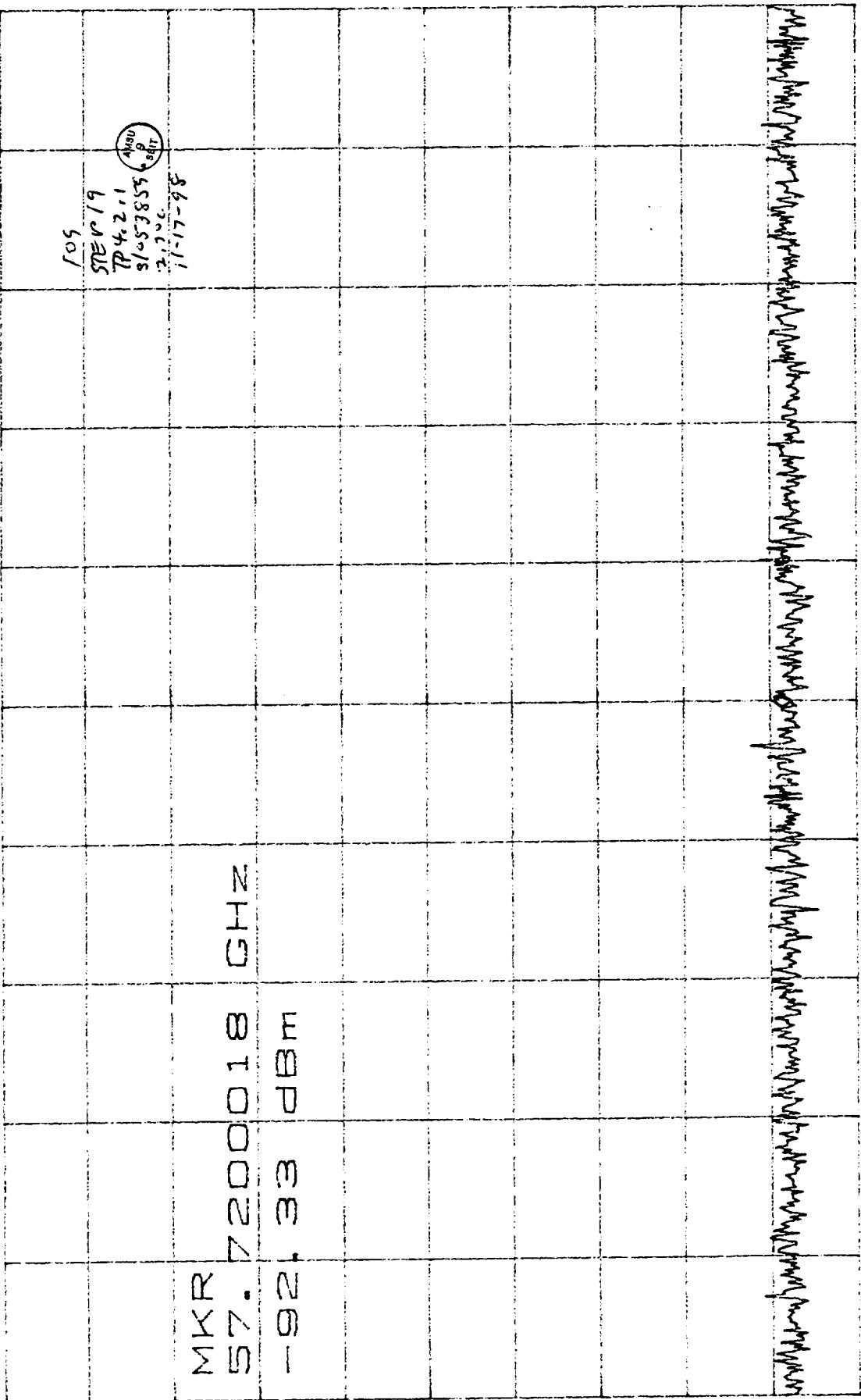
MKR -94.17dBm  
57.5767760GHz



CENTER 57.5767760GHz  
\*RBW 3.0kHz \*VBW 1.0kHz  
SPAN 500.0kHz  
\*SWP 2.00sec

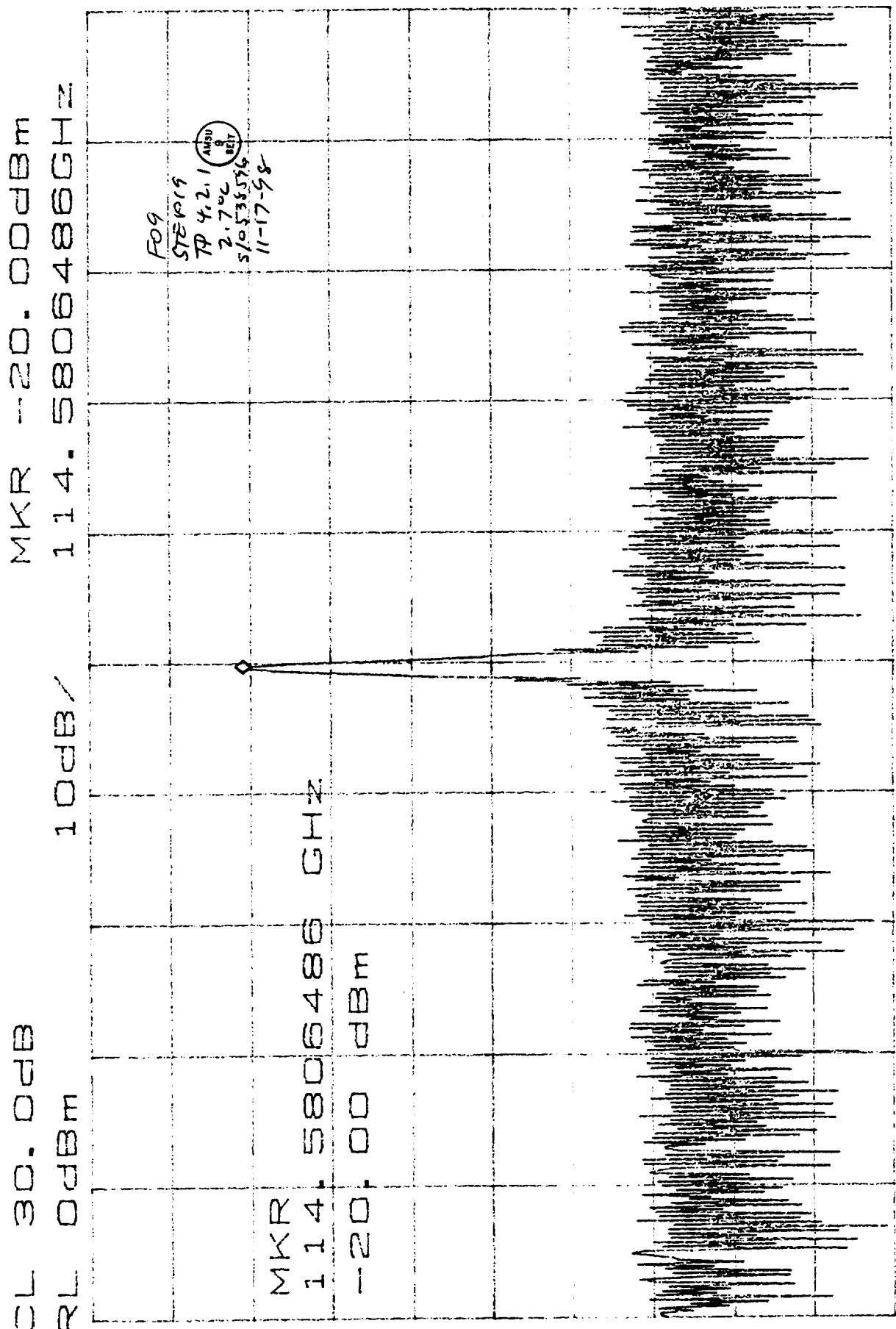
CL 30. DBB V AVG 2  
RL DBM 10DB

MKR-92-33DBE  
57-7200018CHN



□

CENTER 57.7200018GHz SPAN 500.0kHz  
\*RBW 3.0Hz \*VBW 1.0kHz \*SWP 2.00sec



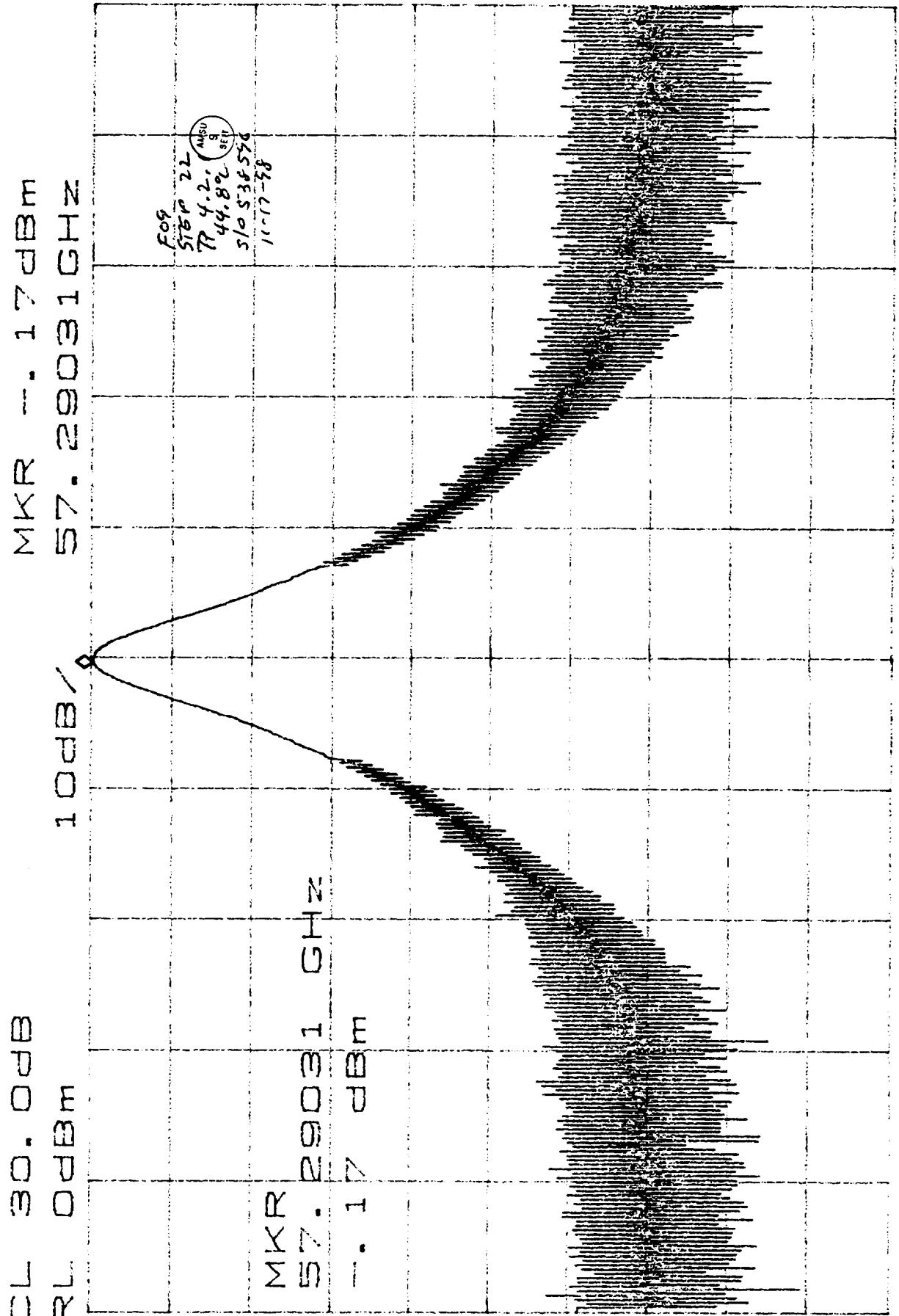
CENTER 114. 5806488GHz \*VBW 1. 0kHz \*RBW 300Hz  
 SPAN 100. 0kHz \*SWP 2. 80sec

TEST DATA SHEET 6C (Sheet 3 of 4)  
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

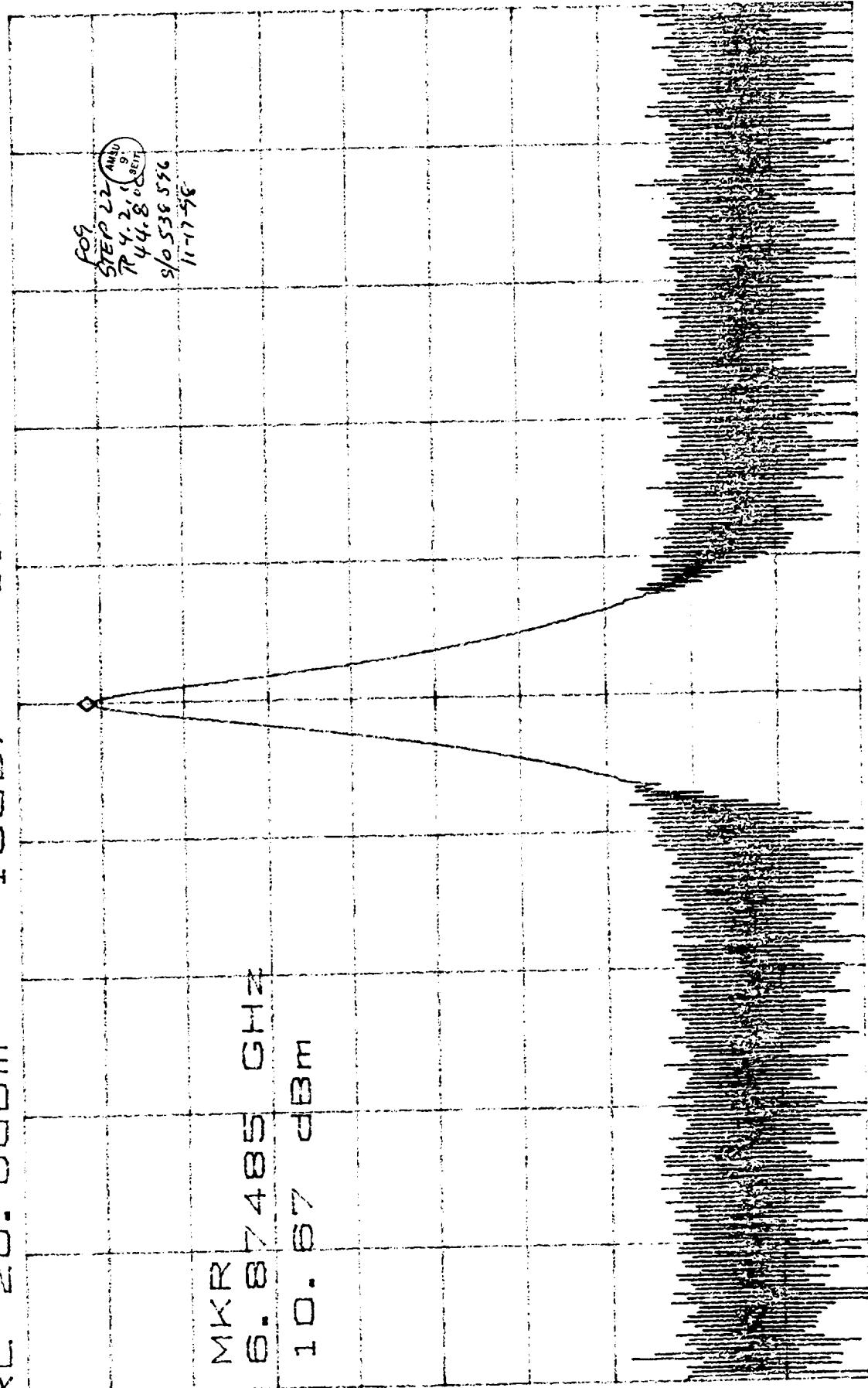
Step	Test	Expected	Measured	Pass/ Fail
19 (Cont)	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+15.2 $\pm$ 0.05 V	+Voltage = <u>15.2</u> V	<u>Pass</u>
		-15.2 $\pm$ 0.05 V	-Voltage = <u>-15.2</u> V	
		57.290344 $\pm$ .0002 GHz	Freq. = <u>57.290344394</u> GHz	
		17 to 20 dBm	Power = <u>18.62</u> dBm	
	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+14.8 $\pm$ 0.05 V	+Voltage = <u>+14.8</u> V	
		-14.8 $\pm$ 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 $\pm$ .0002 GHz	Freq. = <u>57.2903424236</u> GHz	
		17 to 20 dBm	Power = <u>18.62</u> dBm	
	Spurious and Sub	-200 to -90 dBc	<u>See plots</u>	
	Power level of 114.58 GHz signal	<-10 dBm	<u>-20</u> dBm	<u>Pass</u>
Load VSWR and Frequency Pulling				
	2:1 mismatch over 1 $\lambda$	N/A	Worst Case Freq = <u>6.6</u>	N/A
	2:1 mismatch over 1 $\lambda$	N/A	Worst Case Power = <u>0.7</u> dB	N/A
21	Operating Temperature @ +44°C Baseplate	TC1 = 44 $\pm$ 2°C	TC1 = <u>44</u> °C	<u>Pass</u>
			TC2 = <u>43.9</u> °C	N/A
			TC3 = <u>43.8</u> °C	N/A
		0 - 1V	DRO L/A = <u>139</u> mV	<u>Pass</u>
		S/N: F06, F07, F08 = 14.6 $\pm$ 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.54</u> V	
22	Input Voltage and Current			
	VM1 Voltage	+15 $\pm$ 0.1 V	VM1 = <u>15.0</u> V	
	VM2 Voltage	-15 $\pm$ 0.1 V	VM2 = <u>-15.0</u> V	
	IM1 Current	600 mA max.	IM1 = <u>534</u> mA	
	IM2 Current	100 mA max.	IM2 = <u>-65</u> mA	
	DRO L/A Voltage	0 to 1V	DRO L/A = <u>140</u> mV	
	PLO L/A Voltage	S/N: F06, F07, F08 = 14.6 $\pm$ 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u>4.54</u> V	
	RF Output Power and Frequency	17 to 20 dBm	Power = <u>17.66</u> dBm	
			Freq. = <u>57.290325503</u> GHz	<u>Pass</u>



CENTER 57. 29034GHz  
 \*RBW 300kHz VBW 300kHz  
 SPAN 10. 00MHz \*SWP 50. 0ms

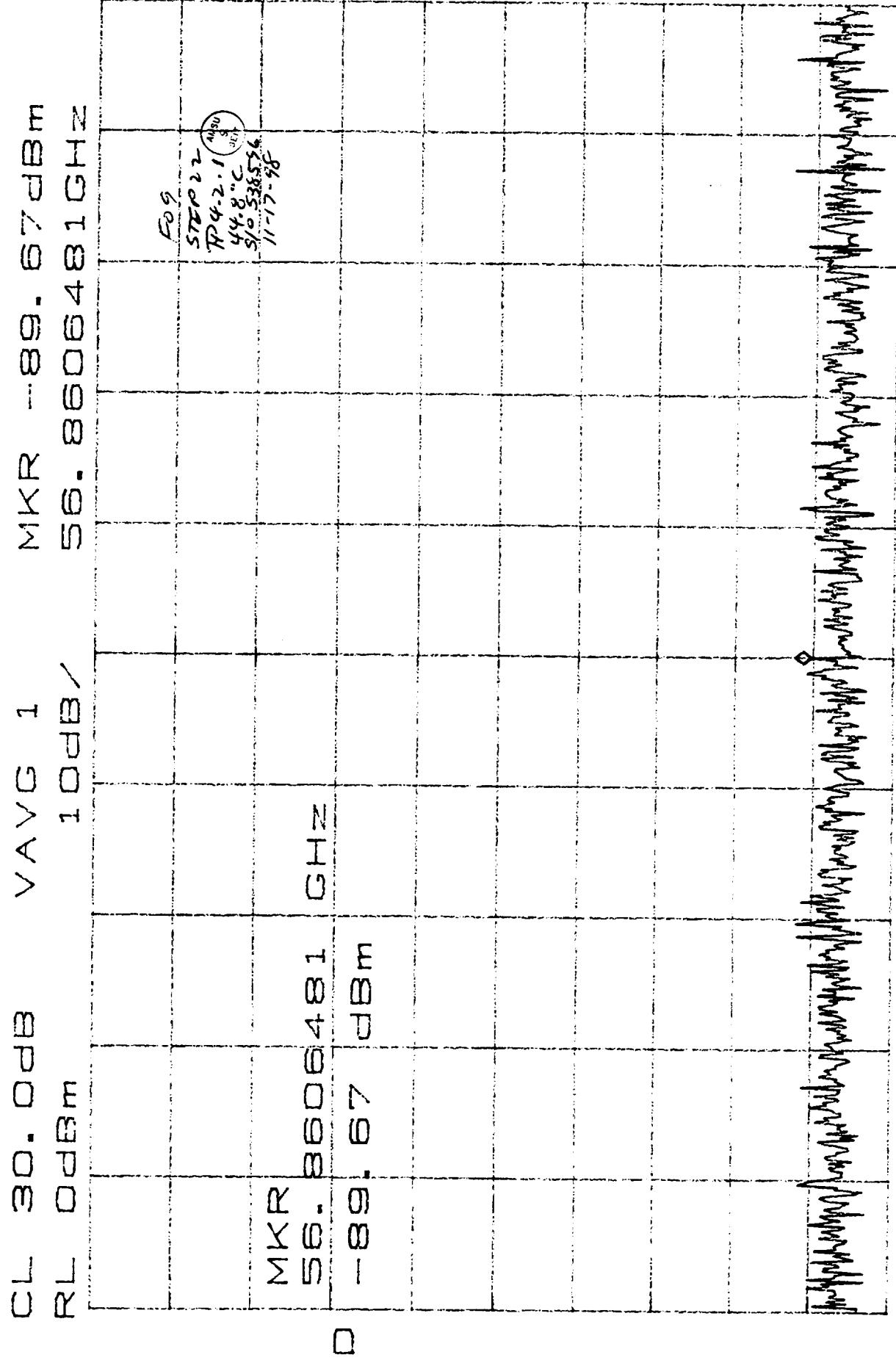
ATTEN 30dB  
RL 20.0dBm

MKR 10.67dBm  
6.87485GHz



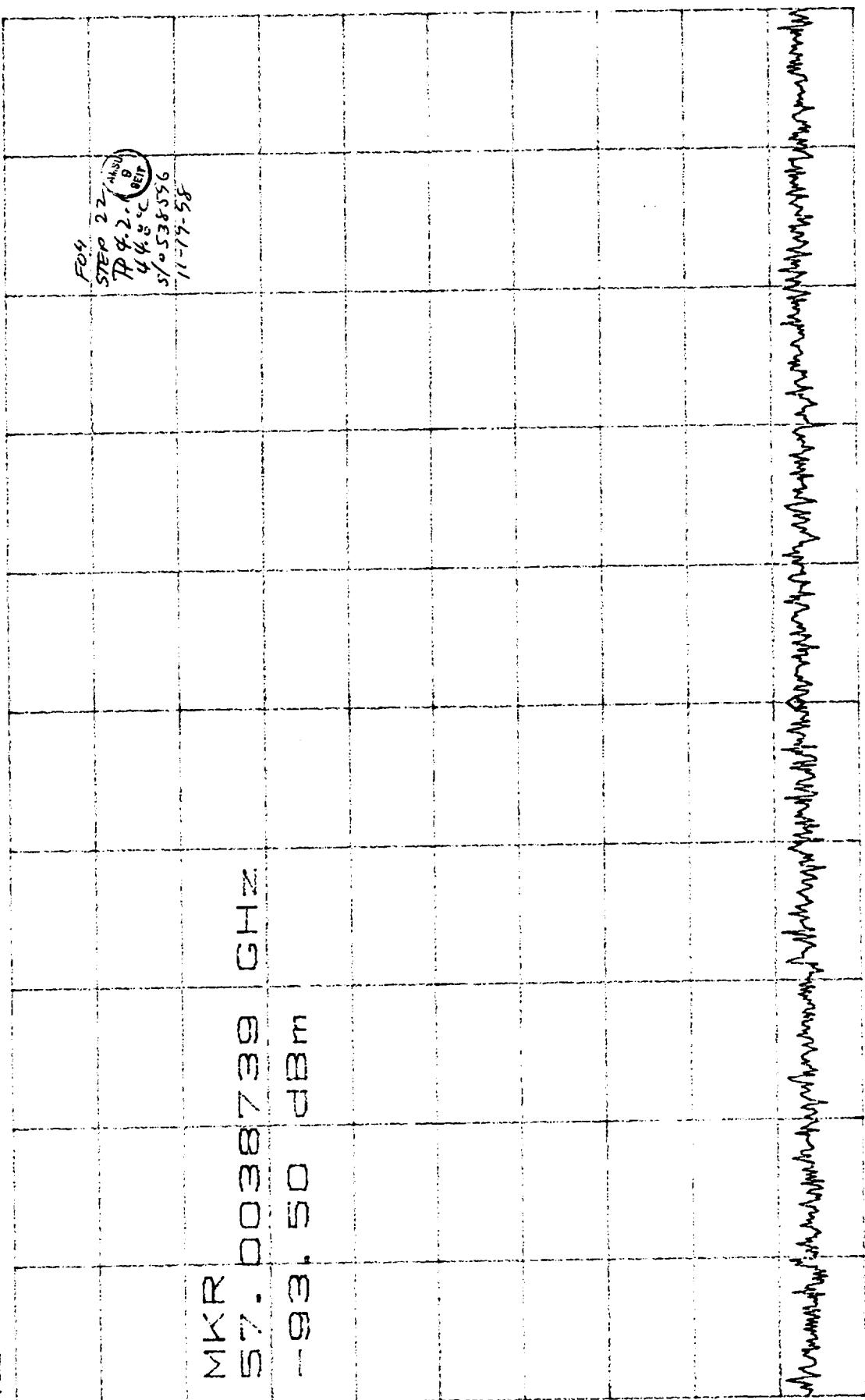
CENTER 6.87485GHz  
RBW 100kHz VBW 100kHz

SPAN 10.00MHz  
SWP 50.0ms



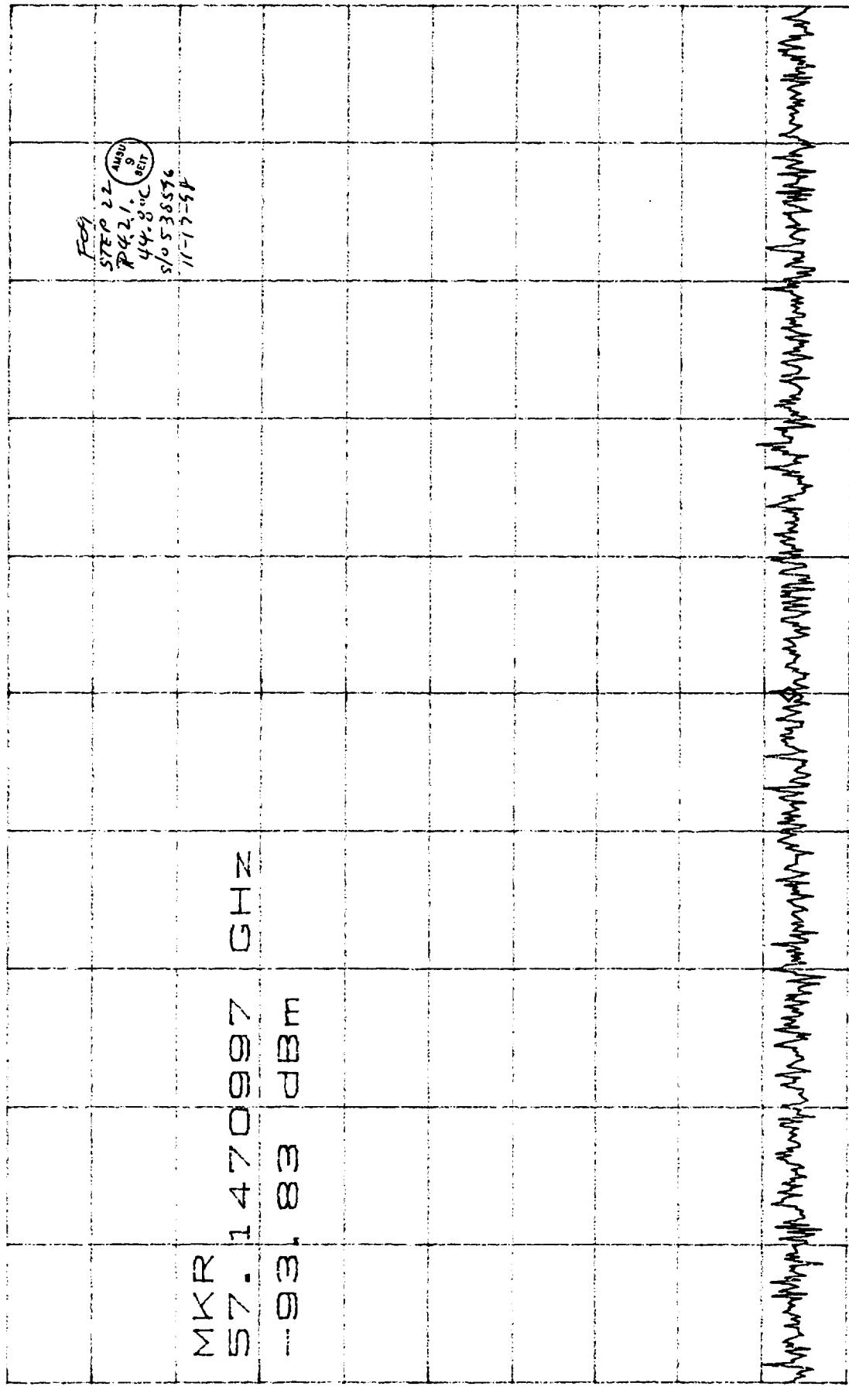
SPAN 500.0KHz  
CENTER 57.0038739GHz \*VSW 1.0KHz  
RBW 3.0KHz

CL 30.0dB VAVG 3 MKR --93.50dBm  
RL 0dBm 57.0038739GHz



CL 30.0dB VAVG 2  
RL 0dBm

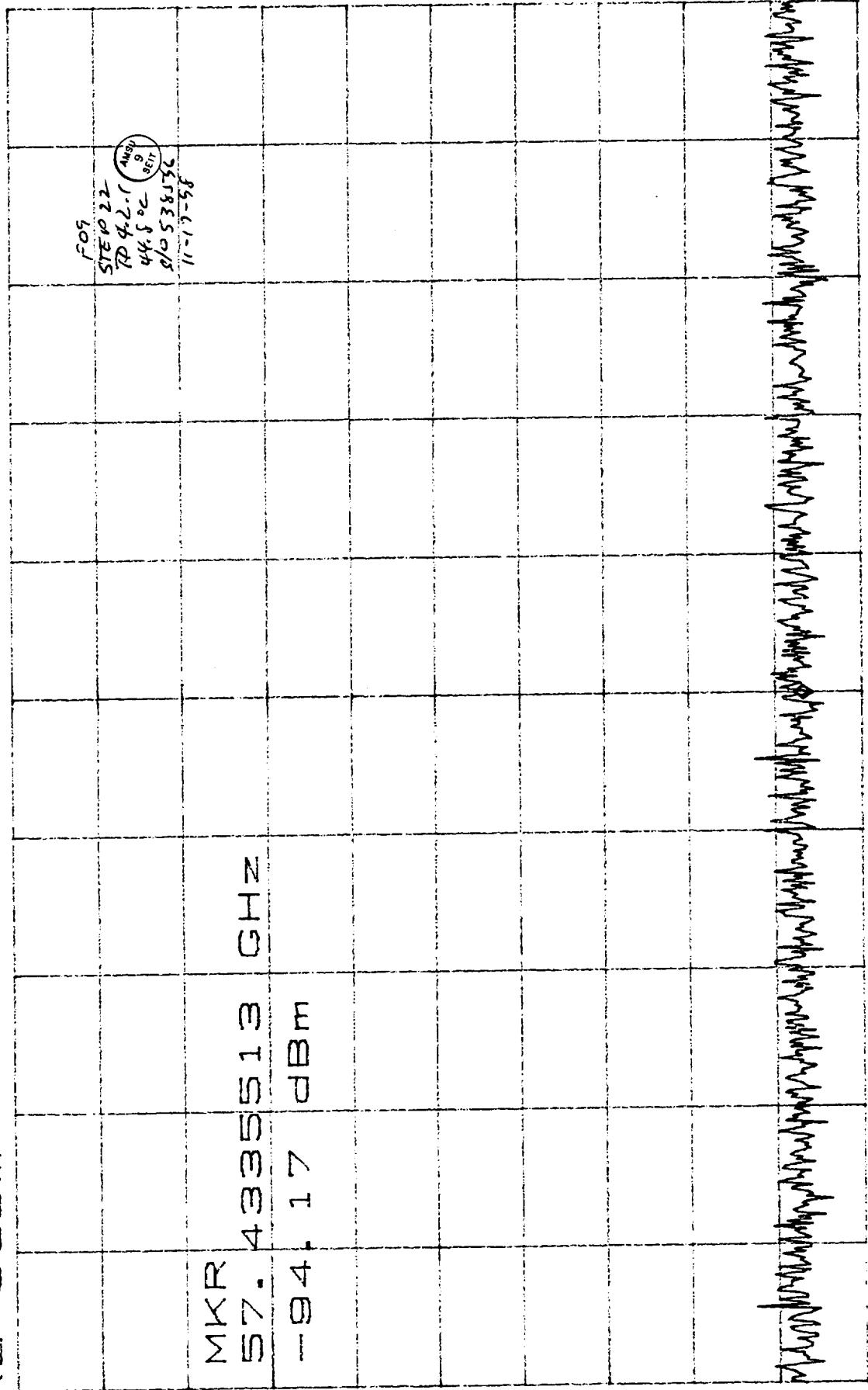
MKR -93.83dBm  
57.1470997GHz



CENTER 57.1470997GHz  
RBW 3.0kHz \*VBW 1.0kHz  
SPAN 500.0kHz \*SWP 2.00sec

CL 30.0dB  
RL. 0dBm

VAVG 2  
10dB/  
MKR -94.17dBm



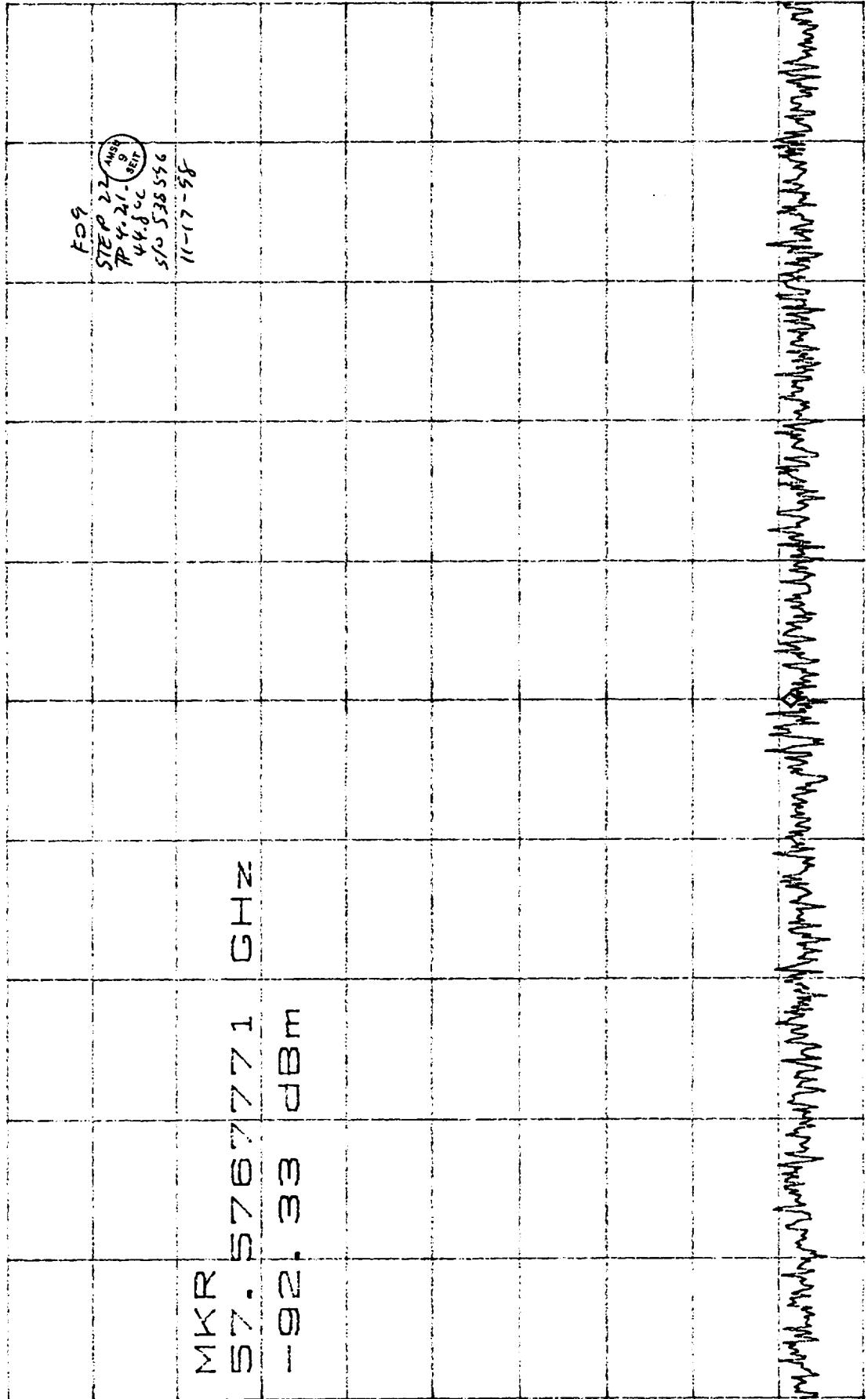
□

CENTER 57.4335513 GHz  
RBW 3.0kHz \*VBW 1.0kHz  
SPAN 500.0kHz  
\*SWP 2.00sec

SPAN 500.0kHz

CL 30.0dB VAVG 2 10dB/  
RL 0dBm

MKR -92.33dBm  
57.5767771GHz

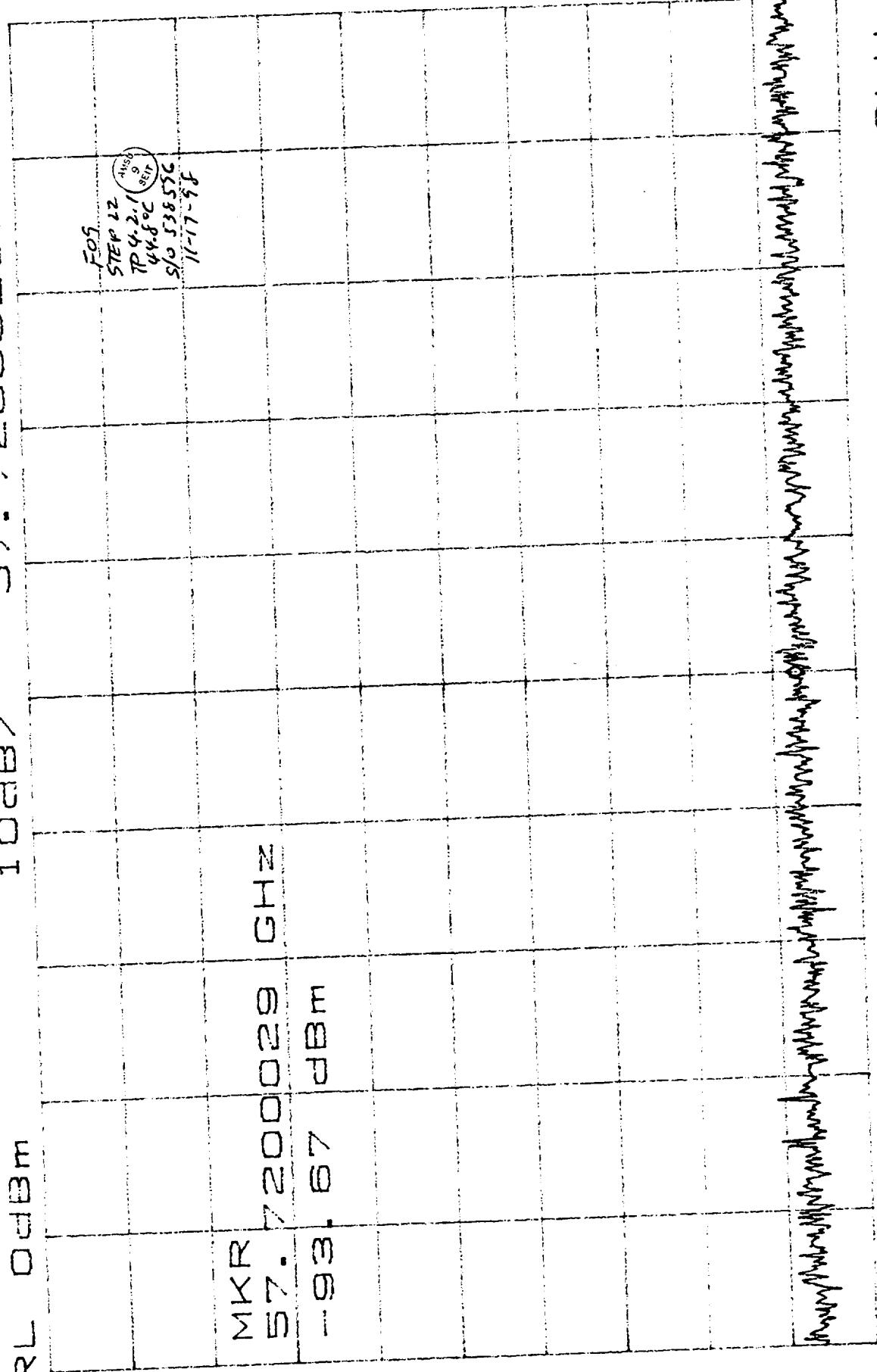


□

CENTER 57.5767771GHz \*VBW 1.0kHz SPAN 500.0kHz  
RBW 3.0kHz \*SWP 2.00sec

CL 30.0dB  
RL 0dBm

MKR -93. 67dBm  
57. 7200029GHz



CENTER 57.7200029GHz \*RBW 3.0kHz  
SPAN 500.0kHz \*\*SWP 2.00sec

CL 30. 0dB

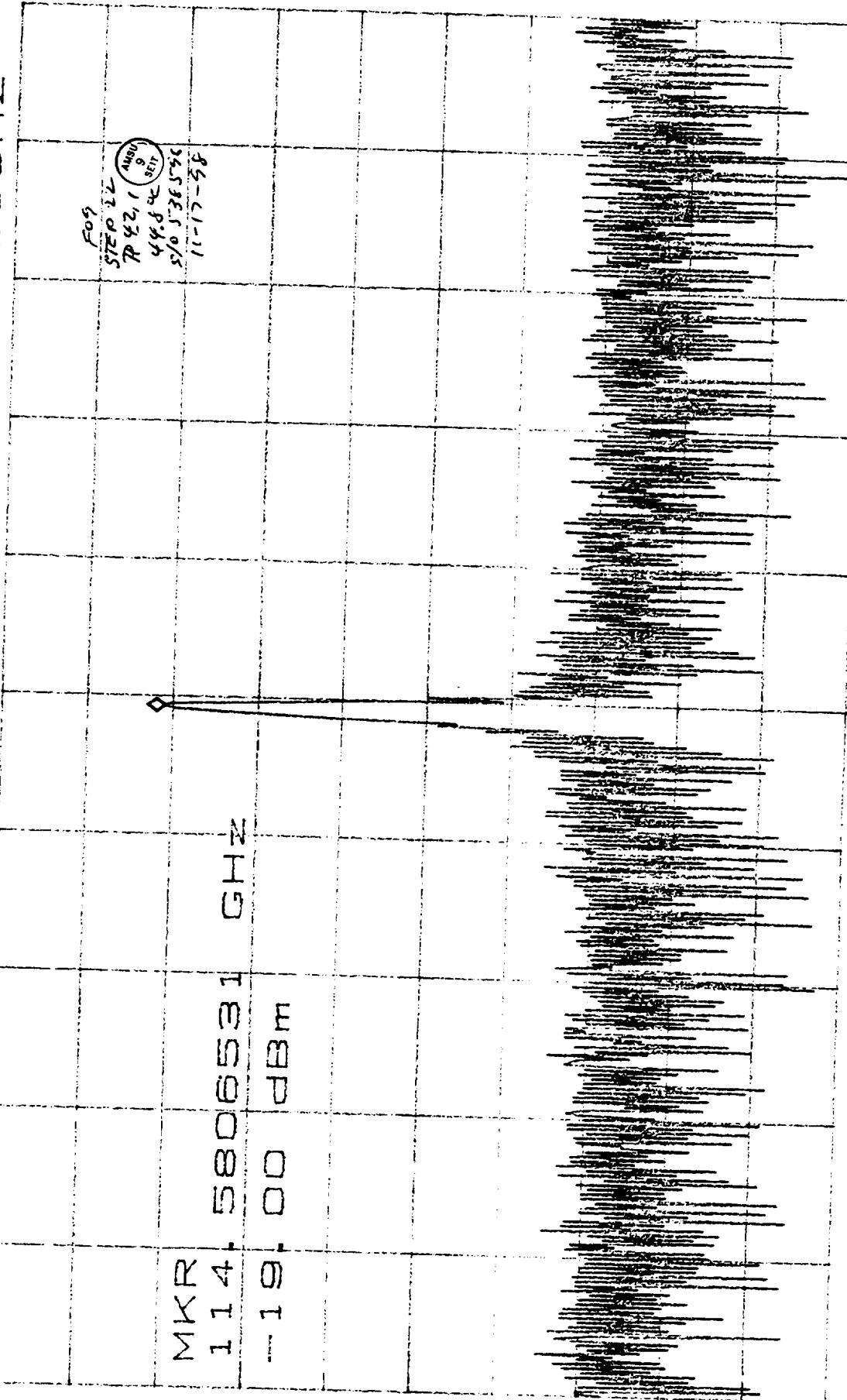
RL 0dBm

MKR

-19. 00dBm

114.

5806531GHz



CENTER 114.5806538GHz  
\*RBW 300Hz \*\*VBW 1.0kHz

SPAN 100.0kHz  
\*SWP 2.80sec

TEST DATA SHEET 6C (Sheet 4 of 4)  
Functional Testing (Paragraph 4.2.1)

## Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
22 (Cont)	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+15.2 $\pm$ 0.05 V	+Voltage = <u>15.2</u> V	Pass
		-15.2 $\pm$ 0.05 V	-Voltage = <u>-15.2</u> V	↑
		57.290344 $\pm$ .0002 GHz	Freq. = <u>57.290325594</u> GHz	
		17 to 20 dBm	Power = <u>17.36</u> dBm	
	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+14.8 $\pm$ 0.05 V	+Voltage = <u>14.8</u> V	
		-14.8 $\pm$ 0.05 V	-Voltage = <u>-14.8</u> V	
		57.290344 $\pm$ .0002 GHz	Freq. = <u>57.290344</u> GHz	
		17 to 20 dBm	Power = <u>17.58</u> dBm	
	Spurious and Sub	-200 to -90 dBc	see plots	
	Power level of 114.58 GHz signal	<-10 dBm	<u>-19</u> dBm	Pass
Load VSWR and Frequency Pulling				
2:1 mismatch over 1 $\lambda$	N/A	Worst Case Freq = <u>1 Hz</u>	N/A	
2:1 mismatch over 1 $\lambda$	N/A	Worst Case Power = <u>1.0</u> dB	N/A	

Shop Order No.: 538596Operation: 0170Unit Serial No.: F09Date: 11-17-98Test Engineer: R. E. Quee 100704 18Quality Control: W. J. H. 100704 18Govt. Rep.: W. J. H. 100704 18



### Section 5B: Final Functional Testing - F10

This section contains the results of a full functional test over temperature taken after PLO F10 endured thermal cycling. All tests passed.



TEST DATA SHEET 6C (Sheet 1 of 4)  
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Test Setup Verified: J. Ruyard  
Signature

Paragraph 4.2.1.3, Functional Testing:

Step	Test	Expected	Measured	Pass/ Fail
1	Potential Difference from $\pm 15$ V RTN to:			
	PLO Base Plate	< 1.0 Vac	0.01 V	Pass
	Spectrum Analyzer	< 1.0 Vac	0.02 V	Pass
	Frequency Counter Chassis	< 1.0 Vac	0.06 V	Pass
4	Power Meter Chassis	< 1.0 Vac	0.02 V	Pass
	Evacuate vacuum chamber and record pressure	< $10^{-2}$ torr	Pressure = _____ torr	*
5	Thermal couple readings	TC1 = $22 \pm 2$ °C	TC1 = 23.4 °C	
			TC2 = 24.0 °C	N/A
			TC3 = 22.9 °C	N/A
6	DRO L/A	0 to 1V	DRO L/A = 73 mV	Pass
	PLO L/A	S/N: F06, F08 = $14.6 \pm 0.4$ V S/N: F07 = 0 to 1V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = 4.54 V	Pass
	Is PLO locked?	Yes	Yes <input checked="" type="checkbox"/>	Pass
7	PLO Frequency	$57.290344 \pm .0002$ GHz	Freq. = 57.290346129 GHz	Pass
	PLO Power	17 to 20 dBm	P = 17.9 dBm	Pass
8	Input Voltage and Current			
		+15 ± 0.1 V	VM1 = +15.18 V	Pass
		-15 ± 0.1 V	VM2 = -15.20 V	Pass
		600 mA max.	IM1 = 533 mA	Pass
		100 mA max.	IM2 = -70.2 mA	Pass
		0 to 1V	DRO L/A = 73 mV	Pass
		S/N: F06, F07, F08 = $14.6 \pm 0.4$ V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = 4.54 V	Pass
12	RF Output Power and Frequency	17 to 20 dBm	P = 17.9 dBm	Pass
		$57.290344 \pm .0002$ GHz	Freq. = 57.290346129 GHz	Pass
	Baseplate Temp. (TC1)	TC1 = $22 \pm 2$ °C	TC1 = 23.6 °C	Pass

\*Record data only if performing test under vacuum

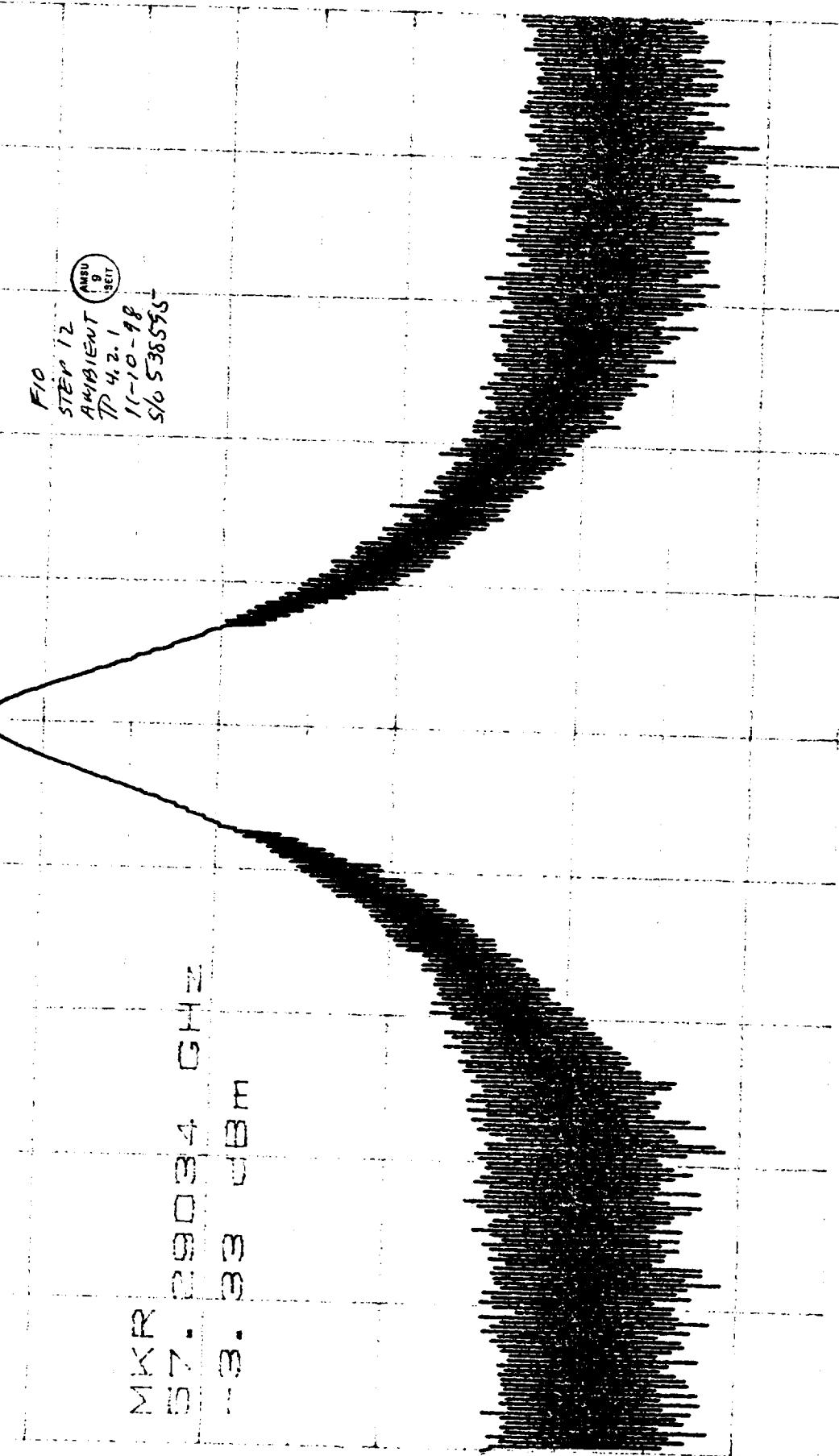
L 30.0 dBm  
R 1.0 dBm

MKR -3.33dBm  
57.29034GHz

MKR  
57.29034 GHz  
-3.33 dBm

10 dBm

F0  
STEP 12  
AMBIENT  
9  
7/4.2.1  
11-10-98  
S/N 538555



CENTER 57.29034GHz  
\*RBW 300kHz  
\*\*VBW 1.0MHz

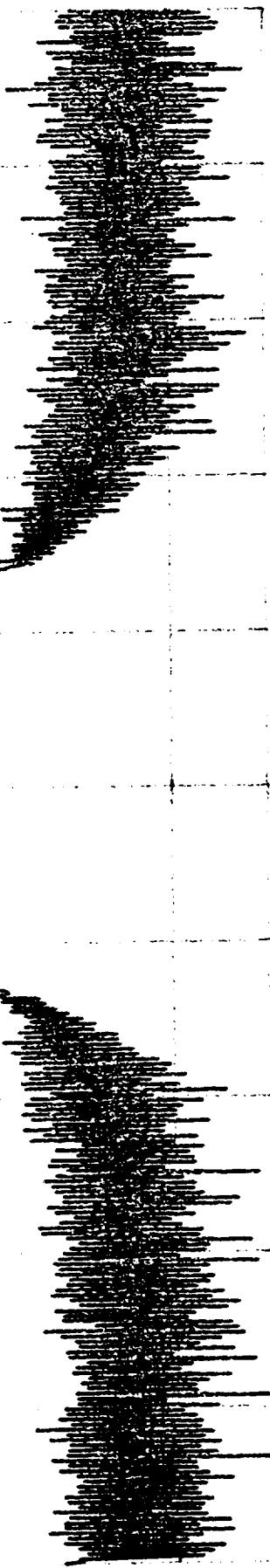
SPAN 10.00MHz  
SWP 50.0ms

ATTEN 30dB  
RL 20.0dBm

MKR 12.17 dBm  
6.874858 GHz

F10  
STEP 1/2  
AMBIENT  
ABU  
9  
TP 4.2-1  
1170-98  
5/6 536555

MKR  
6.874858 GHz  
12.17 dBm

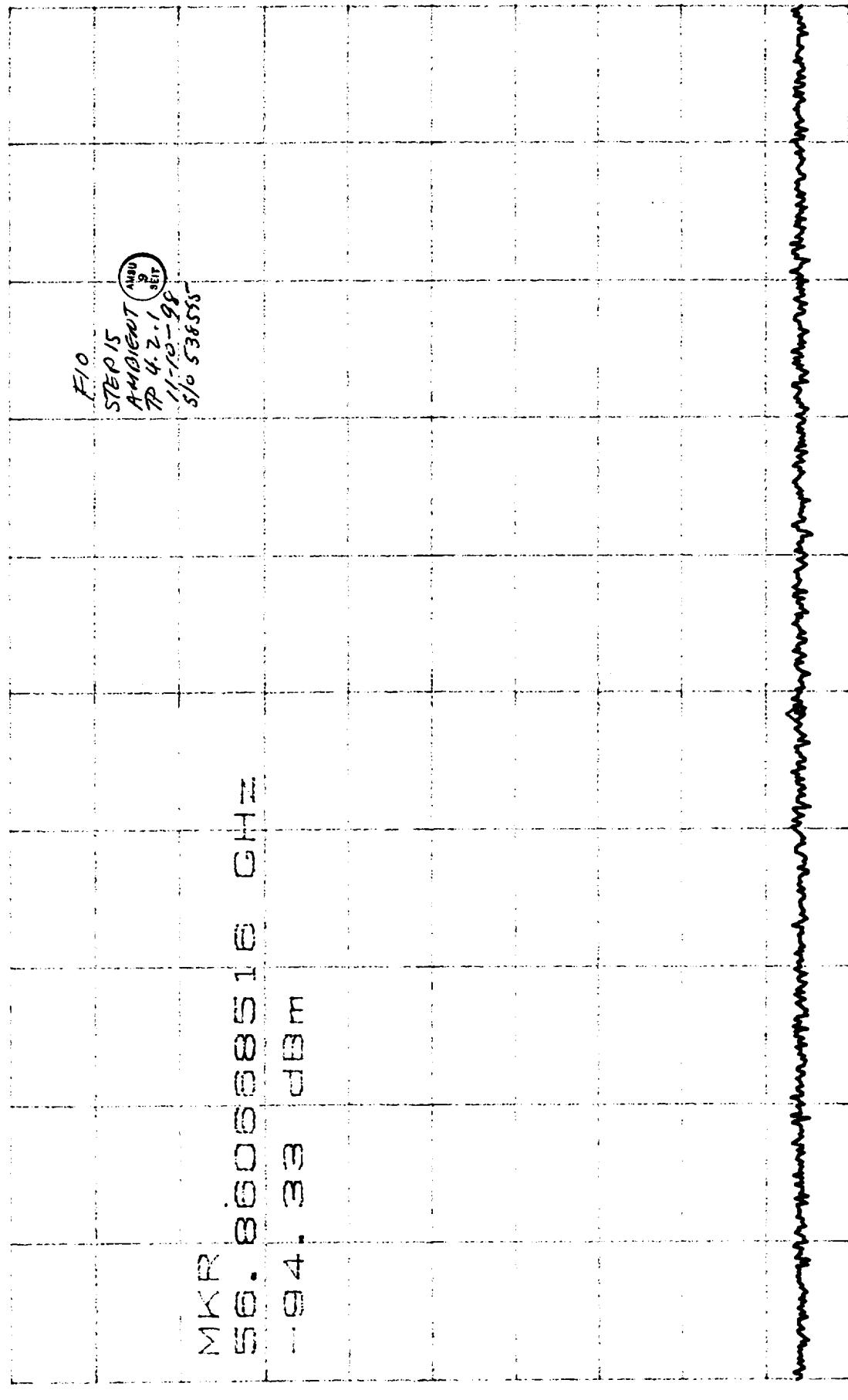


CENTER 6.874858 GHz VBW 100kHz  
\*RBW 100kHz

SPAN 5.000MHz  
SWP 50.0ms

CL 30.0 dB  
RL 0 dB

MKR -94.33 dBm  
56.360668516 GHz



CENTER 56.360668533 GHz \*VBW 3.0 kHz  
\*RBW 3.0 kHz SPAN 1.0000 kHz  
SWP 57.0 ms

MKR -93. 67 dBm  
57. 003894381 GHz

CL 30. 0 dB  
RL 0 dBm

VAVG 56

MKR  
57. 003894381 GHz  
-93. 67 dBm

F10

STEP 15  
AMBIENT <sup>AMBIENT</sup>  
TP 4.2.1  
11-10-96  
5/0 536595

SPAN 1. 000 kHz  
SWP 67. 0 ms

CENTER 57. 003894388 GHz  
\*RBW 3. 0 kHz

CL 30.0dB VAVG 68  
RL 0dBm

MKR -94.17dBm  
57.147120247GHz

MKR  
57.147120247 GHz  
-94.17 dBm

□

F10  
STEP 15  
D 4.2.1  
AMBIENT  
11-10-98  
S/N 538555

CENTER 57.147120264GHz \*VBW 3.0kHz  
x RBW 3.0kHz SPAN 1.000kHz

SWP 67.0ms

CL 30.0dB VAVG 26 MKR -94.67dBm  
RL 0dBm

MKR 57.433571977 GHz  
-94.67 dBm

D

FIO  
Step 15  
AUGMENT ANNU  
P.4.2.  
11-10-56  
9/15/58551

CENTER 57.433571994 GHz  
\*RBW 3.0kHz \*VBW 3.0kHz

SPAN 1.000 kHz  
SWP 67.0ms

CL 30.0dB VAVG 15 MKR -94.33dBm

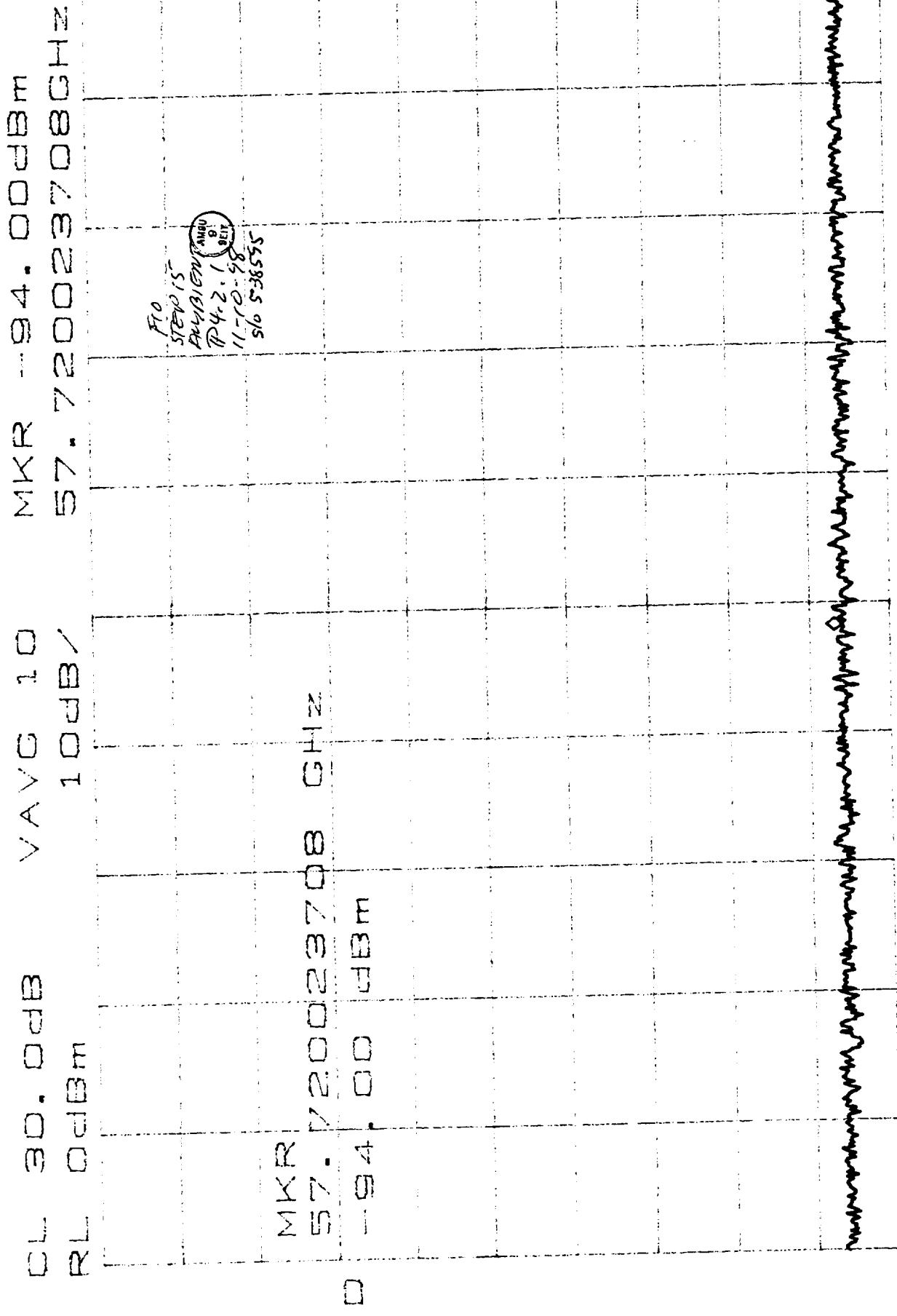
RL 0dBm 57.576797843GHz

MKR 57.576797843 GHz  
-94.33 dBm

D

50  
20.15  
AMBEN  
AUS  
D42.1  
9  
810  
1170-98-  
S/0 538595

CENTER 57.576797860GHz SPAN 1.000kHz  
\*RBW 3.0kHz \*VBW 3.0kHz SWP 67.0ms



SPAN 1.000kHz  
 CENTER 57.720023725GHz  
 \*RBW 3.0kHz \*VBW 3.0kHz  
 SWP 67.0ms

CL - 30.0 dB  
RL 0 dBm

MKR - 70. 33 dBm  
114. 580556 GHz

10 dBm

MKR  
114. 580556 GHz  
-70. 33 dBm

F10  
STEP 16 AMIG  
P 4.2.1  
AMBIGUITY  
1170.76  
S10536535

CENTER 114. 580556 GHz  
RBW 1.0 kHz  
\*\*VBW 1.0 kHz

SPAN 1.000 MHz  
SWP 2.50000

**TEST DATA SHEET 6C (Sheet 2 of 4)**  
**Functional Testing (Paragraph 4.2.1)**

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/ Fail
13	Frequency vs. Voltage			
	$\pm 15$ V Supplies	$+15.2 \pm 0.05$ V	+Voltage = <u><math>+15.20</math></u> V	Pass
	-	$-15.2 \pm 0.05$ V	-Voltage = <u><math>-15.20</math></u> V	Pass
	-	$57.290344 \pm .0002$ GHz	Freq. = <u><math>57.290346667</math></u> GHz	Pass
	-	17 to 20 dBm	P = <u><math>17.83</math></u> dBm	Pass
14	Frequency vs. Voltage			
	$\pm 15$ V Supplies	$+14.8 \pm 0.05$ V	+Voltage = <u><math>+14.80</math></u> V	Pass
	-	$-14.8 \pm 0.05$ V	-Voltage = <u><math>-14.80</math></u> V	Pass
	-	$57.290344 \pm .0002$ GHz	Freq. = <u><math>57.290354969</math></u> GHz	Pass
	-	17 to 20 dBm	P = <u><math>17.81</math></u> dBm	Pass
15	Spurious and Sub	-200 to -90 dBc	See Plot 5	Pass
16	Power level of 114.58 GHz signal	<-10 dBm	<u>-70.33</u> dBm	Pass
17	Load VSWR and Frequency Pulling			
	2:1 mismatch over $1\lambda$	N/A	Worst Case Freq = <u><math>4.6</math></u> Hz	N/A
	2:1 mismatch over $1\lambda$	N/A	Worst Case Power = <u><math>0.7</math></u> dB Peak	N/A
18	Operating Temperature @ $1^\circ\text{C}$ baseplate	TC1 = $1 \pm 2^\circ\text{C}$	TC1 = <u><math>1.7</math></u> $^\circ\text{C}$	
			TC2 = <u><math>2.4</math></u> $^\circ\text{C}$	N/A
			TC3 = <u><math>1.1</math></u> $^\circ\text{C}$	N/A
			DRO L/A = <u><math>1.60</math></u> mV	Pass
			PLO L/A = <u><math>4.55</math></u> V	Pass
19	Input Voltage and Current			
	VM1 Voltage	$+15 \pm 0.1$ V	VM1 = <u><math>+15.0</math></u> V	Pass
	VM2 Voltage	$-15 \pm 0.1$ V	VM2 = <u><math>-15.0</math></u> V	Pass
	IM1 Current	600 mA max.	IM1 = <u><math>520</math></u> mA	Pass
	IM2 Current	100 mA max.	IM2 = <u><math>~66.7</math></u> mA	Pass
	DRO L/A Voltage	0 to 1V	DRO L/A = <u><math>60</math></u> mV	Pass
	PLO L/A Voltage	S/N: F06, F07, F08 = $14.6 \pm 0.4$ V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = <u><math>4.55</math></u> V	Pass
	RF Output Power	17 to 20 dBm	Power = <u><math>18.75</math></u> dBm	Pass
	Frequency	$57.290344 \pm .0002$ GHz	Freq. = <u><math>57.290339351</math></u> GHz	Pass

L 30. 0dB  
RL 0dBm

MKR -3. 00dBm  
57. 29034GHz

10dB

MKR  
57. 29034GHz  
-3. 00 dBm

F10  
STEP 19  
P42.11  
11-00C  
11-0-95  
S10538535

CENTER 57. 29034GHz  
\*RBW 300kHz VBW 300kHz SPAN 10. 00MHz  
SWP 50. 0ms

ATTEN 30dB  
RL 20.0dBm

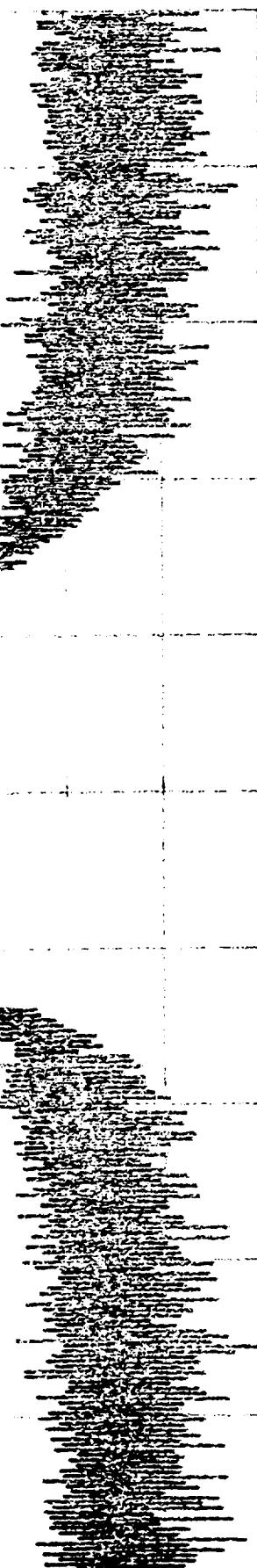
MKR 12.50dBm

6.874850GHz

10dB

MKR  
6.874850GHz  
12.50dBm

F10  
STW 19  
TP 4.2.1  
AMSU  
1.0.0C  
9  
REIT  
11-10-58  
S/N 538555



CENTER 6.874850GHz VBW 100kHz  
\*RBW 100kHz

SPAN 5.000MHz  
SWP 50.0ms

CL 30.0dBm V AVG 16 10dB/  
RL 0dBm

MKR -94.00dBm  
55.860661789GHz

PC  
1°C  
P4.2.1  
STEP 1/16  
11-10-98  
S/N 538555

MKR  
55.860661789GHz  
-94.00 dBm

□

CENTER 55.860661806GHz \*VBW 3.0kHz  
\*REF 3.0kHz SWF 67.0ms  
SPAN 1.000kHz

CL 30.0dB MKR -92.50dBm

VAVG 37 10dB/<sup>1</sup>

RL 0dBm

MKR 57.003888154 GHz  
-92.50 dBm

F10  
STEP 19  
PQ2.1  
1000-  
11-10-58  
3/0536555

CENTER 57.003888154 GHz SPAN 1.000kHz  
\*RBW 3.0kHz \*VBW 3.0kHz SWP 67.0ms

CL -30. 0dB  
RL 0dBm  
VAVG 25  
10dB/  
MKR -93. 33dBm  
57. 147113503GHz

MKR  
57. 147113503 GHz  
-93. 33 dBm

F10  
57019  
P. 4.2.  
100  
11-10-58  
3/6 33555

CENTER 57. 147113503GHz \*RBW 3. 0kHz SPAN 1. 000kHz  
\*RBW 3. 0kHz SWP 67. 0ms

MIXR - 57. 67 dBm  
57. 433565199GHZ

CL - 30. 0dB  
RL - 0dBm  
VAVG 13  
10dB

MIXR  
57. 433565199 GHZ  
- 94. 67 dBm

Fro  
Loc  
STEP 19  
AUX  
P 42. 1  
11-10-98  
S/N 538375

CENTER 57. 433565199GHZ  
\*RBW 3. 0KHz \*VBW 3. 0KHz  
SPAN 1. 000KHz  
SWP 67. 0ms

CL 30.0483  
X 10483m

WAVS 10

MKR 102.50483m  
ES 7.5787910483m

CL 30.0483  
X 10483m  
MKR 102.50483m  
ES 7.5787910483m

PRO  
1°C  
STEP 19  
P4.2.1  
11-10-98  
861  
S6 536555

CENTER 57.5787910483m  
\*RE3W 3.0483m  
DIRECTION \*VIB W 3.0483m

SPAN 1.000483m  
SWP 67.0m

CU 30. Oct 83 VAVCS 122

RL 0dBm MKR -93. 67 dBm

57. 720016896GHZ

FRO  
Aug 8  
1°C  
STEP 1/  
P4.2.1  
11-10-88  
96538555

MKR 720016896 GHZ  
-93. 67 dBm

C

SPAN 1 - COCHET HUE  
SWP 67. COMES

DENTER 57. 720016896GHZ  
\*RBW 3. DKEHUE \*\*VFBW 3. DKEHUE

CL 30. Oct 13

RIBW 0.0dBm

150dBm

MKR -59. 83dBm  
114. 580dBm

MKR  
114. 580dBm  
-59. 83 dBm

F10  
STEP 1.9 <sup>AUDIO</sup>  
TP 4.2.  
100  
11-10-98  
S1653555

CENTER 114. 580dBm  
\*RIBW 1. 0dBm \*VFBW 1. 0dBm

SPAN 1. 000MHz SWP 2. 50sec

TEST DATA SHEET 6C (Sheet 3 of 4)  
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/ Fail
19 (Cont)	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+15.2 ± 0.05 V	+Voltage = +15.23 V	Pass
		-15.2 ± 0.05 V	-Voltage = -15.23 V	Pass
		57.290344 ± .0002 GHz	Freq. = 57.29034337429 GHz	Pass
		17 to 20 dBm	Power = 18.2 dBm	Pass
	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+14.8 ± 0.05 V	+Voltage = +14.85 V	Pass
		-14.8 ± 0.05 V	-Voltage = -14.85 V	Pass
		57.290344 ± .0002 GHz	Freq. = 57.290333111 GHz	Pass
		17 to 20 dBm	Power = 18.6 dBm	Pass
20	Spurious and Sub	-200 to -90 dBc	see plots	Pass
	Power level of 114.58 GHz signal	<-10 dBm	~69 dBm	Pass
	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1λ	N/A	Worst Case Freq = 5 Hz	N/A
	2:1 mismatch over 1λ	N/A	Worst Case Power = 0.7 dB	N/A
21	Operating Temperature @ +44°C Baseplate	TC1 = 44 ± 2°C	TC1 = 43.3	
			TC2 = 43.2	N/A
			TC3 = 42.8	N/A
		0 - 1V	DRO L/A = 110 mV	Pass
		S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = 4.55 V	Pass
22	Input Voltage and Current			
	VM1 Voltage	+15 ± 0.1 V	VM1 = +15.0 V	Pass
	VM2 Voltage	-15 ± 0.1 V	VM2 = -15.0 V	Pass
	IM1 Current	600 mA max.	IM1 = 343 mA	Pass
	IM2 Current	100 mA max.	IM2 = 71.3 mA	Pass
	DRO L/A Voltage	0 to 1V	DRO L/A = 110 mV	Pass
	PLO L/A Voltage	S/N: F06, F07, F08 = 14.6 ± 0.4V S/N: F05, F09 - F14 = 4.3 to 4.7V	PLO L/A = 4.55 V	Pass
	RF Output Power and Frequency	17 to 20 dBm	Power = 17.1 dBm	Pass
			Freq. = 57.290341590 GHz	Pass

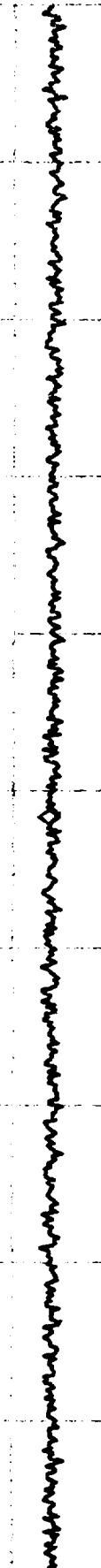
CL. 30. Oct 13  
RL. Oct 13m

VAVS 29

MKR - 94. 67 dBm  
56. 850554011 GHz

MKR  
56. 850554011 GHz  
- 94. 67 dBm

FRO  
STEP 22  
P4.2.1 AMBI  
9°  
44°C  
11-10-98  
S/O 538595



CENTER 56. 850554023 GHz \* VBW 3. 0 kHz  
\* FBW 3. 0 kHz SPAN 1. 000 kHz  
SWP 67. 0 ms

CL. 30. 0dB

VAVG 8

10dB/  
RL

MKR -94. 67dBm  
57. 00338865 GHz

MKR

57. 00338865 GHz  
-94. 67 dBm

FRO  
9700 22  
44. 6  
1025  
S/05338565

CENTER 57. 0kHz \*V3W 3. 0kHz  
\*R3W 3. 0kHz SPAN 1. 00001Hz

SPAN 1. 00001ms SWP 67. 0ms

CL 30.0dB VAVG 7  
RL 0dBm

MKR -93.33dBm  
S7. 147115719GHz

MKR  
S7. 147115719 GHz  
-93.33 dBm

D

F10  
STEP 22  
TP 4.2.  
44°C  
11-10-95  
S10 536555

CENTER S7. 147115736GHz  
\*RBW 3.0kHz \*VBW 3.0kHz  
SPAN 1.000kHz  
SWP 67.0ms

CL 30. DDE

VAVC 100

100dB

MKR -94. 50dBm

RL 0dBm

100dB

100dB

MKR  
-97. 433567427 GHz  
-94. 50dBm

Fo  
STEP 22  
TP 4.2.1 AMU  
44°C SEIT  
11-10-68  
S/0 538595

D

CENTER 57. 433567444.4 GHz  
\*RBW 3. 0kHz \*\*VBW 3. 0kHz

SPAN 1. 0000kHz  
SWP 67. 0ms

CH. 30. OUTS

VAVS 16

10WB/

MKR - 94. 50WB  
57. 575293281 GHI

RL. OUTB

MKR  
57. 575293281 GHI  
54. 50WB

Fro  
STEP 22  
ANSD  
9  
SEIT  
P 4.2.1  
44°C  
1170-98  
S/05365531

CENTER 55. 57529328GHI  
\*R3W 3. OUTB  
\*V3W 3. OUTB

SFPAN 1. 0000KHz  
SWP 67. OUT



GL 30. Dec 03

R1 50 dBm

1 Oct 03

T

NMR -69. 50 dBm  
114. 580690 GHz

NMR  
114. 580690 GHz  
-69. 50 dBm

PRO  
STEP 2.2  
RP 4.2.1  
44°C  
11-10-98  
310538565

CHINTAR 114. 580690 GHz  
xR13W 1. Oct 03  
SPAN 1. 000MHz  
SWP 2. 500e0

TEST DATA SHEET 6C (Sheet 4 of 4)  
Functional Testing (Paragraph 4.2.1)

Post-Thermal Cycling CPT

Paragraph 4.2.1.3 (Cont):

Step	Test	Expected	Measured	Pass/Fail
22 (Cont)	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+15.2 $\pm$ 0.05 V	+Voltage = <u>+15.24</u> V	Pass
		-15.2 $\pm$ 0.05 V	-Voltage = <u>-15.26</u> V	Pass
		57.290344 $\pm$ .0002 GHz	Freq. = <u>57.290342419</u> GHz	Pass
		17 to 20 dBm	Power = <u>17.1</u> dBm	Pass
	Frequency vs. Voltage			
	$\pm 15$ V Supplies	+14.8 $\pm$ 0.05 V	+Voltage = <u>+14.85</u> V	Pass
		-14.8 $\pm$ 0.05 V	-Voltage = <u>-14.84</u> V	Pass
		57.290344 $\pm$ .0002 GHz	Freq. = <u>57.290342793</u> GHz	Pass
		17 to 20 dBm	Power = <u>17.1</u> dBm	Pass
	Spurious and Sub	-200 to -90 dBc	see plots	Pass
	Power level of 114.58 GHz signal	<-10 dBm	<u>-69</u> dBm	Pass
	Load VSWR and Frequency Pulling			
	2:1 mismatch over 1 $\lambda$	N/A	Worst Case Freq = <u>0.5 Hz</u>	N/A
	2:1 mismatch over 1 $\lambda$	N/A	Worst Case Power = <u>0.6</u> dB	N/A

Shop Order No.: 538595

Operation: 0170

Unit Serial No.: F10

Date: 11-10-98

Test Engineer: AMSU  
9 SEPT

Quality Control: TA  
268 NOV 10 98

Govt. Rep.: 11/11/98

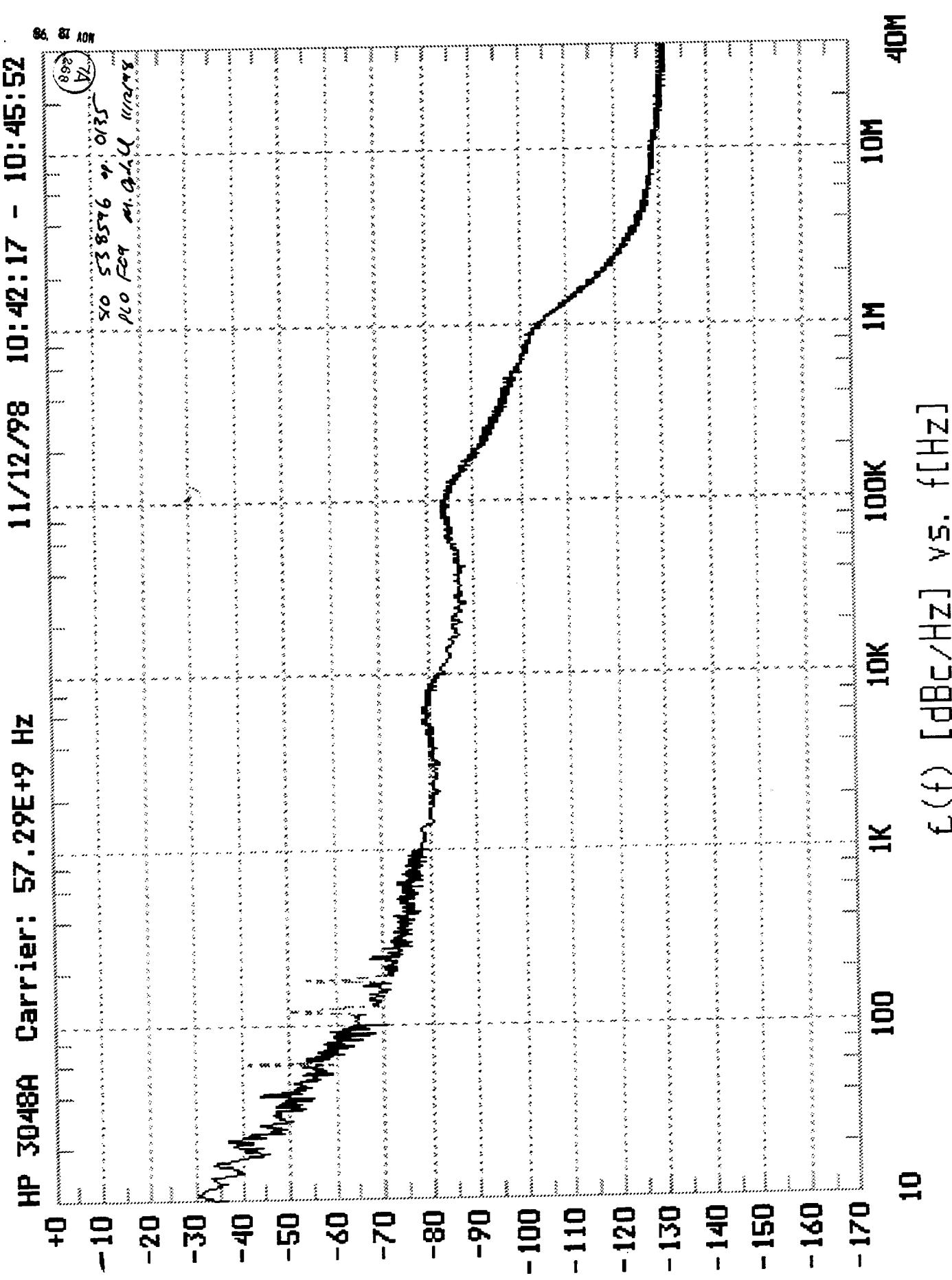


### Section 6A: AM/FM Testing - F09

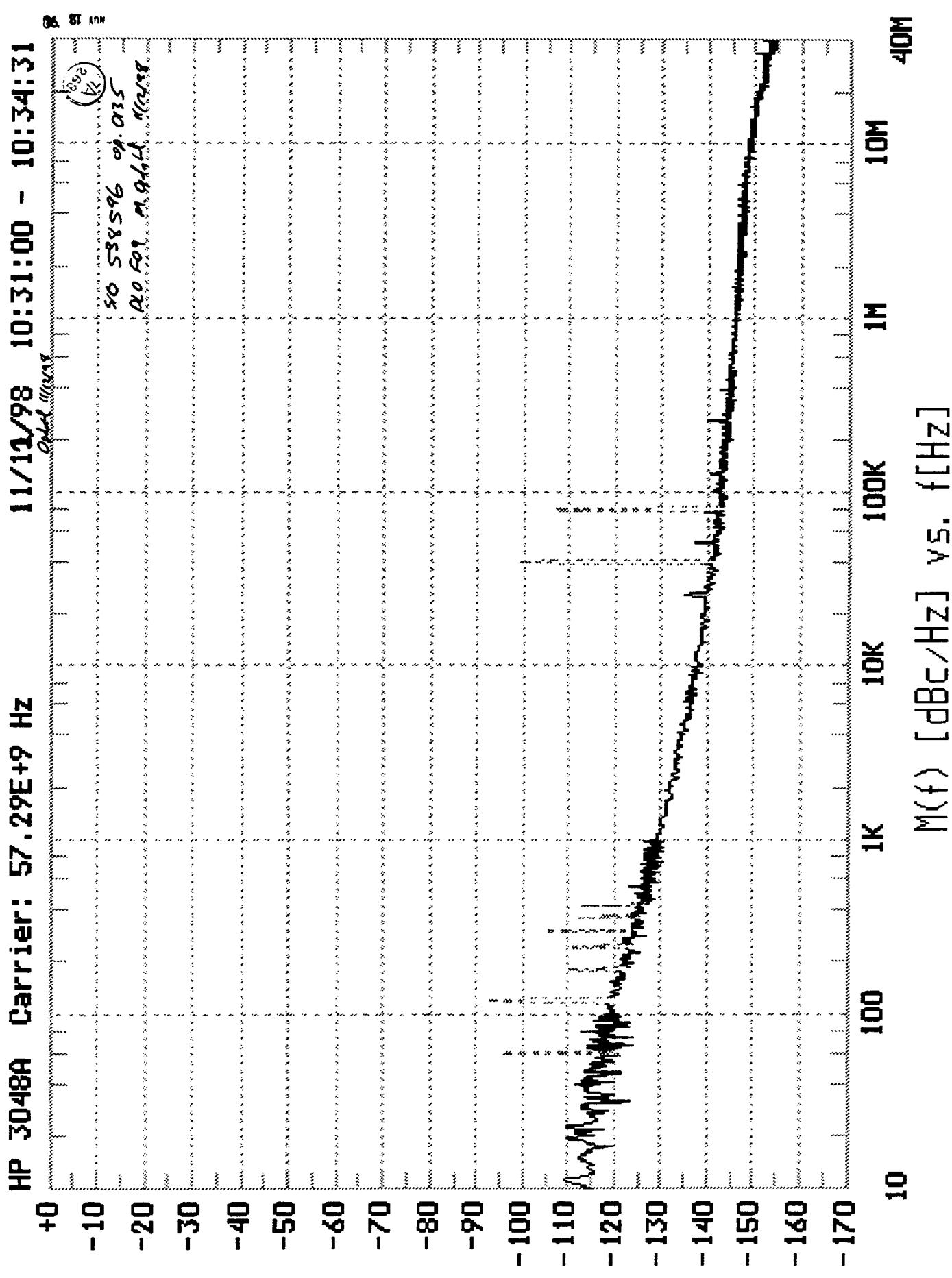
The following section contains the raw data from the AM/FM Noise Tests. Requirements are that the FM Noise level be less than -100 dBc/Hz for frequencies greater than 1 MHz. Requirements are that the AM Noise level be less than 130 dBc/Hz for all frequencies greater than 1 MHz. Both Tests Pass.

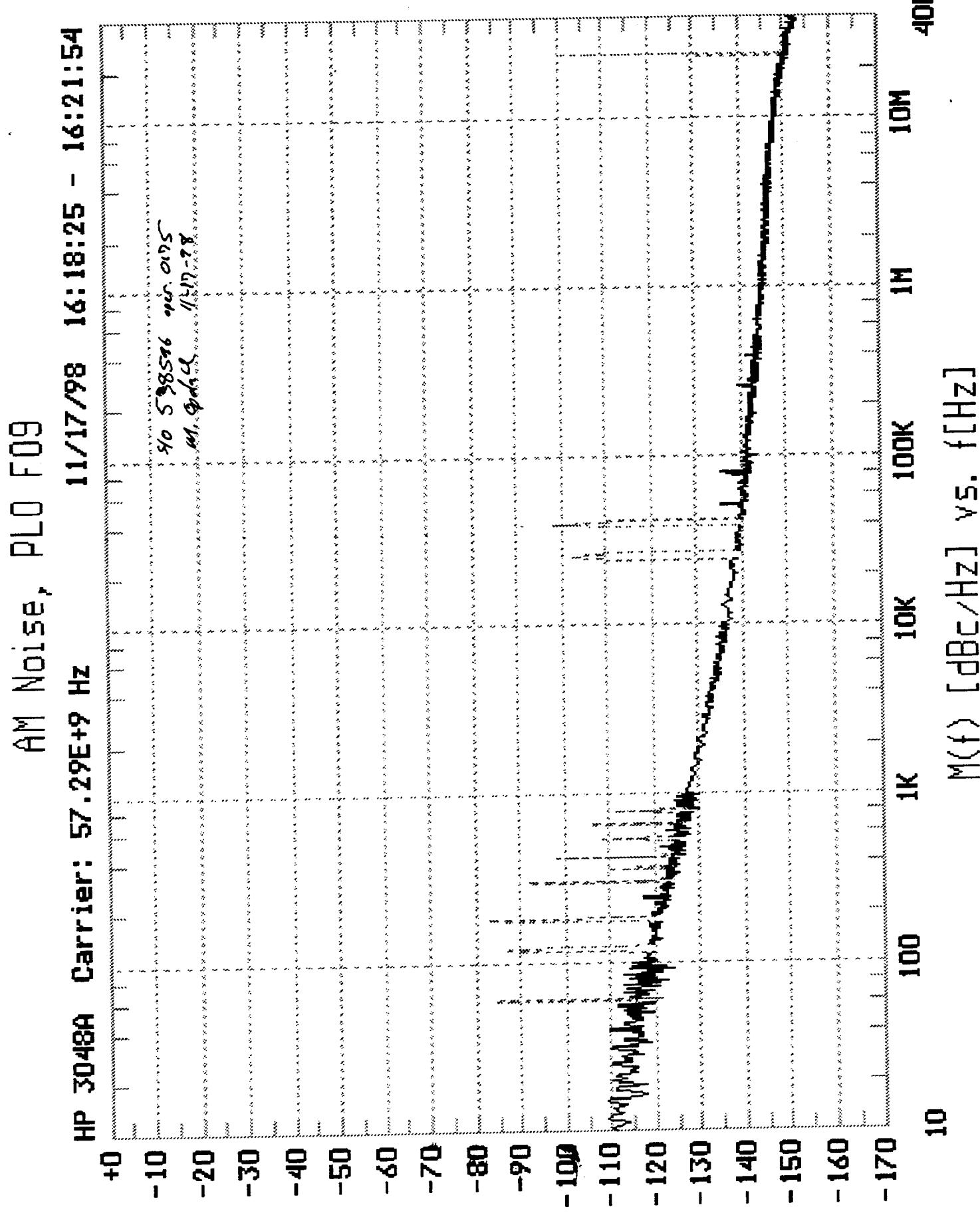


# FM Noise Test, F09

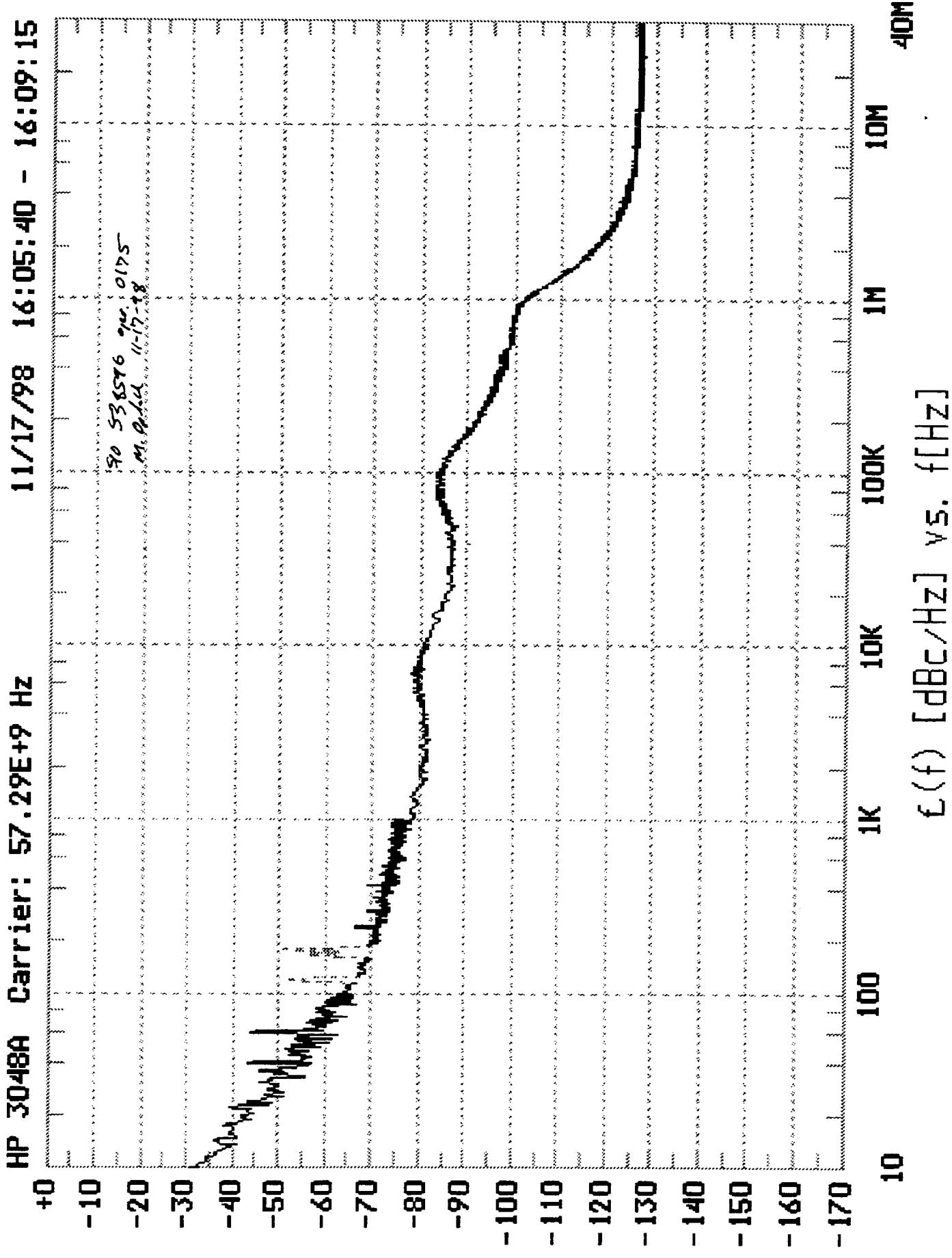


# AM Noise, F09





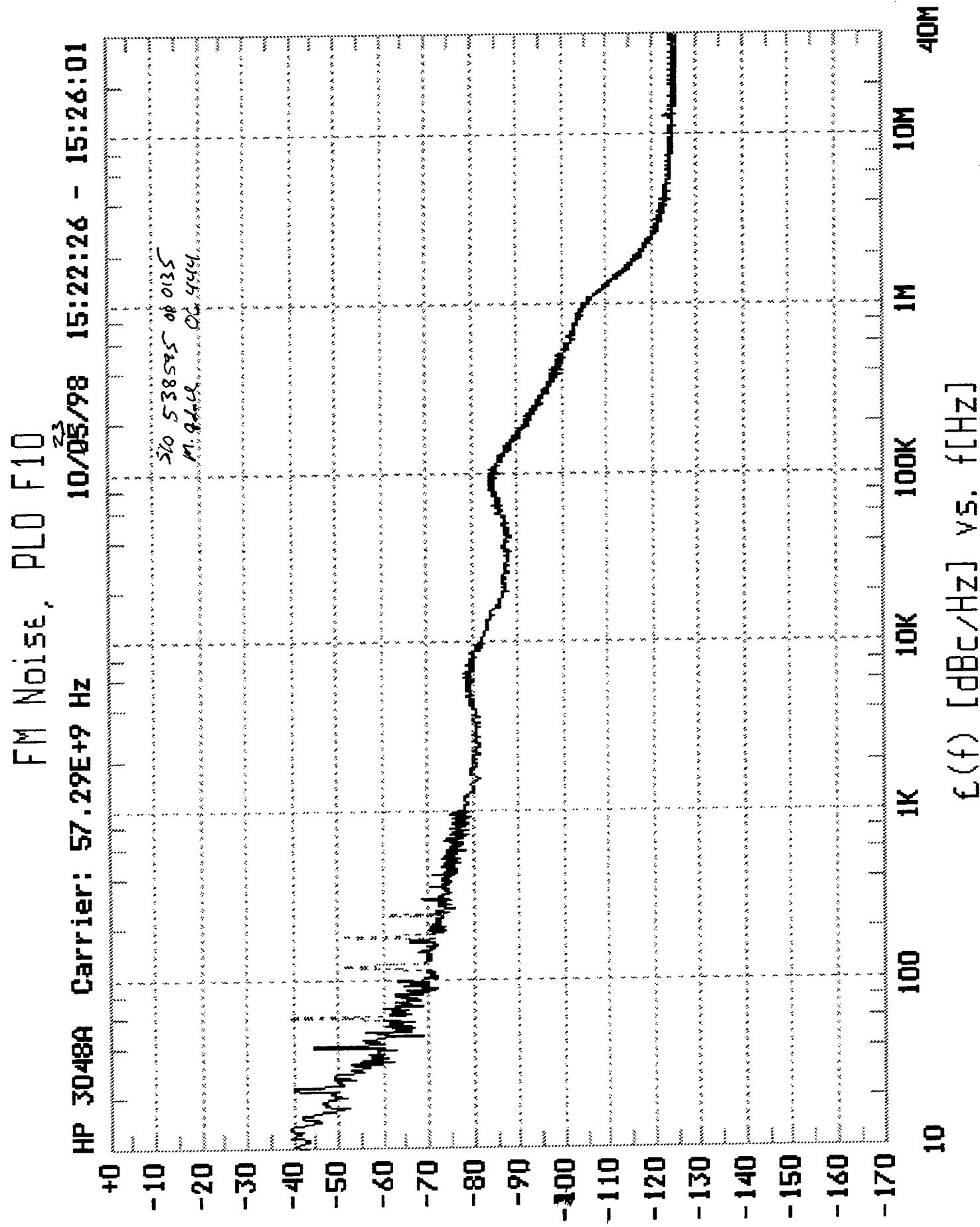
# FM Noise Test, PLO F09



### Section 6B: AM/FM - F10

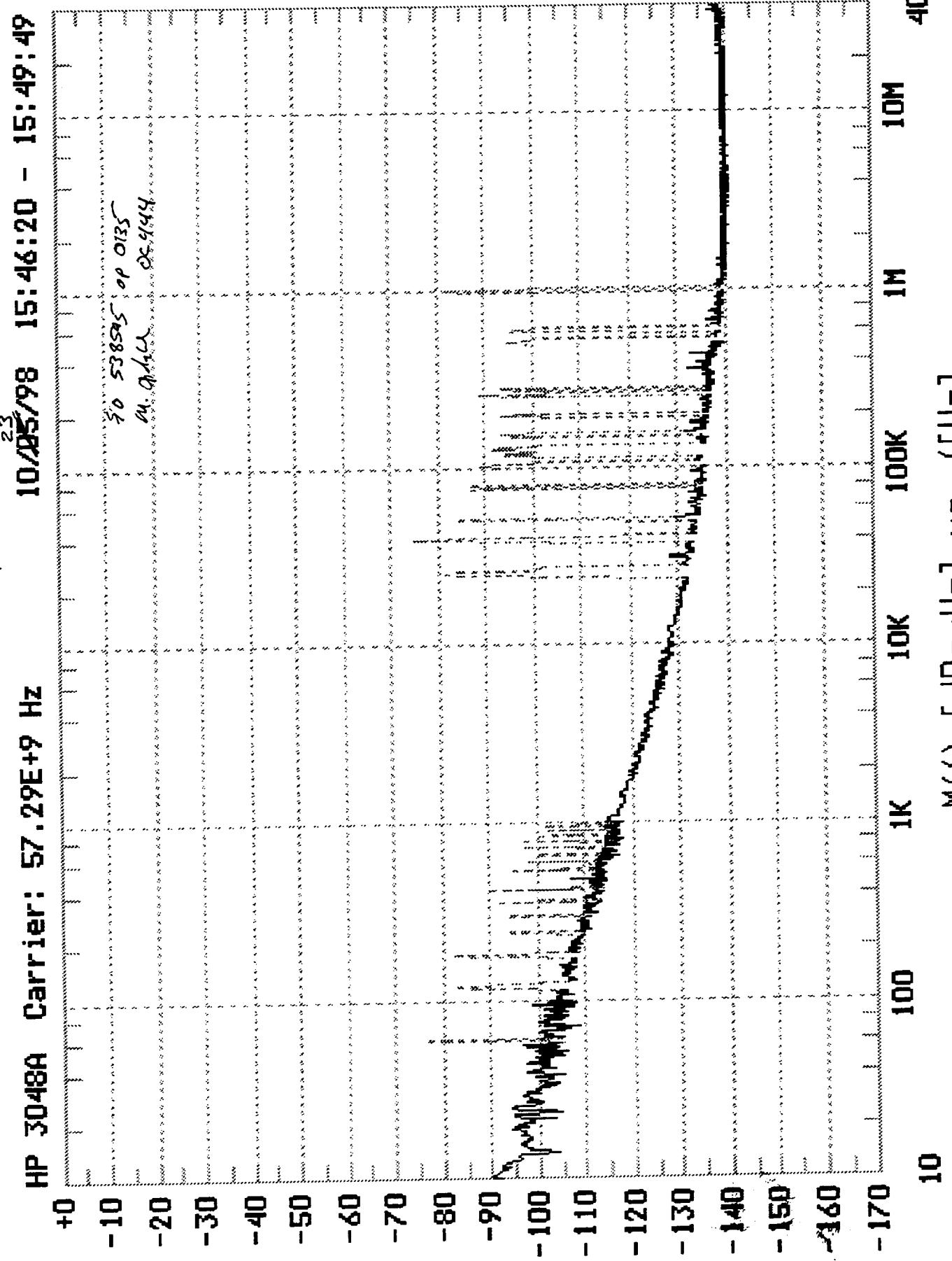
The following section contains the raw data from the AM/FM Noise Tests. Requirements are that the FM Noise level be less than -100 dBc/Hz for frequencies greater than 1 MHz. Requirements are that the AM Noise level be less than 130 dBc/Hz for all frequencies greater than 1 MHz. Both Tests pass.







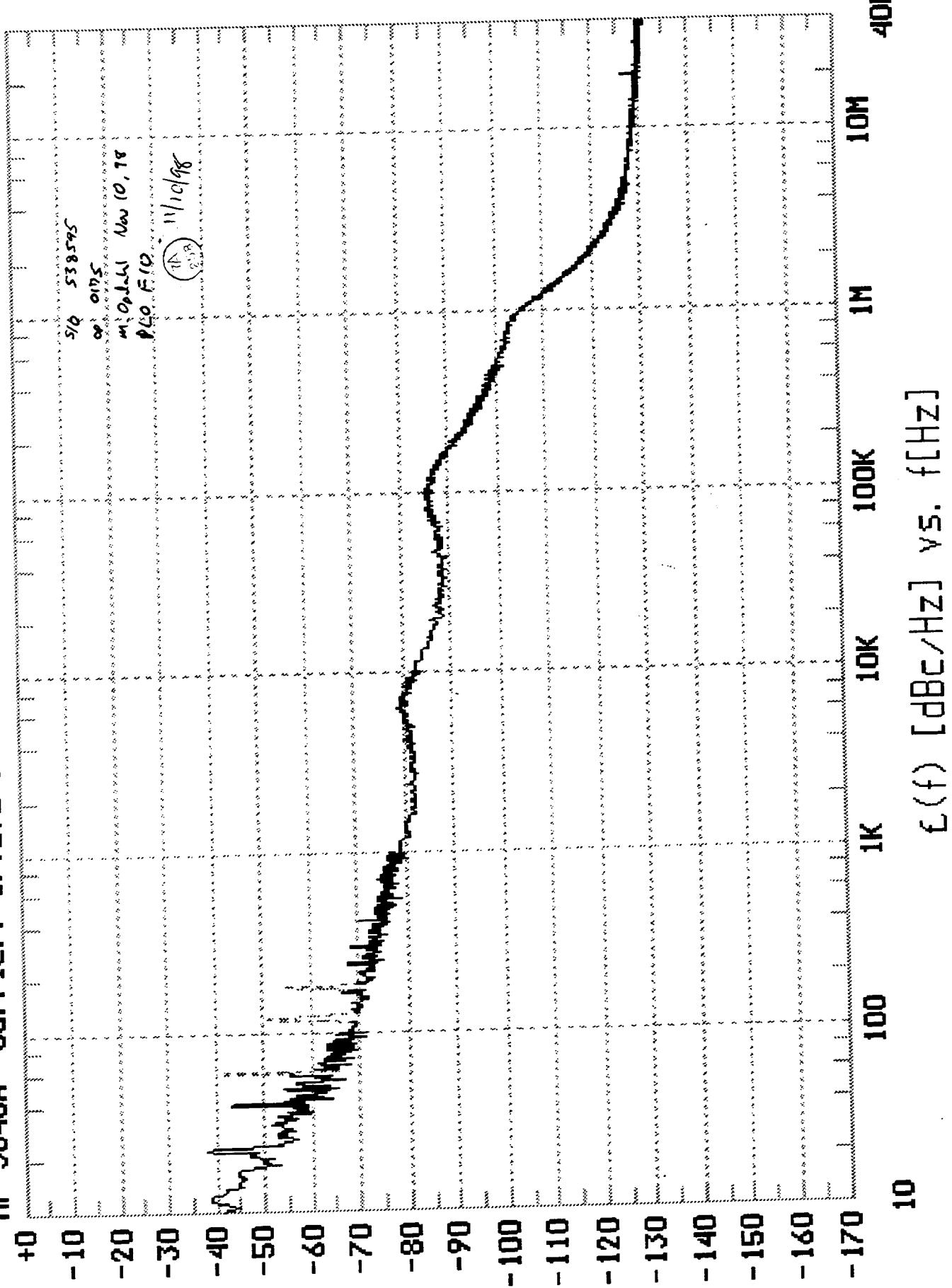
AM noi 2, F10





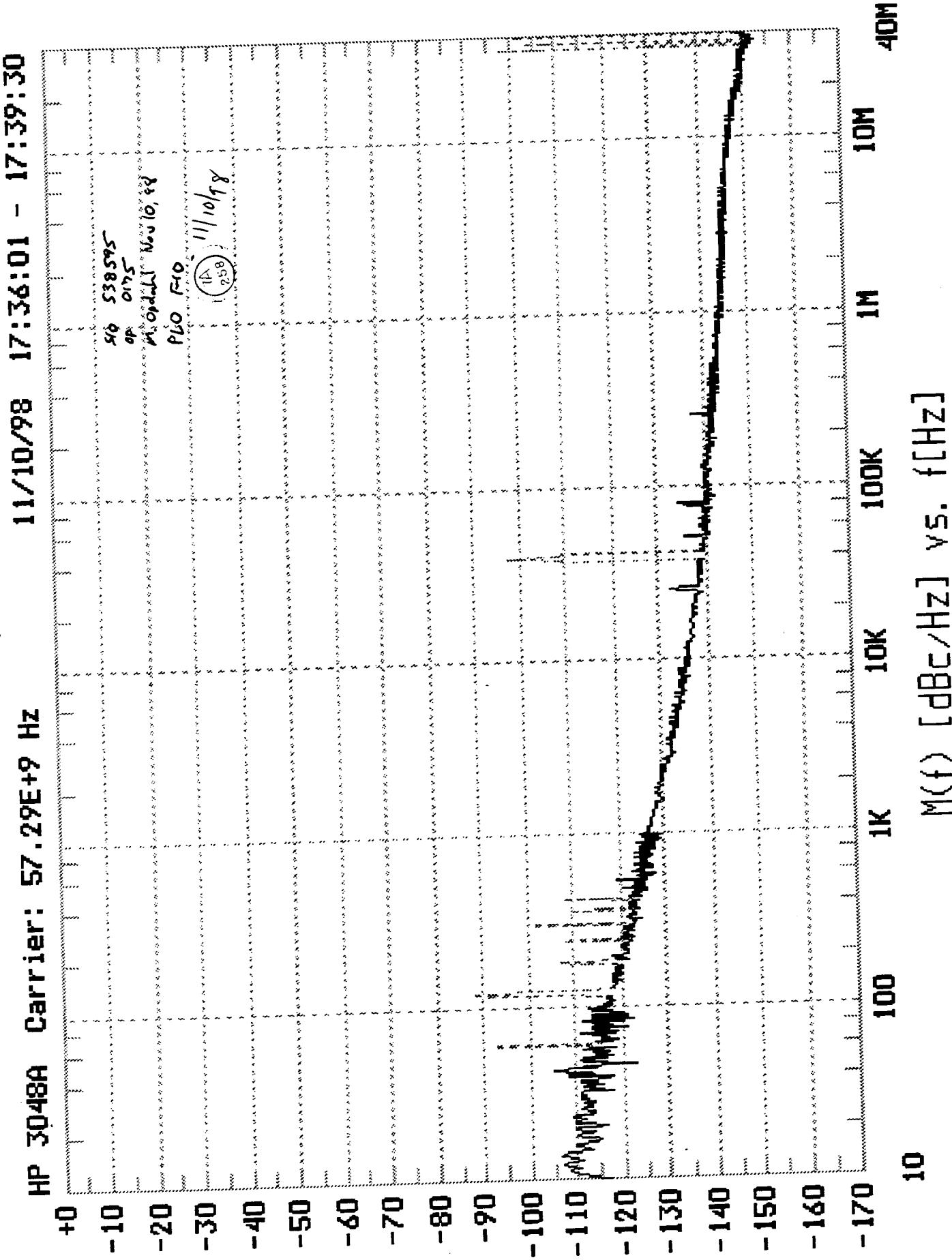
הנִמְלָאָה מִלְבָד

11/10/98 17:50:03 - 17:53:39  
Herriger, E. 57-299E+9 Hz





ת. ו. מ. ל. ב. מ. פ. ל. ו. י. ת. ו. מ. ל. ב.

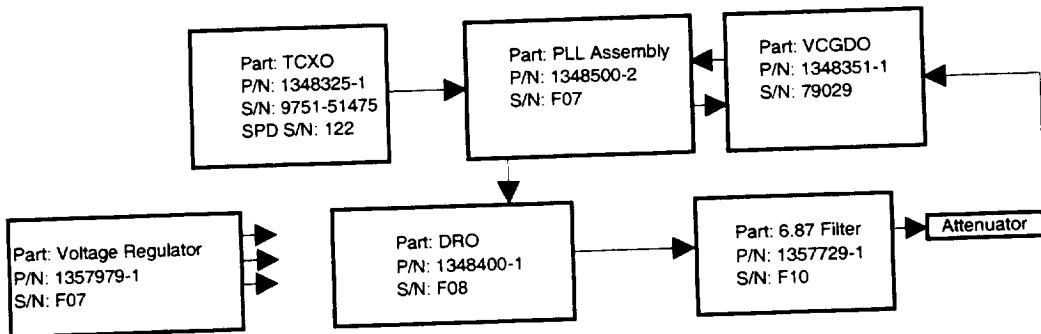




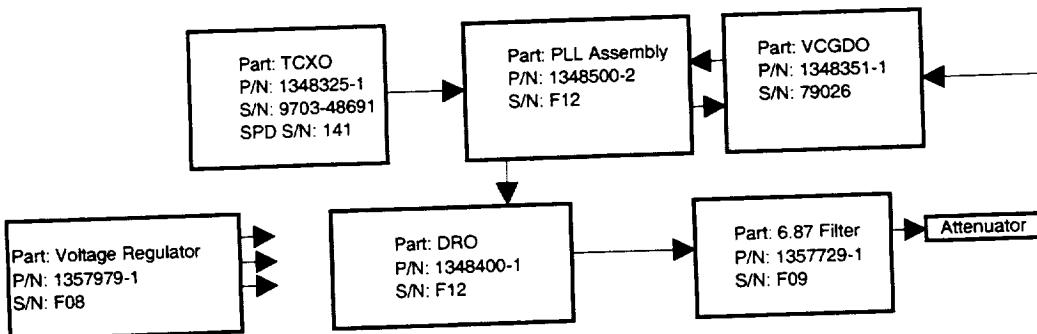
## PLO As-Built Configuration

Part Name	Part Number	Serial Number	
		F09	F10
TCXO	1348325-1	51475	48691
VCGDO	1348351-1	79029	79026
PLL Assembly	1348500-2	F07	F10
DRO Assembly	1348400-1	F08	F12
Voltage Regulator	1357979-1	F07	F08

## PLO F09



## PLO F10





## FORMS



National Aeronautics and  
Space Administration

## Report Documentation Page

1. Report No. ---	2. Government Accession No. ---	3. Recipient's Catalog No. ---	
4. Title and Subtitle  Integrated Advanced Microwave Sounding Unit-A (AMSU-A), Performance Verification Report		5. Report Date January 1999	
		6. Performing Organization Code ---	
7. Author(s)  D. Pines		8. Performing Organization Report No. 11384	
		10. Work Unit No. ---	
9. Performing Organization Name and Address Aerojet 1100 W. Hollyvale Azusa, CA 91702		11. Contract or Grant No. NAS 5-32314	
12. Sponsoring Agency Name and Address NASA Goddard Space Flight Center Greenbelt, Maryland 20771		13. Type of Report and Period Covered Final	
15. Supplementary Notes  ---		14. Sponsoring Agency Code ---	
16. ABSTRACT (Maximum 200 words )  This is the Performance Verification Report, METSAT Phase Locked Oscillator Assembly, P/N 1348360-1, S/N F09 and F10, for the Integrated Advanced Microwave Sounding Unit-A (AMSU-A).			
17. Key Words (Suggested by Author(s))  EOS Microwave System		18. Distribution Statement  Unclassified --- Unlimited	
19. Security Classif. (of this report)  Unclassified	20. Security Classif. (of this page)  Unclassified	21. No. of pages	22. Price ---

NASA FORM 1626 OCT 86



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1. AGENCY USE ONLY (Leave blank)	2. REPORT DATE	3. REPORT TYPE AND DATES COVERED	
4. TITLE AND SUBTITLE  Integrated Advanced Microwave Sounding Unit-A (AMSU-A), Performance Verification Report		5. FUNDING NUMBERS  NAS 5-32314	
6. AUTHOR(S) D. Pines		8. PERFORMING ORGANIZATION REPORT NUMBER  11384 January 1999	
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) Aerojet 1100 W. Hollyvale Azusa, CA 91702		10. SPONSORING/MONITORING AGENCY REPORT NUMBER  ---	
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES) NASA Goddard Space Flight Center Greenbelt, Maryland 20771			
11. SUPPLEMENTARY NOTES  ---			
12a. DISTRIBUTION/AVAILABILITY STATEMENT  ---		12b. DISTRIBUTION CODE  ---	
13. ABSTRACT (Maximum 200 words)  This is the Performance Verification Report, METSAT Phase Locked Oscillator Assembly, P/N 1348360-1, S/N F09 and F10, for the Integrated Advanced Microwave Sounding Unit-A (AMSU-A).			
14. SUBJECT TERMS  EOS Microwave System			15. NUMBER OF PAGES
			16. PRICE CODE  ---
17. SECURITY CLASSIFICATION OF REPORT Unclassified	18. SECURITY CLASSIFICATION OF THIS PAGE Unclassified	19. SECURITY CLASSIFICATION OF ABSTRACT Unclassified	20. LIMITATION OF ABSTRACT SAR



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INPUT FROM: D. Pines	CDRL: 208	SPECIFICATION ENGINEER: N/A	DATE
CHECKED BY: N/A	DATE	JOB NUMBER: N/A	DATE
APPROVED SIGNATURES		DEPT. NO.	DATE
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Systems Engineer (R. Platt) <u>Robert H. Platt</u>		8341	2/1/99
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